Radiation Report

TPS7H6015-SP Total Ionizing Dose (TID) Radiation Report

ABSTRACT

This report discusses the results of the total ionizing dose (TID) testing for the Texas Instruments TPS7H6015-SP radiation hardness-assured 60V, 1.3A, 2.5A, half bridge gate driver. The study was done to determine TID effects at 100krad(Si) High Dose Rate (HDR). The results show that all samples pass within device specified test limits.

Table of Contents

Trademarks

All trademarks are the property of their respective owners.

1 Device Information

1.1 Product Description

The TPS7H6015-SP is a 60V radiation-hardness-assured, gate driver for GaN FETs for space applications. The TPS7H6015-SP is designed for high-frequency, high-efficiency applications. The driver features adjustable dead time capability, small 30ns propagation delay and 5.5ns high-side and low-side matching. This part also includes internal high-side and low-side LDOs which specifies a drive voltage of 5V regardless of supply voltage. The TPS7H6015-SP is packaged in a 56-DCA (HTSSOP) package.

1.2 Device Details

Testing was performed per MIL-STD-883, Test Method 1019, with a sample size per MIL-PRF-38535, Appendix C, test condition A (high dose rate).

Table 1-1. Device and Exposure Details

RHA TID Details: Up to 100 krad(Si)	
Device Function	Half Bridge Gate Driver
Die Name	RTPS7H6005A0VM
Package	56-pin HTSSOP DCA
Technology	LBC7 (250nm Linear BiCMOS)
Quantity tested	HDR : • Five biased and five unbiased units at 100-krad(Si) levels • Two correlation units
Lot Accept/Reject	Passes 100krad(Si); no observed fails
HDR Radiation Facility	Texas Instruments CLAB Dallas, Texas
Die Lot Number and Assembly Lot Number	4095497TI1 / 4476157ML4
HDR Dose Rate	171.3 rad (Si) / s
HDR Radiation Source	Gammacell 220 Excel (GC-220E) Co-60
Irradiation and Test Temperature	Ambient, room temperature controlled to 25°C ±6°C per MIL-STD-883 and MIL-STD-750

Figure 1-1. Device Used in Exposure (Front)

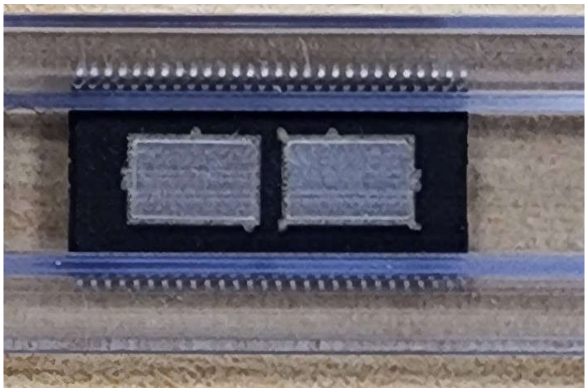


Figure 1-2. Device Used in Exposure (Back)

2 Total Dose Test Setup

2.1 Test Overview

The TPS7H6015-SP was tested according to MIL-STD-883, Test Method 1019.9. For this testing, condition A was used. For this test, the product was irradiated up to the target radiation level, and then put through full electrical parametric testing on the production Automated Test Equipment (ATE). All devices remained functional passing all parametric test limits.

2.2 Test Description and Facilities

The TPS7H6015-SP HDR exposure was performed on biased devices in a Co-60 Gammacell at the TI Dallas C-Lab facility in Dallas, Texas. The unattenuated dose rate of this cell is 171.3rad (Si)/s. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and post-radiation electrical testing at TI Dallas Forest Lane facility. Test limit guard bands are set within SMD electrical test limits.

Post-radiation measurements were taken within 30 minutes after removing device from the dry ice container. The devices were allowed to reach room temperature prior to electrical post-radiation measurements.

2.3 Test Setup Details

The devices under HDR exposure were tested in two conditions, biased and unbiased, as described in the following sections.

2.3.1 Unbiased

For the unbiased HDR conditions, the exposure was performed with all pins grounded.

2.3.2 Biased

Table 2-1. DUT Power Supply Bias and V_{out} Measurements

Power Supply Bias				
	Edge Connector	BUS	Typical	Comments
Power Supply	BUS A	VIN	14VDC	14VDC - Fixed power supply
	BUS D	BOOT	12VDC	14VDCWRTSW - Floating power supply WRT to SW
	BUS B	ASW	0-150V	Increase HV gradually. Recommend using safety interlock HV protection when working with high voltage.
DUT Measurements				
VOUT Test Points	TP_VIN	VIN	14V	14VDC - Fixed power supply
	TP_BOOT	BOOT	12V	12VDCWRTSW - Floating power supply WRT to SW
	TP_SW	SW = PSW = ASW	0-150V	SW = PSW = ASW

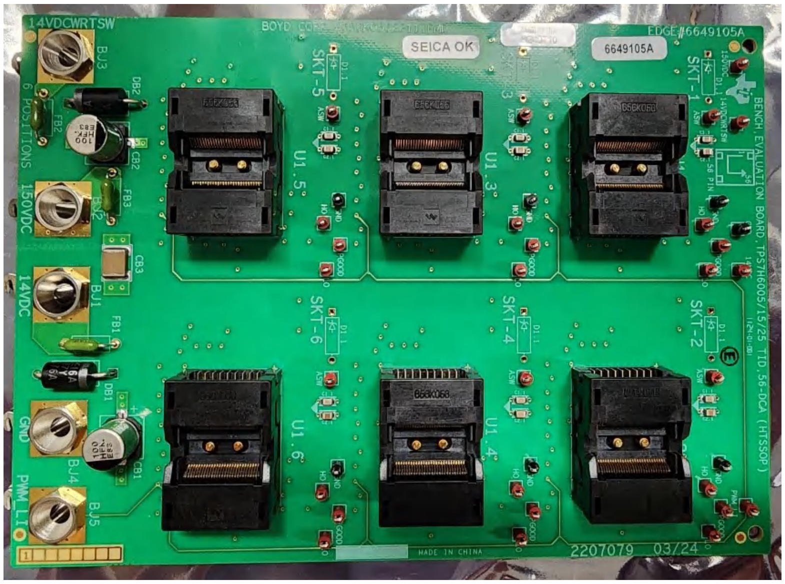


Figure 2-1. HDR TID Hardware

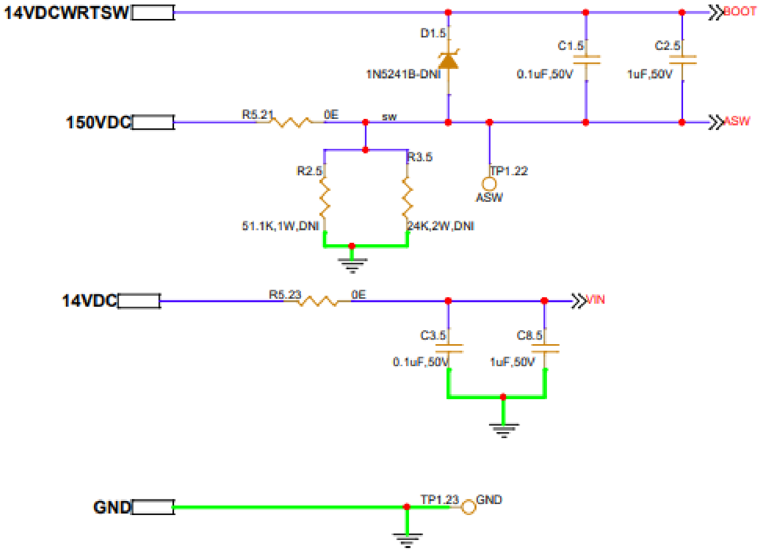


Figure 2-2. Supplies and GND HDR TID Bias Diagram

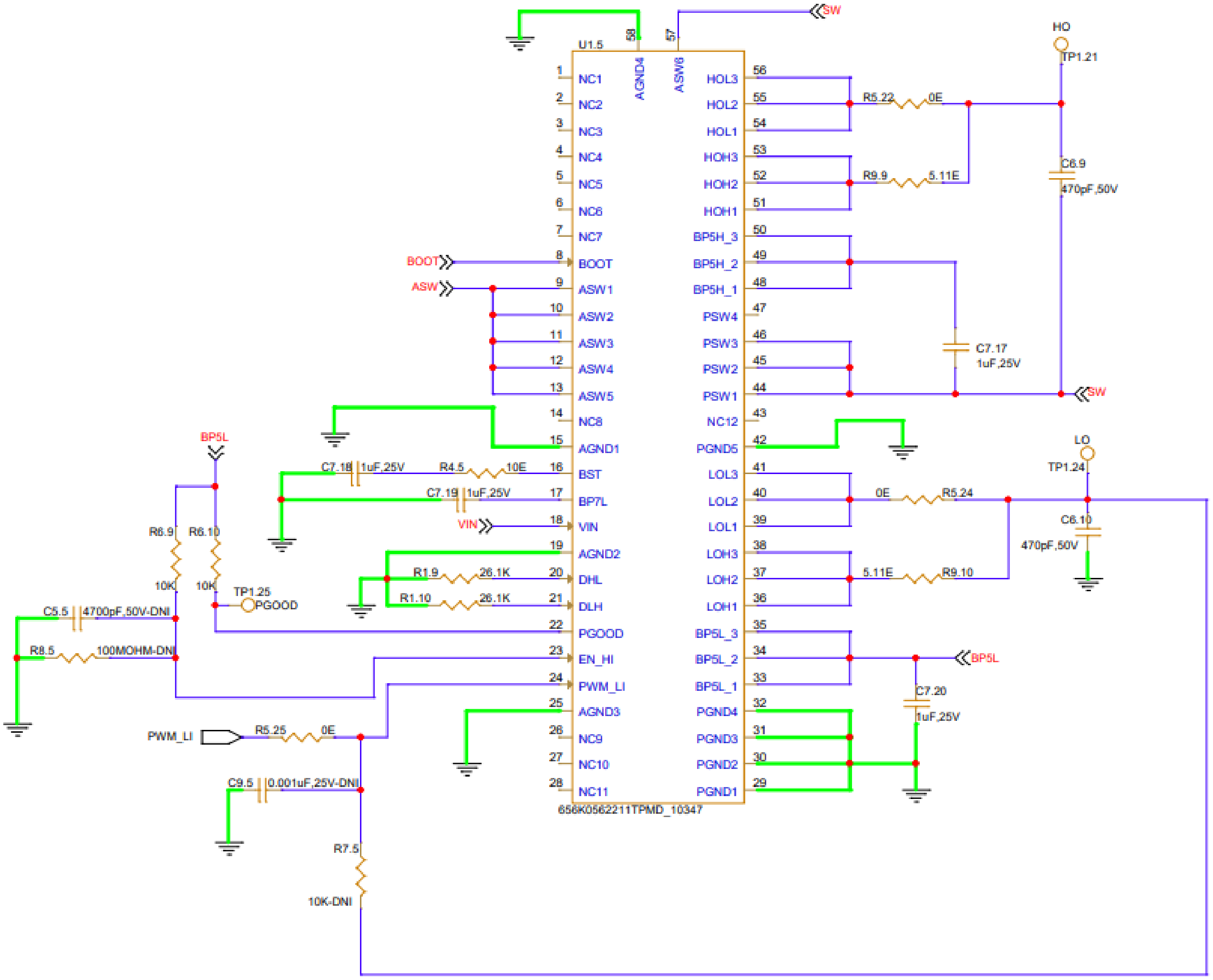


Figure 2-3. HDR TID Bias Diagram

2.4 Test Configuration and Conditions

HDR devices were stressed up to 100krad (Si) for biased and unbiased conditions.

Table 2-2. HDR Biased Device Information

Total Samples: 5 units + 2 control	
Exposure Levels:	
Control	100 krad (Si)
1, 2	Removed 23, 24, 25, 26, 27

Table 2-3. HDR Unbiased Device Information

Total Samples: 5 units + 2 control	
Exposure Levels:	
Control	100 krad (Si)
1, 2	48, 49, 50, 51, 52

3 TID Characterization Test Results

3.1 TID Characterization Results Summary

Test results show devices are fully functional and within specification limits up to 100krad(Si) HDR. Overall, device TPS7H6015-SP is radiation harden to TID HDR exposure levels at 100krad(Si) under bias and un-bias conditions. Performance is measured based on the difference between pre- and post-irradiation with respect to SMD electrical minimum and maximum specification. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each dose level for both biased and unbiased (see Section 3.2 for the electrical parameters). Note that test numbers are listed only for parameters tested post-TID.

See Appendix A for HDR report.

3.2 Data Sheet Electrical Parameters

Specifications are at ambient temperature TA = 25°C, VIN = 10V to 14V, VBP5L = VBP5H = 5V, and no load on LOH, LOL, HOH, and HOL (unless otherwise noted).

Table 3-1. TPS7H6015-SP Data Sheet Electrical Parameters

Parameter		Test Conditions		MIN	MAX	UNIT	Test Number
SUPPLY CURRENTS							
I_{QLS}	Low-side quiescent current	VIN = 12V, BOOT = 10V	MODE = PWM, EN = 0V		6.8	mA	35.0, 36.0, 37.0
			MODE = IIM LI = HI = 0V		8		35.2, 36.2, 37.2
I_{QHS}	High-side quiescent current	VIN = 12V, BOOT = 10V	MODE = PWM EN = 0V		6.3	mA	35.1, 36.1, 37.1
			MODE = IIM LI = HI = 0V		6.3		35.3, 36.3, 37.3
I_{OP_LS}	Low-side operating current	MODE = PWM, no load for HOL and HOH	f = 500kHz		9	mA	35.6, 36.6, 37.6
			f = 1MHz		11		35.8, 36.8, 37.8
			f = 2MHz		16		35.1, 36.1, 37.1
			f = 5MHz		30		35.12, 36.12, 37.12
		MODE = IIM, no load for HOL and HOH	f = 500kHz		9		35.14, 36.14, 37.14
			f = 1MHz		12		35.16, 36.16, 37.16
			f = 2MHz		17		35.18, 36.18, 37.18
			f = 5MHz		30		35.2, 36.2, 37.2
I_{OP_HS}	High-side operating current	MODE = PWM, no load for HOL and HOH	f = 500kHz		6.5	mA	35.7, 36.7, 37.7
			f = 1MHz		8		35.9, 36.9, 37.9
			f = 2MHz		10.5		35.11, 36.11, 37.11
			f = 5MHz		19		35.13, 36.13, 37.13
		MODE = IIM, no load for HOL and HOH	f = 500kHz		6.5		35.15, 36.15, 37.15
			f = 1MHz		8		35.17, 36.17, 37.17
			f = 2MHz		10.5		35.19, 36.19, 37.19
			f = 5MHz		15		35.21, 36.21, 37.21
GATE DRIVER							
V_{OL}	Low-level output voltage	I_{OL} = 100mA			0.15	V	45.0, 46.0, 47.0
BP5x – V_{OH}	High-level output voltage	I_{OH} = 100mA			0.3	V	45.2, 46.2, 47.2
I_{OH}	Peak source current	HOH, LOH = 0V, BP5x = 5V		0.7	2.3	A	50, 50.1, 51, 51.1, 52, 52.1
I_{OL}	Peak sink current	HOL, LOL = 5V, BP5x = 5V		1.6	4.6	A	50.2, 51.2, 52.2
INTERNAL REGULATORS							
V_{BP5L}	Low-side 5V regulator output voltage	C_{BP5L} = 1µF		4.75	5.175	V	60.1, 60.4, 60.7, 60.10, 60.13, 60.16, 60.19, 60.22, 61.1, 61.4, 61.7, 61.1, 61.13, 61.16, 61.19, 61.22, 62.1, 62.4, 62.7, 62.1, 62.13, 62.16, 62.19, 62.22
V_{BP5H}	High-side 5V regulator output voltage	C_{BP5H} = 1µF		4.75	5.175	V	60.2, 60.5, 60.8, 60.11, 60.14, 60.17, 60.2, 60.23, 61.2, 61.5, 61.8, 61.11, 61.14, 61.17, 61.2, 61.23, 62.2, 62.5, 62.8, 62.11, 62.14, 62.17, 62.2, 62.23
V_{BP7L}	7V regulator output voltage	C_{BP7L} = 1µF		6.65	7.35	V	60.0, 60.3, 60.6, 60.9, 60.12, 60.15, 60.18, 60.21, 61.0, 61.3, 61.6, 61.9, 61.12, 61.15, 61.18, 61.21, 61.23, 62.0, 62.3, 62.6, 62.9, 62.12, 62.15, 62.18, 62.21
UNDERVOLTAGE PROTECTION							
$BP5H_R$	BP5H UVLO rising threshold	C_{BP5H} = 1µF		4	4.5	V	85.1, 86.1, 87.1(1)
$BP5H_F$	BP5H UVLO falling threshold	C_{BP5H} = 1µF		3.8	4.3	V	85.2, 86.2, 87.2(1)
$BP5L_R$	BP5L UVLO rising threshold	C_{BP5L} = 1µF		4	4.5	V	80.1, 81.1, 82.1(1)
$BP5L_F$	BP5L UVLO falling threshold	C_{BP5L} = 1µF		3.8	4.3	V	80.2, 81.2, 82.2(1)
$BP7L_R$	BP7L UVLO rising threshold	C_{BP7L} = 1µF		6.2	6.8	V	80.4, 81.4, 82.4(1)

Table 3-1. TPS7H6015-SP Data Sheet Electrical Parameters (continued)

Parameter		Test Conditions		MIN	MAX	UNIT	Test Number
$BP7L_F$	BP7L UVLO falling threshold	C_{BP7L} = 1µF		5.9	6.5	V	80.5, 81.5, 82.5(1)
VIN_R	VIN UVLO rising threshold			8	9	V	70.0
VIN_F	VIN UVLO falling threshold			7.5	8.5	V	70.1
$BOOT_R$	BOOT UVLO rising threshold			6.6	7.4	V	75.0
$BOOT_F$	BOOT UVLO falling threshold			6.2	7	V	75.1
INPUT PINS							
V_{IR}	Input rising edge threshold			1.80	2.65	V	90.0, 91.0, 92.0, 90.3, 91.3, 92.3
V_{IF}	Input falling edge threshold			1.15	1.85	V	90.1, 91.1, 92.1, 90.4, 91.4, 92.4
R_{PD}	Input pull-down resistance	V = 2.15V applied at input (EN_HI or PWM_LI)		100	400	kΩ	90.6, 90.7, 91.6, 91.7, 92.6, 92.7
PROGRAMMABLE DEAD TIME							
T_{DLH}	LO off to HO on dead time	MODE = PWM, LO falling to HO rising (90% to 10%), f ≤ 2MHz	RLH = 3.32kΩ	0	10	ns	95.0, 95.5, 95.1, 96, 96.5, 96.10, 97, 97.5, 97.1
			RLH = 11.8kΩ	8	15.5		95.1, 95.6, 95.11, 96.1, 96.6, 96.11, 97.1, 97.6, 97.11
			RLH = 21kΩ	15.5	24		95.2, 95.7, 95.12, 96.2, 96.7, 96.12, 97.2, 97.7, 97.12
			RLH = 52.3kΩ	36	59		95.3, 95.8, 95.13, 96.3, 96.8, 96.13, 97.3, 97.8, 97.13
			RLH = 105kΩ	74	113.5		95.4, 95.9, 95.14, 96.4, 96.9, 96.14, 97.4, 97.9, 97.14
T_{DHL}	HO off to LO on dead time	MODE = PWM, HO falling to LO rising (90% to 10%), f ≤ 2MHz	RHL = 7.87kΩ	0	10	ns	95.19, 95.24, 95.29, 96.19, 96.24, 96.29, 97.19, 97.24, 97.29
			RHL = 13.3kΩ	6	14		95.20, 95.25, 95.30, 96.20, 96.25, 96.30, 97.20, 97.25, 97.30
			RHL = 23.7kΩ	16	24.5		95.21, 95.26, 95.31, 96.21, 96.26, 96.31, 97.21, 97.26, 97.31
			RHL = 57.6kΩ	44	61		95.22, 95.27, 95.32, 96.22, 96.27, 96.32, 97.22, 97.27, 97.32
			RHL = 113kΩ	81	125		95.23, 95.28, 95.33, 96.23, 96.28, 96.33, 97.23, 97.28, 97.33
BOOTSTRAP DIODE SWITCH							
	Bootstrap diode switch parallel resistance	I_{BST_SW} = 1mA		0.8	1.2	kΩ	100.1, 101.1, 102.1
POWER GOOD							
	Logic-low output	I_{FLT}= 1mA			0.4	V	105.0, 106.0, 107.0
	PGOOD internal resistance	BP5L = 5V, BP7L = 7V, VIN = 12V		0.7	1.9	MΩ	105.2, 106.2, 107.2
	Minimum BP5L voltage for valid PGOOD output				2.45	V	105.1, 106.1, 107.1

(1) Tests are only tested in production or SPI test mode.

Table 3-2. TPS7H6015-SP Switching Characteristics

Parameter		Test Conditions		MIN	MAX	UNIT	Test Number
t_{LPHL}	LO turnoff propagation delay	MODE = PWM	PWM rising to LOL falling		48	ns	110, 111, 112
		MODE = IIM	LI falling to LOL falling		38	ns	110.3, 110.7, 111.3, 111.7, 112.3, 112.7
t_{LPLH}	LO turnon propagation delay	MODE = IIM	LI rising to LOH rising		38	ns	110.2, 110.6, 111.2, 111.6, 112.2, 112.6
t_{HPHL}	HO turnoff propagation delay	MODE = PWM	PWM falling to HOL falling		50	ns	110.1, 111.1,112.1
		MODE = IIM	HI falling to HOL falling		40		110.5, 110.9, 111.5, 111.9, 112.5, 112.9
t_{HPLH}	HO turnon propagation delay	MODE = IIM	HI rising to HOH rising		40	ns	110.4, 110.8, 111.4, 111.8, 112.4, 112.8
t_{MON}	Delay matching LO on and HO off	MODE = IIM			12	ns	110.12, 111.12, 112.12
t_{MOFF}	Delay matching LO off and HO on	MODE = IIM			4	ns	110.11, 110.13, 111.11, 111.13, 112.11, 112.13
t_{HRC}	HO rise time	C_L = 1000pF	10% to 90%		7.5	ns	115, 116, 117
t_{LRC}	LO rise time				7.5	ns	115.2, 116.2, 117.2
t_{HFC}	HO fall time		90% to 10%		5.5	ns	115.1, 116.1, 117.1
t_{LFC}	LO fall time				5.5	ns	115.3, 116.3, 117.3
t_{PW_IIM}	Minimum input pulse width (turn-on)	MODE = IIM			8	ns	120, 120.2, 120.4, 121, 121.2, 121.4, 122, 122.2, 122.4
$t_{PW\_IIM\_OFF}$	Minimum input pulse width (turn-off)	MODE = IIM			12	ns	120.1, 120.3, 120.5, 121.1, 121.3, 121.5, 122.1, 122.3, 122.5

4 Applicable and Reference Documents

4.1 Applicable Documents

- Texas Instruments, *TPS7H6015-SP Radiation-Hardness-Assured 60-V, 1.3A, 2.5A, Half-Bridge GaN FET Gate Driver*, data sheet.
- Texas Instruments, *TPS7H6005EVM-CVAL Evaluation Module User's Guide*, EVM user's guide.
- Texas Instruments, *TPS7H6005-SP Single-Event Effects (SEE) Report*, radiation report.

4.2 Reference Documents

Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

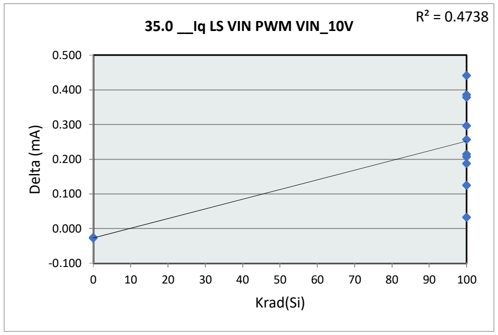
A Appendix: HDR TID Report

A Appendix: HDR TID Report

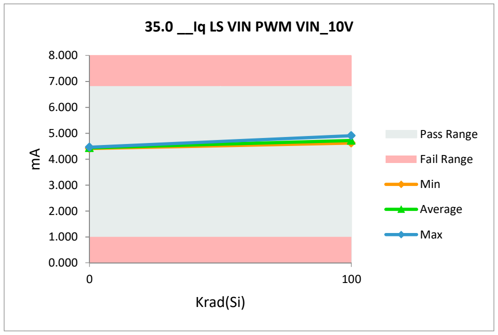
This appendix provides the TPS7H6015-SP HDR TID report data.

TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.0 __Iq LS VIN PWM VIN_10V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.8	6.8	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.481	4.453	-0.028
0	2	4.433	4.407	-0.026
100	23	4.538	4.662	0.124
100	24	4.492	4.788	0.296
100	25	4.517	4.902	0.385
100	26	4.289	4.730	0.441
100	27	4.532	4.788	0.256
100	48u	4.441	4.628	0.187
100	49u	4.408	4.621	0.214
100	50u	4.446	4.652	0.206
100	51u	4.437	4.815	0.378
100	52u	4.590	4.622	0.032
	Max	4.590	4.902	0.441
	Average	4.467	4.672	0.206
	Min	4.289	4.407	-0.028
	Std Dev	0.078	0.144	0.158



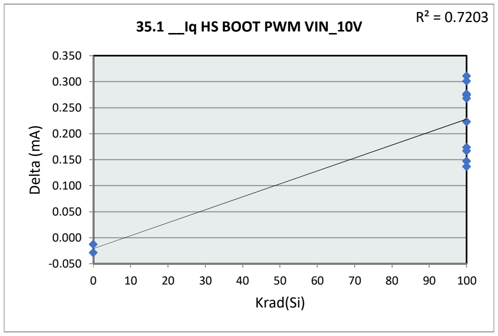
	35.0 __Iq LS VIN PWM VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.407	4.621
Average	4.430	4.721
Max	4.453	4.902
UL	6.800	6.800



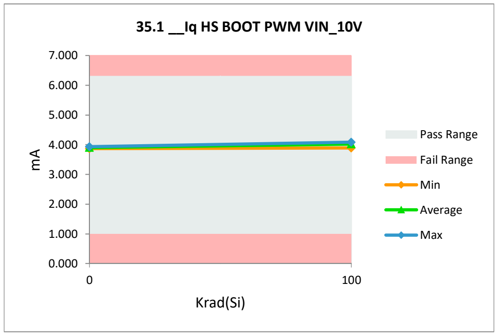
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	35.1 __Iq HS BOOT PWM VIN_1	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	mA	mA
Max Limit	6.3	6.3
Min Limit	1	1

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.881	3.868	-0.013
0	2	3.957	3.929	-0.029
100	23	3.770	4.081	0.311
100	24	3.802	4.069	0.268
100	25	3.779	4.081	0.301
100	26	3.742	3.890	0.148
100	27	3.746	3.969	0.223
100	48u	3.936	4.073	0.137
100	49u	3.838	4.011	0.174
100	50u	3.876	4.043	0.167
100	51u	3.682	3.957	0.274
100	52u	3.784	4.061	0.277
	Max	3.957	4.081	0.311
	Average	3.816	4.003	0.186
	Min	3.682	3.868	-0.029
	Std Dev	0.083	0.078	0.114

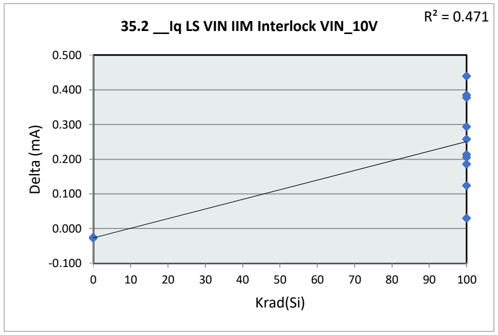


	35.1 __Iq HS BOOT PWM VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.3	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	3.868	3.890
Average	3.899	4.023
Max	3.929	4.081
UL	6.300	6.300

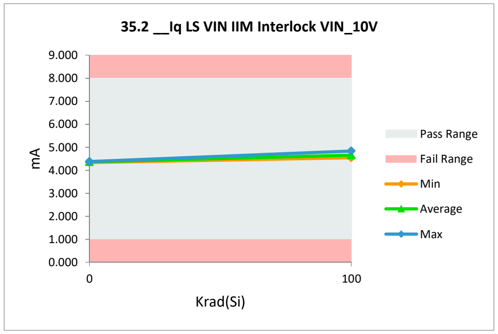


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.2 __Iq LS VIN IIM Interlock V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.409	4.381	-0.028
0	2	4.362	4.336	-0.026
100	23	4.465	4.589	0.123
100	24	4.421	4.714	0.293
100	25	4.445	4.830	0.385
100	26	4.217	4.656	0.439
100	27	4.461	4.718	0.257
100	48u	4.369	4.555	0.186
100	49u	4.336	4.549	0.213
100	50u	4.374	4.579	0.205
100	51u	4.366	4.743	0.377
100	52u	4.519	4.548	0.030
	Max	4.519	4.830	0.439
	Average	4.395	4.600	0.205
	Min	4.217	4.336	-0.028
	Std Dev	0.078	0.144	0.157

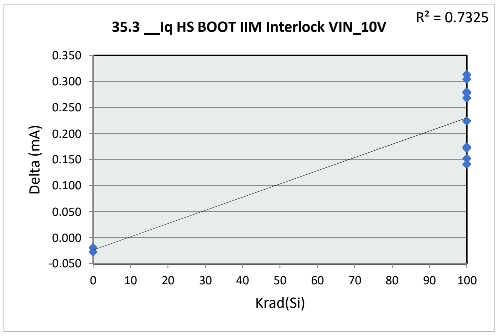


	35.2 __Iq LS VIN IIM Interlock VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.336	4.548
Average	4.359	4.648
Max	4.381	4.830
UL	8.000	8.000

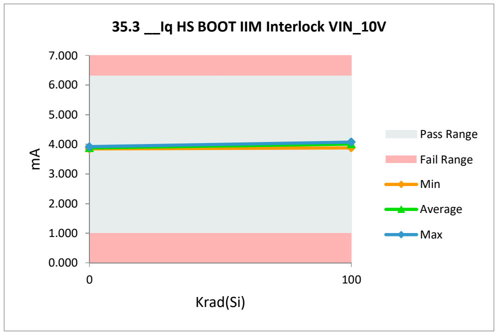


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.3 __Iq HS BOOT IIM Interloc		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.3	6.3	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.868	3.849	-0.020
0	2	3.945	3.917	-0.028
100	23	3.757	4.070	0.313
100	24	3.790	4.058	0.268
100	25	3.765	4.070	0.305
100	26	3.728	3.880	0.152
100	27	3.733	3.957	0.224
100	48u	3.923	4.064	0.141
100	49u	3.825	3.999	0.174
100	50u	3.863	4.035	0.172
100	51u	3.669	3.947	0.278
100	52u	3.772	4.052	0.280
	Max	3.945	4.070	0.313
	Average	3.803	3.991	0.188
	Min	3.669	3.849	-0.028
	Std Dev	0.083	0.079	0.116

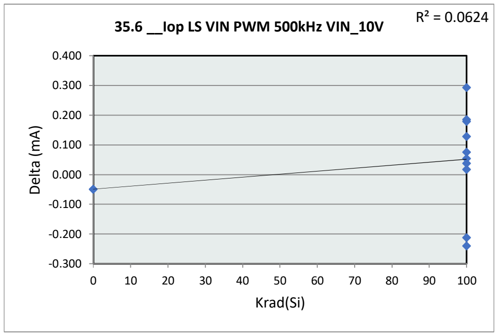


	35.3 __Iq HS BOOT IIM Interlock VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.3	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	3.849	3.880
Average	3.883	4.013
Max	3.917	4.070
UL	6.300	6.300

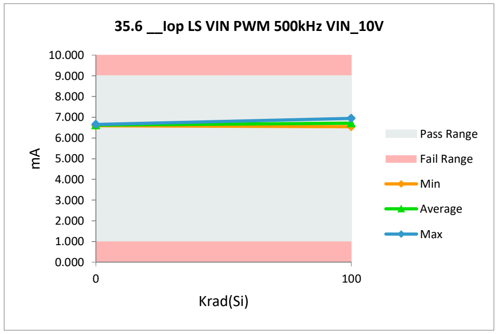


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.6 __Iop LS VIN PWM 500kHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		9	9	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	6.696	6.647	-0.049
0	2	6.634	6.584	-0.049
100	23	6.791	6.579	-0.212
100	24	6.690	6.818	0.128
100	25	6.755	6.941	0.185
100	26	6.477	6.770	0.293
100	27	6.721	6.738	0.017
100	48u	6.536	6.573	0.038
100	49u	6.611	6.687	0.076
100	50u	6.612	6.666	0.054
100	51u	6.670	6.848	0.178
100	52u	6.785	6.546	-0.240
	Max	6.791	6.941	0.293
	Average	6.665	6.700	0.035
	Min	6.477	6.546	-0.240
	Std Dev	0.096	0.125	0.157

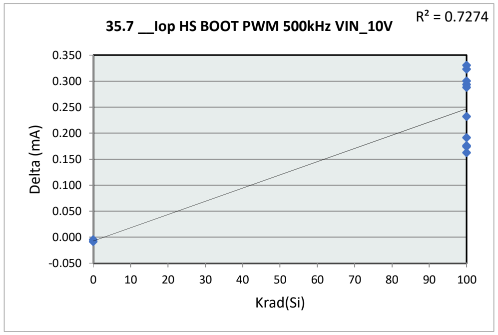


	35.6 __Iop LS VIN PWM 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	6.585	6.546
Average	6.616	6.717
Max	6.647	6.941
UL	9.000	9.000

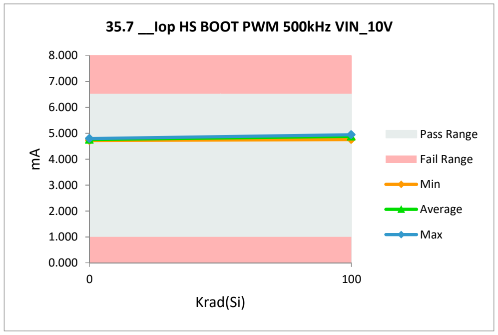


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.7 __Iop HS BOOT PWM 500kH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		6.5	6.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.723	4.718	-0.005
0	2	4.798	4.789	-0.009
100	23	4.608	4.938	0.330
100	24	4.643	4.931	0.288
100	25	4.619	4.942	0.323
100	26	4.578	4.752	0.174
100	27	4.586	4.818	0.232
100	48u	4.778	4.941	0.162
100	49u	4.673	4.849	0.176
100	50u	4.720	4.911	0.191
100	51u	4.524	4.818	0.293
100	52u	4.623	4.923	0.300
	Max	4.798	4.942	0.330
	Average	4.656	4.861	0.205
	Min	4.524	4.718	-0.009
	Std Dev	0.084	0.081	0.116

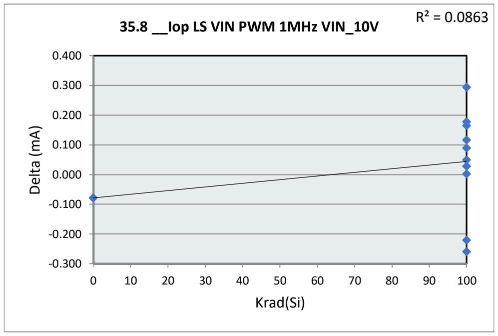


	35.7 __Iop HS BOOT PWM 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.718	4.752
Average	4.753	4.882
Max	4.789	4.942
UL	6.500	6.500

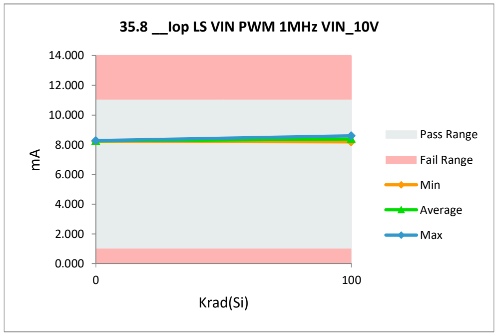


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.8 __Iop LS VIN PWM 1MHz VI		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		11	11	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	8.353	8.275	-0.078
0	2	8.300	8.221	-0.079
100	23	8.452	8.231	-0.221
100	24	8.352	8.468	0.116
100	25	8.422	8.599	0.178
100	26	8.141	8.435	0.293
100	27	8.384	8.386	0.002
100	48u	8.201	8.229	0.028
100	49u	8.280	8.370	0.089
100	50u	8.277	8.326	0.049
100	51u	8.333	8.498	0.164
100	52u	8.452	8.193	-0.259
	Max	8.452	8.599	0.293
	Average	8.329	8.353	0.024
	Min	8.141	8.193	-0.259
	Std Dev	0.096	0.129	0.163

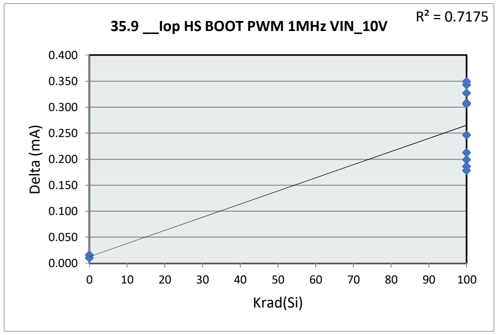


	35.8 __Iop LS VIN PWM 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	11	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	8.221	8.193
Average	8.248	8.373
Max	8.275	8.599
UL	11.000	11.000

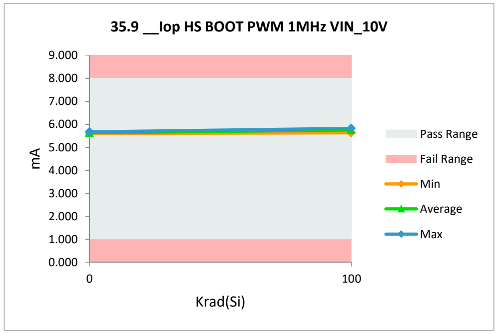


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.9 __Iop HS BOOT PWM 1MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.578	5.594	0.016
0	2	5.655	5.665	0.010
100	23	5.460	5.809	0.349
100	24	5.498	5.805	0.307
100	25	5.474	5.817	0.343
100	26	5.430	5.628	0.199
100	27	5.440	5.686	0.246
100	48u	5.637	5.823	0.186
100	49u	5.528	5.706	0.178
100	50u	5.578	5.791	0.212
100	51u	5.383	5.689	0.306
100	52u	5.477	5.804	0.327
	Max	5.655	5.823	0.349
	Average	5.511	5.735	0.223
	Min	5.383	5.594	0.010
	Std Dev	0.085	0.082	0.116

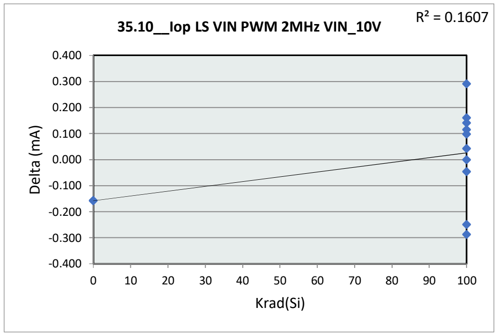


	35.9 __Iop HS BOOT PWM 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.594	5.628
Average	5.629	5.756
Max	5.665	5.823
UL	8.000	8.000

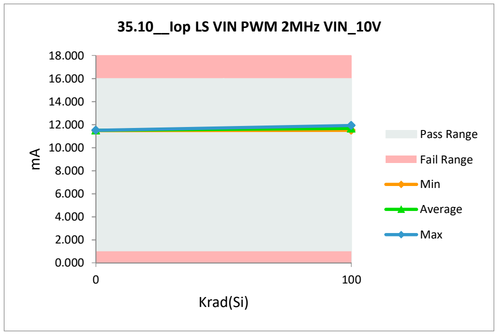


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.10__Iop LS VIN PWM 2MHz V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	16	16	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	11.668	11.509	-0.158
0	2	11.629	11.471	-0.158
100	23	11.770	11.520	-0.250
100	24	11.665	11.763	0.098
100	25	11.750	11.910	0.160
100	26	11.468	11.759	0.290
100	27	11.707	11.660	-0.047
100	48u	11.515	11.514	-0.001
100	49u	11.615	11.729	0.114
100	50u	11.606	11.648	0.042
100	51u	11.657	11.797	0.141
100	52u	11.788	11.500	-0.288
	Max	11.788	11.910	0.290
	Average	11.653	11.648	-0.005
	Min	11.468	11.471	-0.288
	Std Dev	0.096	0.145	0.179

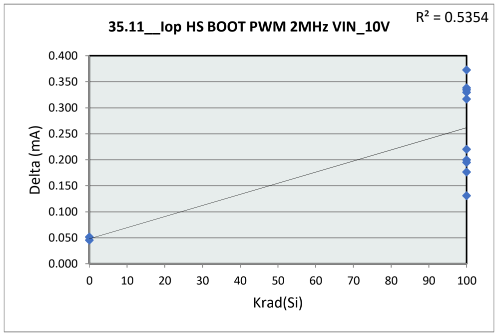


	35.10__Iop LS VIN PWM 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	16	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	11.471	11.500
Average	11.490	11.680
Max	11.509	11.910
UL	16.000	16.000

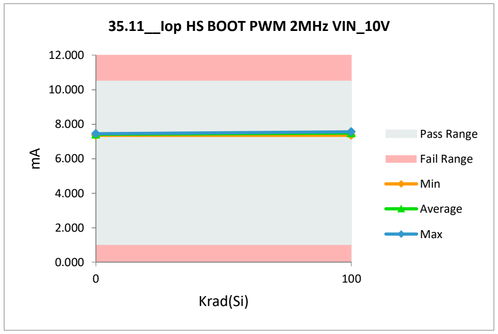


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.11__Iop HS BOOT PWM 2MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		10.5	10.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.314	7.359	0.045
0	2	7.394	7.446	0.051
100	23	7.148	7.521	0.373
100	24	7.203	7.537	0.335
100	25	7.220	7.550	0.330
100	26	7.164	7.359	0.195
100	27	7.181	7.401	0.220
100	48u	7.376	7.552	0.176
100	49u	7.262	7.393	0.131
100	50u	7.322	7.522	0.200
100	51u	7.132	7.449	0.317
100	52u	7.206	7.544	0.338
	Max	7.394	7.552	0.373
	Average	7.243	7.469	0.226
	Min	7.132	7.359	0.045
	Std Dev	0.089	0.077	0.113

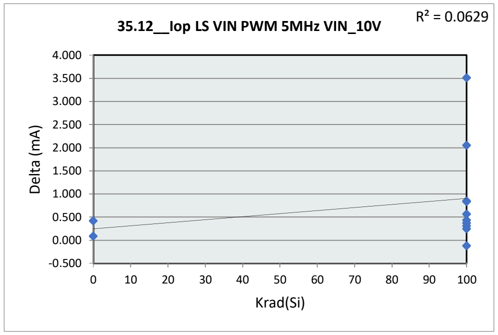


	35.11__Iop HS BOOT PWM 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.359	7.359
Average	7.402	7.483
Max	7.446	7.552
UL	10.500	10.500

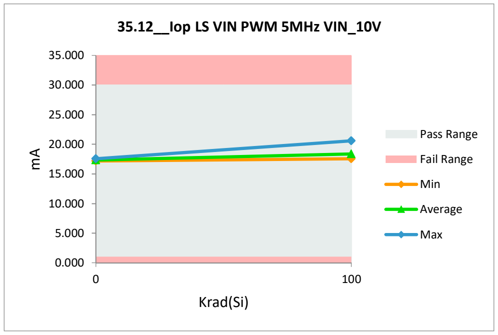


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.12__Iop LS VIN PWM 5MHz V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		30	30	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	17.155	17.567	0.412
0	2	17.086	17.167	0.081
100	23	17.719	17.596	-0.123
100	24	17.569	17.934	0.365
100	25	17.380	18.226	0.846
100	26	16.965	17.793	0.829
100	27	17.687	17.928	0.241
100	48u	17.288	17.850	0.563
100	49u	17.278	17.580	0.302
100	50u	17.282	17.712	0.430
100	51u	17.095	20.604	3.509
100	52u	18.383	20.432	2.048
	Max	18.383	20.604	3.509
	Average	17.407	18.199	0.792
	Min	16.965	17.167	-0.123
	Std Dev	0.389	1.114	1.016

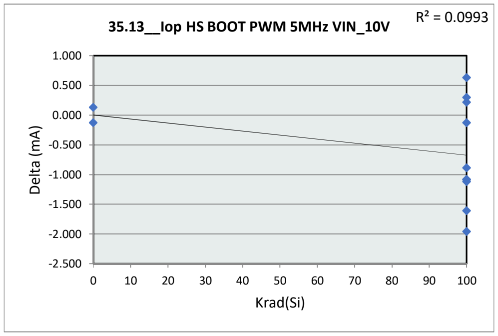


	35.12__Iop LS VIN PWM 5MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	17.167	17.580
Average	17.367	18.365
Max	17.567	20.604
UL	30.000	30.000

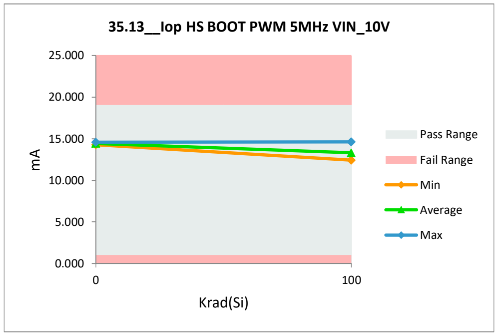


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.13__Iop HS BOOT PWM 5MHz		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	19	19	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	14.467	14.599	0.132
0	2	14.392	14.263	-0.129
100	23	12.556	12.426	-0.130
100	24	13.258	13.473	0.215
100	25	14.222	13.337	-0.885
100	26	14.162	13.079	-1.083
100	27	14.326	13.241	-1.085
100	48u	14.572	12.613	-1.959
100	49u	14.372	13.255	-1.117
100	50u	14.430	12.821	-1.609
100	51u	13.997	14.628	0.631
100	52u	13.777	14.073	0.296
	Max	14.572	14.628	0.631
	Average	14.044	13.484	-0.560
	Min	12.556	12.426	-1.959
	Std Dev	0.593	0.746	0.832

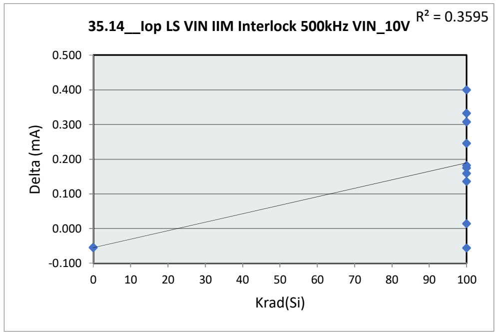


35.13__Iop HS BOOT PWM 5MHz VIN_10V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	19	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	14.263	12.426
Average	14.431	13.295
Max	14.599	14.628
UL	19.000	19.000

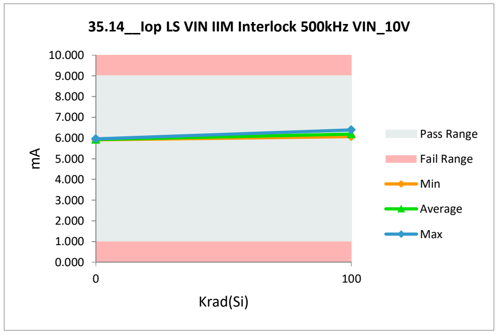


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.14__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		9	9	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	6.013	5.958	-0.055
0	2	5.964	5.909	-0.055
100	23	6.087	6.101	0.014
100	24	6.023	6.268	0.245
100	25	6.060	6.392	0.332
100	26	5.817	6.217	0.400
100	27	6.057	6.232	0.174
100	48u	5.936	6.072	0.136
100	49u	5.945	6.126	0.182
100	50u	5.967	6.126	0.159
100	51u	5.978	6.285	0.308
100	52u	6.119	6.063	-0.057
	Max	6.119	6.392	0.400
	Average	5.997	6.146	0.149
	Min	5.817	5.909	-0.057
	Std Dev	0.081	0.140	0.159

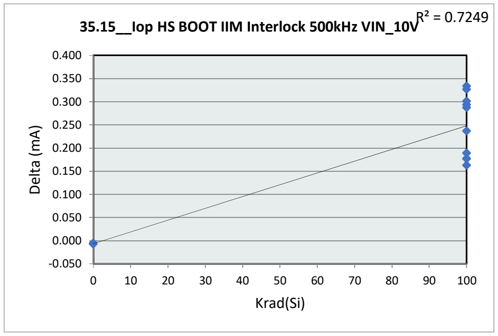


	35.14__Iop LS VIN IIM Interlock 500kHz VI	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.909	6.063
Average	5.934	6.188
Max	5.958	6.392
UL	9.000	9.000

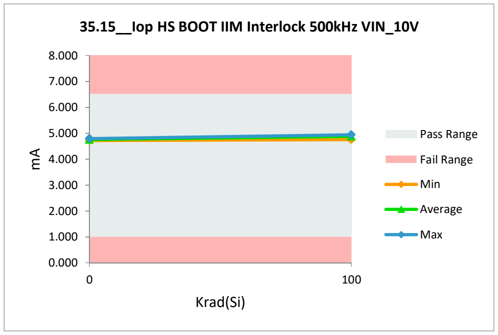


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.15__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.5	6.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.718	4.712	-0.006
0	2	4.795	4.787	-0.007
100	23	4.605	4.939	0.334
100	24	4.642	4.929	0.287
100	25	4.615	4.941	0.326
100	26	4.575	4.752	0.177
100	27	4.581	4.817	0.236
100	48u	4.776	4.938	0.162
100	49u	4.671	4.847	0.176
100	50u	4.718	4.907	0.189
100	51u	4.522	4.815	0.293
100	52u	4.621	4.922	0.301
	Max	4.795	4.941	0.334
	Average	4.653	4.859	0.206
	Min	4.522	4.712	-0.007
	Std Dev	0.084	0.081	0.116

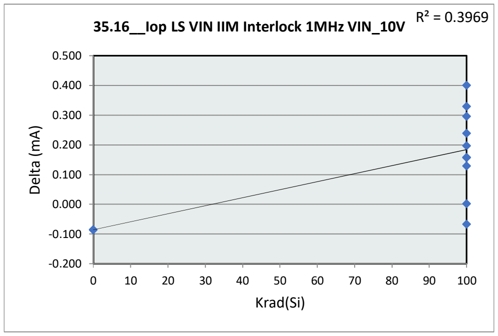


	35.15__Iop HS BOOT IIM Interlock 500kHz V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.712	4.752
Average	4.750	4.881
Max	4.787	4.941
UL	6.500	6.500

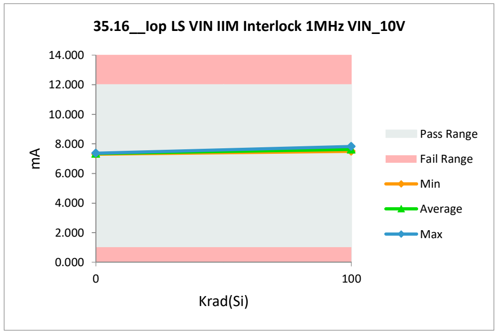


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.16__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	12	12	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.448	7.362	-0.086
0	2	7.400	7.315	-0.085
100	23	7.524	7.526	0.002
100	24	7.456	7.695	0.239
100	25	7.497	7.826	0.329
100	26	7.254	7.655	0.401
100	27	7.495	7.653	0.158
100	48u	7.372	7.501	0.129
100	49u	7.385	7.582	0.197
100	50u	7.404	7.561	0.157
100	51u	7.413	7.709	0.296
100	52u	7.558	7.491	-0.067
	Max	7.558	7.826	0.401
	Average	7.434	7.573	0.139
	Min	7.254	7.315	-0.086
	Std Dev	0.081	0.147	0.167

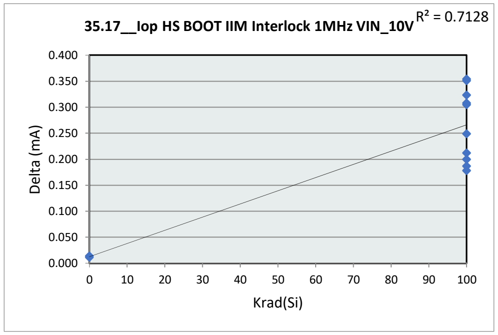


	35.16__Iop LS VIN IIM Interlock 1MHz VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.315	7.491
Average	7.338	7.620
Max	7.362	7.826
UL	12.000	12.000

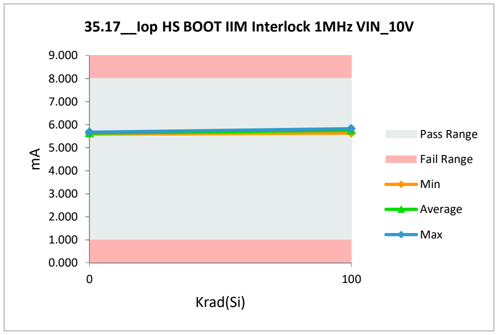


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.17__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.572	5.586	0.014
0	2	5.651	5.663	0.011
100	23	5.459	5.812	0.354
100	24	5.499	5.804	0.305
100	25	5.466	5.817	0.351
100	26	5.425	5.625	0.200
100	27	5.435	5.684	0.249
100	48u	5.633	5.819	0.186
100	49u	5.524	5.702	0.178
100	50u	5.578	5.789	0.212
100	51u	5.379	5.686	0.308
100	52u	5.473	5.797	0.323
	Max	5.651	5.819	0.354
	Average	5.508	5.732	0.224
	Min	5.379	5.586	0.011
	Std Dev	0.085	0.084	0.117

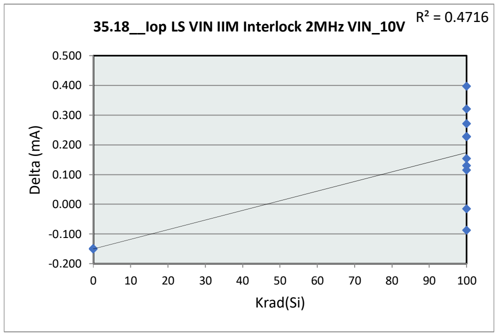


	35.17__Iop HS BOOT IIM Interlock 1MHz VI	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.586	5.625
Average	5.624	5.754
Max	5.663	5.819
UL	8.000	8.000

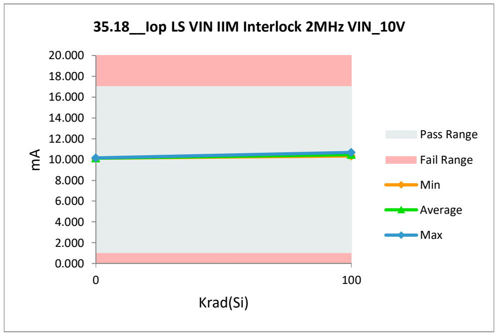


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.18__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	17	17	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	10.306	10.155	-0.151
0	2	10.262	10.113	-0.149
100	23	10.383	10.367	-0.015
100	24	10.314	10.542	0.227
100	25	10.362	10.682	0.320
100	26	10.120	10.517	0.397
100	27	10.358	10.489	0.131
100	48u	10.231	10.346	0.115
100	49u	10.256	10.484	0.228
100	50u	10.268	10.422	0.154
100	51u	10.273	10.545	0.272
100	52u	10.424	10.337	-0.087
	Max	10.424	10.682	0.397
	Average	10.296	10.417	0.120
	Min	10.120	10.113	-0.151
	Std Dev	0.081	0.164	0.184



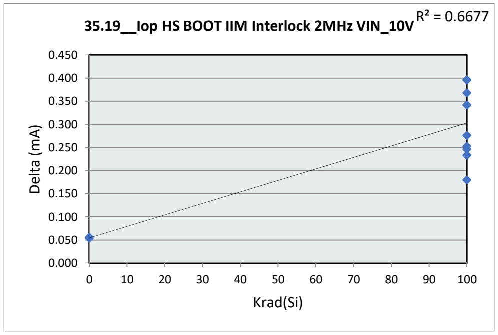
	35.18__Iop LS VIN IIM Interlock 2MHz VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	17	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	10.113	10.337
Average	10.134	10.473
Max	10.155	10.682
UL	17.000	17.000



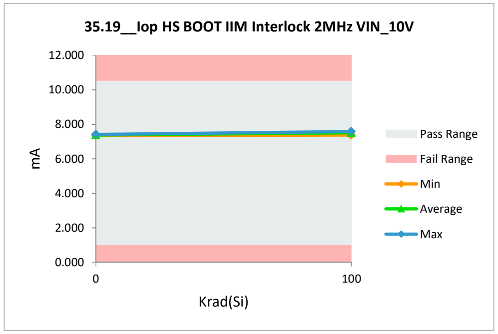
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	35.19__Iop HS BOOT IIM Interlo	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	mA	mA
Max Limit	10.5	10.5
Min Limit	1	1

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.281	7.336	0.055
0	2	7.361	7.415	0.054
100	23	7.167	7.562	0.395
100	24	7.215	7.556	0.341
100	25	7.175	7.571	0.396
100	26	7.129	7.375	0.246
100	27	7.142	7.418	0.276
100	48u	7.350	7.583	0.233
100	49u	7.230	7.409	0.179
100	50u	7.301	7.554	0.252
100	51u	7.095	7.436	0.341
100	52u	7.182	7.549	0.368
	Max	7.361	7.583	0.396
	Average	7.219	7.480	0.261
	Min	7.095	7.336	0.054
	Std Dev	0.087	0.090	0.118

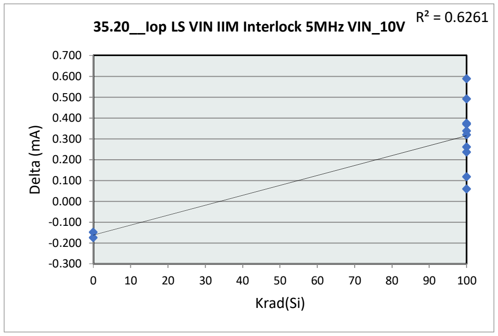


	35.19__Iop HS BOOT IIM Interlock 2MHz VI	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.336	7.375
Average	7.375	7.501
Max	7.415	7.583
UL	10.500	10.500

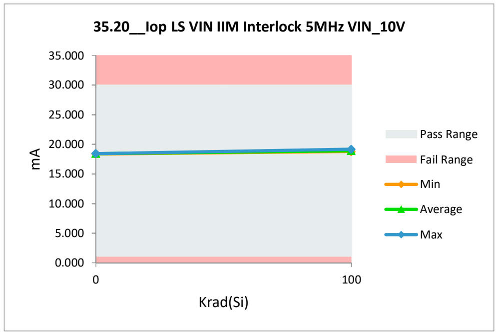


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.20__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	30	30	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.589	18.439	-0.149
0	2	18.568	18.393	-0.176
100	23	18.675	18.792	0.117
100	24	18.602	18.971	0.369
100	25	18.662	19.153	0.491
100	26	18.402	18.990	0.587
100	27	18.655	18.890	0.235
100	48u	18.525	18.785	0.260
100	49u	18.551	18.887	0.337
100	50u	18.568	18.887	0.319
100	51u	18.562	18.936	0.374
100	52u	18.717	18.776	0.059
	Max	18.717	19.153	0.587
	Average	18.590	18.825	0.235
	Min	18.402	18.393	-0.176
	Std Dev	0.083	0.218	0.235

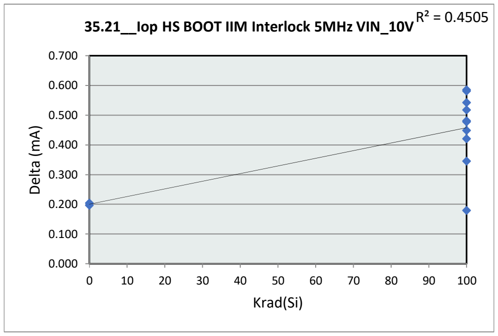


	35.20__Iop LS VIN IIM Interlock 5MHz VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	18.393	18.776
Average	18.416	18.907
Max	18.439	19.153
UL	30.000	30.000

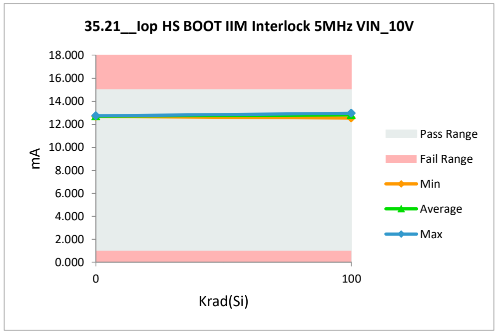


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.21__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	15	15	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	12.457	12.660	0.204
0	2	12.538	12.735	0.197
100	23	12.310	12.891	0.581
100	24	12.360	12.841	0.481
100	25	12.320	12.906	0.586
100	26	12.267	12.744	0.477
100	27	12.352	12.697	0.345
100	48u	12.539	12.960	0.421
100	49u	12.359	12.539	0.180
100	50u	12.468	12.916	0.448
100	51u	12.236	12.754	0.517
100	52u	12.349	12.892	0.542
	Max	12.539	12.960	0.586
	Average	12.380	12.795	0.415
	Min	12.236	12.539	0.180
	Std Dev	0.099	0.126	0.149

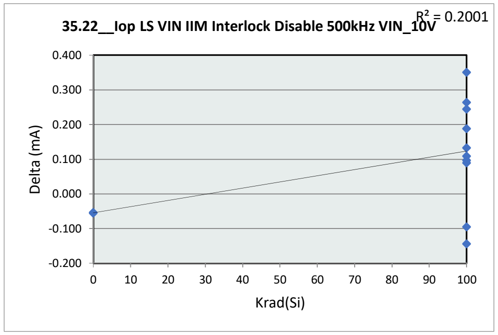


	35.21__Iop HS BOOT IIM Interlock 5MHz VI	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	12.661	12.539
Average	12.698	12.814
Max	12.735	12.960
UL	15.000	15.000

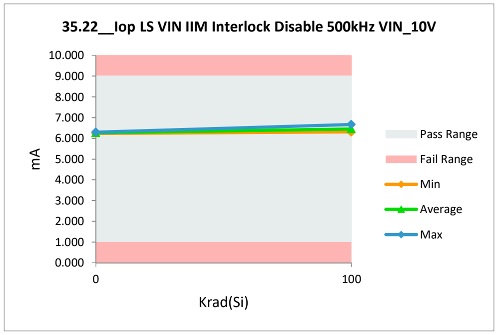


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.22__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	9	9	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	6.354	6.298	-0.056
0	2	6.296	6.242	-0.054
100	23	6.438	6.342	-0.095
100	24	6.357	6.544	0.187
100	25	6.405	6.668	0.264
100	26	6.146	6.496	0.350
100	27	6.388	6.485	0.097
100	48u	6.235	6.325	0.089
100	49u	6.276	6.409	0.133
100	50u	6.289	6.397	0.109
100	51u	6.322	6.566	0.244
100	52u	6.450	6.306	-0.144
	Max	6.450	6.668	0.350
	Average	6.330	6.423	0.094
	Min	6.146	6.242	-0.144
	Std Dev	0.088	0.129	0.155

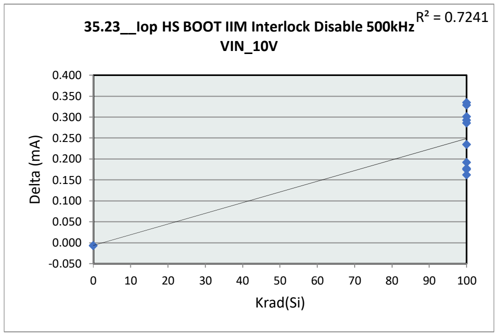


	35.22__Iop LS VIN IIM Interlock Disable 50	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	6.242	6.306
Average	6.270	6.454
Max	6.298	6.668
UL	9.000	9.000

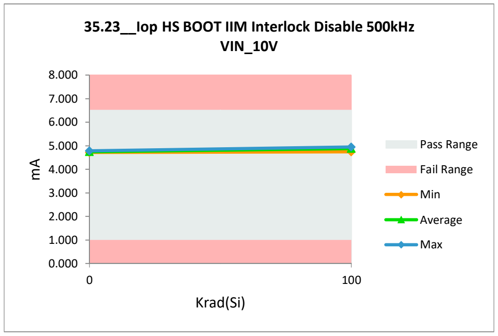


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.23__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		6.5	6.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.717	4.710	-0.007
0	2	4.794	4.787	-0.006
100	23	4.604	4.939	0.335
100	24	4.641	4.927	0.286
100	25	4.614	4.942	0.329
100	26	4.574	4.749	0.175
100	27	4.581	4.816	0.234
100	48u	4.774	4.936	0.162
100	49u	4.671	4.848	0.177
100	50u	4.716	4.909	0.192
100	51u	4.521	4.814	0.293
100	52u	4.620	4.921	0.301
	Max	4.794	4.942	0.335
	Average	4.652	4.858	0.206
	Min	4.521	4.710	-0.007
	Std Dev	0.084	0.082	0.117

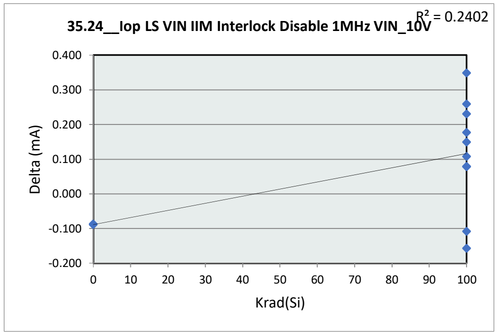


	35.23__Iop HS BOOT IIM Interlock Disable 5	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.710	4.749
Average	4.749	4.880
Max	4.788	4.942
UL	6.500	6.500

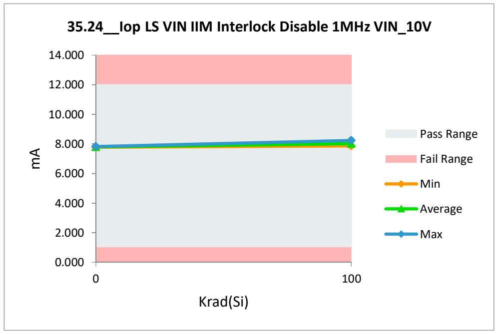


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.24__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	12	12	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.914	7.825	-0.089
0	2	7.860	7.773	-0.087
100	23	8.002	7.894	-0.108
100	24	7.918	8.095	0.177
100	25	7.969	8.228	0.259
100	26	7.709	8.057	0.348
100	27	7.952	8.031	0.079
100	48u	7.798	7.876	0.078
100	49u	7.844	7.993	0.149
100	50u	7.852	7.959	0.107
100	51u	7.884	8.114	0.230
100	52u	8.016	7.858	-0.158
	Max	8.016	8.228	0.348
	Average	7.893	7.975	0.082
	Min	7.709	7.773	-0.158
	Std Dev	0.088	0.136	0.162



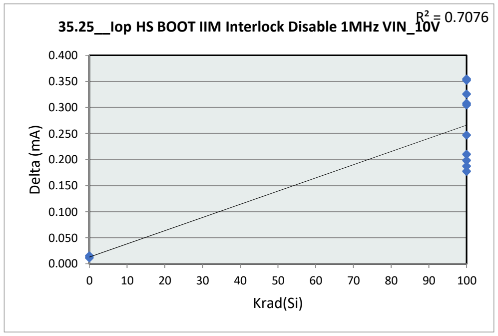
	35.24__Iop LS VIN IIM Interlock Disable 1M	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.773	7.858
Average	7.799	8.011
Max	7.825	8.228
UL	12.000	12.000



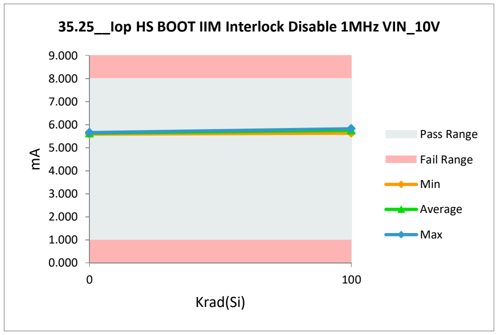
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	35.25__Iop HS BOOT IIM Interlo	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	mA	mA
Max Limit	8	8
Min Limit	1	1

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.570	5.585	0.015
0	2	5.649	5.661	0.011
100	23	5.457	5.812	0.354
100	24	5.497	5.802	0.304
100	25	5.465	5.817	0.352
100	26	5.425	5.623	0.198
100	27	5.433	5.680	0.247
100	48u	5.631	5.818	0.187
100	49u	5.524	5.702	0.178
100	50u	5.578	5.788	0.210
100	51u	5.378	5.686	0.307
100	52u	5.471	5.797	0.326
	Max	5.649	5.818	0.354
	Average	5.507	5.731	0.224
	Min	5.378	5.585	0.011
	Std Dev	0.085	0.084	0.117

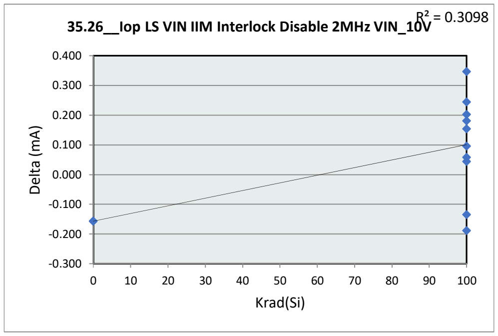


	35.25__Iop HS BOOT IIM Interlock Disable	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.585	5.623
Average	5.623	5.752
Max	5.661	5.818
UL	8.000	8.000

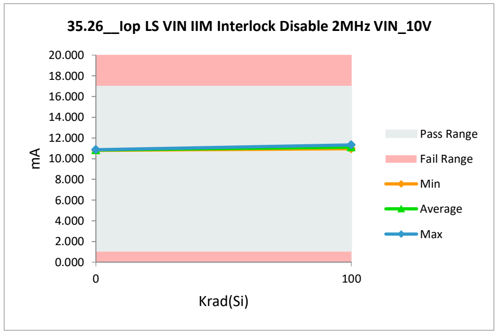


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.26__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	17	17	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	11.025	10.868	-0.157
0	2	10.975	10.819	-0.156
100	23	11.117	10.983	-0.134
100	24	11.032	11.186	0.154
100	25	11.087	11.331	0.244
100	26	10.825	11.172	0.347
100	27	11.069	11.113	0.044
100	48u	10.910	10.968	0.058
100	49u	10.968	11.149	0.181
100	50u	10.970	11.066	0.096
100	51u	10.995	11.197	0.203
100	52u	11.137	10.948	-0.189
	Max	11.137	11.331	0.347
	Average	11.009	11.067	0.058
	Min	10.825	10.819	-0.189
	Std Dev	0.089	0.152	0.180



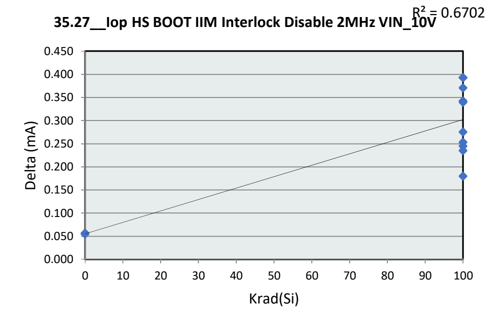
	35.26__Iop LS VIN IIM Interlock Disable 2M	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	17	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	10.820	10.948
Average	10.844	11.111
Max	10.868	11.331
UL	17.000	17.000



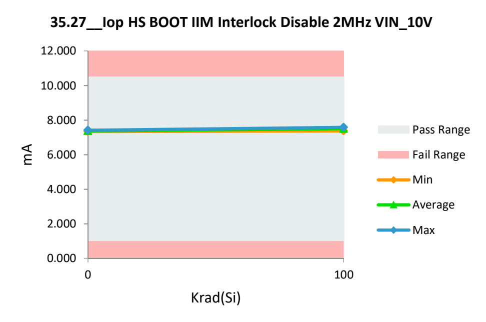
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	35.27__Iop HS BOOT IIM Interlo	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	mA	mA
Max Limit	10.5	10.5
Min Limit	1	1

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.279	7.335	0.056
0	2	7.359	7.413	0.054
100	23	7.167	7.560	0.393
100	24	7.214	7.554	0.339
100	25	7.174	7.567	0.393
100	26	7.128	7.372	0.244
100	27	7.140	7.415	0.275
100	48u	7.348	7.582	0.235
100	49u	7.227	7.407	0.180
100	50u	7.299	7.552	0.253
100	51u	7.092	7.434	0.342
100	52u	7.180	7.551	0.370
	Max	7.359	7.582	0.393
	Average	7.217	7.478	0.261
	Min	7.092	7.335	0.054
	Std Dev	0.087	0.090	0.118

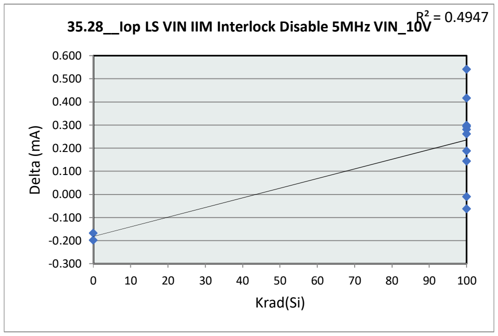


	35.27__Iop HS BOOT IIM Interlock Disable 2	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.335	7.372
Average	7.374	7.499
Max	7.413	7.582
UL	10.500	10.500

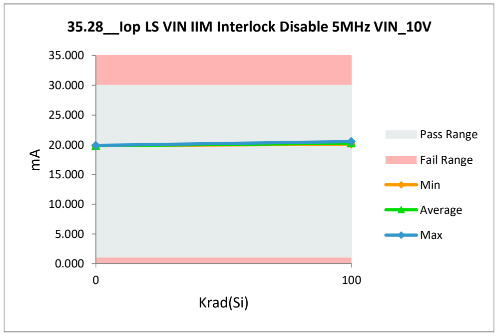


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.28__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		30	30	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	20.025	19.858	-0.167
0	2	20.017	19.820	-0.198
100	23	20.136	20.126	-0.010
100	24	20.045	20.326	0.280
100	25	20.111	20.528	0.417
100	26	19.832	20.373	0.541
100	27	20.090	20.235	0.145
100	48u	19.933	20.121	0.188
100	49u	19.983	20.277	0.294
100	50u	19.998	20.260	0.261
100	51u	20.011	20.310	0.299
100	52u	20.160	20.097	-0.063
	Max	20.160	20.528	0.541
	Average	20.029	20.194	0.166
	Min	19.832	19.820	-0.198
	Std Dev	0.091	0.204	0.231

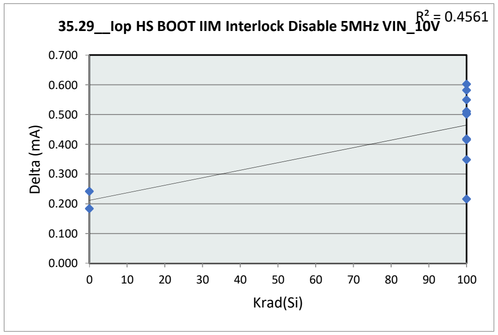


	35.28__Iop LS VIN IIM Interlock Disable 5M	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	19.820	20.097
Average	19.839	20.265
Max	19.858	20.528
UL	30.000	30.000

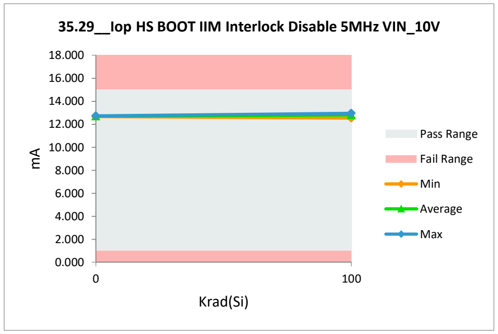


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		35.29__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	15	15	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	12.426	12.667	0.241
0	2	12.548	12.732	0.183
100	23	12.289	12.891	0.602
100	24	12.330	12.841	0.511
100	25	12.324	12.906	0.582
100	26	12.231	12.734	0.503
100	27	12.337	12.686	0.348
100	48u	12.545	12.959	0.414
100	49u	12.324	12.540	0.216
100	50u	12.488	12.906	0.418
100	51u	12.247	12.748	0.500
100	52u	12.340	12.888	0.549
	Max	12.548	12.959	0.602
	Average	12.369	12.791	0.422
	Min	12.231	12.540	0.183
	Std Dev	0.108	0.126	0.145

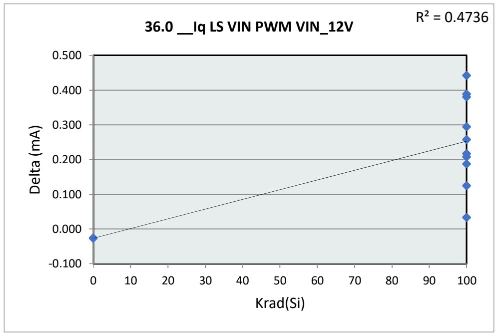


35.29__Iop HS BOOT IIM Interlock Disable 5		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	12.667	12.540
Average	12.699	12.810
Max	12.732	12.959
UL	15.000	15.000

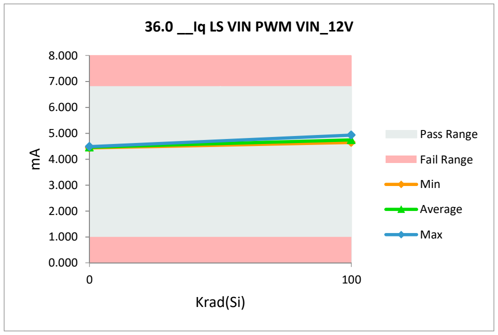


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.0 __Iq LS VIN PWM VIN_12V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.8	6.8	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.504	4.478	-0.027
0	2	4.457	4.431	-0.026
100	23	4.561	4.685	0.124
100	24	4.515	4.809	0.294
100	25	4.540	4.928	0.388
100	26	4.312	4.754	0.442
100	27	4.555	4.812	0.257
100	48u	4.463	4.650	0.188
100	49u	4.430	4.647	0.217
100	50u	4.468	4.675	0.207
100	51u	4.459	4.840	0.380
100	52u	4.613	4.646	0.033
	Max	4.613	4.928	0.442
	Average	4.490	4.696	0.207
	Min	4.312	4.431	-0.027
	Std Dev	0.077	0.145	0.158

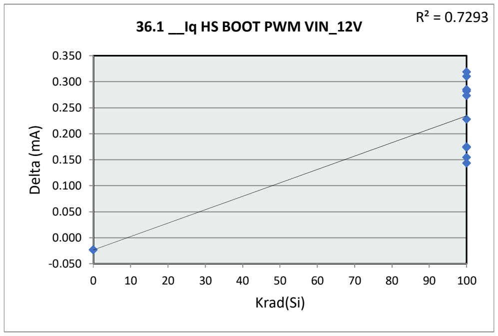


	36.0 __Iq LS VIN PWM VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.431	4.646
Average	4.454	4.745
Max	4.478	4.928
UL	6.800	6.800

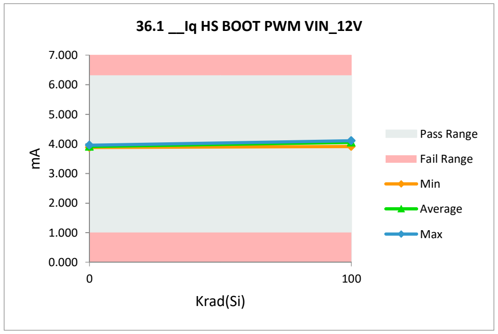


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.1 __Iq HS BOOT PWM VIN_12		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		6.3	6.3	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.902	3.878	-0.023
0	2	3.977	3.954	-0.023
100	23	3.788	4.107	0.319
100	24	3.822	4.096	0.274
100	25	3.798	4.109	0.310
100	26	3.761	3.916	0.155
100	27	3.765	3.993	0.228
100	48u	3.956	4.100	0.143
100	49u	3.858	4.033	0.175
100	50u	3.896	4.070	0.174
100	51u	3.703	3.984	0.282
100	52u	3.805	4.090	0.285
	Max	3.977	4.109	0.319
	Average	3.836	4.027	0.192
	Min	3.703	3.878	-0.023
	Std Dev	0.083	0.081	0.117

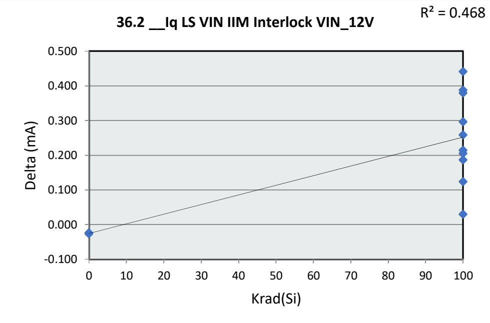


	36.1 __Iq HS BOOT PWM VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.3	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	3.878	3.916
Average	3.916	4.050
Max	3.954	4.109
UL	6.300	6.300

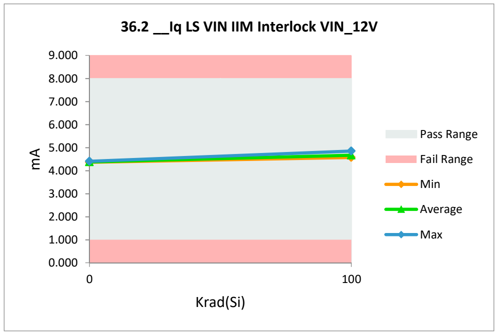


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.2 __Iq LS VIN IIM Interlock V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.432	4.405	-0.027
0	2	4.384	4.360	-0.024
100	23	4.490	4.613	0.123
100	24	4.443	4.739	0.296
100	25	4.467	4.855	0.387
100	26	4.240	4.681	0.441
100	27	4.482	4.740	0.258
100	48u	4.391	4.577	0.187
100	49u	4.359	4.574	0.214
100	50u	4.397	4.602	0.205
100	51u	4.388	4.768	0.379
100	52u	4.542	4.572	0.030
	Max	4.542	4.855	0.441
	Average	4.418	4.624	0.206
	Min	4.240	4.360	-0.027
	Std Dev	0.078	0.145	0.158

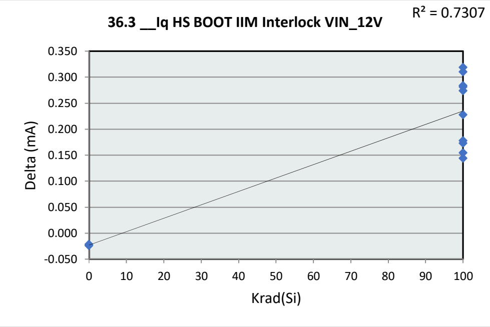


	36.2 __Iq LS VIN IIM Interlock VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.360	4.572
Average	4.382	4.672
Max	4.405	4.855
UL	8.000	8.000

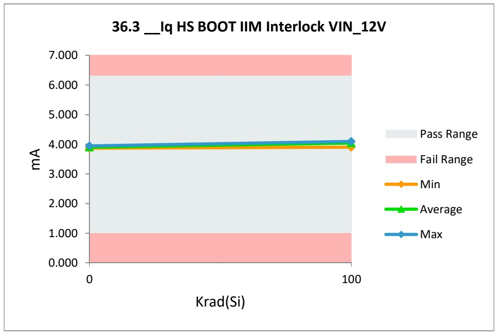


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.3 __Iq HS BOOT IIM Interloc		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		6.3	6.3	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.888	3.867	-0.021
0	2	3.965	3.942	-0.024
100	23	3.776	4.095	0.319
100	24	3.809	4.083	0.274
100	25	3.785	4.096	0.310
100	26	3.749	3.903	0.154
100	27	3.752	3.980	0.228
100	48u	3.944	4.088	0.144
100	49u	3.845	4.023	0.178
100	50u	3.884	4.057	0.173
100	51u	3.690	3.971	0.282
100	52u	3.792	4.076	0.284
	Max	3.965	4.096	0.319
	Average	3.823	4.015	0.192
	Min	3.690	3.867	-0.024
	Std Dev	0.083	0.081	0.117

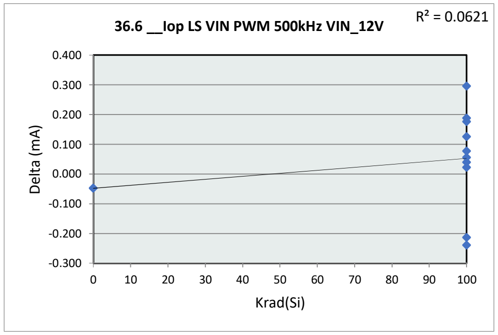


	36.3 __Iq HS BOOT IIM Interlock VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.3	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	3.867	3.903
Average	3.904	4.037
Max	3.942	4.096
UL	6.300	6.300

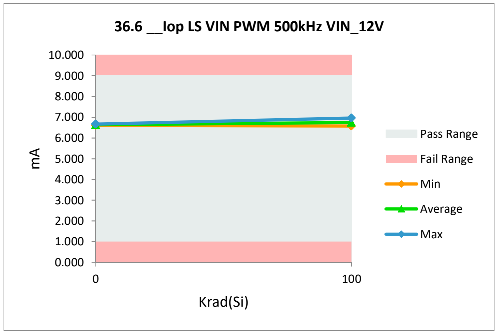


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.6 __Iop LS VIN PWM 500kHz		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	9	9	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	6.718	6.670	-0.048
0	2	6.656	6.608	-0.048
100	23	6.814	6.601	-0.213
100	24	6.714	6.840	0.126
100	25	6.779	6.966	0.188
100	26	6.501	6.796	0.295
100	27	6.743	6.765	0.022
100	48u	6.558	6.598	0.040
100	49u	6.634	6.712	0.077
100	50u	6.634	6.689	0.055
100	51u	6.695	6.871	0.176
100	52u	6.809	6.570	-0.239
	Max	6.814	6.966	0.295
	Average	6.688	6.724	0.036
	Min	6.501	6.570	-0.239
	Std Dev	0.096	0.126	0.157

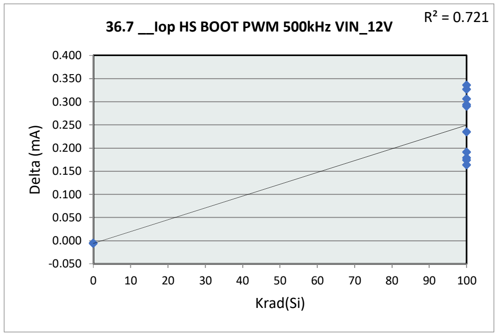


	36.6 __Iop LS VIN PWM 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	6.608	6.570
Average	6.639	6.741
Max	6.670	6.967
UL	9.000	9.000

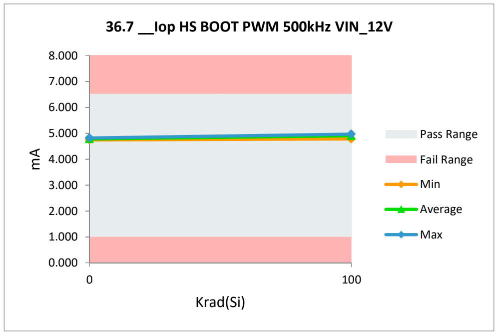


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.7 __Iop HS BOOT PWM 500kH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.5	6.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.744	4.738	-0.006
0	2	4.819	4.813	-0.006
100	23	4.628	4.963	0.336
100	24	4.664	4.954	0.290
100	25	4.639	4.966	0.327
100	26	4.600	4.774	0.174
100	27	4.606	4.841	0.234
100	48u	4.800	4.963	0.163
100	49u	4.696	4.875	0.179
100	50u	4.740	4.931	0.191
100	51u	4.546	4.839	0.294
100	52u	4.643	4.949	0.306
	Max	4.819	4.966	0.336
	Average	4.677	4.884	0.207
	Min	4.546	4.738	-0.006
	Std Dev	0.084	0.082	0.117

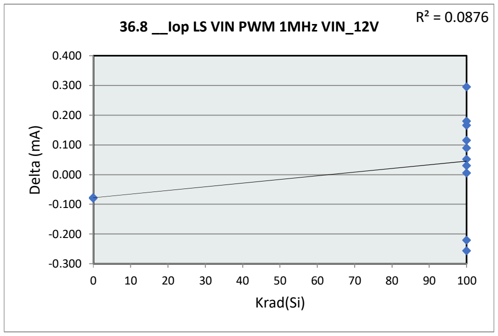


	36.7 __Iop HS BOOT PWM 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.738	4.774
Average	4.776	4.906
Max	4.813	4.966
UL	6.500	6.500

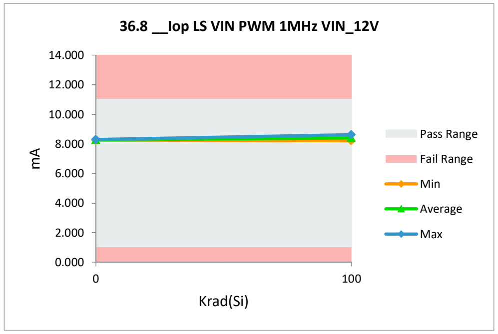


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.8 __Iop LS VIN PWM 1MHz VI		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		11	11	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	8.377	8.300	-0.078
0	2	8.323	8.244	-0.079
100	23	8.476	8.255	-0.221
100	24	8.376	8.491	0.115
100	25	8.446	8.626	0.180
100	26	8.166	8.461	0.295
100	27	8.408	8.413	0.005
100	48u	8.224	8.254	0.030
100	49u	8.304	8.393	0.090
100	50u	8.301	8.352	0.051
100	51u	8.357	8.523	0.166
100	52u	8.477	8.220	-0.256
	Max	8.477	8.626	0.295
	Average	8.353	8.378	0.025
	Min	8.166	8.220	-0.256
	Std Dev	0.096	0.129	0.163

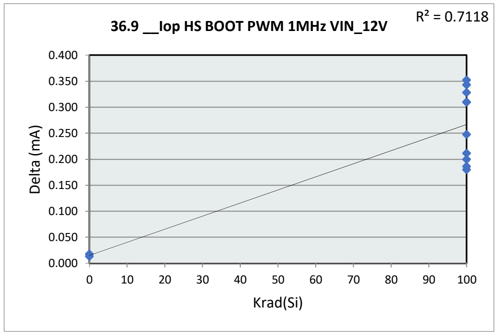


	36.8 __Iop LS VIN PWM 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	11	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	8.244	8.220
Average	8.272	8.399
Max	8.300	8.626
UL	11.000	11.000

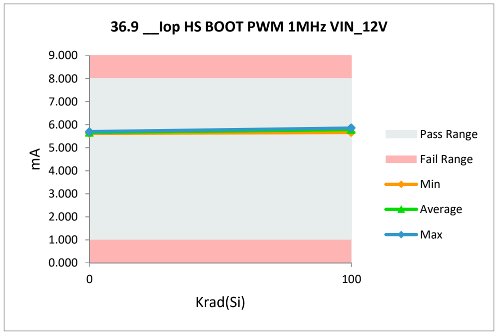


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.9 __Iop HS BOOT PWM 1MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.599	5.616	0.017
0	2	5.676	5.689	0.013
100	23	5.481	5.833	0.352
100	24	5.518	5.828	0.310
100	25	5.496	5.839	0.343
100	26	5.450	5.649	0.199
100	27	5.459	5.707	0.247
100	48u	5.659	5.844	0.186
100	49u	5.549	5.729	0.180
100	50u	5.600	5.812	0.211
100	51u	5.403	5.712	0.309
100	52u	5.499	5.827	0.328
	Max	5.676	5.844	0.352
	Average	5.532	5.757	0.225
	Min	5.403	5.616	0.013
	Std Dev	0.085	0.082	0.116

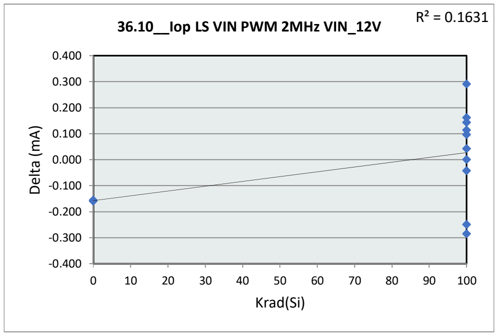


	36.9 __Iop HS BOOT PWM 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.616	5.649
Average	5.652	5.778
Max	5.689	5.844
UL	8.000	8.000

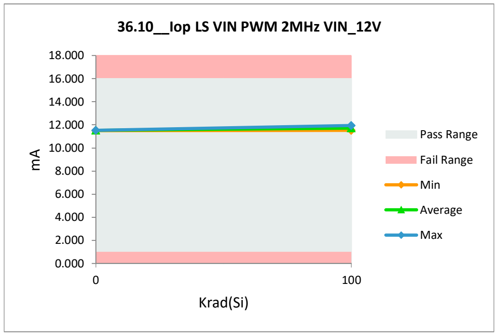


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.10__Iop LS VIN PWM 2MHz V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		16	16	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	11.694	11.535	-0.159
0	2	11.654	11.498	-0.156
100	23	11.796	11.547	-0.249
100	24	11.692	11.789	0.097
100	25	11.776	11.938	0.163
100	26	11.496	11.786	0.291
100	27	11.733	11.690	-0.042
100	48u	11.540	11.542	0.001
100	49u	11.642	11.756	0.114
100	50u	11.631	11.674	0.043
100	51u	11.682	11.826	0.144
100	52u	11.811	11.527	-0.284
	Max	11.811	11.938	0.291
	Average	11.679	11.676	-0.003
	Min	11.496	11.498	-0.284
	Std Dev	0.096	0.145	0.178

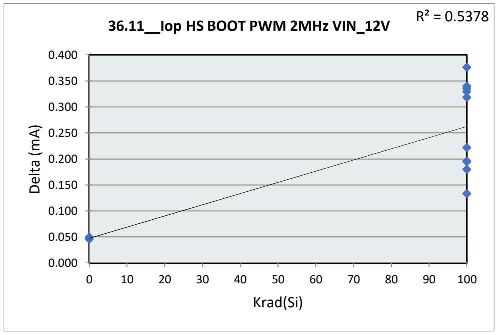


	36.10__Iop LS VIN PWM 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	16	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	11.498	11.527
Average	11.517	11.708
Max	11.535	11.938
UL	16.000	16.000

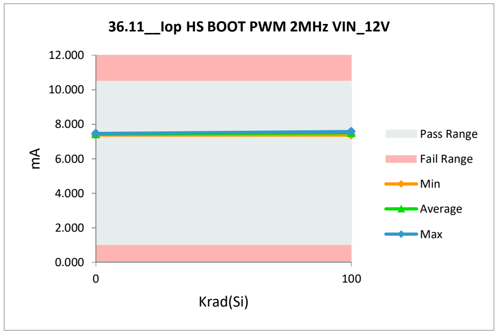


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	36.11__Iop HS BOOT PWM 2MHz			
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	10.5	10.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.333	7.379	0.046
0	2	7.418	7.467	0.049
100	23	7.167	7.543	0.376
100	24	7.223	7.559	0.336
100	25	7.243	7.572	0.329
100	26	7.184	7.379	0.195
100	27	7.200	7.421	0.221
100	48u	7.396	7.576	0.180
100	49u	7.285	7.418	0.133
100	50u	7.345	7.540	0.196
100	51u	7.153	7.471	0.318
100	52u	7.229	7.569	0.340
	Max	7.418	7.576	0.376
	Average	7.265	7.491	0.227
	Min	7.153	7.379	0.046
	Std Dev	0.090	0.077	0.114

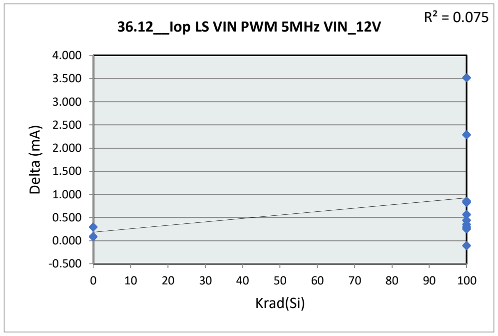


	36.11__Iop HS BOOT PWM 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.379	7.379
Average	7.423	7.505
Max	7.467	7.576
UL	10.500	10.500

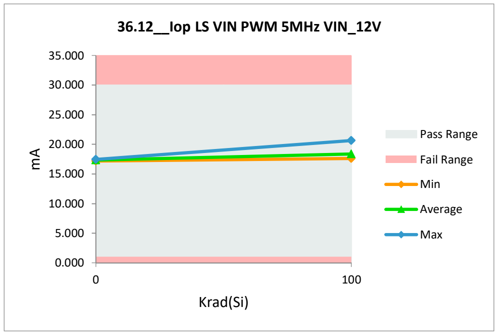


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.12__Iop LS VIN PWM 5MHz V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		30	30	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	17.177	17.465	0.288
0	2	17.111	17.194	0.083
100	23	17.744	17.631	-0.113
100	24	17.594	17.941	0.348
100	25	17.406	18.254	0.848
100	26	16.990	17.816	0.826
100	27	17.707	17.959	0.252
100	48u	17.313	17.873	0.559
100	49u	17.307	17.601	0.294
100	50u	17.306	17.743	0.437
100	51u	17.122	20.641	3.519
100	52u	18.041	20.322	2.281
	Max	18.041	20.641	3.519
	Average	17.402	18.203	0.802
	Min	16.990	17.194	-0.113
	Std Dev	0.311	1.099	1.051



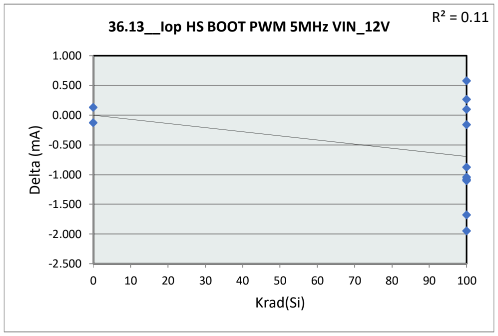
	36.12__Iop LS VIN PWM 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	17.195	17.601
Average	17.330	18.378
Max	17.465	20.641
UL	30.000	30.000



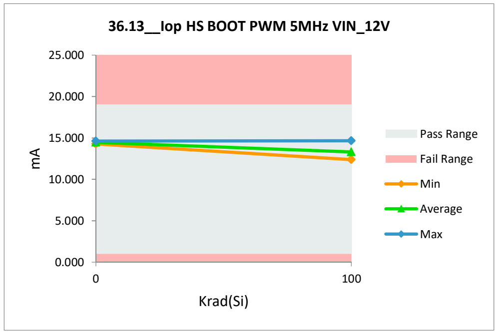
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	36.13__Iop HS BOOT PWM 5MHz	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	mA	mA
Max Limit	19	19
Min Limit	1	1

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	14.497	14.626	0.129
0	2	14.419	14.290	-0.129
100	23	12.567	12.405	-0.162
100	24	13.425	13.524	0.099
100	25	14.247	13.374	-0.874
100	26	14.194	13.152	-1.042
100	27	14.335	13.256	-1.079
100	48u	14.601	12.654	-1.946
100	49u	14.402	13.302	-1.100
100	50u	14.501	12.822	-1.679
100	51u	14.068	14.648	0.580
100	52u	13.796	14.061	0.265
	Max	14.601	14.648	0.580
	Average	14.088	13.509	-0.578
	Min	12.567	12.405	-1.946
	Std Dev	0.584	0.747	0.814

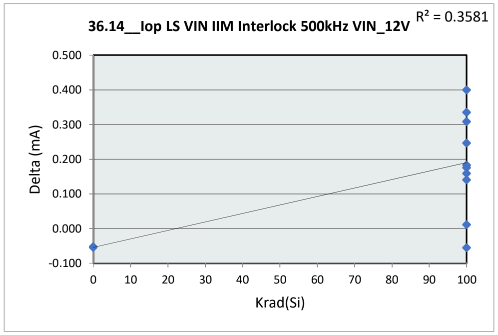


	36.13__Iop HS BOOT PWM 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	19	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	14.290	12.405
Average	14.458	13.320
Max	14.626	14.648
UL	19.000	19.000

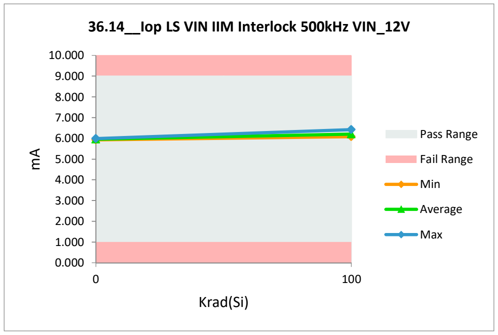


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.14__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		9	9	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	6.037	5.983	-0.055
0	2	5.988	5.935	-0.053
100	23	6.111	6.122	0.011
100	24	6.046	6.292	0.246
100	25	6.082	6.417	0.335
100	26	5.841	6.241	0.400
100	27	6.080	6.256	0.176
100	48u	5.959	6.100	0.141
100	49u	5.968	6.150	0.182
100	50u	5.991	6.149	0.159
100	51u	6.002	6.310	0.308
100	52u	6.142	6.087	-0.055
	Max	6.142	6.417	0.400
	Average	6.021	6.170	0.150
	Min	5.841	5.935	-0.055
	Std Dev	0.081	0.139	0.159

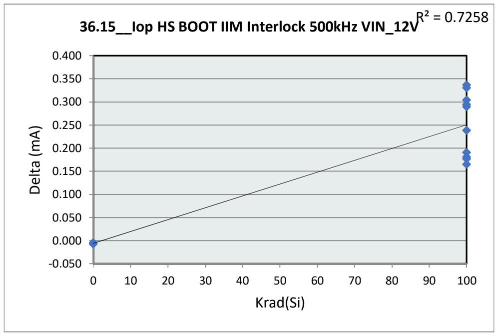


	36.14__Iop LS VIN IIM Interlock 500kHz VI	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.935	6.087
Average	5.959	6.212
Max	5.983	6.417
UL	9.000	9.000

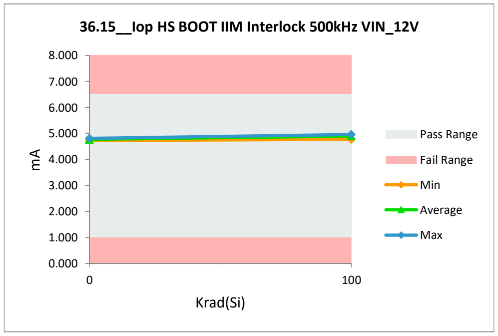


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.15__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		6.5	6.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.738	4.734	-0.004
0	2	4.817	4.810	-0.007
100	23	4.627	4.964	0.337
100	24	4.664	4.953	0.289
100	25	4.635	4.965	0.330
100	26	4.597	4.773	0.176
100	27	4.602	4.840	0.238
100	48u	4.797	4.962	0.165
100	49u	4.693	4.874	0.181
100	50u	4.741	4.932	0.191
100	51u	4.543	4.837	0.294
100	52u	4.641	4.946	0.304
	Max	4.817	4.965	0.337
	Average	4.674	4.882	0.208
	Min	4.543	4.734	-0.007
	Std Dev	0.084	0.082	0.117

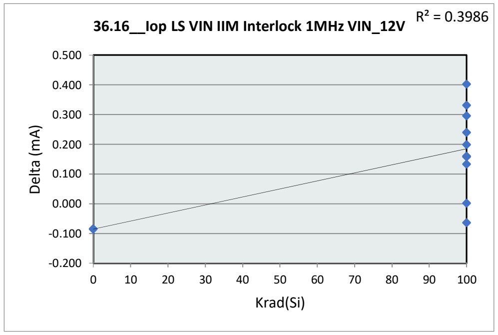


	36.15__Iop HS BOOT IIM Interlock 500kHz V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.734	4.773
Average	4.772	4.904
Max	4.810	4.965
UL	6.500	6.500

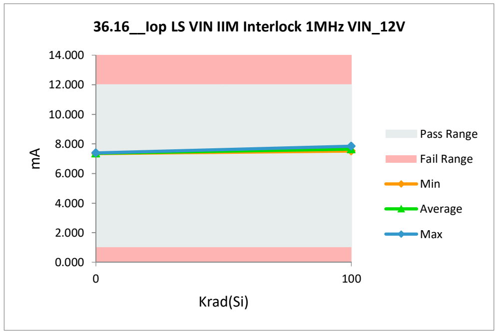


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.16__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	12	12	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.472	7.386	-0.086
0	2	7.424	7.340	-0.084
100	23	7.548	7.549	0.002
100	24	7.481	7.720	0.239
100	25	7.521	7.852	0.332
100	26	7.280	7.682	0.402
100	27	7.518	7.678	0.160
100	48u	7.394	7.528	0.133
100	49u	7.409	7.608	0.199
100	50u	7.428	7.585	0.157
100	51u	7.438	7.733	0.296
100	52u	7.581	7.516	-0.065
	Max	7.581	7.852	0.402
	Average	7.458	7.598	0.140
	Min	7.280	7.340	-0.086
	Std Dev	0.081	0.147	0.167

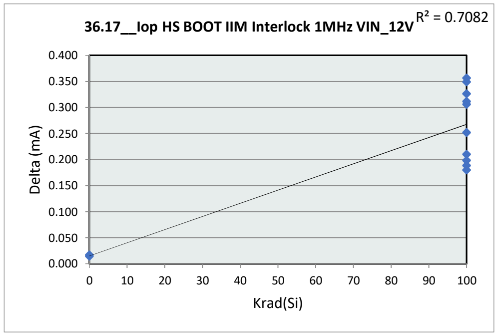


	36.16__Iop LS VIN IIM Interlock 1MHz VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.340	7.516
Average	7.363	7.645
Max	7.386	7.852
UL	12.000	12.000

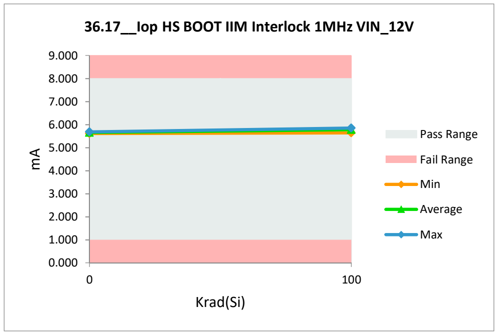


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.17__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.592	5.609	0.017
0	2	5.672	5.687	0.014
100	23	5.480	5.836	0.357
100	24	5.521	5.827	0.306
100	25	5.489	5.838	0.349
100	26	5.448	5.646	0.198
100	27	5.456	5.707	0.252
100	48u	5.654	5.842	0.188
100	49u	5.546	5.726	0.180
100	50u	5.602	5.812	0.210
100	51u	5.400	5.712	0.312
100	52u	5.495	5.821	0.326
	Max	5.672	5.842	0.357
	Average	5.530	5.755	0.226
	Min	5.400	5.609	0.014
	Std Dev	0.085	0.084	0.117

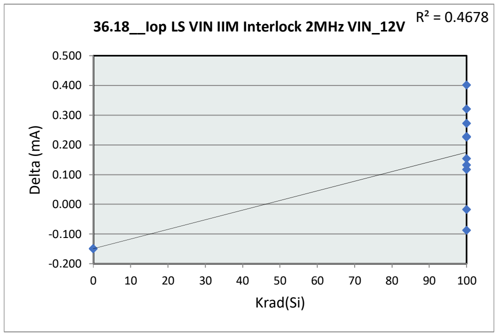


	36.17__Iop HS BOOT IIM Interlock 1MHz VI	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.609	5.646
Average	5.648	5.777
Max	5.687	5.842
UL	8.000	8.000

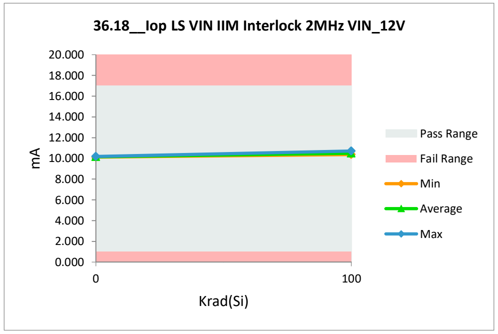


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.18__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		17	17	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	10.332	10.182	-0.150
0	2	10.289	10.141	-0.148
100	23	10.411	10.393	-0.018
100	24	10.342	10.568	0.226
100	25	10.388	10.708	0.321
100	26	10.145	10.547	0.402
100	27	10.384	10.516	0.132
100	48u	10.256	10.373	0.117
100	49u	10.284	10.512	0.228
100	50u	10.294	10.448	0.154
100	51u	10.299	10.571	0.272
100	52u	10.450	10.363	-0.087
	Max	10.450	10.708	0.402
	Average	10.323	10.444	0.121
	Min	10.145	10.141	-0.150
	Std Dev	0.081	0.164	0.184

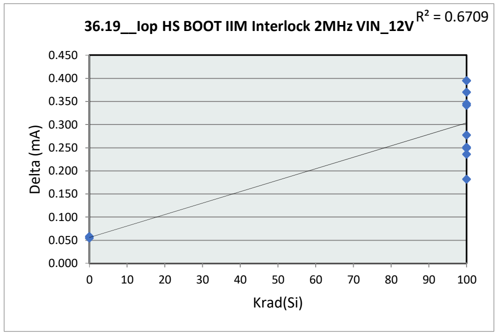


	36.18__Iop LS VIN IIM Interlock 2MHz VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	17	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	10.141	10.363
Average	10.161	10.500
Max	10.182	10.708
UL	17.000	17.000

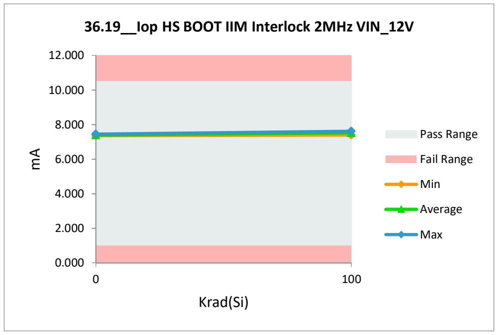


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.19__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		10.5	10.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.302	7.359	0.057
0	2	7.384	7.438	0.054
100	23	7.190	7.585	0.394
100	24	7.236	7.577	0.341
100	25	7.198	7.593	0.395
100	26	7.149	7.398	0.248
100	27	7.162	7.440	0.277
100	48u	7.372	7.607	0.235
100	49u	7.252	7.434	0.182
100	50u	7.323	7.574	0.251
100	51u	7.116	7.461	0.345
100	52u	7.205	7.575	0.370
	Max	7.384	7.607	0.395
	Average	7.241	7.503	0.263
	Min	7.116	7.359	0.054
	Std Dev	0.087	0.089	0.118

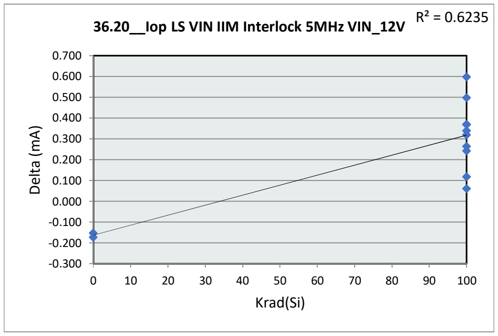


	36.19__Iop HS BOOT IIM Interlock 2MHz VI	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.360	7.398
Average	7.399	7.524
Max	7.438	7.607
UL	10.500	10.500

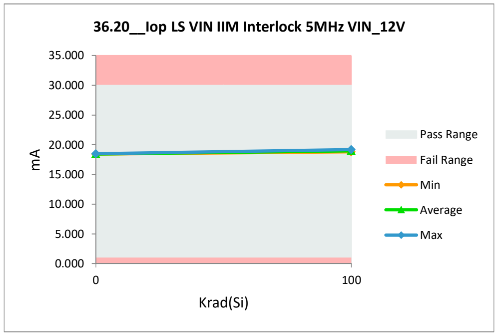


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.20__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		30	30	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.620	18.468	-0.152
0	2	18.600	18.427	-0.173
100	23	18.706	18.824	0.117
100	24	18.635	19.003	0.368
100	25	18.695	19.193	0.498
100	26	18.435	19.033	0.598
100	27	18.688	18.931	0.243
100	48u	18.557	18.821	0.264
100	49u	18.588	18.927	0.339
100	50u	18.604	18.923	0.319
100	51u	18.599	18.970	0.371
100	52u	18.745	18.805	0.060
	Max	18.745	19.193	0.598
	Average	18.623	18.860	0.238
	Min	18.435	18.427	-0.173
	Std Dev	0.082	0.220	0.237

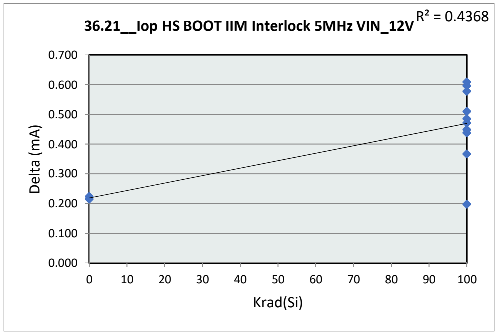


	36.20__Iop LS VIN IIM Interlock 5MHz VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	18.427	18.805
Average	18.448	18.943
Max	18.468	19.193
UL	30.000	30.000

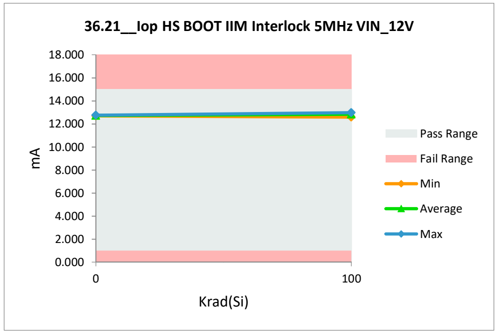


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.21__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	15	15	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	12.475	12.697	0.223
0	2	12.548	12.763	0.215
100	23	12.308	12.917	0.609
100	24	12.378	12.863	0.485
100	25	12.326	12.922	0.596
100	26	12.286	12.757	0.471
100	27	12.351	12.718	0.367
100	48u	12.550	12.987	0.437
100	49u	12.379	12.576	0.197
100	50u	12.490	12.937	0.448
100	51u	12.273	12.782	0.509
100	52u	12.345	12.922	0.577
	Max	12.550	12.987	0.609
	Average	12.392	12.820	0.428
	Min	12.273	12.576	0.197
	Std Dev	0.099	0.123	0.148

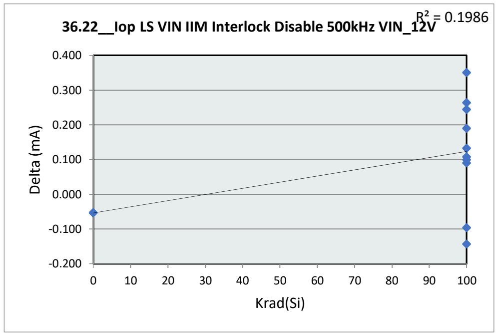


	36.21__Iop HS BOOT IIM Interlock 5MHz VI	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	12.697	12.576
Average	12.730	12.838
Max	12.763	12.987
UL	15.000	15.000

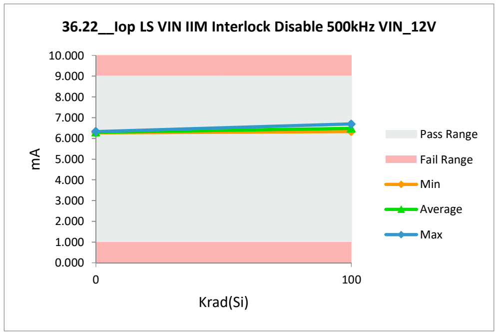


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.22__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	9	9	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	6.376	6.323	-0.053
0	2	6.319	6.265	-0.054
100	23	6.462	6.365	-0.097
100	24	6.379	6.569	0.190
100	25	6.428	6.691	0.263
100	26	6.169	6.520	0.351
100	27	6.412	6.511	0.099
100	48u	6.259	6.349	0.090
100	49u	6.300	6.433	0.133
100	50u	6.312	6.420	0.107
100	51u	6.345	6.589	0.244
100	52u	6.473	6.330	-0.143
	Max	6.473	6.691	0.351
	Average	6.353	6.447	0.094
	Min	6.169	6.265	-0.143
	Std Dev	0.088	0.129	0.155

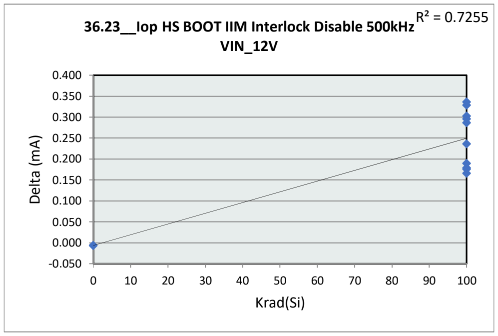


	36.22__Iop LS VIN IIM Interlock Disable 50	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	6.265	6.330
Average	6.294	6.478
Max	6.323	6.691
UL	9.000	9.000

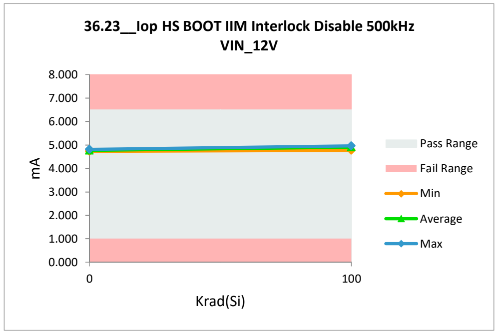


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.23__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.5	6.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.738	4.731	-0.007
0	2	4.816	4.810	-0.006
100	23	4.626	4.962	0.336
100	24	4.664	4.951	0.287
100	25	4.635	4.964	0.329
100	26	4.595	4.771	0.176
100	27	4.602	4.838	0.236
100	48u	4.796	4.961	0.166
100	49u	4.692	4.871	0.179
100	50u	4.740	4.930	0.190
100	51u	4.542	4.838	0.296
100	52u	4.641	4.943	0.302
	Max	4.816	4.964	0.336
	Average	4.674	4.881	0.207
	Min	4.542	4.731	-0.007
	Std Dev	0.084	0.082	0.117

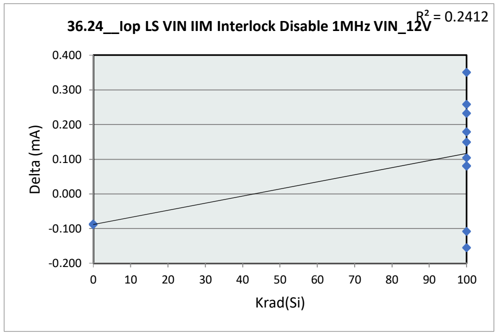


	36.23__Iop HS BOOT IIM Interlock Disable 5	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.731	4.771
Average	4.771	4.903
Max	4.810	4.964
UL	6.500	6.500

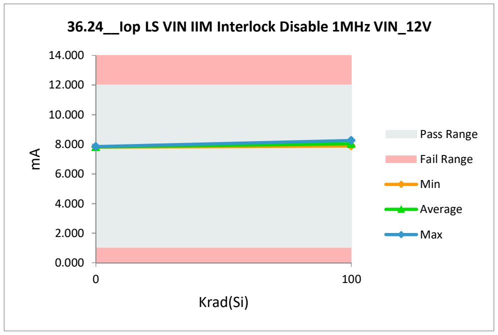


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.24__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		12	12	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.939	7.850	-0.089
0	2	7.885	7.797	-0.088
100	23	8.025	7.917	-0.108
100	24	7.942	8.121	0.178
100	25	7.994	8.252	0.258
100	26	7.734	8.084	0.350
100	27	7.977	8.057	0.080
100	48u	7.822	7.902	0.079
100	49u	7.869	8.018	0.149
100	50u	7.877	7.982	0.104
100	51u	7.908	8.139	0.232
100	52u	8.040	7.884	-0.156
	Max	8.040	8.252	0.350
	Average	7.918	8.000	0.083
	Min	7.734	7.797	-0.156
	Std Dev	0.088	0.136	0.162

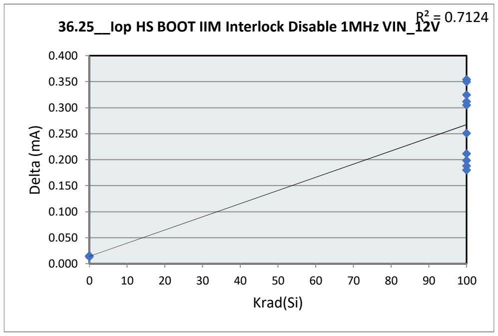


	36.24__Iop LS VIN IIM Interlock Disable 1M	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.797	7.884
Average	7.824	8.036
Max	7.850	8.252
UL	12.000	12.000

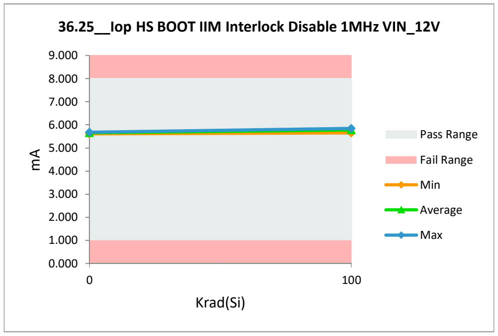


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.25__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.593	5.608	0.016
0	2	5.672	5.685	0.013
100	23	5.480	5.834	0.354
100	24	5.520	5.825	0.305
100	25	5.488	5.838	0.350
100	26	5.448	5.646	0.198
100	27	5.455	5.706	0.251
100	48u	5.654	5.842	0.188
100	49u	5.545	5.725	0.180
100	50u	5.601	5.812	0.211
100	51u	5.399	5.711	0.312
100	52u	5.495	5.820	0.325
	Max	5.672	5.842	0.354
	Average	5.529	5.754	0.225
	Min	5.399	5.608	0.013
	Std Dev	0.085	0.083	0.117

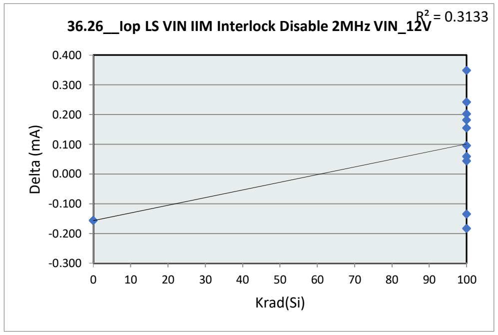


	36.25__Iop HS BOOT IIM Interlock Disable 1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.608	5.646
Average	5.647	5.776
Max	5.685	5.842
UL	8.000	8.000

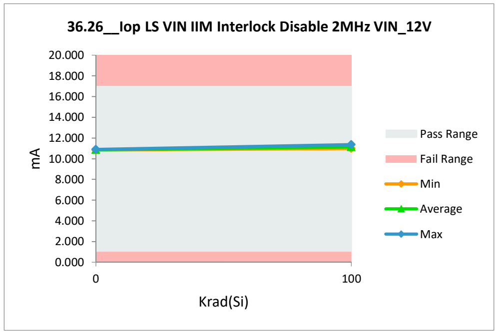


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.26__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	17	17	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	11.051	10.894	-0.157
0	2	11.002	10.846	-0.156
100	23	11.143	11.008	-0.135
100	24	11.058	11.212	0.154
100	25	11.114	11.356	0.242
100	26	10.851	11.199	0.349
100	27	11.096	11.141	0.044
100	48u	10.936	10.995	0.059
100	49u	10.997	11.178	0.181
100	50u	10.996	11.092	0.096
100	51u	11.022	11.224	0.202
100	52u	11.161	10.977	-0.183
	Max	11.161	11.356	0.349
	Average	11.036	11.094	0.058
	Min	10.851	10.846	-0.183
	Std Dev	0.088	0.151	0.179



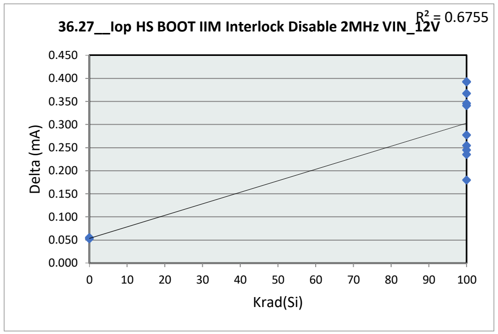
	36.26__Iop LS VIN IIM Interlock Disable 2M	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	17	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	10.846	10.977
Average	10.870	11.138
Max	10.894	11.356
UL	17.000	17.000



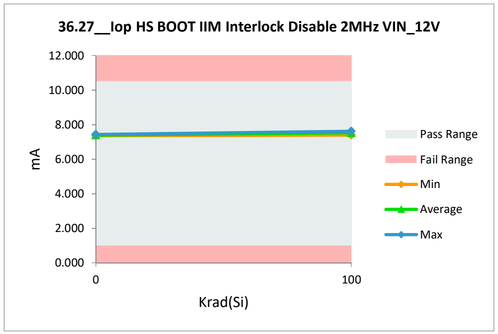
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	36.27__Iop HS BOOT IIM Interlo	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	mA	mA
Max Limit	10.5	10.5
Min Limit	1	1

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.302	7.357	0.055
0	2	7.383	7.435	0.052
100	23	7.189	7.582	0.392
100	24	7.235	7.576	0.341
100	25	7.196	7.589	0.393
100	26	7.150	7.394	0.245
100	27	7.162	7.439	0.277
100	48u	7.370	7.605	0.235
100	49u	7.251	7.430	0.179
100	50u	7.321	7.576	0.254
100	51u	7.115	7.460	0.345
100	52u	7.204	7.571	0.367
	Max	7.383	7.605	0.393
	Average	7.240	7.501	0.261
	Min	7.115	7.357	0.052
	Std Dev	0.087	0.089	0.118

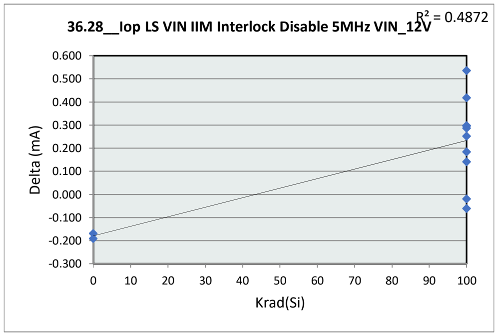


	36.27__Iop HS BOOT IIM Interlock Disable 2	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.357	7.394
Average	7.396	7.522
Max	7.435	7.605
UL	10.500	10.500

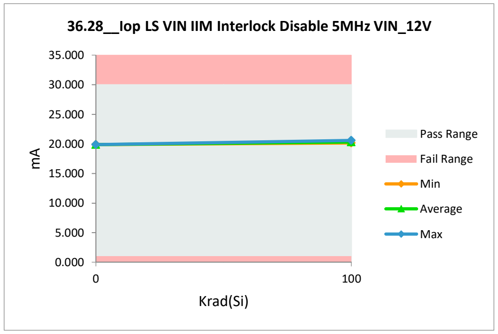


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.28__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	30	30	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	20.062	19.893	-0.168
0	2	20.048	19.857	-0.191
100	23	20.171	20.152	-0.019
100	24	20.082	20.369	0.287
100	25	20.147	20.565	0.418
100	26	19.868	20.403	0.535
100	27	20.125	20.265	0.141
100	48u	19.969	20.152	0.184
100	49u	20.023	20.321	0.298
100	50u	20.036	20.288	0.252
100	51u	20.046	20.343	0.297
100	52u	20.189	20.127	-0.061
	Max	20.189	20.565	0.535
	Average	20.064	20.228	0.164
	Min	19.868	19.857	-0.191
	Std Dev	0.090	0.205	0.230

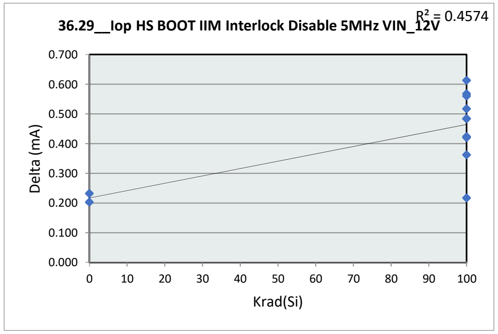


	36.28__Iop LS VIN IIM Interlock Disable 5M	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	19.857	20.127
Average	19.875	20.299
Max	19.893	20.565
UL	30.000	30.000

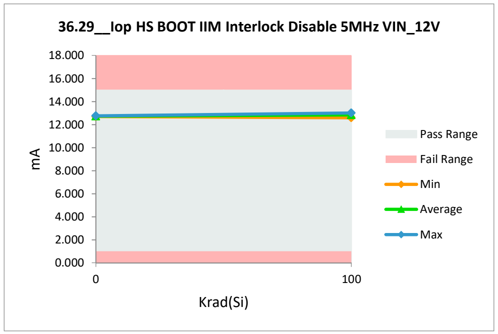


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		36.29__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		15	15	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	12.461	12.692	0.231
0	2	12.555	12.758	0.203
100	23	12.302	12.916	0.613
100	24	12.369	12.852	0.483
100	25	12.352	12.920	0.568
100	26	12.275	12.758	0.483
100	27	12.351	12.714	0.362
100	48u	12.565	12.989	0.424
100	49u	12.367	12.583	0.217
100	50u	12.516	12.937	0.421
100	51u	12.265	12.782	0.517
100	52u	12.359	12.919	0.560
	Max	12.565	12.989	0.613
	Average	12.395	12.818	0.424
	Min	12.265	12.583	0.203
	Std Dev	0.105	0.122	0.143

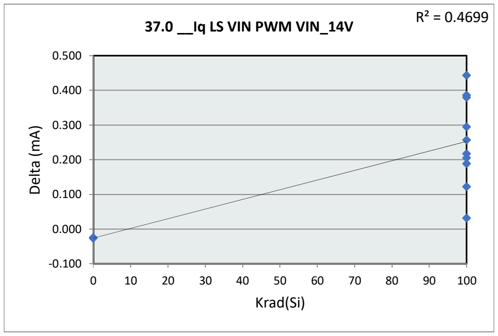


	36.29__Iop HS BOOT IIM Interlock Disable 5	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	12.692	12.583
Average	12.725	12.837
Max	12.758	12.989
UL	15.000	15.000

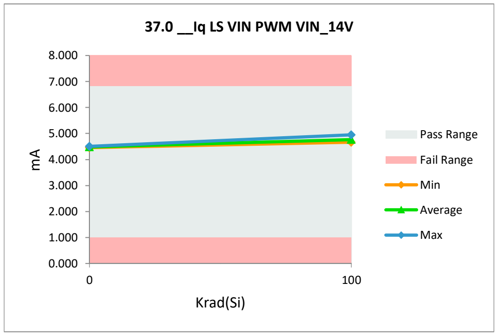


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.0 __Iq LS VIN PWM VIN_14V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		6.8	6.8	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.528	4.501	-0.027
0	2	4.479	4.454	-0.025
100	23	4.584	4.707	0.122
100	24	4.538	4.833	0.295
100	25	4.563	4.950	0.386
100	26	4.335	4.778	0.443
100	27	4.577	4.835	0.257
100	48u	4.485	4.674	0.188
100	49u	4.455	4.671	0.217
100	50u	4.492	4.697	0.205
100	51u	4.483	4.863	0.380
100	52u	4.636	4.668	0.032
	Max	4.636	4.950	0.443
	Average	4.513	4.719	0.206
	Min	4.335	4.454	-0.027
	Std Dev	0.077	0.144	0.158

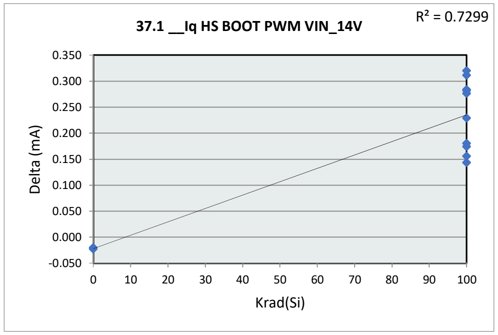


	37.0 __Iq LS VIN PWM VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.454	4.668
Average	4.478	4.768
Max	4.501	4.950
UL	6.800	6.800

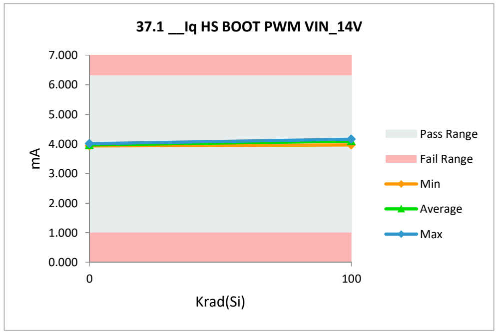


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.1 __Iq HS BOOT PWM VIN_14		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		6.3	6.3	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.949	3.928	-0.020
0	2	4.027	4.004	-0.023
100	23	3.837	4.157	0.320
100	24	3.869	4.146	0.276
100	25	3.847	4.158	0.311
100	26	3.808	3.964	0.156
100	27	3.812	4.041	0.229
100	48u	4.005	4.148	0.143
100	49u	3.905	4.085	0.180
100	50u	3.944	4.118	0.174
100	51u	3.750	4.032	0.282
100	52u	3.853	4.137	0.284
	Max	4.027	4.158	0.320
	Average	3.884	4.076	0.193
	Min	3.750	3.928	-0.023
	Std Dev	0.084	0.081	0.117

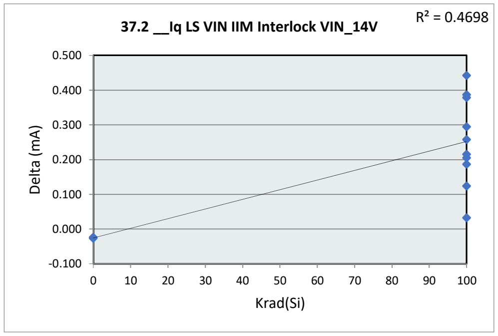


	37.1 __Iq HS BOOT PWM VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.3	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	3.929	3.964
Average	3.966	4.098
Max	4.004	4.158
UL	6.300	6.300

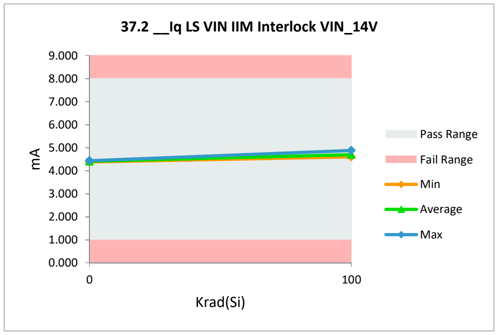


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.2 __Iq LS VIN IIM Interlock V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.455	4.429	-0.027
0	2	4.407	4.383	-0.024
100	23	4.512	4.635	0.123
100	24	4.466	4.760	0.294
100	25	4.491	4.878	0.386
100	26	4.264	4.706	0.442
100	27	4.506	4.763	0.257
100	48u	4.414	4.600	0.186
100	49u	4.382	4.598	0.215
100	50u	4.419	4.624	0.205
100	51u	4.412	4.790	0.378
100	52u	4.565	4.597	0.032
	Max	4.565	4.878	0.442
	Average	4.441	4.647	0.206
	Min	4.264	4.383	-0.027
	Std Dev	0.078	0.144	0.158



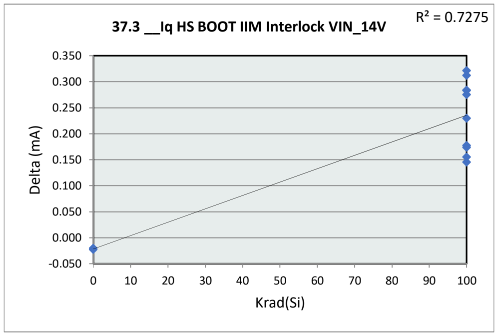
	37.2 __Iq LS VIN IIM Interlock VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.383	4.598
Average	4.406	4.695
Max	4.429	4.878
UL	8.000	8.000



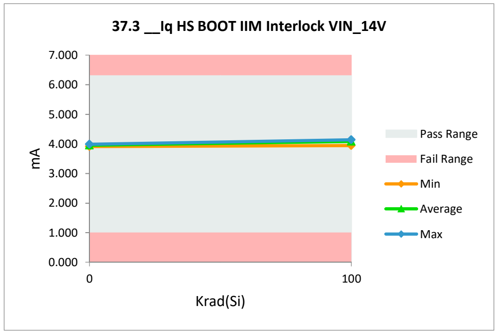
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	37.3 __Iq HS BOOT IIM Interloc	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	mA	mA
Max Limit	6.3	6.3
Min Limit	1	1

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.933	3.913	-0.020
0	2	4.010	3.988	-0.023
100	23	3.820	4.142	0.322
100	24	3.854	4.129	0.275
100	25	3.830	4.143	0.312
100	26	3.793	3.948	0.155
100	27	3.795	4.025	0.229
100	48u	3.989	4.134	0.145
100	49u	3.890	4.067	0.178
100	50u	3.929	4.102	0.174
100	51u	3.734	4.017	0.283
100	52u	3.838	4.121	0.284
	Max	4.010	4.143	0.322
	Average	3.868	4.061	0.193
	Min	3.734	3.913	-0.023
	Std Dev	0.084	0.081	0.117

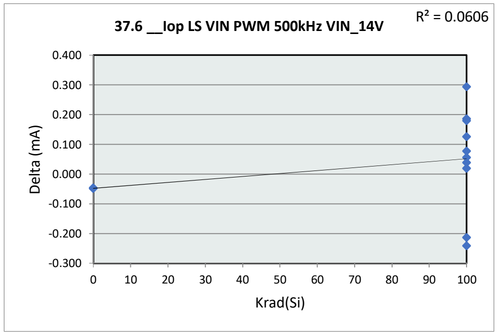


	37.3 __Iq HS BOOT IIM Interlock VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.3	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	3.913	3.948
Average	3.950	4.083
Max	3.988	4.143
UL	6.300	6.300

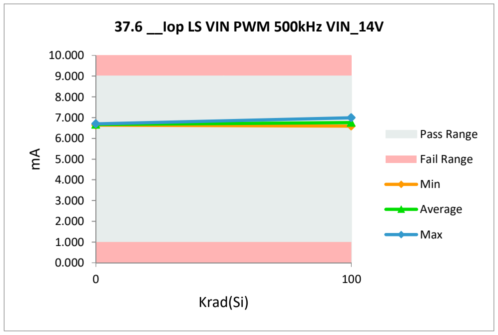


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.6 __Iop LS VIN PWM 500kHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		9	9	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	6.742	6.693	-0.049
0	2	6.679	6.632	-0.047
100	23	6.837	6.624	-0.214
100	24	6.738	6.864	0.126
100	25	6.802	6.988	0.186
100	26	6.525	6.819	0.294
100	27	6.766	6.785	0.019
100	48u	6.582	6.620	0.038
100	49u	6.658	6.735	0.077
100	50u	6.657	6.713	0.055
100	51u	6.717	6.897	0.180
100	52u	6.832	6.590	-0.242
	Max	6.837	6.988	0.294
	Average	6.711	6.747	0.035
	Min	6.525	6.590	-0.242
	Std Dev	0.096	0.126	0.158

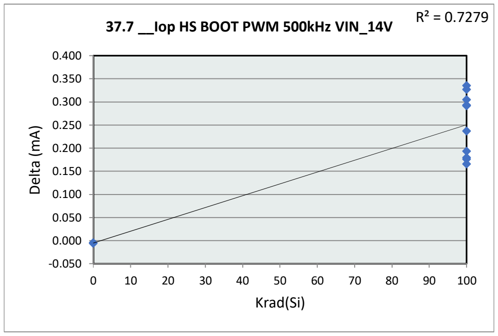


	37.6 __Iop LS VIN PWM 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	6.632	6.590
Average	6.662	6.763
Max	6.693	6.988
UL	9.000	9.000

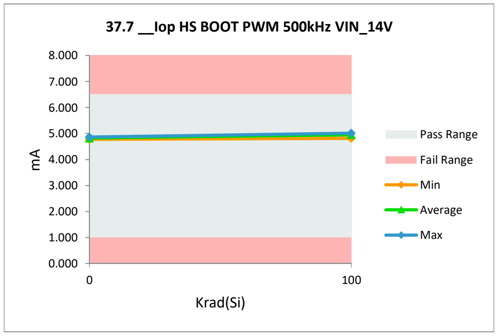


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.7 __Iop HS BOOT PWM 500kH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.5	6.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.787	4.783	-0.004
0	2	4.865	4.859	-0.006
100	23	4.673	5.008	0.335
100	24	4.706	4.998	0.292
100	25	4.684	5.011	0.327
100	26	4.642	4.818	0.176
100	27	4.650	4.887	0.237
100	48u	4.845	5.010	0.166
100	49u	4.741	4.920	0.180
100	50u	4.786	4.979	0.194
100	51u	4.592	4.885	0.293
100	52u	4.690	4.996	0.305
	Max	4.865	5.011	0.335
	Average	4.722	4.930	0.208
	Min	4.592	4.783	-0.006
	Std Dev	0.084	0.082	0.117

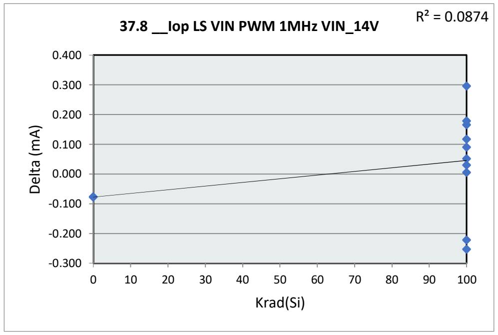


	37.7 __Iop HS BOOT PWM 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.783	4.818
Average	4.821	4.951
Max	4.859	5.011
UL	6.500	6.500

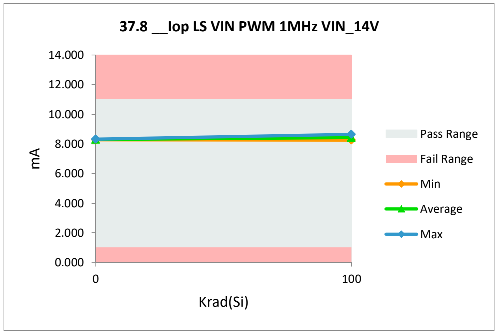


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.8 __Iop LS VIN PWM 1MHz VI		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		11	11	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	8.402	8.324	-0.078
0	2	8.346	8.269	-0.077
100	23	8.502	8.280	-0.222
100	24	8.399	8.516	0.117
100	25	8.471	8.649	0.178
100	26	8.191	8.487	0.296
100	27	8.431	8.436	0.005
100	48u	8.249	8.278	0.030
100	49u	8.329	8.420	0.090
100	50u	8.325	8.376	0.051
100	51u	8.381	8.547	0.166
100	52u	8.500	8.247	-0.253
	Max	8.502	8.649	0.296
	Average	8.377	8.402	0.025
	Min	8.191	8.247	-0.253
	Std Dev	0.096	0.129	0.162

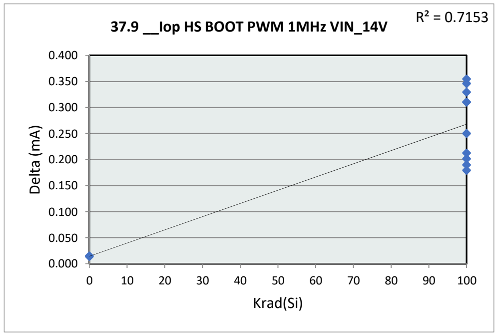


	37.8 __Iop LS VIN PWM 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	11	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	8.269	8.247
Average	8.296	8.424
Max	8.324	8.649
UL	11.000	11.000

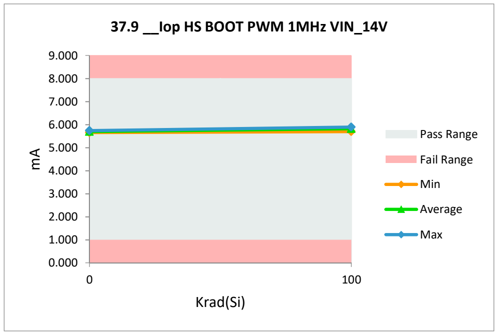


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.9 __Iop HS BOOT PWM 1MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.646	5.661	0.015
0	2	5.722	5.735	0.014
100	23	5.527	5.881	0.355
100	24	5.563	5.873	0.310
100	25	5.540	5.886	0.346
100	26	5.493	5.695	0.201
100	27	5.503	5.753	0.250
100	48u	5.703	5.893	0.189
100	49u	5.595	5.774	0.179
100	50u	5.644	5.857	0.212
100	51u	5.448	5.757	0.310
100	52u	5.545	5.874	0.329
	Max	5.722	5.893	0.355
	Average	5.577	5.803	0.226
	Min	5.448	5.661	0.014
	Std Dev	0.086	0.083	0.117

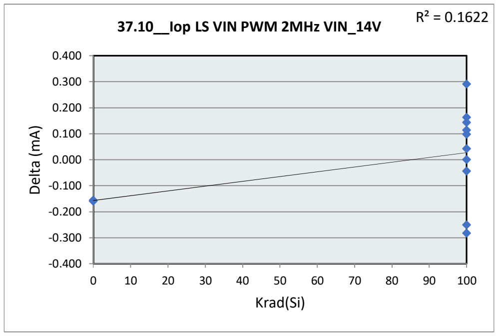


	37.9 __Iop HS BOOT PWM 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.661	5.695
Average	5.698	5.824
Max	5.736	5.893
UL	8.000	8.000

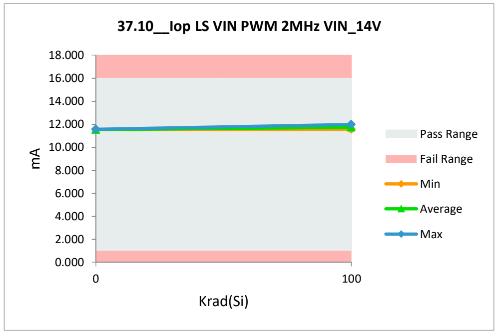


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.10__Iop LS VIN PWM 2MHz V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	16	16	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	11.720	11.562	-0.159
0	2	11.679	11.525	-0.155
100	23	11.822	11.572	-0.251
100	24	11.718	11.816	0.098
100	25	11.801	11.964	0.163
100	26	11.523	11.814	0.291
100	27	11.759	11.715	-0.043
100	48u	11.567	11.567	0.001
100	49u	11.670	11.783	0.114
100	50u	11.659	11.702	0.043
100	51u	11.709	11.852	0.143
100	52u	11.837	11.555	-0.282
	Max	11.837	11.964	0.291
	Average	11.705	11.702	-0.003
	Min	11.523	11.525	-0.282
	Std Dev	0.095	0.145	0.178

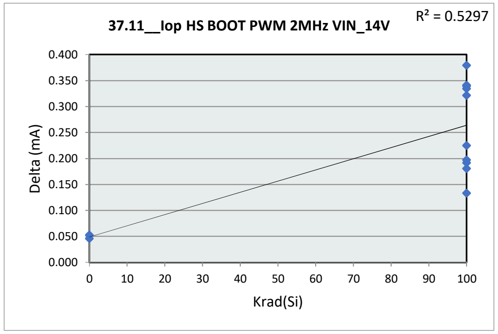


	37.10__Iop LS VIN PWM 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	16	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	11.525	11.555
Average	11.543	11.734
Max	11.562	11.964
UL	16.000	16.000

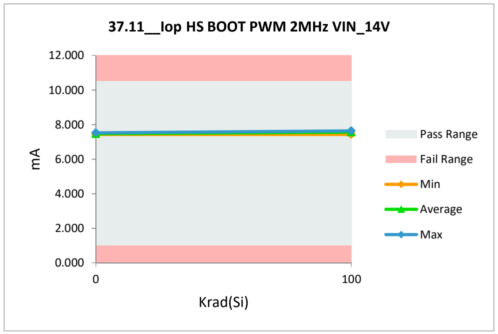


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.11__Iop HS BOOT PWM 2MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		10.5	10.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.380	7.426	0.046
0	2	7.464	7.516	0.052
100	23	7.215	7.594	0.379
100	24	7.267	7.607	0.339
100	25	7.287	7.621	0.334
100	26	7.231	7.422	0.191
100	27	7.244	7.469	0.225
100	48u	7.444	7.624	0.180
100	49u	7.331	7.464	0.133
100	50u	7.392	7.589	0.197
100	51u	7.199	7.520	0.321
100	52u	7.275	7.616	0.341
	Max	7.464	7.624	0.379
	Average	7.311	7.539	0.228
	Min	7.199	7.422	0.046
	Std Dev	0.090	0.079	0.115

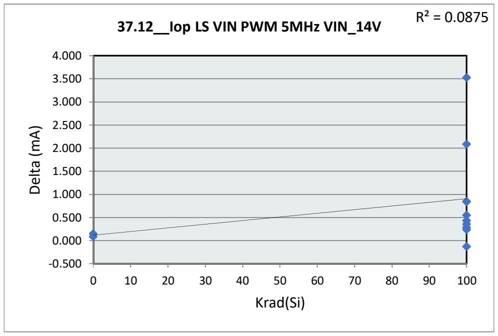


	37.11__Iop HS BOOT PWM 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.426	7.422
Average	7.471	7.552
Max	7.516	7.624
UL	10.500	10.500

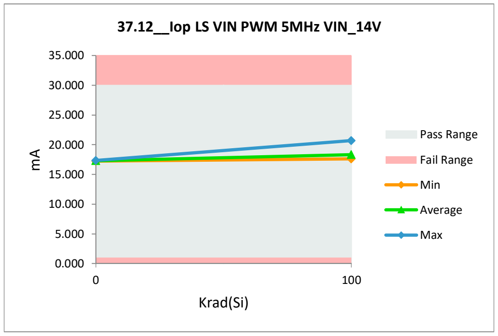


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.12__Iop LS VIN PWM 5MHz V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	30	30	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	17.196	17.343	0.147
0	2	17.132	17.215	0.084
100	23	17.771	17.645	-0.126
100	24	17.621	17.976	0.355
100	25	17.433	18.272	0.839
100	26	17.005	17.854	0.849
100	27	17.734	17.974	0.240
100	48u	17.339	17.892	0.552
100	49u	17.333	17.622	0.289
100	50u	17.332	17.764	0.433
100	51u	17.144	20.670	3.526
100	52u	17.524	19.611	2.087
	Max	17.771	20.670	3.526
	Average	17.380	18.153	0.773
	Min	17.005	17.215	-0.126
	Std Dev	0.245	0.997	1.038



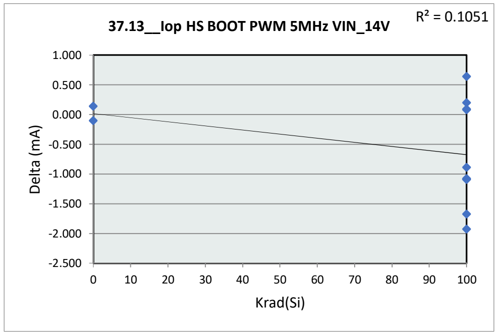
	37.12__Iop LS VIN PWM 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	17.216	17.622
Average	17.279	18.328
Max	17.343	20.670
UL	30.000	30.000



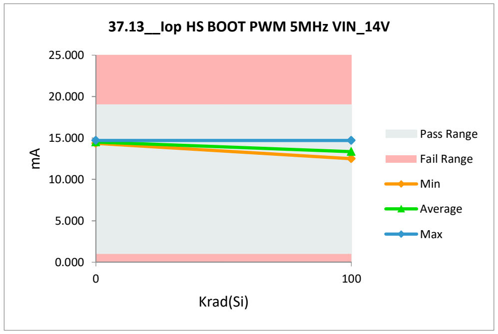
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	37.13__Iop HS BOOT PWM 5MHz	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	mA	mA
Max Limit	19	19
Min Limit	1	1

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	14.549	14.690	0.141
0	2	14.470	14.365	-0.105
100	23	12.414	12.495	0.080
100	24	13.454	13.544	0.090
100	25	14.311	13.422	-0.890
100	26	14.240	13.164	-1.076
100	27	14.407	13.321	-1.086
100	48u	14.663	12.733	-1.930
100	49u	14.460	13.367	-1.093
100	50u	14.550	12.877	-1.673
100	51u	14.077	14.717	0.639
100	52u	13.861	14.059	0.197
	Max	14.663	14.717	0.639
	Average	14.121	13.563	-0.559
	Min	12.414	12.495	-1.930
	Std Dev	0.636	0.743	0.831

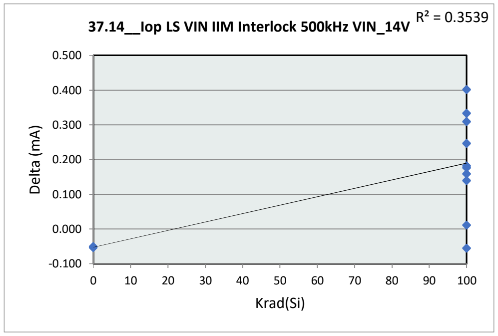


	37.13__Iop HS BOOT PWM 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	19	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	14.365	12.495
Average	14.528	13.370
Max	14.690	14.717
UL	19.000	19.000

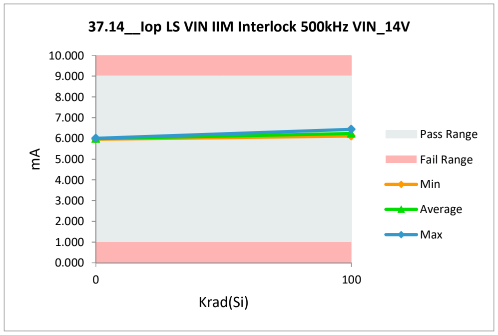


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.14__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		9	9	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	6.060	6.006	-0.054
0	2	6.009	5.958	-0.051
100	23	6.136	6.147	0.011
100	24	6.070	6.316	0.247
100	25	6.107	6.439	0.333
100	26	5.866	6.267	0.401
100	27	6.104	6.280	0.176
100	48u	5.983	6.122	0.139
100	49u	5.992	6.173	0.181
100	50u	6.015	6.173	0.159
100	51u	6.027	6.335	0.309
100	52u	6.165	6.109	-0.056
	Max	6.165	6.439	0.401
	Average	6.044	6.194	0.150
	Min	5.866	5.958	-0.056
	Std Dev	0.081	0.140	0.158

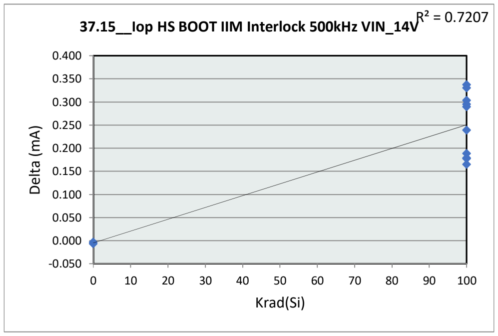


	37.14__Iop LS VIN IIM Interlock 500kHz VI	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.959	6.109
Average	5.982	6.236
Max	6.006	6.440
UL	9.000	9.000

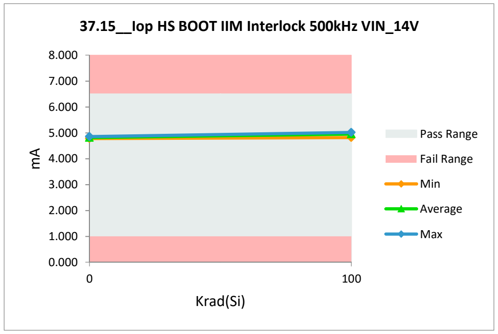


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.15__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.5	6.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.783	4.780	-0.003
0	2	4.864	4.857	-0.006
100	23	4.672	5.009	0.337
100	24	4.707	4.996	0.289
100	25	4.680	5.011	0.331
100	26	4.640	4.817	0.177
100	27	4.646	4.885	0.239
100	48u	4.843	5.008	0.165
100	49u	4.739	4.917	0.179
100	50u	4.787	4.975	0.188
100	51u	4.588	4.883	0.295
100	52u	4.688	4.991	0.303
	Max	4.864	5.011	0.337
	Average	4.720	4.928	0.208
	Min	4.588	4.780	-0.006
	Std Dev	0.085	0.082	0.117

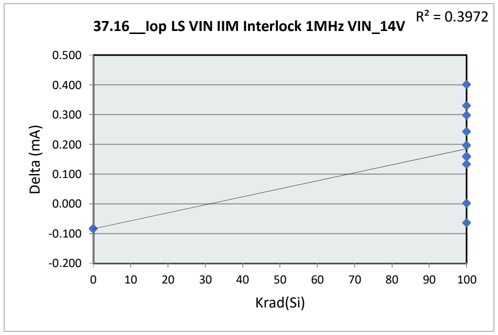


	37.15__Iop HS BOOT IIM Interlock 500kHz V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.780	4.817
Average	4.819	4.949
Max	4.857	5.011
UL	6.500	6.500

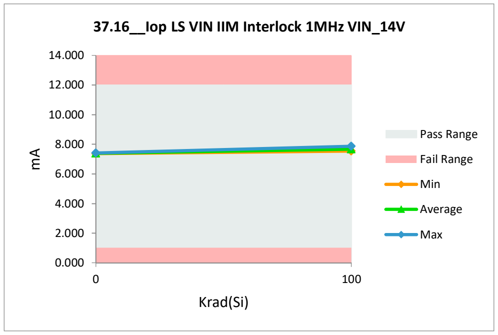


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.16__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		12	12	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.496	7.411	-0.084
0	2	7.448	7.365	-0.083
100	23	7.572	7.574	0.002
100	24	7.505	7.748	0.243
100	25	7.546	7.876	0.330
100	26	7.306	7.707	0.401
100	27	7.544	7.703	0.160
100	48u	7.419	7.551	0.132
100	49u	7.435	7.632	0.197
100	50u	7.453	7.611	0.158
100	51u	7.462	7.760	0.298
100	52u	7.605	7.541	-0.064
	Max	7.605	7.876	0.401
	Average	7.483	7.623	0.141
	Min	7.306	7.365	-0.084
	Std Dev	0.081	0.147	0.166



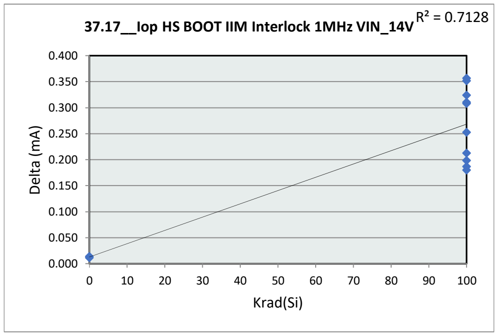
	37.16__Iop LS VIN IIM Interlock 1MHz VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.365	7.541
Average	7.388	7.670
Max	7.411	7.876
UL	12.000	12.000



TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

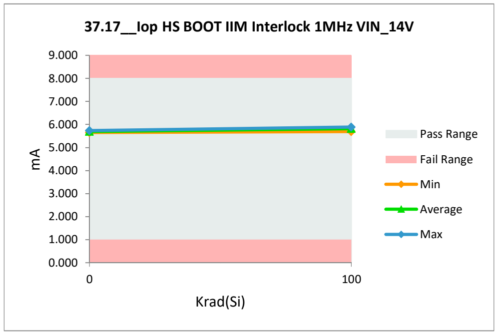
37.17__Iop HS BOOT IIM Interlo

Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.639	5.653	0.014
0	2	5.721	5.733	0.012
100	23	5.525	5.882	0.357
100	24	5.564	5.872	0.308
100	25	5.534	5.885	0.352
100	26	5.491	5.690	0.199
100	27	5.498	5.751	0.253
100	48u	5.702	5.889	0.187
100	49u	5.592	5.772	0.180
100	50u	5.645	5.858	0.212
100	51u	5.446	5.757	0.311
100	52u	5.542	5.866	0.324
	Max	5.721	5.889	0.357
	Average	5.575	5.801	0.226
	Min	5.446	5.653	0.012
	Std Dev	0.086	0.084	0.118


37.17__Iop HS BOOT IIM Interlock 1MHz VIN_14V

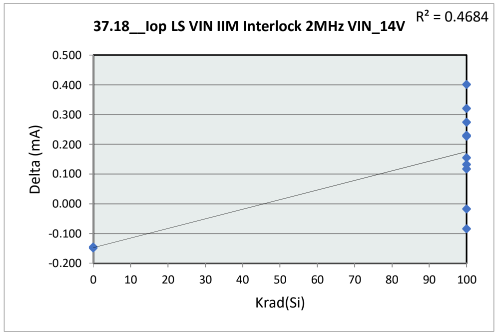
37.17__Iop HS BOOT IIM Interlock 1MHz VI

Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.653	5.690
Average	5.693	5.822
Max	5.733	5.889
UL	8.000	8.000

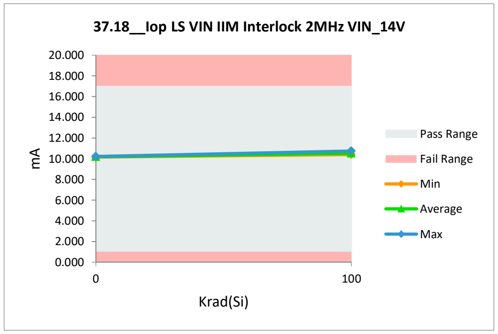

37.17__Iop HS BOOT IIM Interlock 1MHz VIN_14V

TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.18__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	17	17	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	10.358	10.209	-0.149
0	2	10.314	10.167	-0.146
100	23	10.437	10.419	-0.018
100	24	10.368	10.595	0.226
100	25	10.415	10.735	0.320
100	26	10.175	10.575	0.401
100	27	10.410	10.542	0.132
100	48u	10.283	10.401	0.117
100	49u	10.311	10.541	0.230
100	50u	10.321	10.475	0.155
100	51u	10.326	10.600	0.274
100	52u	10.474	10.390	-0.084
	Max	10.474	10.735	0.401
	Average	10.349	10.471	0.121
	Min	10.175	10.167	-0.149
	Std Dev	0.080	0.164	0.184

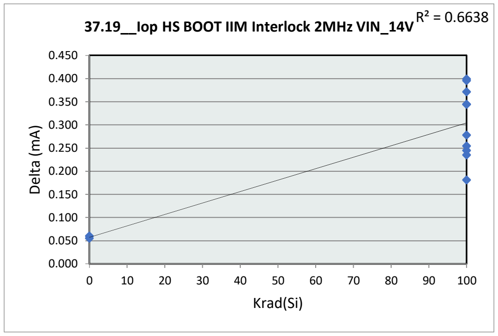


	37.18__Iop LS VIN IIM Interlock 2MHz VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	17	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	10.167	10.390
Average	10.188	10.527
Max	10.209	10.735
UL	17.000	17.000

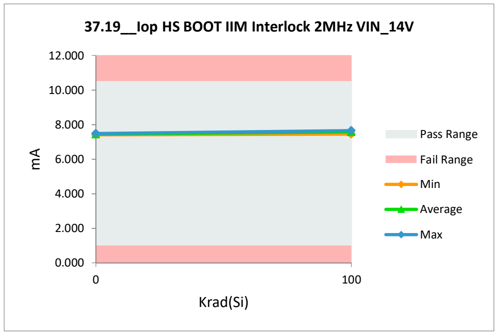


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.19__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		10.5	10.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.348	7.407	0.059
0	2	7.431	7.486	0.055
100	23	7.234	7.633	0.399
100	24	7.280	7.625	0.344
100	25	7.244	7.639	0.395
100	26	7.195	7.439	0.244
100	27	7.207	7.484	0.277
100	48u	7.418	7.653	0.235
100	49u	7.298	7.479	0.181
100	50u	7.368	7.622	0.254
100	51u	7.162	7.506	0.344
100	52u	7.251	7.622	0.371
	Max	7.431	7.653	0.399
	Average	7.286	7.550	0.263
	Min	7.162	7.407	0.055
	Std Dev	0.088	0.090	0.118



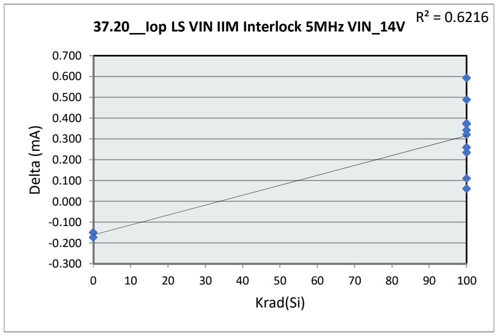
	37.19__Iop HS BOOT IIM Interlock 2MHz VI	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.407	7.439
Average	7.447	7.570
Max	7.486	7.653
UL	10.500	10.500



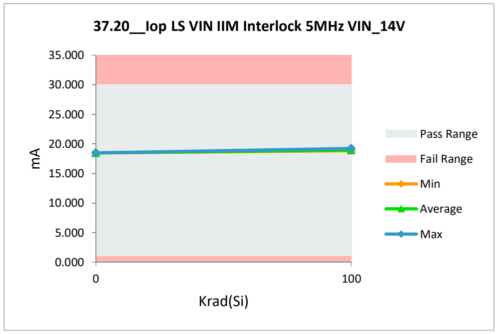
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	37.20__Iop LS VIN IIM Interlock	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	mA	mA
Max Limit	30	30
Min Limit	1	1

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.652	18.502	-0.149
0	2	18.636	18.462	-0.173
100	23	18.743	18.853	0.110
100	24	18.670	19.045	0.375
100	25	18.735	19.224	0.489
100	26	18.474	19.067	0.592
100	27	18.724	18.958	0.235
100	48u	18.592	18.852	0.260
100	49u	18.622	18.965	0.343
100	50u	18.643	18.963	0.320
100	51u	18.634	19.006	0.372
100	52u	18.776	18.838	0.062
	Max	18.776	19.224	0.592
	Average	18.658	18.895	0.236
	Min	18.474	18.462	-0.173
	Std Dev	0.081	0.220	0.236

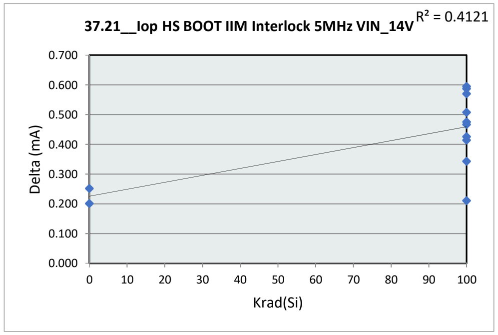


	37.20__Iop LS VIN IIM Interlock 5MHz VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	18.462	18.838
Average	18.482	18.977
Max	18.502	19.224
UL	30.000	30.000

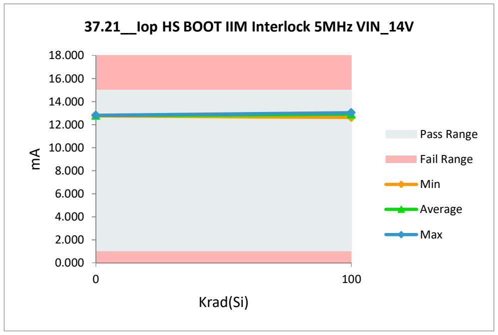


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.21__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		15	15	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	12.496	12.747	0.251
0	2	12.612	12.812	0.200
100	23	12.378	12.972	0.594
100	24	12.426	12.901	0.476
100	25	12.412	12.981	0.569
100	26	12.339	12.806	0.466
100	27	12.425	12.767	0.342
100	48u	12.613	13.038	0.425
100	49u	12.414	12.624	0.210
100	50u	12.570	12.984	0.414
100	51u	12.324	12.832	0.508
100	52u	12.388	12.975	0.587
	Max	12.613	13.038	0.594
	Average	12.450	12.870	0.420
	Min	12.324	12.624	0.200
	Std Dev	0.100	0.125	0.142

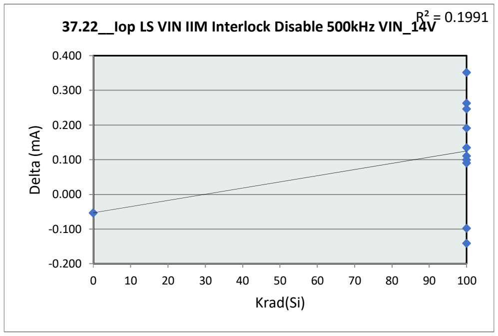


	37.21__Iop HS BOOT IIM Interlock 5MHz VI	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	12.747	12.624
Average	12.779	12.888
Max	12.812	13.038
UL	15.000	15.000

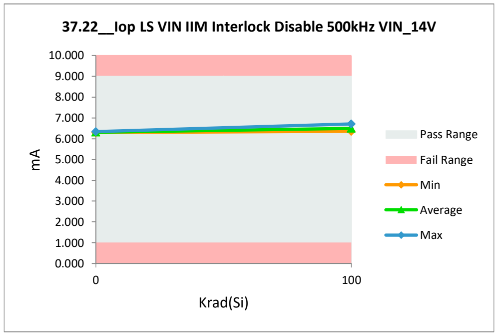


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.22__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		9	9	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	6.400	6.347	-0.054
0	2	6.343	6.290	-0.053
100	23	6.485	6.387	-0.098
100	24	6.403	6.594	0.191
100	25	6.452	6.715	0.263
100	26	6.193	6.545	0.352
100	27	6.435	6.535	0.099
100	48u	6.282	6.372	0.090
100	49u	6.323	6.458	0.135
100	50u	6.335	6.445	0.110
100	51u	6.370	6.616	0.246
100	52u	6.496	6.354	-0.142
	Max	6.496	6.715	0.352
	Average	6.376	6.471	0.095
	Min	6.193	6.290	-0.142
	Std Dev	0.088	0.129	0.155

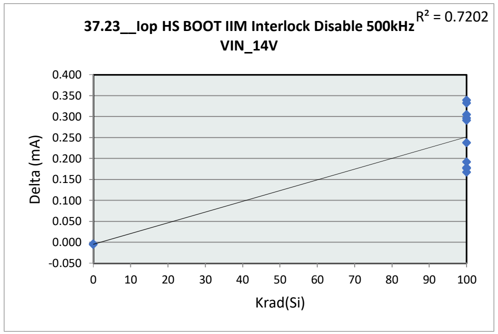


	37.22__Iop LS VIN IIM Interlock Disable 50	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	6.290	6.355
Average	6.318	6.502
Max	6.347	6.715
UL	9.000	9.000

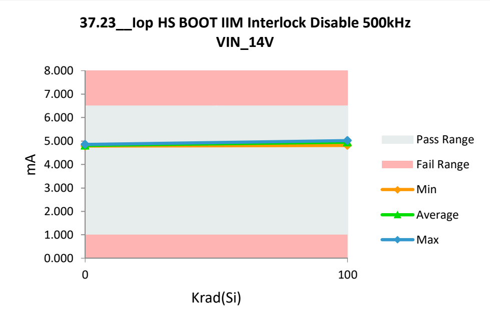


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.23__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		6.5	6.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.783	4.779	-0.004
0	2	4.863	4.857	-0.005
100	23	4.672	5.011	0.339
100	24	4.708	4.999	0.291
100	25	4.680	5.012	0.332
100	26	4.640	4.816	0.176
100	27	4.646	4.884	0.238
100	48u	4.842	5.009	0.167
100	49u	4.738	4.916	0.178
100	50u	4.785	4.976	0.192
100	51u	4.587	4.883	0.296
100	52u	4.687	4.991	0.304
	Max	4.863	5.012	0.339
	Average	4.719	4.928	0.209
	Min	4.587	4.779	-0.005
	Std Dev	0.084	0.083	0.117



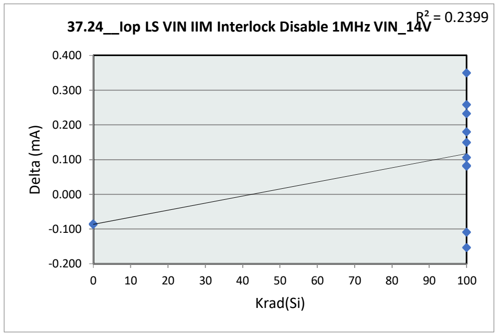
	37.23__Iop HS BOOT IIM Interlock Disable 5	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.779	4.816
Average	4.818	4.950
Max	4.857	5.012
UL	6.500	6.500



TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

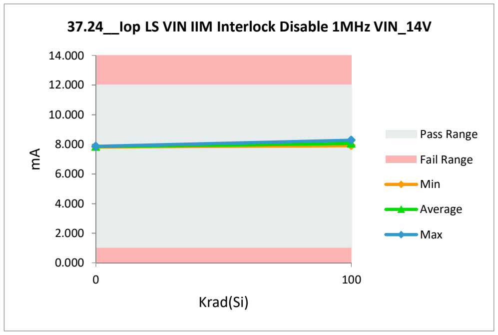
37.24__Iop LS VIN IIM Interlock

Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		12	12	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.963	7.876	-0.087
0	2	7.908	7.822	-0.085
100	23	8.051	7.942	-0.109
100	24	7.967	8.147	0.180
100	25	8.018	8.276	0.258
100	26	7.759	8.109	0.350
100	27	8.001	8.082	0.081
100	48u	7.845	7.928	0.083
100	49u	7.894	8.043	0.149
100	50u	7.902	8.007	0.106
100	51u	7.933	8.165	0.232
100	52u	8.063	7.910	-0.153
	Max	8.063	8.276	0.350
	Average	7.942	8.025	0.083
	Min	7.759	7.822	-0.153
	Std Dev	0.088	0.135	0.162



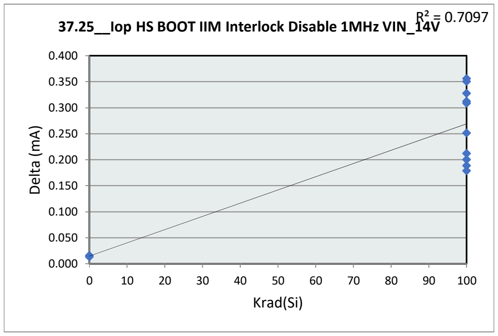
37.24__Iop LS VIN IIM Interlock Disable 1M

Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.822	7.910
Average	7.849	8.061
Max	7.876	8.276
UL	12.000	12.000

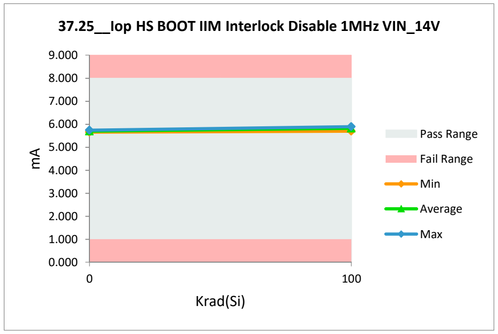


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.25__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.637	5.654	0.016
0	2	5.719	5.733	0.013
100	23	5.526	5.882	0.356
100	24	5.564	5.873	0.309
100	25	5.534	5.885	0.351
100	26	5.492	5.692	0.200
100	27	5.499	5.750	0.252
100	48u	5.700	5.889	0.189
100	49u	5.591	5.770	0.179
100	50u	5.646	5.858	0.212
100	51u	5.444	5.756	0.312
100	52u	5.541	5.869	0.328
	Max	5.719	5.889	0.356
	Average	5.574	5.801	0.226
	Min	5.444	5.654	0.013
	Std Dev	0.086	0.084	0.117

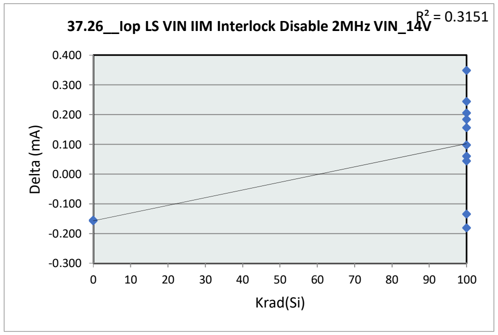


	37.25__Iop HS BOOT IIM Interlock Disable 1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.654	5.692
Average	5.693	5.822
Max	5.733	5.889
UL	8.000	8.000

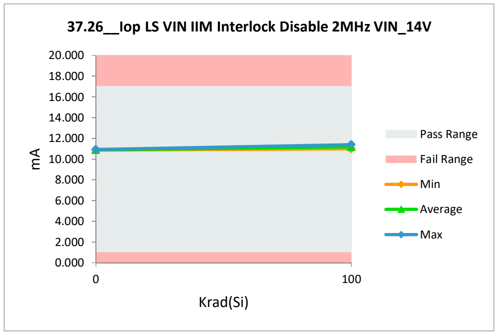


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.26__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	17	17	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	11.079	10.921	-0.158
0	2	11.028	10.873	-0.156
100	23	11.170	11.034	-0.135
100	24	11.085	11.240	0.156
100	25	11.141	11.385	0.244
100	26	10.879	11.228	0.349
100	27	11.122	11.166	0.044
100	48u	10.962	11.022	0.060
100	49u	11.023	11.206	0.183
100	50u	11.023	11.121	0.098
100	51u	11.049	11.253	0.205
100	52u	11.186	11.005	-0.181
	Max	11.186	11.385	0.349
	Average	11.062	11.121	0.059
	Min	10.879	10.873	-0.181
	Std Dev	0.088	0.152	0.180

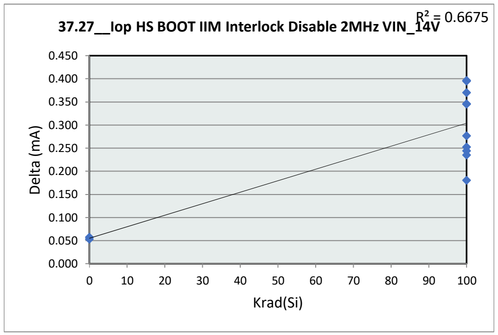


	37.26__Iop LS VIN IIM Interlock Disable 2M	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	17	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	10.873	11.005
Average	10.897	11.166
Max	10.921	11.385
UL	17.000	17.000

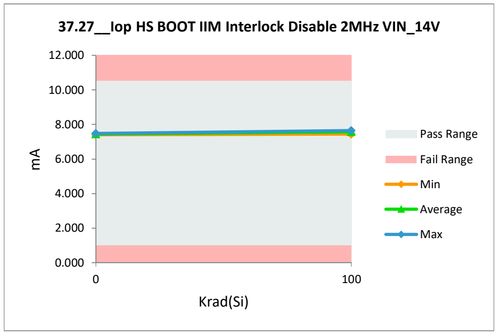


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.27__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		10.5	10.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.347	7.404	0.057
0	2	7.431	7.484	0.053
100	23	7.236	7.631	0.395
100	24	7.280	7.625	0.345
100	25	7.243	7.639	0.396
100	26	7.195	7.439	0.244
100	27	7.207	7.484	0.277
100	48u	7.417	7.652	0.235
100	49u	7.297	7.477	0.181
100	50u	7.367	7.620	0.252
100	51u	7.162	7.507	0.346
100	52u	7.250	7.620	0.370
	Max	7.431	7.652	0.396
	Average	7.286	7.548	0.263
	Min	7.162	7.404	0.053
	Std Dev	0.087	0.090	0.119

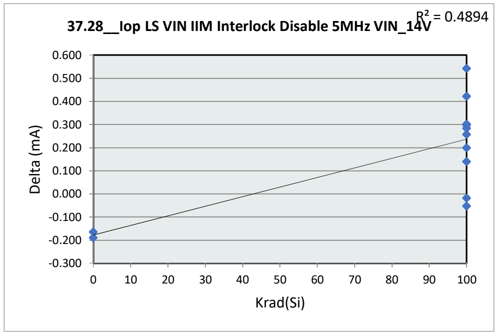


	37.27__Iop HS BOOT IIM Interlock Disable 2	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.404	7.439
Average	7.444	7.569
Max	7.484	7.652
UL	10.500	10.500

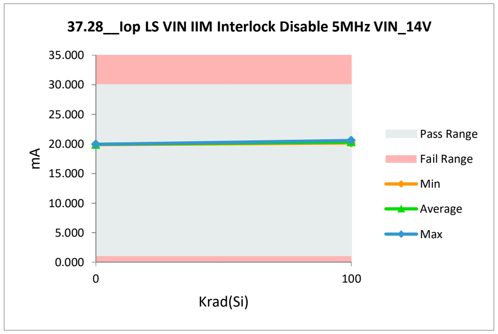


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.28__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	30	30	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	20.094	19.928	-0.165
0	2	20.080	19.890	-0.191
100	23	20.205	20.186	-0.019
100	24	20.115	20.398	0.282
100	25	20.182	20.603	0.421
100	26	19.903	20.445	0.542
100	27	20.157	20.296	0.139
100	48u	19.996	20.195	0.198
100	49u	20.057	20.353	0.297
100	50u	20.068	20.325	0.257
100	51u	20.078	20.379	0.301
100	52u	20.218	20.164	-0.054
	Max	20.218	20.603	0.542
	Average	20.096	20.264	0.167
	Min	19.903	19.890	-0.191
	Std Dev	0.090	0.206	0.230

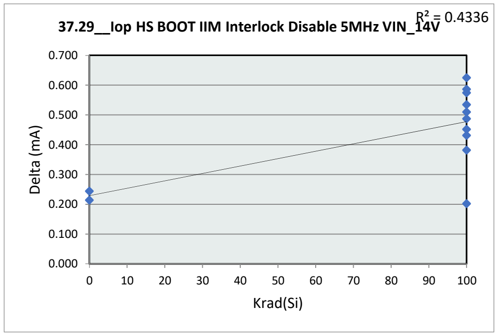


	37.28__Iop LS VIN IIM Interlock Disable 5M	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	19.890	20.164
Average	19.909	20.334
Max	19.929	20.603
UL	30.000	30.000

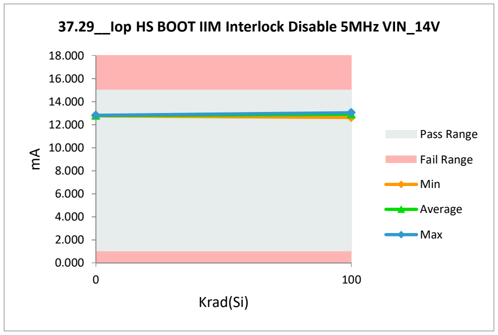


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		37.29__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	15	15	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	12.498	12.742	0.243
0	2	12.597	12.810	0.214
100	23	12.349	12.974	0.625
100	24	12.403	12.912	0.509
100	25	12.400	12.974	0.574
100	26	12.314	12.801	0.487
100	27	12.383	12.764	0.381
100	48u	12.580	13.032	0.452
100	49u	12.400	12.602	0.202
100	50u	12.556	12.987	0.431
100	51u	12.294	12.828	0.534
100	52u	12.387	12.972	0.586
	Max	12.597	13.032	0.625
	Average	12.430	12.867	0.436
	Min	12.294	12.602	0.202
	Std Dev	0.103	0.129	0.147

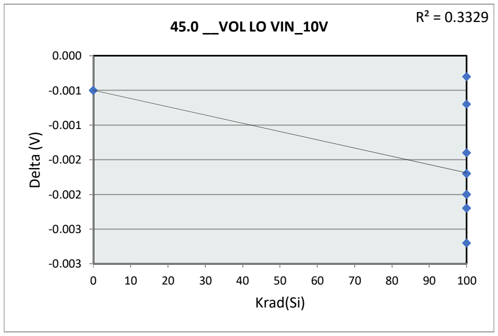


	37.29__Iop HS BOOT IIM Interlock Disable 5	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	12.742	12.602
Average	12.776	12.885
Max	12.810	13.032
UL	15.000	15.000

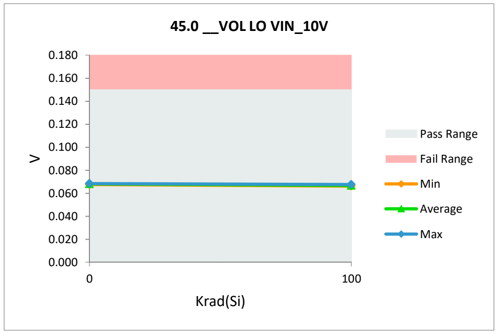


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		45.0 __VOL LO VIN_10V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		0.15	0.15	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	0.068	0.068	-0.001
0	2	0.069	0.068	-0.001
100	23	0.068	0.068	-0.001
100	24	0.069	0.067	-0.002
100	25	0.068	0.066	-0.002
100	26	0.069	0.067	-0.002
100	27	0.068	0.067	0.000
100	48u	0.069	0.067	-0.002
100	49u	0.068	0.066	-0.002
100	50u	0.068	0.066	-0.002
100	51u	0.068	0.067	-0.001
100	52u	0.069	0.066	-0.003
	Max	0.069	0.068	0.000
	Average	0.068	0.067	-0.001
	Min	0.068	0.066	-0.003
	Std Dev	0.000	0.001	0.001

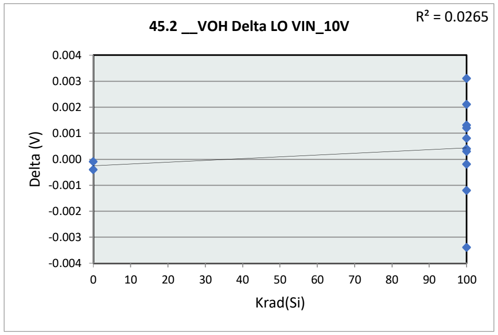


	45.0 __VOL LO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.15	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.068	0.066
Average	0.068	0.067
Max	0.069	0.068
UL	0.150	0.150

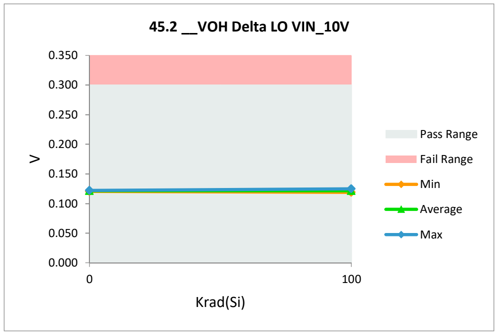


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		45.2 __VOH Delta LO VIN_10V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	0.3	0.3	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	0.121	0.121	0.000
0	2	0.122	0.122	0.000
100	23	0.122	0.121	-0.001
100	24	0.121	0.122	0.000
100	25	0.123	0.123	0.000
100	26	0.122	0.121	0.000
100	27	0.122	0.119	-0.003
100	48u	0.120	0.123	0.002
100	49u	0.120	0.121	0.001
100	50u	0.120	0.121	0.001
100	51u	0.122	0.123	0.001
100	52u	0.122	0.125	0.003
	Max	0.123	0.125	0.003
	Average	0.121	0.122	0.000
	Min	0.120	0.119	-0.003
	Std Dev	0.001	0.001	0.002



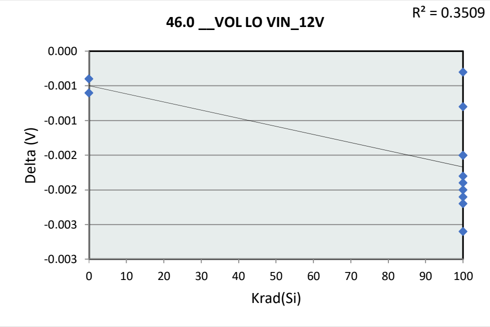
	45.2 __VOH Delta LO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.3	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.121	0.119
Average	0.121	0.122
Max	0.122	0.125
UL	0.300	0.300



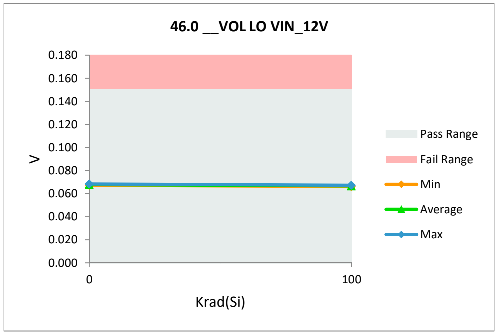
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	46.0 __VOL LO VIN_12V	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	V	V
Max Limit	0.15	0.15
Min Limit	0	0

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	0.068	0.067	-0.001
0	2	0.069	0.068	0.000
100	23	0.068	0.067	-0.001
100	24	0.069	0.067	-0.002
100	25	0.068	0.066	-0.002
100	26	0.068	0.066	-0.002
100	27	0.068	0.067	0.000
100	48u	0.069	0.067	-0.002
100	49u	0.068	0.066	-0.002
100	50u	0.068	0.066	-0.002
100	51u	0.068	0.067	-0.001
100	52u	0.069	0.066	-0.003
	Max	0.069	0.068	0.000
	Average	0.068	0.067	-0.001
	Min	0.068	0.066	-0.003
	Std Dev	0.000	0.001	0.001

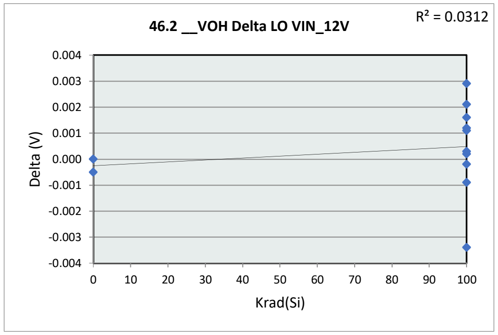


	46.0 __VOL LO VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.15	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.067	0.066
Average	0.068	0.067
Max	0.068	0.067
UL	0.150	0.150

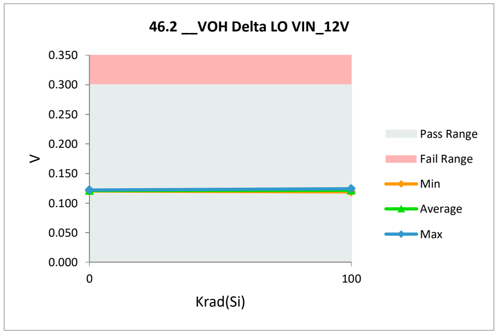


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		46.2 __VOH Delta LO VIN_12V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	0.3	0.3	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	0.121	0.121	-0.001
0	2	0.122	0.122	0.000
100	23	0.122	0.121	-0.001
100	24	0.121	0.122	0.000
100	25	0.122	0.123	0.000
100	26	0.121	0.121	0.000
100	27	0.122	0.119	-0.003
100	48u	0.120	0.122	0.002
100	49u	0.120	0.121	0.001
100	50u	0.120	0.121	0.001
100	51u	0.122	0.123	0.002
100	52u	0.122	0.124	0.003
	Max	0.122	0.124	0.003
	Average	0.121	0.122	0.000
	Min	0.120	0.119	-0.003
	Std Dev	0.001	0.001	0.002

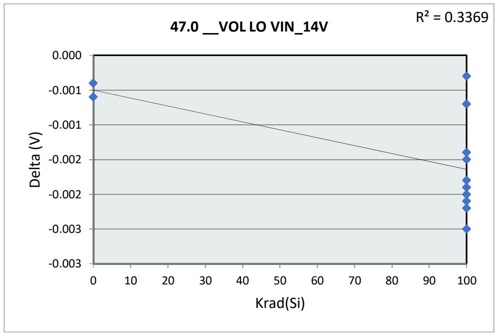


	46.2 __VOH Delta LO VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.3	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.121	0.119
Average	0.121	0.122
Max	0.122	0.124
UL	0.300	0.300

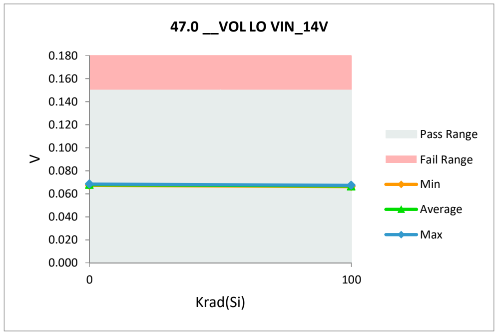


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		47.0 __VOL LO VIN_14V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		0.15	0.15	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	0.068	0.067	-0.001
0	2	0.069	0.068	0.000
100	23	0.068	0.067	-0.001
100	24	0.069	0.067	-0.002
100	25	0.068	0.066	-0.001
100	26	0.068	0.066	-0.002
100	27	0.068	0.067	0.000
100	48u	0.069	0.067	-0.002
100	49u	0.068	0.066	-0.002
100	50u	0.068	0.066	-0.002
100	51u	0.068	0.067	-0.001
100	52u	0.069	0.066	-0.002
	Max	0.069	0.068	0.000
	Average	0.068	0.067	-0.001
	Min	0.068	0.066	-0.002
	Std Dev	0.000	0.001	0.001

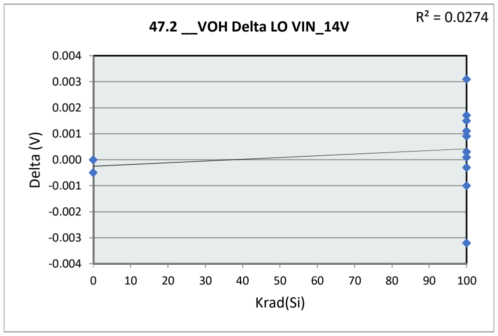


	47.0 __VOL LO VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.15	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.067	0.066
Average	0.068	0.067
Max	0.068	0.067
UL	0.150	0.150

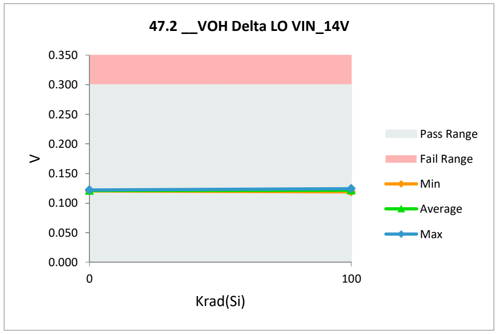


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		47.2 __VOH Delta LO VIN_14V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	0.3	0.3	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	0.121	0.120	-0.001
0	2	0.122	0.122	0.000
100	23	0.122	0.121	-0.001
100	24	0.121	0.122	0.000
100	25	0.122	0.123	0.000
100	26	0.121	0.121	0.000
100	27	0.122	0.119	-0.003
100	48u	0.120	0.122	0.002
100	49u	0.120	0.121	0.001
100	50u	0.120	0.121	0.001
100	51u	0.122	0.123	0.002
100	52u	0.121	0.124	0.003
	Max	0.122	0.124	0.003
	Average	0.121	0.122	0.000
	Min	0.120	0.119	-0.003
	Std Dev	0.001	0.001	0.002

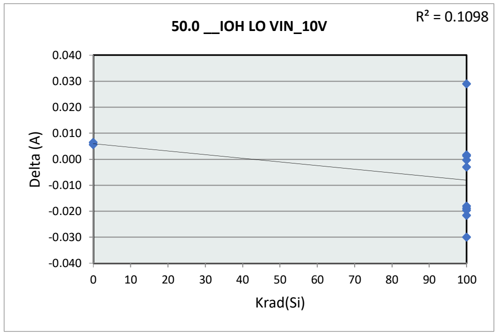


	47.2 __VOH Delta LO VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.3	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.121	0.119
Average	0.121	0.122
Max	0.122	0.124
UL	0.300	0.300

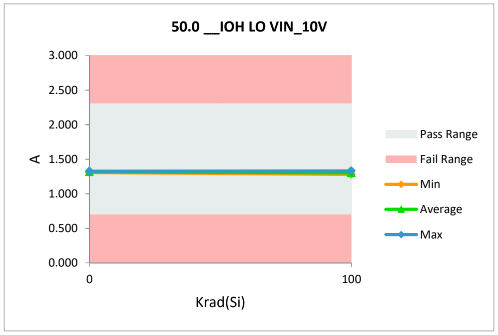


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		50.0 __IOH LO VIN_10V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	A	A	
	Max Limit	2.3	2.3	
	Min Limit	0.7	0.7	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.318	1.324	0.006
0	2	1.300	1.305	0.006
100	23	1.304	1.305	0.002
100	24	1.306	1.308	0.001
100	25	1.299	1.296	-0.003
100	26	1.310	1.310	0.000
100	27	1.303	1.332	0.029
100	48u	1.313	1.293	-0.020
100	49u	1.324	1.302	-0.022
100	50u	1.316	1.298	-0.018
100	51u	1.309	1.290	-0.019
100	52u	1.310	1.280	-0.030
	Max	1.324	1.332	0.029
	Average	1.309	1.304	-0.006
	Min	1.299	1.280	-0.030
	Std Dev	0.007	0.014	0.016

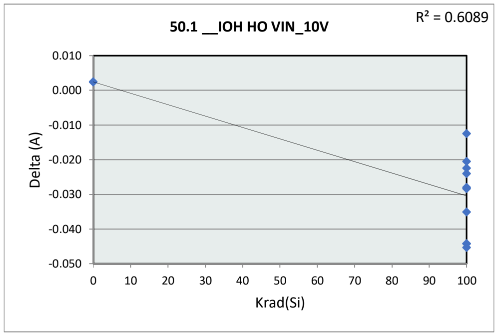


	50.0 __IOH LO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.3	A
Min Limit	0.7	A
Krad(Si)	0	100
LL	0.700	0.700
Min	1.305	1.280
Average	1.315	1.301
Max	1.324	1.332
UL	2.300	2.300

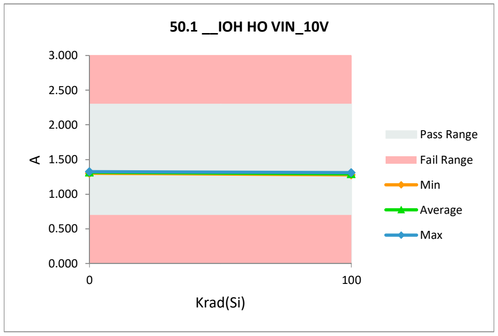


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		50.1 __IOH HO VIN_10V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		A	A	
Max Limit		2.3	2.3	
Min Limit		0.7	0.7	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.324	1.327	0.003
0	2	1.299	1.301	0.002
100	23	1.321	1.277	-0.044
100	24	1.334	1.289	-0.045
100	25	1.320	1.291	-0.028
100	26	1.337	1.309	-0.028
100	27	1.337	1.302	-0.035
100	48u	1.306	1.282	-0.024
100	49u	1.324	1.303	-0.021
100	50u	1.313	1.291	-0.022
100	51u	1.311	1.298	-0.013
100	52u	1.321	1.277	-0.044
	Max	1.337	1.327	0.003
	Average	1.321	1.296	-0.025
	Min	1.299	1.277	-0.045
	Std Dev	0.012	0.014	0.016

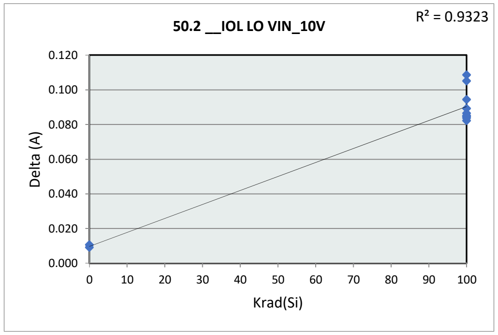


	50.1 __IOH HO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.3	A
Min Limit	0.7	A
Krad(Si)	0	100
LL	0.700	0.700
Min	1.301	1.277
Average	1.314	1.292
Max	1.327	1.309
UL	2.300	2.300

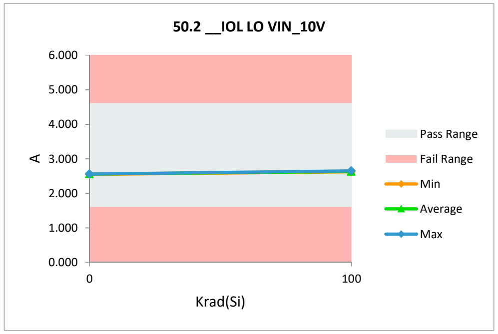


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		50.2 __IOL LO VIN_10V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	A	A	
	Max Limit	4.6	4.6	
	Min Limit	1.6	1.6	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.551	2.561	0.011
0	2	2.536	2.545	0.009
100	23	2.519	2.628	0.109
100	24	2.533	2.622	0.089
100	25	2.538	2.624	0.086
100	26	2.526	2.620	0.094
100	27	2.549	2.634	0.085
100	48u	2.540	2.624	0.084
100	49u	2.545	2.629	0.084
100	50u	2.541	2.626	0.085
100	51u	2.542	2.624	0.082
100	52u	2.542	2.647	0.105
	Max	2.551	2.647	0.109
	Average	2.539	2.615	0.077
	Min	2.519	2.545	0.009
	Std Dev	0.009	0.030	0.032

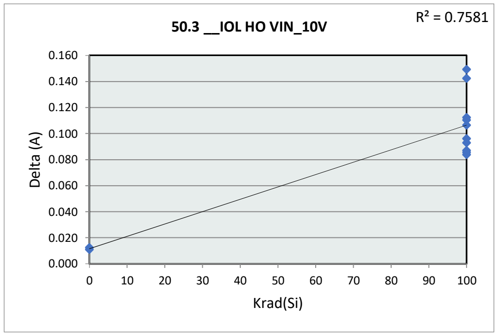


	50.2 __IOL LO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	4.6	A
Min Limit	1.6	A
Krad(Si)	0	100
LL	1.600	1.600
Min	2.545	2.620
Average	2.553	2.628
Max	2.561	2.647
UL	4.600	4.600

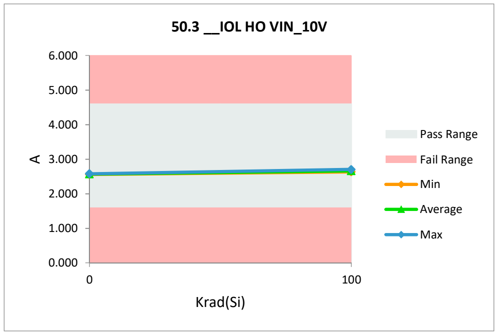


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		50.3 __IOL HO VIN_10V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		A	A	
Max Limit		4.6	4.6	
Min Limit		1.6	1.6	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.565	2.577	0.012
0	2	2.545	2.556	0.011
100	23	2.562	2.668	0.106
100	24	2.558	2.701	0.142
100	25	2.548	2.697	0.149
100	26	2.548	2.644	0.096
100	27	2.581	2.693	0.112
100	48u	2.548	2.634	0.085
100	49u	2.553	2.637	0.084
100	50u	2.547	2.634	0.087
100	51u	2.546	2.656	0.110
100	52u	2.574	2.667	0.093
	Max	2.581	2.701	0.149
	Average	2.556	2.647	0.091
	Min	2.545	2.556	0.011
	Std Dev	0.012	0.045	0.042

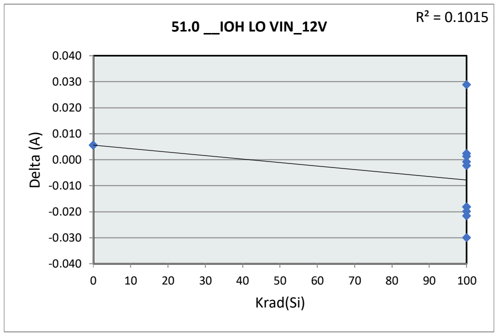


	50.3 __IOL HO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	4.6	A
Min Limit	1.6	A
Krad(Si)	0	100
LL	1.600	1.600
Min	2.556	2.634
Average	2.567	2.663
Max	2.577	2.701
UL	4.600	4.600

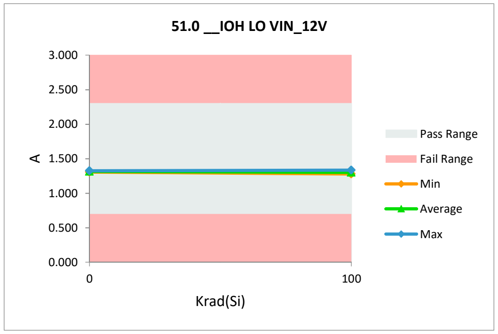


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		51.0 __IOH LO VIN_12V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	A	A	
	Max Limit	2.3	2.3	
	Min Limit	0.7	0.7	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.318	1.324	0.006
0	2	1.300	1.306	0.006
100	23	1.304	1.307	0.002
100	24	1.307	1.308	0.001
100	25	1.299	1.297	-0.002
100	26	1.311	1.310	-0.001
100	27	1.303	1.332	0.029
100	48u	1.313	1.293	-0.020
100	49u	1.324	1.303	-0.022
100	50u	1.317	1.299	-0.018
100	51u	1.310	1.292	-0.018
100	52u	1.311	1.281	-0.030
	Max	1.324	1.332	0.029
	Average	1.310	1.304	-0.006
	Min	1.299	1.281	-0.030
	Std Dev	0.008	0.014	0.016

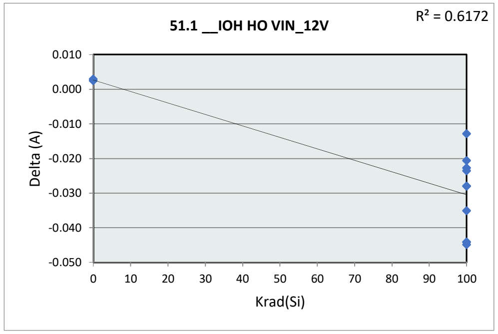


	51.0 __IOH LO VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.3	A
Min Limit	0.7	A
Krad(Si)	0	100
LL	0.700	0.700
Min	1.306	1.281
Average	1.315	1.302
Max	1.324	1.332
UL	2.300	2.300

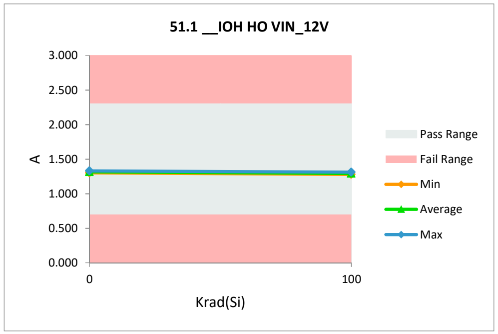


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		51.1 __IOH HO VIN_12V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		A	A	
Max Limit		2.3	2.3	
Min Limit		0.7	0.7	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.324	1.327	0.003
0	2	1.300	1.302	0.002
100	23	1.321	1.277	-0.044
100	24	1.334	1.289	-0.045
100	25	1.320	1.292	-0.028
100	26	1.337	1.309	-0.028
100	27	1.338	1.303	-0.035
100	48u	1.306	1.282	-0.024
100	49u	1.324	1.303	-0.021
100	50u	1.314	1.291	-0.023
100	51u	1.311	1.298	-0.013
100	52u	1.321	1.277	-0.044
	Max	1.338	1.327	0.003
	Average	1.321	1.296	-0.025
	Min	1.300	1.277	-0.045
	Std Dev	0.012	0.014	0.016

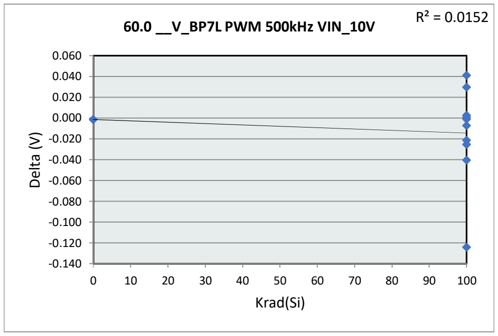


	51.1 __IOH HO VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.3	A
Min Limit	0.7	A
Krad(Si)	0	100
LL	0.700	0.700
Min	1.302	1.277
Average	1.315	1.292
Max	1.327	1.310
UL	2.300	2.300

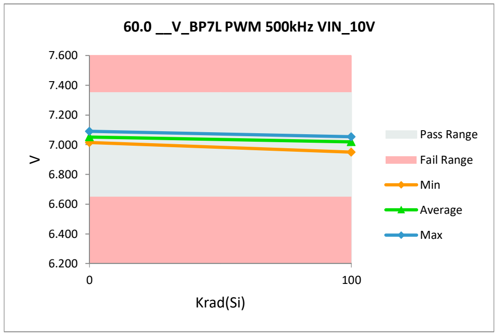


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.0 __V_BP7L PWM 500kHz VI		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.015	7.014	-0.001
0	2	7.091	7.090	-0.001
100	23	7.001	7.031	0.030
100	24	7.049	7.009	-0.040
100	25	7.025	7.028	0.003
100	26	7.013	7.054	0.041
100	27	7.016	7.017	0.001
100	48u	7.020	6.995	-0.025
100	49u	7.056	7.049	-0.007
100	50u	7.027	7.006	-0.021
100	51u	7.045	7.044	-0.001
100	52u	7.075	6.951	-0.124
	Max	7.091	7.090	0.041
	Average	7.036	7.024	-0.012
	Min	7.001	6.951	-0.124
	Std Dev	0.027	0.035	0.041

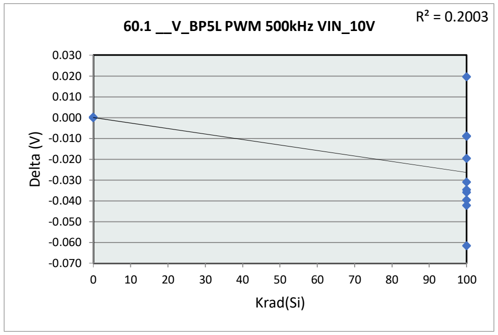


	60.0 __V_BP7L PWM 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.014	6.951
Average	7.052	7.018
Max	7.090	7.054
UL	7.350	7.350

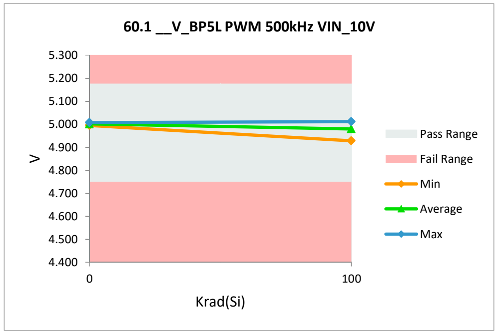


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.1 __V_BP5L PWM 500kHz VI		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.995	4.995	0.000
0	2	5.007	5.007	0.000
100	23	5.011	4.975	-0.036
100	24	5.012	4.977	-0.035
100	25	5.003	4.995	-0.009
100	26	4.984	5.003	0.019
100	27	5.003	4.963	-0.040
100	48u	5.023	4.981	-0.042
100	49u	5.009	4.990	-0.020
100	50u	5.021	5.012	-0.009
100	51u	4.997	4.966	-0.031
100	52u	4.989	4.927	-0.062
	Max	5.023	5.012	0.019
	Average	5.005	4.983	-0.022
	Min	4.984	4.927	-0.062
	Std Dev	0.012	0.023	0.023

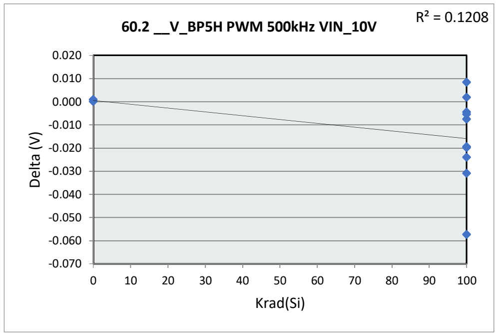


	60.1 __V_BP5L PWM 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.995	4.928
Average	5.001	4.979
Max	5.007	5.012
UL	5.175	5.175

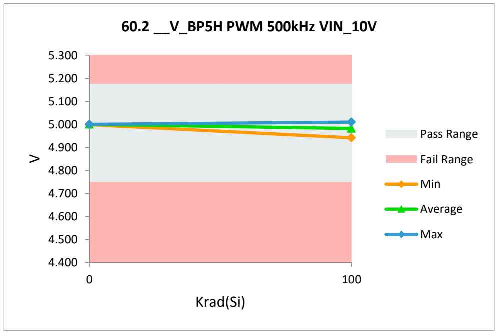


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.2 __V_BP5H PWM 500kHz VI		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.998	4.999	0.001
0	2	5.000	5.000	0.000
100	23	4.988	4.957	-0.031
100	24	5.011	4.992	-0.019
100	25	4.991	4.984	-0.008
100	26	4.999	4.993	-0.005
100	27	4.999	4.942	-0.057
100	48u	4.996	5.005	0.008
100	49u	4.990	4.992	0.002
100	50u	5.015	5.010	-0.004
100	51u	5.000	4.976	-0.024
100	52u	4.992	4.973	-0.020
	Max	5.015	5.010	0.008
	Average	4.998	4.985	-0.013
	Min	4.988	4.942	-0.057
	Std Dev	0.008	0.020	0.018

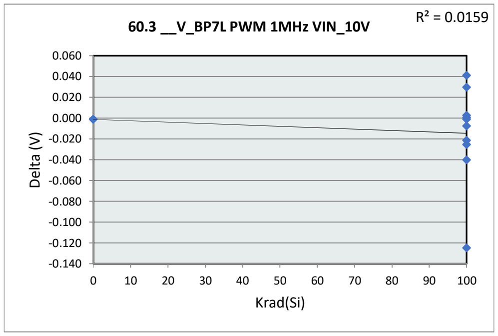


	60.2 __V_BP5H PWM 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.999	4.942
Average	5.000	4.982
Max	5.000	5.011
UL	5.175	5.175

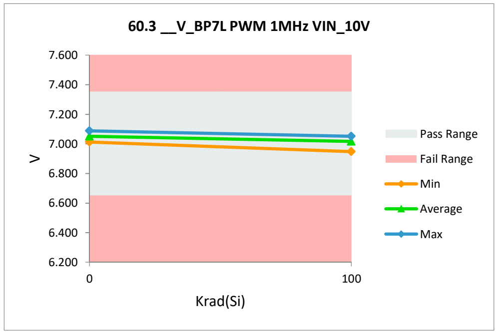


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.3 __V_BP7L PWM 1MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.014	7.013	-0.001
0	2	7.090	7.089	-0.001
100	23	6.999	7.029	0.030
100	24	7.048	7.008	-0.040
100	25	7.024	7.027	0.003
100	26	7.011	7.052	0.041
100	27	7.015	7.016	0.001
100	48u	7.019	6.993	-0.025
100	49u	7.055	7.047	-0.007
100	50u	7.026	7.004	-0.021
100	51u	7.044	7.043	-0.001
100	52u	7.074	6.949	-0.125
	Max	7.090	7.089	0.041
	Average	7.035	7.023	-0.012
	Min	6.999	6.949	-0.125
	Std Dev	0.027	0.035	0.042

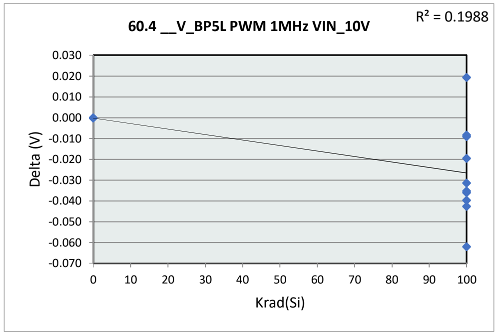


	60.3 __V_BP7L PWM 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.013	6.949
Average	7.051	7.017
Max	7.089	7.052
UL	7.350	7.350

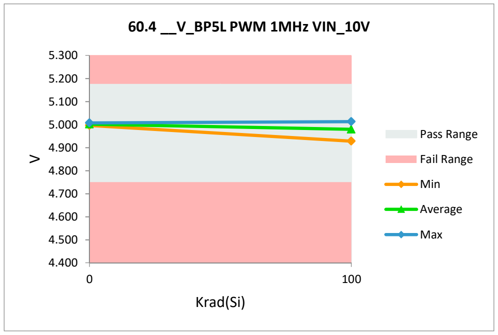


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.4 __V_BP5L PWM 1MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.996	4.996	0.000
0	2	5.008	5.008	0.000
100	23	5.012	4.976	-0.036
100	24	5.013	4.977	-0.035
100	25	5.004	4.996	-0.009
100	26	4.985	5.004	0.019
100	27	5.004	4.964	-0.040
100	48u	5.024	4.981	-0.043
100	49u	5.010	4.990	-0.020
100	50u	5.022	5.012	-0.009
100	51u	4.998	4.967	-0.032
100	52u	4.990	4.928	-0.062
	Max	5.024	5.012	0.019
	Average	5.005	4.983	-0.022
	Min	4.985	4.928	-0.062
	Std Dev	0.012	0.023	0.023

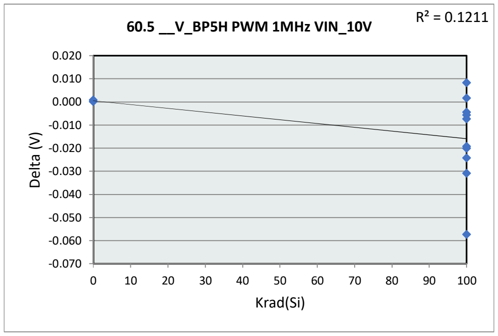


	60.4 __V_BP5L PWM 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.996	4.928
Average	5.002	4.980
Max	5.008	5.012
UL	5.175	5.175

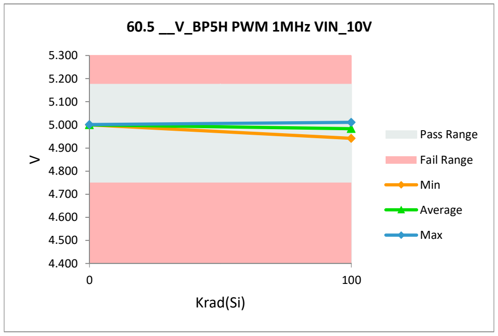


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.5 __V_BP5H PWM 1MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.999	5.000	0.001
0	2	5.001	5.001	0.000
100	23	4.988	4.958	-0.031
100	24	5.012	4.992	-0.019
100	25	4.992	4.984	-0.007
100	26	4.999	4.994	-0.006
100	27	4.999	4.942	-0.057
100	48u	4.997	5.005	0.008
100	49u	4.990	4.992	0.002
100	50u	5.015	5.011	-0.004
100	51u	5.001	4.977	-0.024
100	52u	4.993	4.973	-0.020
	Max	5.015	5.011	0.008
	Average	4.999	4.986	-0.013
	Min	4.988	4.942	-0.057
	Std Dev	0.008	0.020	0.018

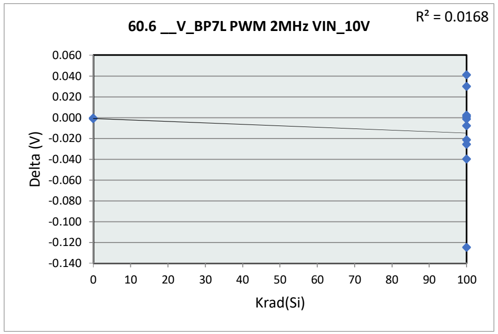


	60.5 __V_BP5H PWM 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.000	4.942
Average	5.000	4.983
Max	5.001	5.011
UL	5.175	5.175

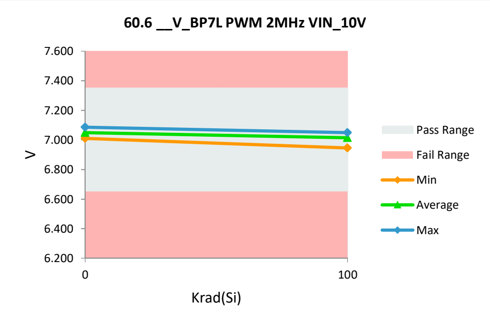


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.6 __V_BP7L PWM 2MHz VIN_		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.012	7.011	-0.001
0	2	7.087	7.087	-0.001
100	23	6.997	7.027	0.030
100	24	7.045	7.005	-0.040
100	25	7.022	7.024	0.002
100	26	7.009	7.050	0.041
100	27	7.013	7.014	0.001
100	48u	7.016	6.991	-0.026
100	49u	7.053	7.045	-0.008
100	50u	7.023	7.002	-0.022
100	51u	7.042	7.040	-0.002
100	52u	7.071	6.946	-0.125
	Max	7.087	7.087	0.041
	Average	7.033	7.020	-0.012
	Min	6.997	6.946	-0.125
	Std Dev	0.027	0.035	0.042

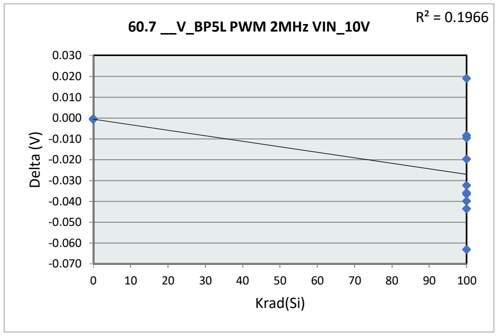


	60.6 __V_BP7L PWM 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.011	6.946
Average	7.049	7.014
Max	7.087	7.050
UL	7.350	7.350

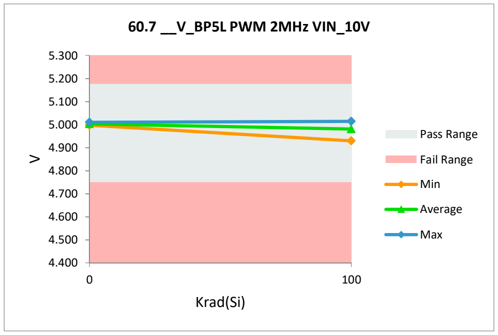


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.7 __V_BP5L PWM 2MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.998	4.997	-0.001
0	2	5.010	5.009	-0.001
100	23	5.014	4.978	-0.037
100	24	5.015	4.979	-0.036
100	25	5.006	4.998	-0.008
100	26	4.987	5.006	0.019
100	27	5.005	4.966	-0.040
100	48u	5.026	4.983	-0.044
100	49u	5.012	4.992	-0.020
100	50u	5.023	5.014	-0.010
100	51u	5.001	4.968	-0.032
100	52u	4.992	4.929	-0.063
	Max	5.026	5.014	0.019
	Average	5.007	4.985	-0.023
	Min	4.987	4.929	-0.063
	Std Dev	0.012	0.024	0.023

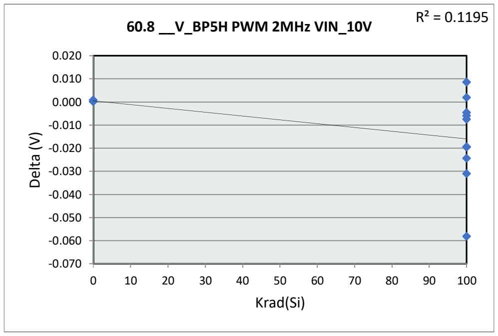


	60.7 __V_BP5L PWM 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.997	4.929
Average	5.003	4.981
Max	5.009	5.014
UL	5.175	5.175

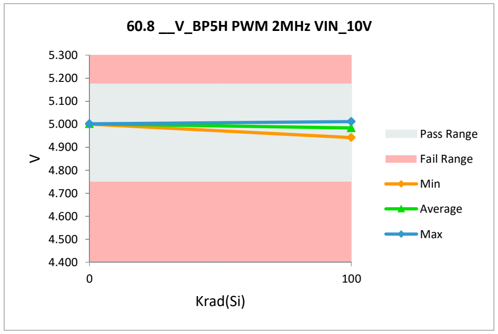


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.8 __V_BP5H PWM 2MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.000	5.001	0.001
0	2	5.002	5.002	0.000
100	23	4.990	4.958	-0.031
100	24	5.013	4.993	-0.020
100	25	4.993	4.985	-0.008
100	26	5.001	4.995	-0.006
100	27	5.001	4.942	-0.058
100	48u	4.998	5.006	0.009
100	49u	4.991	4.993	0.002
100	50u	5.016	5.012	-0.004
100	51u	5.002	4.978	-0.024
100	52u	4.994	4.975	-0.019
	Max	5.016	5.012	0.009
	Average	5.000	4.987	-0.013
	Min	4.990	4.942	-0.058
	Std Dev	0.008	0.020	0.019



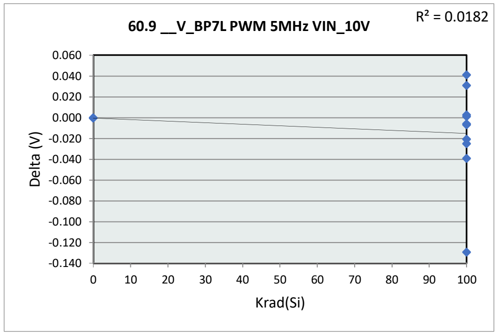
	60.8 __V_BP5H PWM 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.001	4.942
Average	5.001	4.984
Max	5.002	5.012
UL	5.175	5.175



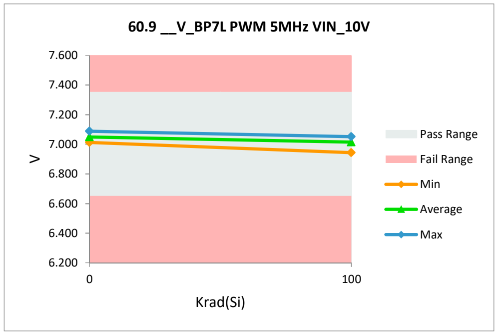
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	60.9 __V_BP7L PWM 5MHz VIN	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	V	V
Max Limit	7.35	7.35
Min Limit	6.65	6.65

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.012	7.012	-0.001
0	2	7.088	7.088	0.000
100	23	6.998	7.029	0.031
100	24	7.046	7.006	-0.039
100	25	7.023	7.025	0.002
100	26	7.010	7.051	0.041
100	27	7.013	7.014	0.001
100	48u	7.017	6.992	-0.025
100	49u	7.053	7.046	-0.007
100	50u	7.024	7.003	-0.021
100	51u	7.042	7.036	-0.006
100	52u	7.072	6.943	-0.129
	Max	7.088	7.088	0.041
	Average	7.033	7.020	-0.013
	Min	6.998	6.943	-0.129
	Std Dev	0.027	0.036	0.043

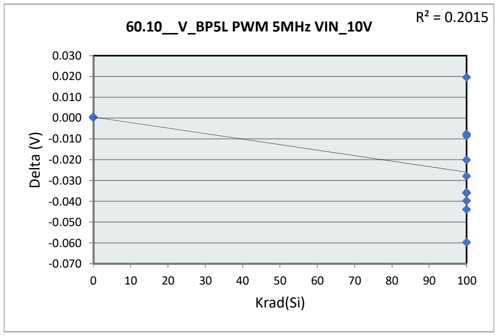


	60.9 __V_BP7L PWM 5MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.012	6.943
Average	7.050	7.014
Max	7.088	7.051
UL	7.350	7.350

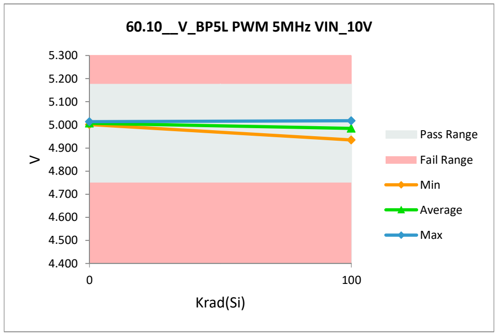


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.10__V_BP5L PWM 5MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.001	5.001	0.001
0	2	5.013	5.013	0.000
100	23	5.017	4.981	-0.036
100	24	5.017	4.982	-0.036
100	25	5.009	5.001	-0.008
100	26	4.990	5.009	0.020
100	27	5.008	4.968	-0.040
100	48u	5.029	4.985	-0.044
100	49u	5.015	4.995	-0.020
100	50u	5.026	5.018	-0.008
100	51u	5.003	4.975	-0.028
100	52u	4.995	4.935	-0.060
	Max	5.029	5.018	0.020
	Average	5.010	4.989	-0.022
	Min	4.990	4.935	-0.060
	Std Dev	0.012	0.023	0.023

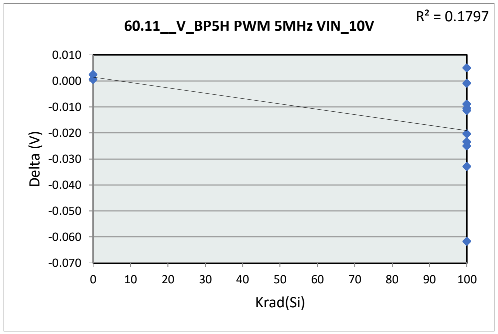


	60.10__V_BP5L PWM 5MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.001	4.935
Average	5.007	4.985
Max	5.013	5.018
UL	5.175	5.175

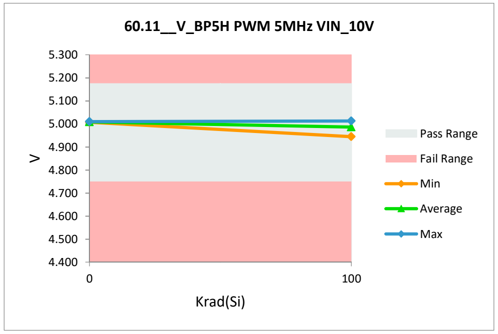


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.11__V_BP5H PWM 5MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.006	5.007	0.000
0	2	5.008	5.010	0.002
100	23	4.991	4.958	-0.033
100	24	5.016	4.996	-0.020
100	25	4.998	4.987	-0.011
100	26	5.006	4.996	-0.011
100	27	5.006	4.944	-0.062
100	48u	5.003	5.008	0.005
100	49u	4.997	4.996	-0.001
100	50u	5.022	5.013	-0.009
100	51u	5.009	4.984	-0.025
100	52u	5.002	4.978	-0.023
	Max	5.022	5.013	0.005
	Average	5.005	4.990	-0.016
	Min	4.991	4.944	-0.062
	Std Dev	0.008	0.021	0.019

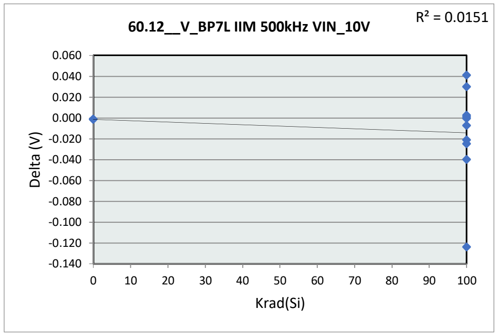


	60.11__V_BP5H PWM 5MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.007	4.944
Average	5.008	4.986
Max	5.010	5.013
UL	5.175	5.175

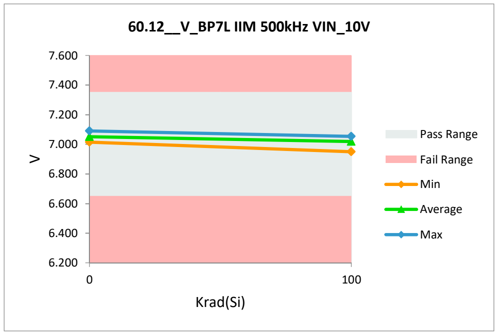


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.12__V_BP7L IIM 500kHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.015	7.014	-0.001
0	2	7.091	7.090	-0.001
100	23	7.001	7.031	0.030
100	24	7.049	7.009	-0.040
100	25	7.025	7.028	0.003
100	26	7.012	7.053	0.041
100	27	7.016	7.017	0.001
100	48u	7.020	6.995	-0.025
100	49u	7.056	7.049	-0.007
100	50u	7.027	7.006	-0.021
100	51u	7.045	7.044	-0.001
100	52u	7.075	6.951	-0.124
	Max	7.091	7.090	0.041
	Average	7.036	7.024	-0.012
	Min	7.001	6.951	-0.124
	Std Dev	0.027	0.035	0.041

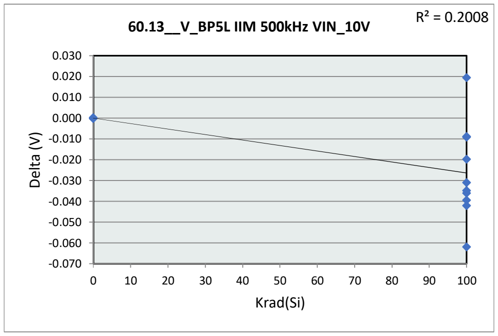


	60.12__V_BP7L IIM 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.014	6.951
Average	7.052	7.018
Max	7.090	7.053
UL	7.350	7.350

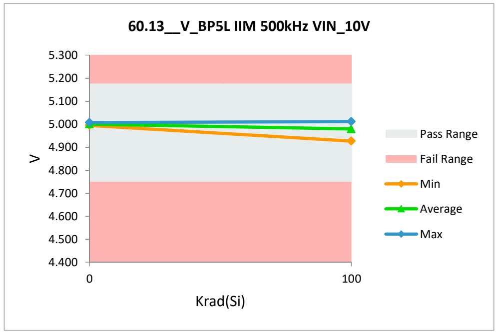


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.13__V_BP5L IIM 500kHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.994	4.995	0.000
0	2	5.007	5.007	0.000
100	23	5.011	4.975	-0.036
100	24	5.012	4.977	-0.035
100	25	5.004	4.994	-0.009
100	26	4.984	5.003	0.019
100	27	5.003	4.963	-0.039
100	48u	5.023	4.981	-0.042
100	49u	5.009	4.990	-0.020
100	50u	5.021	5.012	-0.009
100	51u	4.997	4.966	-0.031
100	52u	4.989	4.927	-0.062
	Max	5.023	5.012	0.019
	Average	5.004	4.983	-0.022
	Min	4.984	4.927	-0.062
	Std Dev	0.012	0.023	0.023

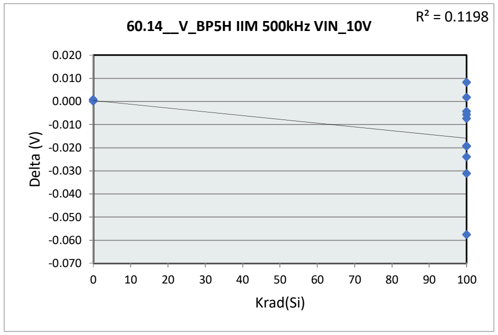


	60.13__V_BP5L IIM 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.995	4.927
Average	5.001	4.979
Max	5.007	5.012
UL	5.175	5.175

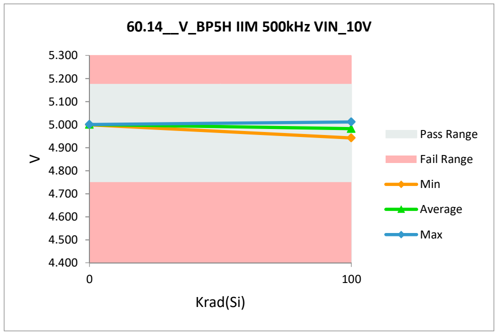


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.14__V_BP5H IIM 500kHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.998	4.999	0.001
0	2	5.000	5.000	0.000
100	23	4.988	4.957	-0.031
100	24	5.011	4.992	-0.019
100	25	4.991	4.984	-0.007
100	26	4.999	4.993	-0.006
100	27	4.999	4.941	-0.058
100	48u	4.996	5.004	0.008
100	49u	4.990	4.992	0.002
100	50u	5.015	5.011	-0.004
100	51u	5.000	4.976	-0.024
100	52u	4.992	4.973	-0.019
	Max	5.015	5.011	0.008
	Average	4.998	4.985	-0.013
	Min	4.988	4.941	-0.058
	Std Dev	0.008	0.020	0.018

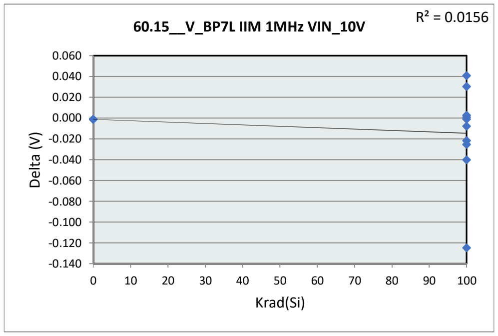


	60.14__V_BP5H IIM 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.999	4.941
Average	5.000	4.982
Max	5.000	5.011
UL	5.175	5.175

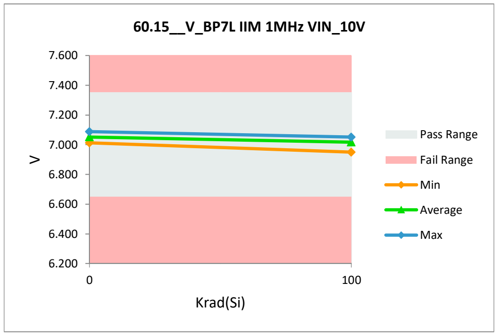


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.15__V_BP7L IIM 1MHz VIN_		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.014	7.013	-0.001
0	2	7.090	7.089	-0.001
100	23	6.999	7.030	0.030
100	24	7.048	7.008	-0.040
100	25	7.024	7.027	0.003
100	26	7.011	7.052	0.041
100	27	7.015	7.016	0.001
100	48u	7.019	6.993	-0.025
100	49u	7.055	7.047	-0.008
100	50u	7.026	7.004	-0.022
100	51u	7.044	7.043	-0.001
100	52u	7.074	6.949	-0.125
	Max	7.090	7.089	0.041
	Average	7.035	7.022	-0.012
	Min	6.999	6.949	-0.125
	Std Dev	0.027	0.035	0.042

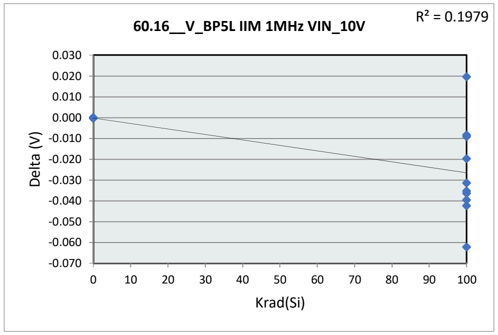


	60.15__V_BP7L IIM 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.013	6.949
Average	7.051	7.017
Max	7.089	7.052
UL	7.350	7.350

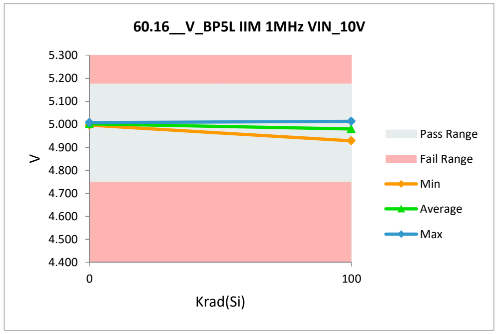


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.16__V_BP5L IIM 1MHz VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.995	4.995	0.000
0	2	5.008	5.008	0.000
100	23	5.012	4.976	-0.036
100	24	5.013	4.977	-0.035
100	25	5.004	4.996	-0.009
100	26	4.985	5.004	0.020
100	27	5.003	4.964	-0.040
100	48u	5.024	4.982	-0.043
100	49u	5.010	4.990	-0.020
100	50u	5.022	5.012	-0.009
100	51u	4.998	4.967	-0.032
100	52u	4.990	4.928	-0.062
	Max	5.024	5.012	0.020
	Average	5.005	4.983	-0.022
	Min	4.985	4.928	-0.062
	Std Dev	0.012	0.023	0.023

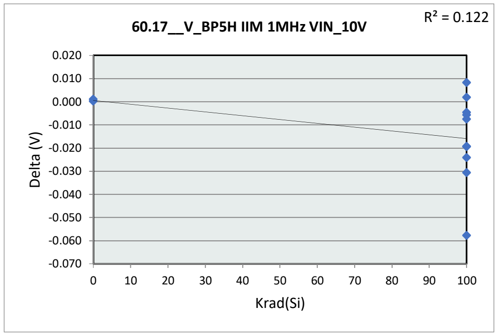


	60.16__V_BP5L IIM 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.995	4.928
Average	5.002	4.980
Max	5.008	5.012
UL	5.175	5.175

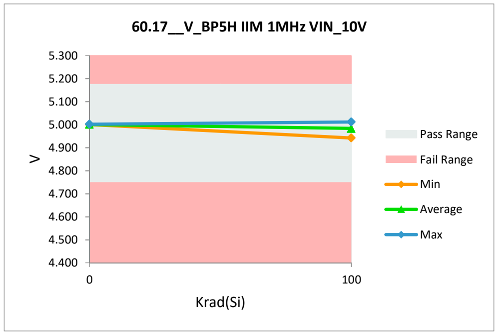


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.17__V_BP5H IIM 1MHz VIN_		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.999	5.000	0.001
0	2	5.001	5.001	0.000
100	23	4.988	4.958	-0.031
100	24	5.012	4.992	-0.019
100	25	4.992	4.984	-0.008
100	26	4.999	4.994	-0.006
100	27	4.999	4.942	-0.058
100	48u	4.997	5.005	0.008
100	49u	4.990	4.992	0.002
100	50u	5.015	5.011	-0.005
100	51u	5.001	4.977	-0.024
100	52u	4.993	4.973	-0.019
	Max	5.015	5.011	0.008
	Average	4.999	4.986	-0.013
	Min	4.988	4.942	-0.058
	Std Dev	0.008	0.020	0.018

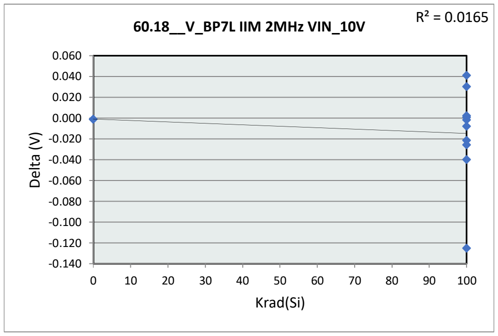


	60.17__V_BP5H IIM 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.000	4.942
Average	5.000	4.983
Max	5.001	5.011
UL	5.175	5.175

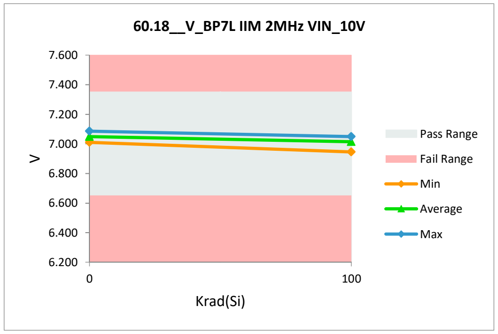


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.18__V_BP7L IIM 2MHz VIN_1		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.011	7.010	-0.001
0	2	7.087	7.086	-0.001
100	23	6.997	7.027	0.030
100	24	7.045	7.005	-0.040
100	25	7.022	7.024	0.002
100	26	7.009	7.050	0.041
100	27	7.013	7.014	0.001
100	48u	7.016	6.991	-0.025
100	49u	7.052	7.044	-0.008
100	50u	7.023	7.002	-0.022
100	51u	7.041	7.040	-0.002
100	52u	7.071	6.946	-0.125
	Max	7.087	7.086	0.041
	Average	7.032	7.020	-0.012
	Min	6.997	6.946	-0.125
	Std Dev	0.027	0.035	0.042

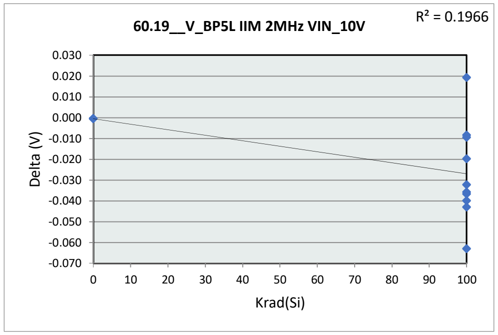


	60.18__V_BP7L IIM 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.011	6.946
Average	7.048	7.014
Max	7.086	7.050
UL	7.350	7.350

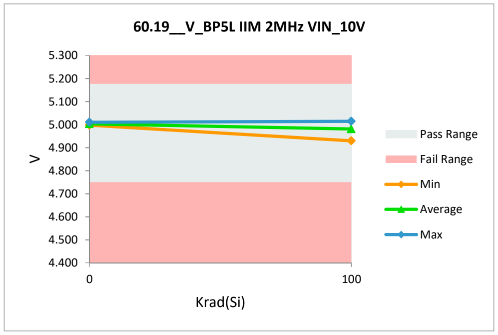


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.19__V_BP5L IIM 2MHz VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.997	4.997	0.000
0	2	5.010	5.009	-0.001
100	23	5.014	4.977	-0.037
100	24	5.015	4.979	-0.036
100	25	5.006	4.998	-0.008
100	26	4.987	5.006	0.019
100	27	5.005	4.965	-0.040
100	48u	5.026	4.983	-0.043
100	49u	5.012	4.992	-0.020
100	50u	5.023	5.014	-0.010
100	51u	5.000	4.968	-0.032
100	52u	4.992	4.929	-0.063
	Max	5.026	5.014	0.019
	Average	5.007	4.985	-0.023
	Min	4.987	4.929	-0.063
	Std Dev	0.012	0.024	0.023

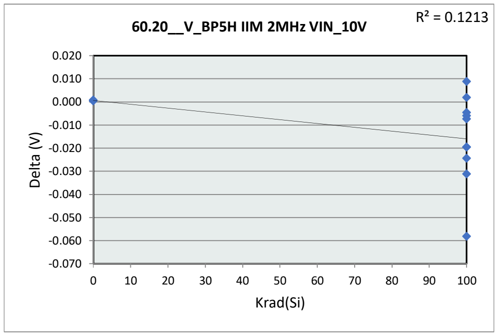


	60.19__V_BP5L IIM 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.997	4.929
Average	5.003	4.981
Max	5.009	5.014
UL	5.175	5.175

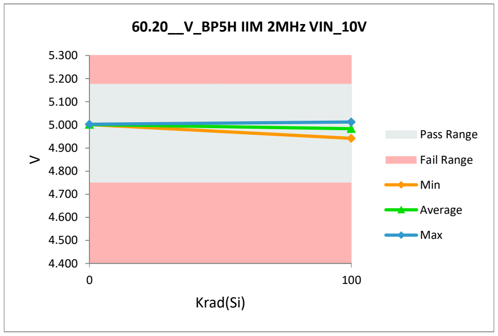


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.20__V_BP5H IIM 2MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.000	5.001	0.001
0	2	5.002	5.002	0.000
100	23	4.990	4.958	-0.031
100	24	5.013	4.993	-0.020
100	25	4.993	4.985	-0.007
100	26	5.001	4.995	-0.006
100	27	5.000	4.942	-0.058
100	48u	4.998	5.007	0.009
100	49u	4.991	4.993	0.002
100	50u	5.016	5.012	-0.005
100	51u	5.002	4.978	-0.024
100	52u	4.994	4.975	-0.019
	Max	5.016	5.012	0.009
	Average	5.000	4.987	-0.013
	Min	4.990	4.942	-0.058
	Std Dev	0.008	0.020	0.019

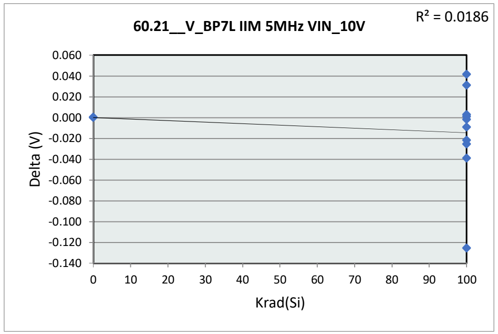


	60.20__V_BP5H IIM 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.001	4.942
Average	5.001	4.984
Max	5.002	5.012
UL	5.175	5.175

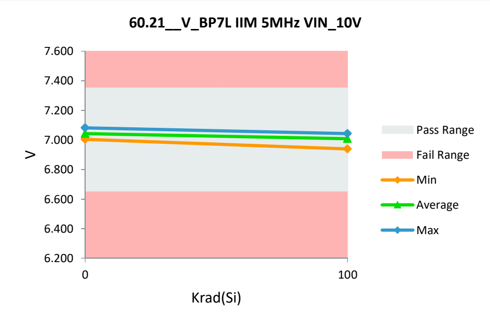


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.21__V_BP7L IIM 5MHz VIN_		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.005	7.005	0.000
0	2	7.081	7.081	0.000
100	23	6.991	7.022	0.031
100	24	7.039	7.000	-0.039
100	25	7.016	7.019	0.003
100	26	7.002	7.044	0.042
100	27	7.006	7.007	0.001
100	48u	7.010	6.984	-0.026
100	49u	7.046	7.037	-0.009
100	50u	7.016	6.995	-0.022
100	51u	7.035	7.033	-0.002
100	52u	7.065	6.939	-0.125
	Max	7.081	7.081	0.042
	Average	7.026	7.014	-0.012
	Min	6.991	6.939	-0.125
	Std Dev	0.027	0.035	0.042

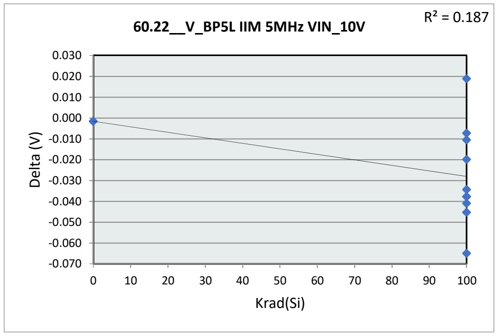


	60.21__V_BP7L IIM 5MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.005	6.939
Average	7.043	7.008
Max	7.081	7.044
UL	7.350	7.350

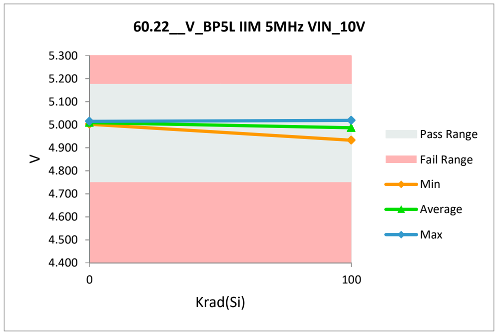


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.22__V_BP5L IIM 5MHz VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.004	5.002	-0.002
0	2	5.016	5.014	-0.002
100	23	5.020	4.982	-0.038
100	24	5.021	4.983	-0.038
100	25	5.011	5.004	-0.007
100	26	4.992	5.011	0.019
100	27	5.011	4.970	-0.041
100	48u	5.032	4.986	-0.045
100	49u	5.017	4.997	-0.020
100	50u	5.029	5.019	-0.011
100	51u	5.006	4.972	-0.034
100	52u	4.997	4.932	-0.065
	Max	5.032	5.019	0.019
	Average	5.013	4.989	-0.024
	Min	4.992	4.932	-0.065
	Std Dev	0.012	0.024	0.024

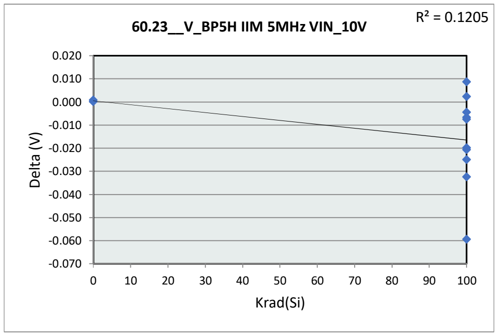


	60.22__V_BP5L IIM 5MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.002	4.932
Average	5.008	4.986
Max	5.014	5.019
UL	5.175	5.175

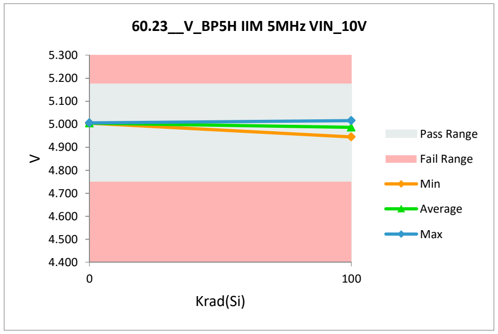


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		60.23__V_BP5H IIM 5MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.003	5.004	0.001
0	2	5.005	5.005	0.000
100	23	4.993	4.961	-0.032
100	24	5.016	4.996	-0.020
100	25	4.996	4.989	-0.008
100	26	5.004	4.997	-0.007
100	27	5.004	4.945	-0.059
100	48u	5.001	5.010	0.009
100	49u	4.995	4.997	0.002
100	50u	5.019	5.015	-0.004
100	51u	5.006	4.981	-0.025
100	52u	4.997	4.977	-0.021
	Max	5.019	5.015	0.009
	Average	5.003	4.990	-0.014
	Min	4.993	4.945	-0.059
	Std Dev	0.008	0.021	0.019

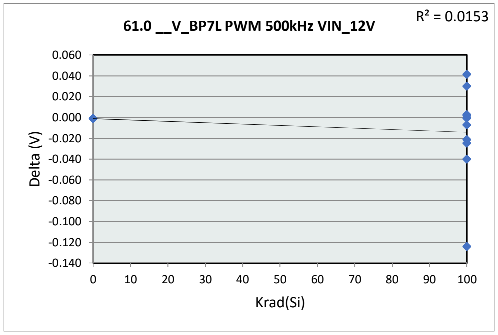


	60.23__V_BP5H IIM 5MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.004	4.945
Average	5.005	4.987
Max	5.005	5.015
UL	5.175	5.175

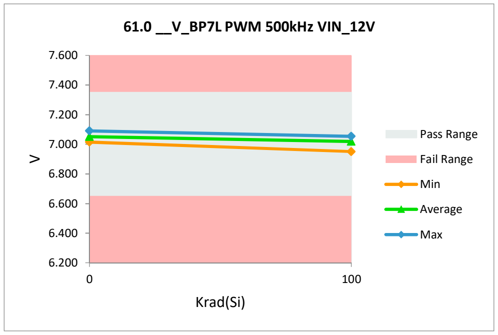


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.0 __V_BP7L PWM 500kHz VI		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.016	7.014	-0.001
0	2	7.091	7.090	-0.001
100	23	7.001	7.031	0.030
100	24	7.049	7.009	-0.040
100	25	7.025	7.028	0.003
100	26	7.013	7.054	0.041
100	27	7.017	7.018	0.002
100	48u	7.020	6.995	-0.025
100	49u	7.056	7.049	-0.007
100	50u	7.027	7.006	-0.021
100	51u	7.045	7.044	-0.001
100	52u	7.075	6.951	-0.124
	Max	7.091	7.090	0.041
	Average	7.036	7.024	-0.012
	Min	7.001	6.951	-0.124
	Std Dev	0.027	0.035	0.042

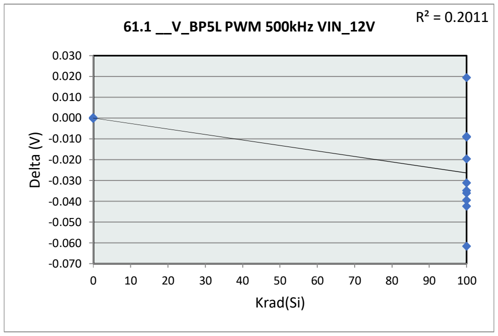


	61.0 __V_BP7L PWM 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.014	6.951
Average	7.052	7.019
Max	7.090	7.054
UL	7.350	7.350

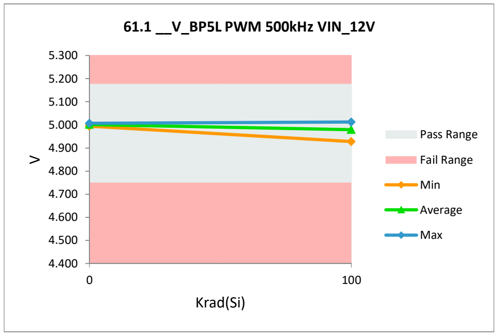


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.1 __V_BP5L PWM 500kHz VI		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.995	4.995	0.000
0	2	5.007	5.007	0.000
100	23	5.011	4.975	-0.036
100	24	5.012	4.977	-0.035
100	25	5.004	4.995	-0.009
100	26	4.984	5.003	0.019
100	27	5.003	4.963	-0.039
100	48u	5.023	4.981	-0.042
100	49u	5.009	4.990	-0.020
100	50u	5.021	5.012	-0.009
100	51u	4.997	4.966	-0.031
100	52u	4.989	4.928	-0.062
	Max	5.023	5.012	0.019
	Average	5.005	4.983	-0.022
	Min	4.984	4.928	-0.062
	Std Dev	0.012	0.023	0.023



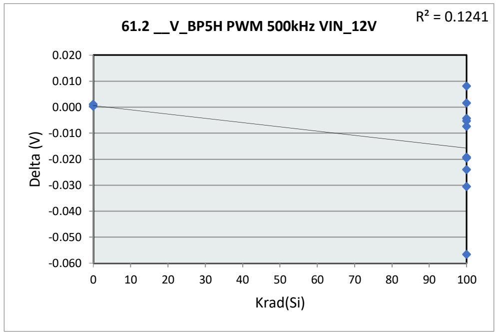
	61.1 __V_BP5L PWM 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.995	4.928
Average	5.001	4.979
Max	5.007	5.012
UL	5.175	5.175



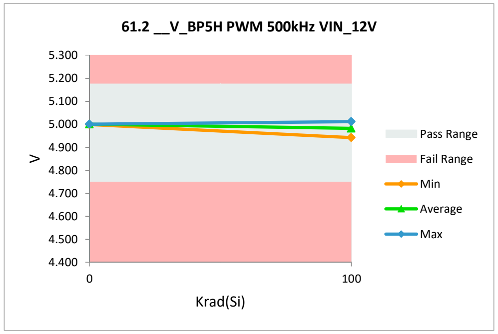
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	61.2 __V_BP5H PWM 500kHz VI	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	V	V
Max Limit	5.175	5.175
Min Limit	4.75	4.75

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.998	4.999	0.001
0	2	5.000	5.001	0.000
100	23	4.988	4.957	-0.031
100	24	5.011	4.992	-0.019
100	25	4.991	4.984	-0.007
100	26	4.999	4.993	-0.005
100	27	4.999	4.942	-0.057
100	48u	4.996	5.004	0.008
100	49u	4.990	4.992	0.002
100	50u	5.015	5.011	-0.004
100	51u	5.000	4.976	-0.024
100	52u	4.992	4.973	-0.020
	Max	5.015	5.011	0.008
	Average	4.998	4.985	-0.013
	Min	4.988	4.942	-0.057
	Std Dev	0.008	0.020	0.018

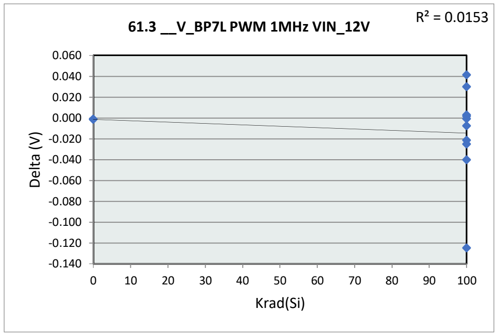


	61.2 __V_BP5H PWM 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.999	4.942
Average	5.000	4.982
Max	5.001	5.011
UL	5.175	5.175

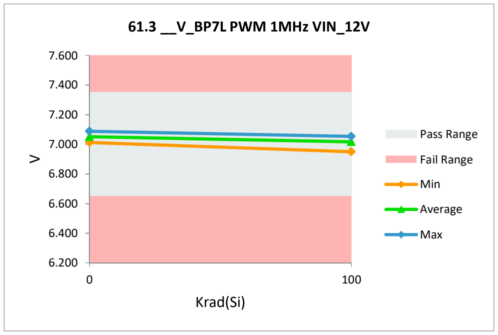


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.3 __V_BP7L PWM 1MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.014	7.013	-0.001
0	2	7.090	7.089	-0.001
100	23	7.000	7.030	0.030
100	24	7.048	7.008	-0.040
100	25	7.024	7.027	0.003
100	26	7.011	7.053	0.041
100	27	7.016	7.017	0.002
100	48u	7.019	6.994	-0.025
100	49u	7.055	7.047	-0.008
100	50u	7.026	7.005	-0.022
100	51u	7.044	7.043	-0.001
100	52u	7.074	6.949	-0.125
	Max	7.090	7.089	0.041
	Average	7.035	7.023	-0.012
	Min	7.000	6.949	-0.125
	Std Dev	0.027	0.035	0.042

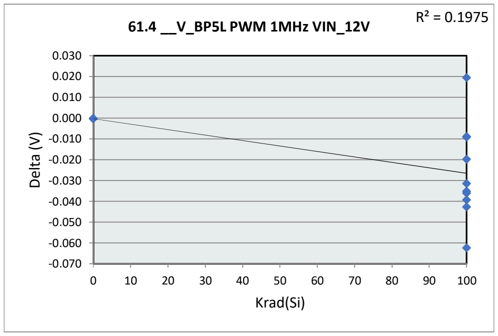


	61.3 __V_BP7L PWM 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.013	6.949
Average	7.051	7.017
Max	7.089	7.053
UL	7.350	7.350

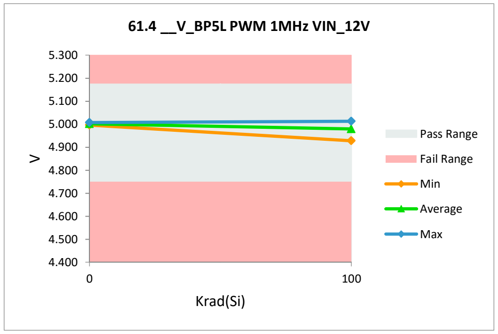


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.4 __V_BP5L PWM 1MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.996	4.996	0.000
0	2	5.008	5.008	0.000
100	23	5.012	4.976	-0.036
100	24	5.013	4.978	-0.035
100	25	5.004	4.996	-0.009
100	26	4.985	5.004	0.019
100	27	5.004	4.964	-0.039
100	48u	5.024	4.981	-0.043
100	49u	5.010	4.990	-0.020
100	50u	5.022	5.012	-0.009
100	51u	4.998	4.967	-0.031
100	52u	4.990	4.928	-0.062
	Max	5.024	5.012	0.019
	Average	5.006	4.983	-0.022
	Min	4.985	4.928	-0.062
	Std Dev	0.012	0.023	0.023



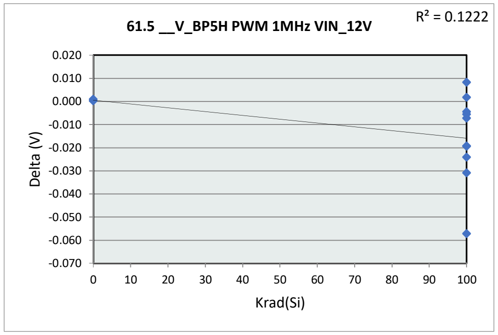
	61.4 __V_BP5L PWM 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.996	4.928
Average	5.002	4.980
Max	5.008	5.013
UL	5.175	5.175



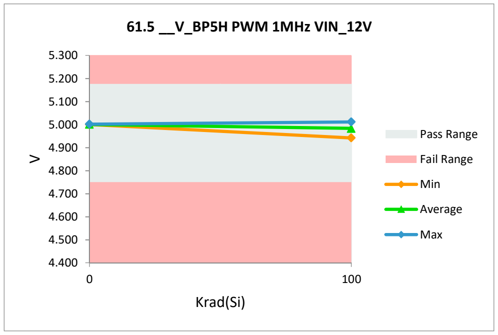
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	61.5 __V_BP5H PWM 1MHz VIN	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	V	V
Max Limit	5.175	5.175
Min Limit	4.75	4.75

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.999	5.000	0.001
0	2	5.001	5.001	0.000
100	23	4.989	4.957	-0.031
100	24	5.012	4.992	-0.019
100	25	4.992	4.984	-0.007
100	26	4.999	4.994	-0.006
100	27	4.999	4.942	-0.057
100	48u	4.997	5.005	0.008
100	49u	4.990	4.992	0.002
100	50u	5.015	5.011	-0.004
100	51u	5.001	4.977	-0.024
100	52u	4.993	4.973	-0.020
	Max	5.015	5.011	0.008
	Average	4.999	4.986	-0.013
	Min	4.989	4.942	-0.057
	Std Dev	0.008	0.020	0.018

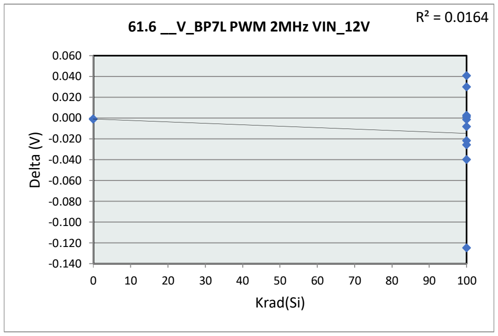


	61.5 __V_BP5H PWM 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.000	4.942
Average	5.000	4.983
Max	5.001	5.011
UL	5.175	5.175

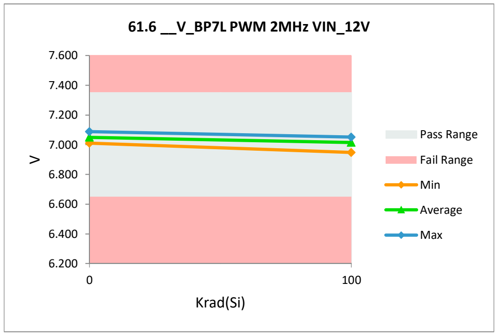


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.6 __V_BP7L PWM 2MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.012	7.011	-0.001
0	2	7.088	7.087	-0.001
100	23	6.998	7.028	0.030
100	24	7.046	7.006	-0.040
100	25	7.022	7.025	0.003
100	26	7.010	7.050	0.041
100	27	7.013	7.014	0.001
100	48u	7.017	6.991	-0.025
100	49u	7.053	7.045	-0.008
100	50u	7.024	7.002	-0.022
100	51u	7.042	7.041	-0.001
100	52u	7.072	6.947	-0.125
	Max	7.088	7.087	0.041
	Average	7.033	7.021	-0.012
	Min	6.998	6.947	-0.125
	Std Dev	0.027	0.035	0.042

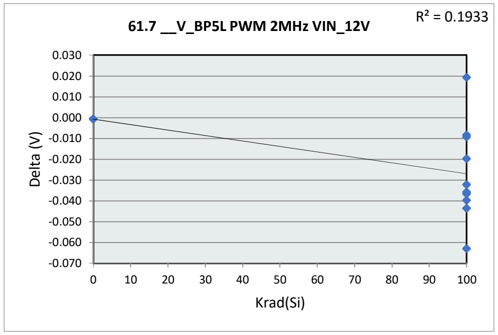


	61.6 __V_BP7L PWM 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.011	6.947
Average	7.049	7.015
Max	7.087	7.050
UL	7.350	7.350

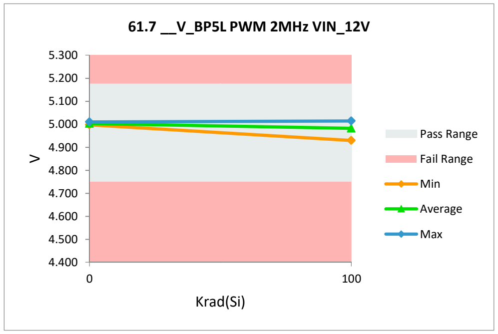


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.7 __V_BP5L PWM 2MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.998	4.997	-0.001
0	2	5.010	5.010	-0.001
100	23	5.014	4.978	-0.037
100	24	5.015	4.979	-0.036
100	25	5.006	4.998	-0.008
100	26	4.987	5.006	0.019
100	27	5.006	4.966	-0.040
100	48u	5.026	4.983	-0.044
100	49u	5.012	4.993	-0.020
100	50u	5.024	5.014	-0.009
100	51u	5.001	4.969	-0.032
100	52u	4.992	4.929	-0.063
	Max	5.026	5.014	0.019
	Average	5.008	4.985	-0.023
	Min	4.987	4.929	-0.063
	Std Dev	0.012	0.024	0.023

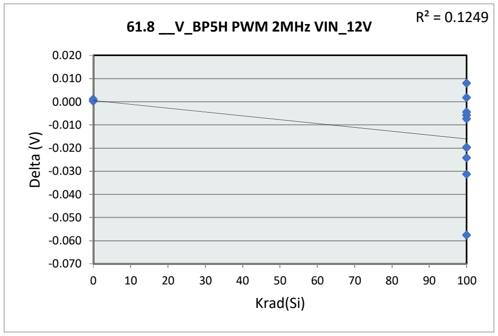


	61.7 __V_BP5L PWM 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.997	4.929
Average	5.004	4.981
Max	5.010	5.014
UL	5.175	5.175

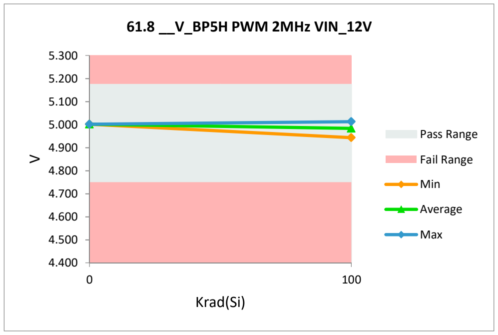


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.8 __V_BP5H PWM 2MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.000	5.001	0.001
0	2	5.002	5.002	0.000
100	23	4.990	4.958	-0.031
100	24	5.013	4.993	-0.020
100	25	4.993	4.985	-0.007
100	26	5.001	4.995	-0.006
100	27	5.001	4.943	-0.058
100	48u	4.998	5.006	0.008
100	49u	4.992	4.993	0.002
100	50u	5.016	5.012	-0.004
100	51u	5.002	4.978	-0.024
100	52u	4.994	4.974	-0.020
	Max	5.016	5.012	0.008
	Average	5.000	4.987	-0.013
	Min	4.990	4.943	-0.058
	Std Dev	0.008	0.020	0.018

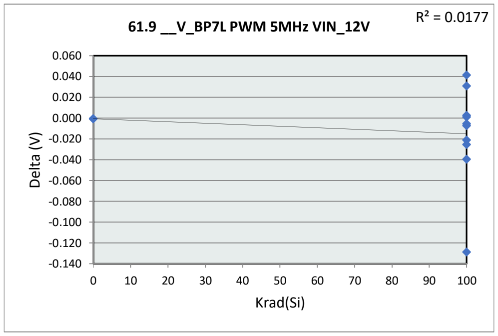


	61.8 __V_BP5H PWM 2MHz VIN_12V		
Test Site	DAL-FL		
Tester	ETS364		
Test Number	EB937004		
Max Limit	5.175		V
Min Limit	4.75		V
Krad(Si)	0	100	
LL	4.750	4.750	
Min	5.001	4.943	
Average	5.002	4.984	
Max	5.002	5.012	
UL	5.175	5.175	

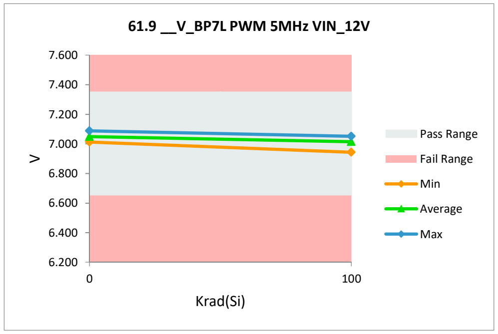


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.9 __V_BP7L PWM 5MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.013	7.012	-0.001
0	2	7.089	7.088	-0.001
100	23	6.998	7.029	0.031
100	24	7.046	7.007	-0.040
100	25	7.023	7.025	0.003
100	26	7.010	7.051	0.041
100	27	7.014	7.015	0.001
100	48u	7.017	6.992	-0.025
100	49u	7.053	7.046	-0.007
100	50u	7.024	7.003	-0.021
100	51u	7.042	7.037	-0.005
100	52u	7.072	6.944	-0.129
	Max	7.089	7.088	0.041
	Average	7.033	7.021	-0.013
	Min	6.998	6.944	-0.129
	Std Dev	0.027	0.035	0.043

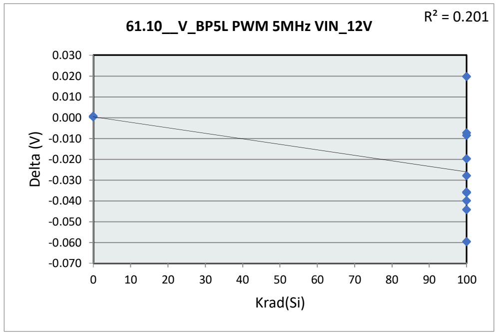


	61.9 __V_BP7L PWM 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.012	6.944
Average	7.050	7.015
Max	7.088	7.051
UL	7.350	7.350

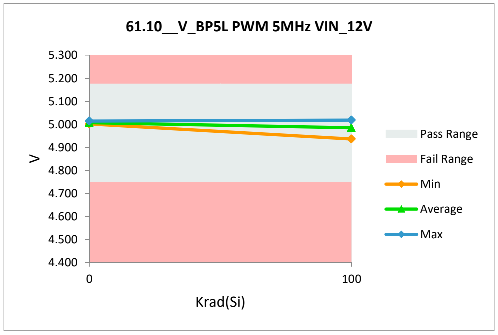


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.10__V_BP5L PWM 5MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.001	5.002	0.001
0	2	5.013	5.014	0.000
100	23	5.017	4.981	-0.036
100	24	5.018	4.982	-0.036
100	25	5.009	5.002	-0.007
100	26	4.990	5.010	0.020
100	27	5.008	4.968	-0.040
100	48u	5.029	4.985	-0.044
100	49u	5.015	4.995	-0.020
100	50u	5.027	5.018	-0.009
100	51u	5.004	4.976	-0.028
100	52u	4.995	4.936	-0.060
	Max	5.029	5.018	0.020
	Average	5.011	4.989	-0.022
	Min	4.990	4.936	-0.060
	Std Dev	0.012	0.023	0.023



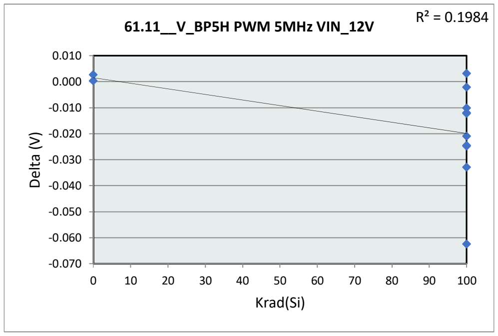
	61.10__V_BP5L PWM 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.002	4.936
Average	5.008	4.985
Max	5.014	5.018
UL	5.175	5.175



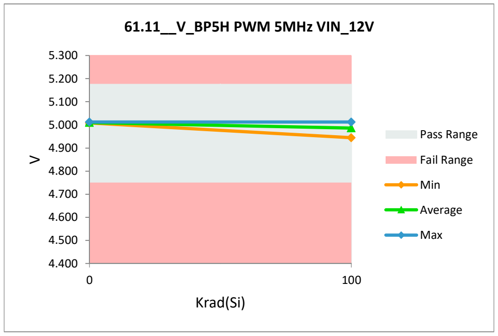
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	61.11__V_BP5H PWM 5MHz VIN	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	V	V
Max Limit	5.175	5.175
Min Limit	4.75	4.75

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.008	5.008	0.000
0	2	5.009	5.012	0.003
100	23	4.991	4.958	-0.033
100	24	5.017	4.996	-0.021
100	25	5.000	4.988	-0.012
100	26	5.008	4.996	-0.012
100	27	5.007	4.945	-0.062
100	48u	5.004	5.007	0.003
100	49u	4.998	4.996	-0.002
100	50u	5.023	5.013	-0.010
100	51u	5.010	4.985	-0.025
100	52u	5.003	4.978	-0.024
	Max	5.023	5.013	0.003
	Average	5.007	4.990	-0.016
	Min	4.991	4.945	-0.062
	Std Dev	0.008	0.021	0.019

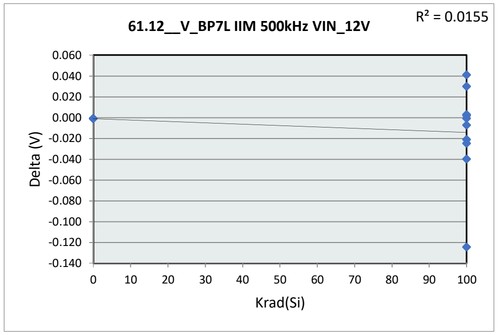


	61.11__V_BP5H PWM 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.008	4.945
Average	5.010	4.986
Max	5.012	5.013
UL	5.175	5.175

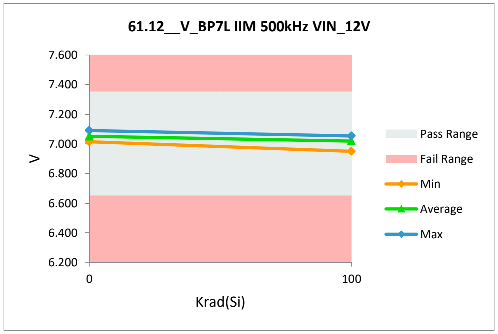


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.12__V_BP7L IIM 500kHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.015	7.014	-0.001
0	2	7.091	7.090	-0.001
100	23	7.001	7.031	0.030
100	24	7.049	7.009	-0.040
100	25	7.025	7.028	0.003
100	26	7.013	7.054	0.041
100	27	7.016	7.018	0.002
100	48u	7.020	6.995	-0.025
100	49u	7.056	7.049	-0.008
100	50u	7.027	7.006	-0.021
100	51u	7.045	7.044	-0.001
100	52u	7.075	6.950	-0.125
	Max	7.091	7.090	0.041
	Average	7.036	7.024	-0.012
	Min	7.001	6.950	-0.125
	Std Dev	0.027	0.035	0.042

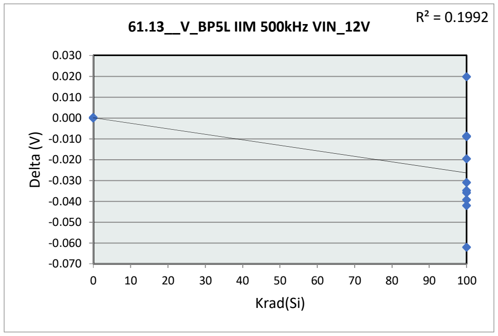


	61.12__V_BP7L IIM 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.014	6.950
Average	7.052	7.018
Max	7.090	7.054
UL	7.350	7.350

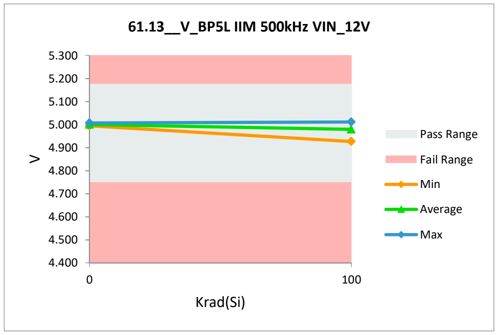


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.13__V_BP5L IIM 500kHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.994	4.995	0.000
0	2	5.007	5.007	0.000
100	23	5.011	4.975	-0.036
100	24	5.012	4.977	-0.035
100	25	5.003	4.995	-0.009
100	26	4.984	5.003	0.020
100	27	5.003	4.963	-0.039
100	48u	5.023	4.981	-0.042
100	49u	5.009	4.990	-0.020
100	50u	5.020	5.012	-0.009
100	51u	4.997	4.966	-0.031
100	52u	4.989	4.927	-0.062
	Max	5.023	5.012	0.020
	Average	5.004	4.983	-0.022
	Min	4.984	4.927	-0.062
	Std Dev	0.012	0.023	0.023

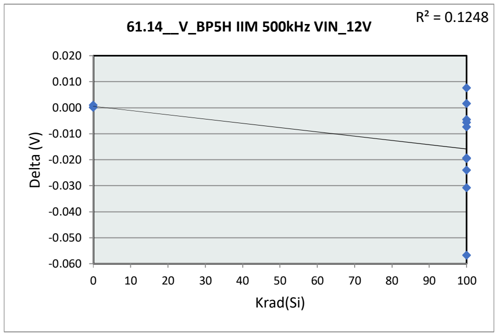


	61.13__V_BP5L IIM 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.995	4.927
Average	5.001	4.979
Max	5.007	5.012
UL	5.175	5.175

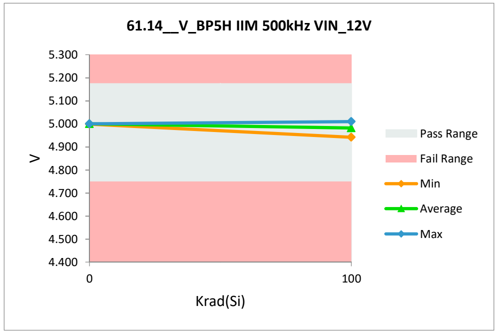


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.14__V_BP5H IIM 500kHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.998	4.999	0.001
0	2	5.000	5.000	0.000
100	23	4.988	4.957	-0.031
100	24	5.011	4.992	-0.019
100	25	4.991	4.984	-0.007
100	26	4.999	4.993	-0.006
100	27	4.999	4.942	-0.057
100	48u	4.996	5.004	0.008
100	49u	4.990	4.991	0.002
100	50u	5.015	5.010	-0.005
100	51u	5.000	4.976	-0.024
100	52u	4.992	4.973	-0.020
	Max	5.015	5.010	0.008
	Average	4.998	4.985	-0.013
	Min	4.988	4.942	-0.057
	Std Dev	0.008	0.020	0.018

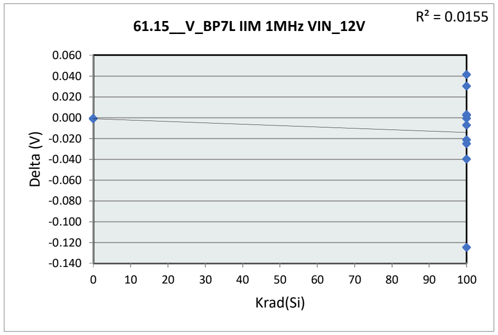


	61.14__V_BP5H IIM 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.999	4.942
Average	5.000	4.982
Max	5.000	5.010
UL	5.175	5.175

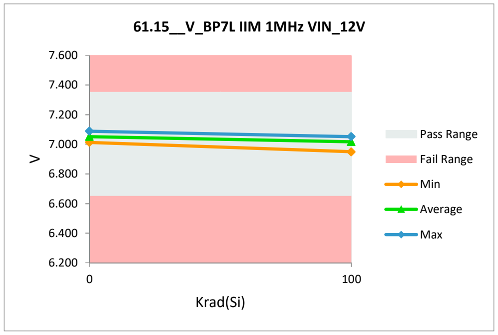


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.15__V_BP7L IIM 1MHz VIN_		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.014	7.013	-0.001
0	2	7.090	7.089	-0.001
100	23	6.999	7.030	0.030
100	24	7.048	7.008	-0.040
100	25	7.024	7.027	0.003
100	26	7.011	7.052	0.041
100	27	7.015	7.018	0.002
100	48u	7.019	6.994	-0.025
100	49u	7.055	7.047	-0.008
100	50u	7.026	7.005	-0.022
100	51u	7.044	7.043	-0.001
100	52u	7.074	6.949	-0.125
	Max	7.090	7.089	0.041
	Average	7.035	7.023	-0.012
	Min	6.999	6.949	-0.125
	Std Dev	0.027	0.035	0.042



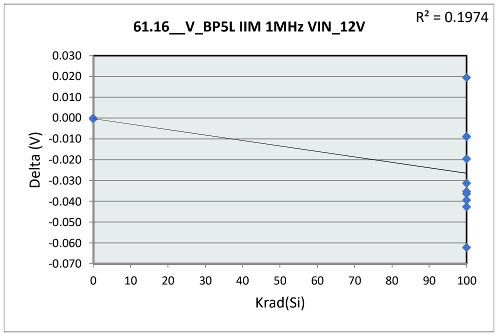
	61.15__V_BP7L IIM 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.013	6.949
Average	7.051	7.017
Max	7.089	7.052
UL	7.350	7.350



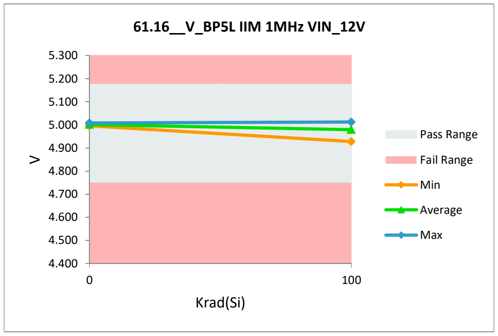
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	61.16__V_BP5L IIM 1MHz VIN_	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	V	V
Max Limit	5.175	5.175
Min Limit	4.75	4.75

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.996	4.996	0.000
0	2	5.008	5.008	0.000
100	23	5.012	4.976	-0.036
100	24	5.013	4.978	-0.035
100	25	5.004	4.996	-0.009
100	26	4.985	5.004	0.019
100	27	5.003	4.964	-0.039
100	48u	5.024	4.982	-0.043
100	49u	5.010	4.991	-0.020
100	50u	5.022	5.012	-0.009
100	51u	4.998	4.967	-0.031
100	52u	4.990	4.928	-0.062
	Max	5.024	5.012	0.019
	Average	5.006	4.983	-0.022
	Min	4.985	4.928	-0.062
	Std Dev	0.012	0.023	0.023

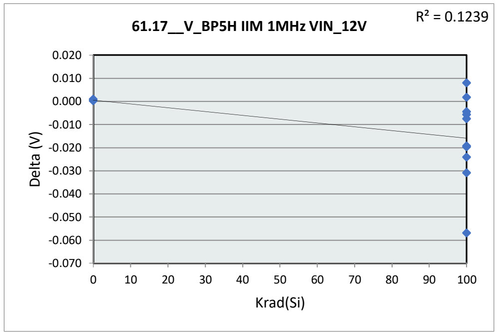


	61.16__V_BP5L IIM 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.996	4.928
Average	5.002	4.980
Max	5.008	5.013
UL	5.175	5.175

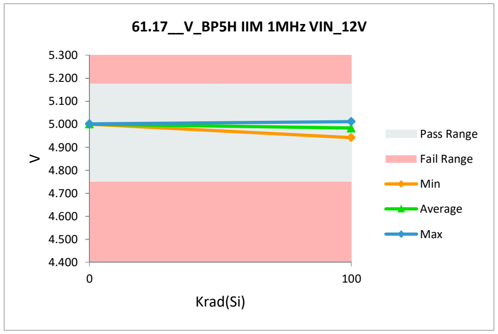


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.17__V_BP5H IIM 1MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.999	5.000	0.001
0	2	5.001	5.001	0.000
100	23	4.989	4.957	-0.031
100	24	5.012	4.992	-0.019
100	25	4.992	4.984	-0.008
100	26	4.999	4.994	-0.006
100	27	4.999	4.942	-0.057
100	48u	4.997	5.005	0.008
100	49u	4.990	4.992	0.002
100	50u	5.016	5.011	-0.004
100	51u	5.001	4.977	-0.024
100	52u	4.993	4.973	-0.020
	Max	5.016	5.011	0.008
	Average	4.999	4.986	-0.013
	Min	4.989	4.942	-0.057
	Std Dev	0.008	0.020	0.018

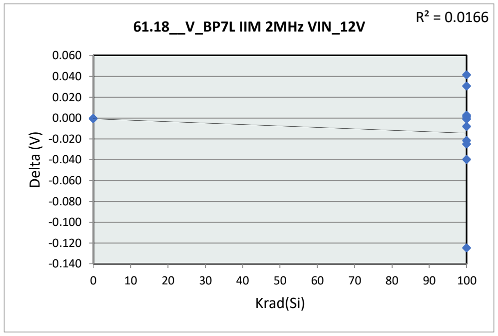


61.17__V_BP5H IIM 1MHz VIN_12V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.000	4.942
Average	5.000	4.983
Max	5.001	5.011
UL	5.175	5.175

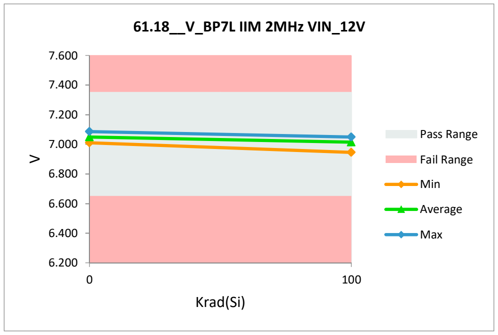


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.18__V_BP7L IIM 2MHz VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.012	7.011	-0.001
0	2	7.088	7.087	-0.001
100	23	6.997	7.028	0.030
100	24	7.046	7.006	-0.040
100	25	7.022	7.025	0.003
100	26	7.009	7.050	0.041
100	27	7.013	7.014	0.001
100	48u	7.016	6.991	-0.025
100	49u	7.053	7.044	-0.008
100	50u	7.024	7.002	-0.022
100	51u	7.042	7.040	-0.001
100	52u	7.072	6.947	-0.125
	Max	7.088	7.087	0.041
	Average	7.033	7.020	-0.012
	Min	6.997	6.947	-0.125
	Std Dev	0.027	0.035	0.042

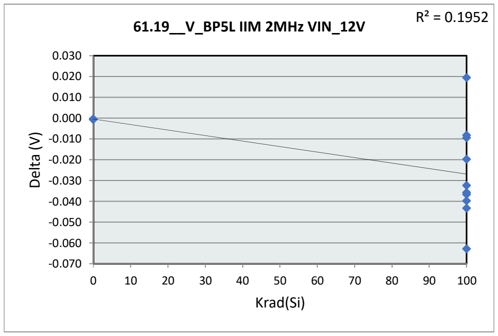


	61.18__V_BP7L IIM 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.011	6.947
Average	7.049	7.015
Max	7.087	7.050
UL	7.350	7.350

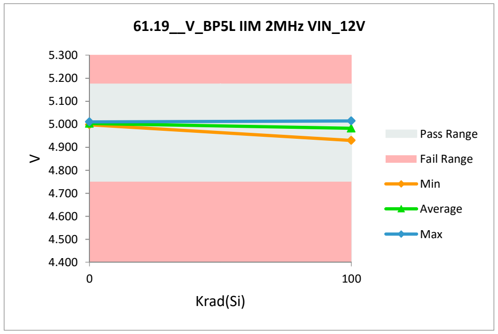


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.19__V_BP5L IIM 2MHz VIN_		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.998	4.997	0.000
0	2	5.010	5.010	-0.001
100	23	5.014	4.978	-0.037
100	24	5.015	4.979	-0.036
100	25	5.006	4.998	-0.008
100	26	4.987	5.006	0.019
100	27	5.005	4.966	-0.040
100	48u	5.026	4.983	-0.043
100	49u	5.012	4.992	-0.020
100	50u	5.024	5.014	-0.009
100	51u	5.001	4.968	-0.032
100	52u	4.992	4.929	-0.063
	Max	5.026	5.014	0.019
	Average	5.008	4.985	-0.022
	Min	4.987	4.929	-0.063
	Std Dev	0.012	0.024	0.023

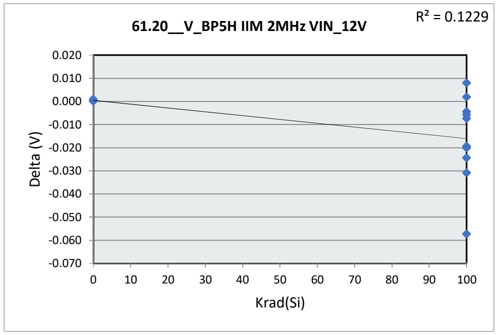


	61.19__V_BP5L IIM 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.998	4.929
Average	5.004	4.981
Max	5.010	5.014
UL	5.175	5.175

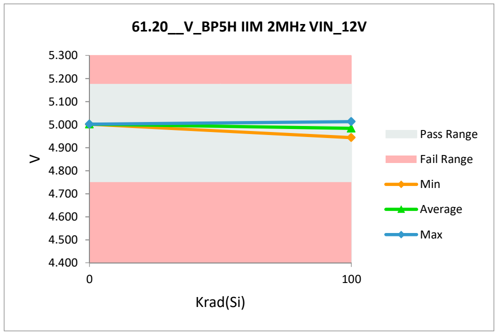


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.20__V_BP5H IIM 2MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.000	5.001	0.001
0	2	5.002	5.002	0.000
100	23	4.990	4.959	-0.031
100	24	5.013	4.993	-0.020
100	25	4.993	4.985	-0.007
100	26	5.001	4.995	-0.006
100	27	5.000	4.943	-0.057
100	48u	4.998	5.006	0.008
100	49u	4.991	4.993	0.002
100	50u	5.016	5.012	-0.004
100	51u	5.002	4.978	-0.024
100	52u	4.994	4.974	-0.020
	Max	5.016	5.012	0.008
	Average	5.000	4.987	-0.013
	Min	4.990	4.943	-0.057
	Std Dev	0.008	0.020	0.018

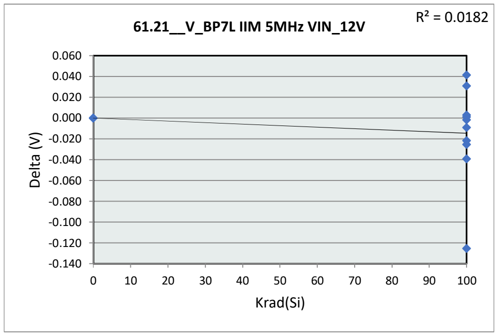


	61.20__V_BP5H IIM 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.001	4.943
Average	5.001	4.984
Max	5.002	5.012
UL	5.175	5.175

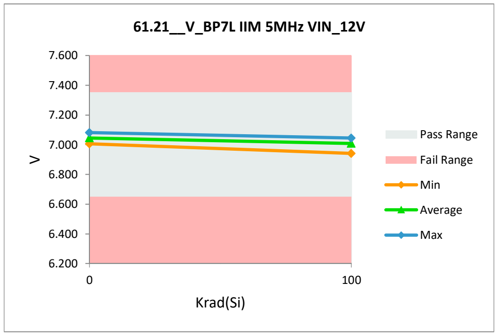


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.21__V_BP7L IIM 5MHz VIN_		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.006	7.006	0.000
0	2	7.082	7.082	0.000
100	23	6.992	7.023	0.031
100	24	7.040	7.001	-0.039
100	25	7.017	7.019	0.003
100	26	7.003	7.044	0.042
100	27	7.007	7.009	0.001
100	48u	7.011	6.985	-0.025
100	49u	7.047	7.038	-0.009
100	50u	7.018	6.996	-0.022
100	51u	7.036	7.034	-0.002
100	52u	7.066	6.940	-0.125
	Max	7.082	7.082	0.042
	Average	7.027	7.015	-0.012
	Min	6.992	6.940	-0.125
	Std Dev	0.027	0.035	0.042

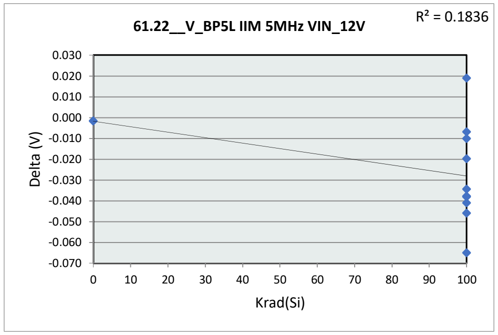


	61.21__V_BP7L IIM 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.006	6.941
Average	7.044	7.009
Max	7.082	7.045
UL	7.350	7.350

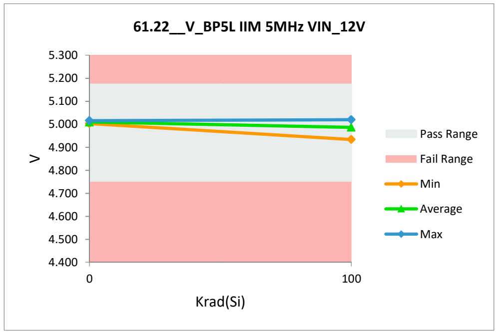


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.22__V_BP5L IIM 5MHz VIN_1		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.005	5.003	-0.002
0	2	5.017	5.015	-0.002
100	23	5.021	4.983	-0.038
100	24	5.022	4.983	-0.038
100	25	5.012	5.005	-0.007
100	26	4.993	5.012	0.019
100	27	5.011	4.970	-0.041
100	48u	5.033	4.987	-0.046
100	49u	5.018	4.998	-0.020
100	50u	5.030	5.020	-0.010
100	51u	5.007	4.973	-0.034
100	52u	4.998	4.933	-0.065
	Max	5.033	5.020	0.019
	Average	5.014	4.990	-0.024
	Min	4.993	4.933	-0.065
	Std Dev	0.012	0.024	0.024

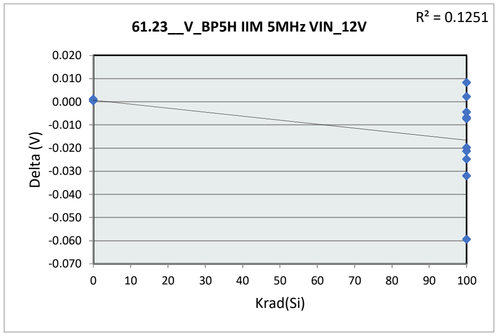


	61.22__V_BP5L IIM 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.003	4.933
Average	5.009	4.987
Max	5.015	5.020
UL	5.175	5.175

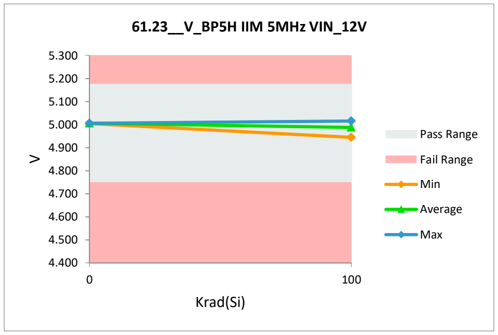


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		61.23__V_BP5H IIM 5MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.004	5.005	0.001
0	2	5.006	5.006	0.000
100	23	4.993	4.961	-0.032
100	24	5.017	4.997	-0.020
100	25	4.996	4.989	-0.007
100	26	5.004	4.998	-0.007
100	27	5.004	4.945	-0.060
100	48u	5.002	5.010	0.008
100	49u	4.995	4.997	0.002
100	50u	5.020	5.016	-0.004
100	51u	5.006	4.981	-0.025
100	52u	4.998	4.976	-0.021
	Max	5.020	5.016	0.008
	Average	5.004	4.990	-0.014
	Min	4.993	4.945	-0.060
	Std Dev	0.008	0.021	0.019

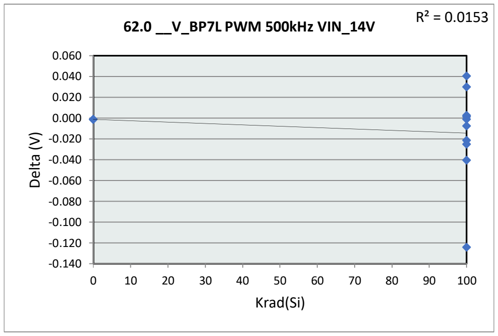


	61.23__V_BP5H IIM 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.005	4.945
Average	5.005	4.987
Max	5.006	5.016
UL	5.175	5.175

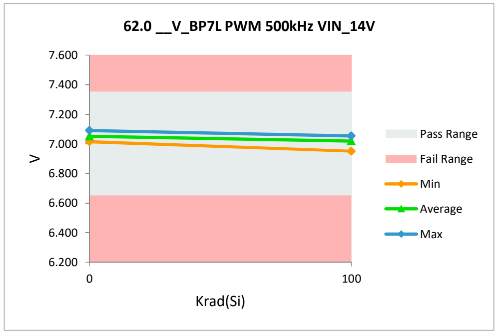


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.0 __V_BP7L PWM 500kHz VI		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.016	7.014	-0.001
0	2	7.091	7.090	-0.001
100	23	7.001	7.031	0.030
100	24	7.049	7.009	-0.040
100	25	7.026	7.028	0.003
100	26	7.013	7.054	0.041
100	27	7.017	7.018	0.001
100	48u	7.020	6.995	-0.025
100	49u	7.056	7.049	-0.007
100	50u	7.028	7.006	-0.021
100	51u	7.045	7.044	-0.001
100	52u	7.075	6.951	-0.124
	Max	7.091	7.090	0.041
	Average	7.036	7.024	-0.012
	Min	7.001	6.951	-0.124
	Std Dev	0.027	0.035	0.041

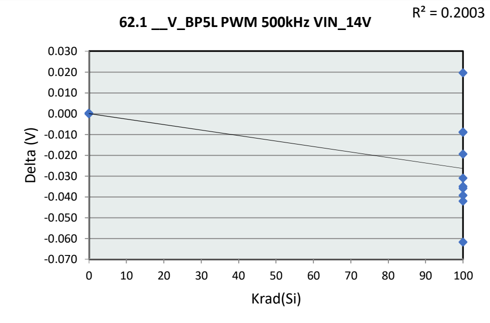


	62.0 __V_BP7L PWM 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.014	6.951
Average	7.052	7.019
Max	7.090	7.054
UL	7.350	7.350

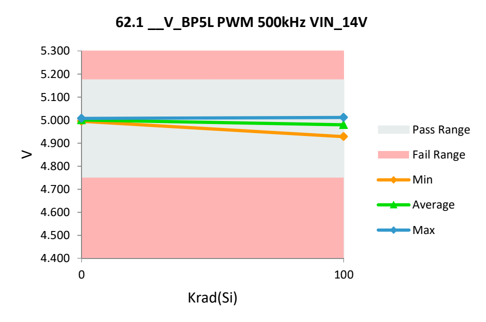


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.1 __V_BP5L PWM 500kHz VI		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.995	4.995	0.000
0	2	5.007	5.007	0.000
100	23	5.011	4.975	-0.036
100	24	5.012	4.977	-0.035
100	25	5.003	4.994	-0.009
100	26	4.984	5.003	0.020
100	27	5.003	4.963	-0.039
100	48u	5.023	4.981	-0.042
100	49u	5.009	4.990	-0.020
100	50u	5.021	5.012	-0.009
100	51u	4.997	4.966	-0.031
100	52u	4.989	4.927	-0.062
	Max	5.023	5.012	0.020
	Average	5.004	4.983	-0.022
	Min	4.984	4.927	-0.062
	Std Dev	0.012	0.023	0.023

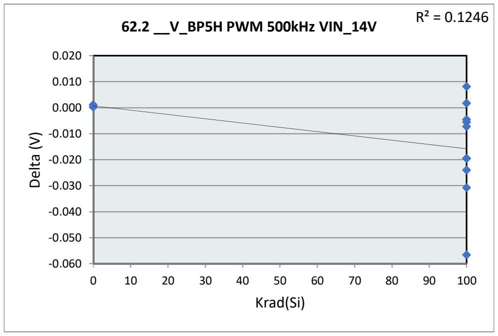


	62.1 __V_BP5L PWM 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.995	4.927
Average	5.001	4.979
Max	5.007	5.012
UL	5.175	5.175

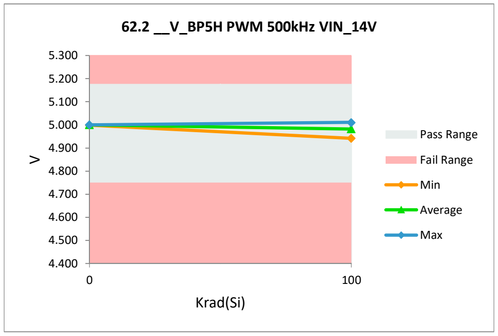


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.2 __V_BP5H PWM 500kHz VI		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.998	4.999	0.001
0	2	5.000	5.000	0.000
100	23	4.988	4.957	-0.031
100	24	5.011	4.992	-0.019
100	25	4.991	4.984	-0.007
100	26	4.999	4.993	-0.006
100	27	4.999	4.942	-0.057
100	48u	4.996	5.004	0.008
100	49u	4.990	4.991	0.002
100	50u	5.015	5.010	-0.005
100	51u	5.000	4.976	-0.024
100	52u	4.992	4.973	-0.019
	Max	5.015	5.010	0.008
	Average	4.998	4.985	-0.013
	Min	4.988	4.942	-0.057
	Std Dev	0.008	0.020	0.018

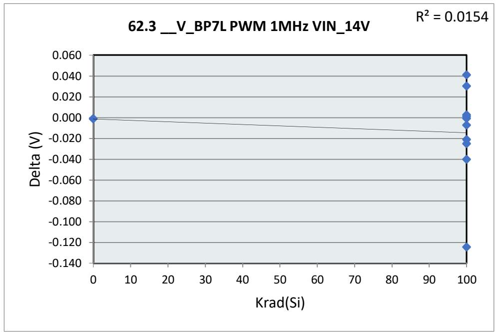


	62.2 __V_BP5H PWM 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.999	4.942
Average	5.000	4.982
Max	5.000	5.010
UL	5.175	5.175

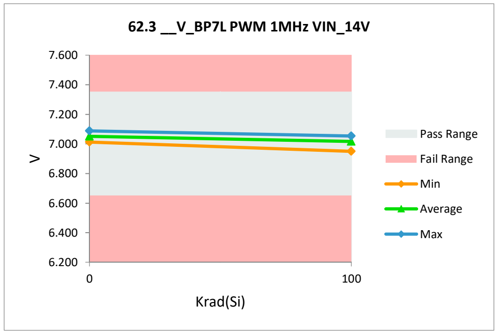


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.3 __V_BP7L PWM 1MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.014	7.013	-0.001
0	2	7.090	7.089	-0.001
100	23	7.000	7.030	0.030
100	24	7.048	7.008	-0.040
100	25	7.024	7.027	0.003
100	26	7.012	7.053	0.041
100	27	7.016	7.017	0.001
100	48u	7.019	6.994	-0.025
100	49u	7.055	7.048	-0.008
100	50u	7.026	7.005	-0.021
100	51u	7.044	7.043	-0.001
100	52u	7.074	6.949	-0.125
	Max	7.090	7.089	0.041
	Average	7.035	7.023	-0.012
	Min	7.000	6.949	-0.125
	Std Dev	0.027	0.035	0.042

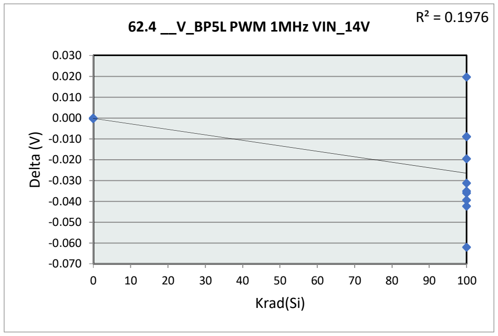


	62.3 __V_BP7L PWM 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.013	6.949
Average	7.051	7.017
Max	7.089	7.053
UL	7.350	7.350

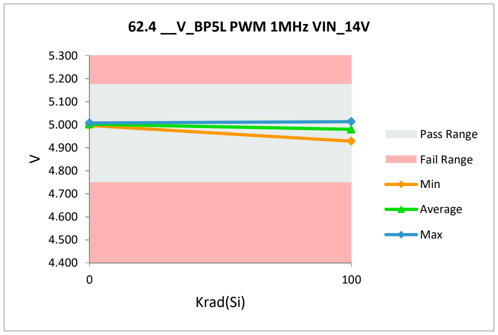


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.4 __V_BP5L PWM 1MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.996	4.996	0.000
0	2	5.008	5.008	0.000
100	23	5.012	4.976	-0.036
100	24	5.013	4.978	-0.035
100	25	5.004	4.996	-0.009
100	26	4.985	5.004	0.019
100	27	5.004	4.964	-0.040
100	48u	5.024	4.982	-0.042
100	49u	5.010	4.991	-0.020
100	50u	5.022	5.013	-0.009
100	51u	4.998	4.967	-0.031
100	52u	4.990	4.928	-0.062
	Max	5.024	5.013	0.019
	Average	5.006	4.983	-0.022
	Min	4.985	4.928	-0.062
	Std Dev	0.012	0.023	0.023

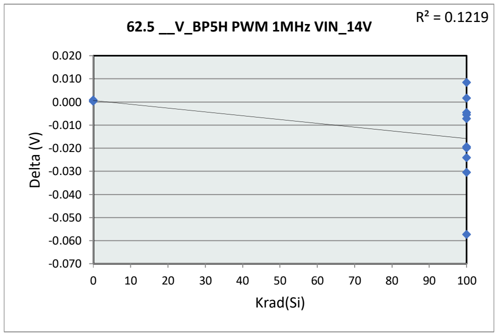


	62.4 __V_BP5L PWM 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.996	4.928
Average	5.002	4.980
Max	5.008	5.013
UL	5.175	5.175

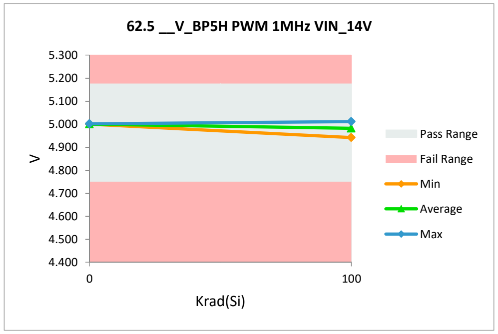


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.5 __V_BP5H PWM 1MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.999	4.999	0.001
0	2	5.001	5.001	0.000
100	23	4.988	4.958	-0.030
100	24	5.012	4.992	-0.019
100	25	4.991	4.984	-0.007
100	26	4.999	4.994	-0.006
100	27	4.999	4.942	-0.057
100	48u	4.997	5.005	0.009
100	49u	4.990	4.992	0.002
100	50u	5.015	5.011	-0.004
100	51u	5.001	4.977	-0.024
100	52u	4.993	4.973	-0.020
	Max	5.015	5.011	0.009
	Average	4.999	4.986	-0.013
	Min	4.988	4.942	-0.057
	Std Dev	0.008	0.020	0.018

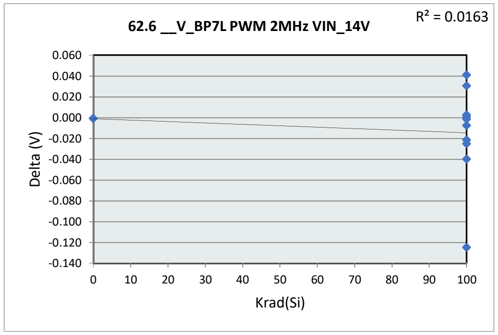


	62.5 __V_BP5H PWM 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.000	4.942
Average	5.000	4.983
Max	5.001	5.011
UL	5.175	5.175

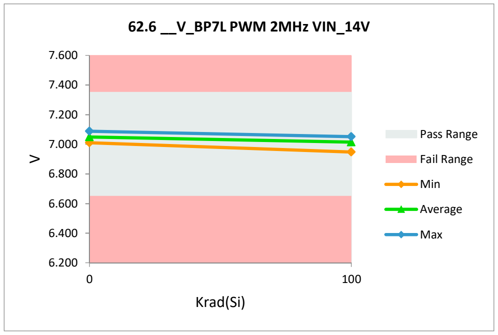


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.6 __V_BP7L PWM 2MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.012	7.011	-0.001
0	2	7.088	7.087	-0.001
100	23	6.998	7.028	0.030
100	24	7.046	7.006	-0.040
100	25	7.023	7.025	0.002
100	26	7.010	7.051	0.041
100	27	7.014	7.014	0.001
100	48u	7.017	6.992	-0.025
100	49u	7.053	7.045	-0.008
100	50u	7.024	7.003	-0.022
100	51u	7.042	7.041	-0.002
100	52u	7.072	6.947	-0.125
	Max	7.088	7.087	0.041
	Average	7.033	7.021	-0.012
	Min	6.998	6.947	-0.125
	Std Dev	0.027	0.035	0.042



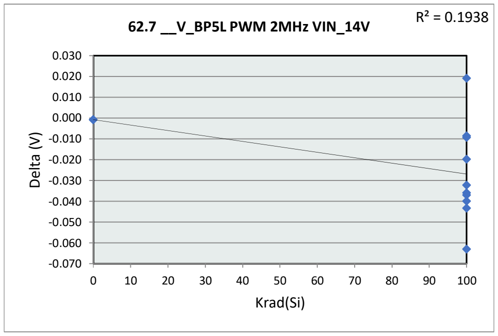
	62.6 __V_BP7L PWM 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.011	6.947
Average	7.049	7.015
Max	7.087	7.051
UL	7.350	7.350



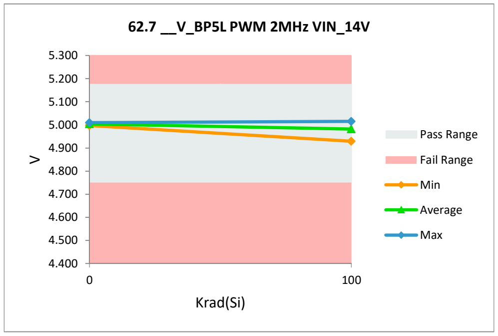
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	62.7 __V_BP5L PWM 2MHz VIN	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	V	V
Max Limit	5.175	5.175
Min Limit	4.75	4.75

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.998	4.998	-0.001
0	2	5.010	5.010	-0.001
100	23	5.015	4.978	-0.037
100	24	5.015	4.979	-0.036
100	25	5.007	4.998	-0.009
100	26	4.987	5.006	0.019
100	27	5.006	4.966	-0.040
100	48u	5.027	4.983	-0.043
100	49u	5.013	4.993	-0.020
100	50u	5.024	5.015	-0.009
100	51u	5.001	4.969	-0.032
100	52u	4.992	4.930	-0.063
	Max	5.027	5.015	0.019
	Average	5.008	4.985	-0.023
	Min	4.987	4.930	-0.063
	Std Dev	0.012	0.024	0.023

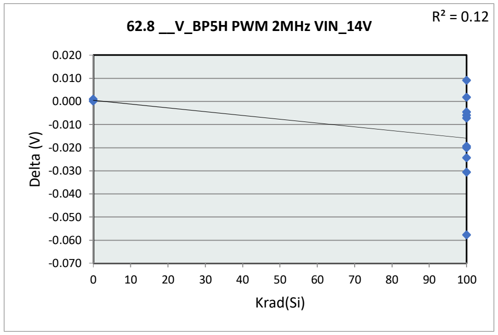


	62.7 __V_BP5L PWM 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.998	4.930
Average	5.004	4.982
Max	5.010	5.015
UL	5.175	5.175

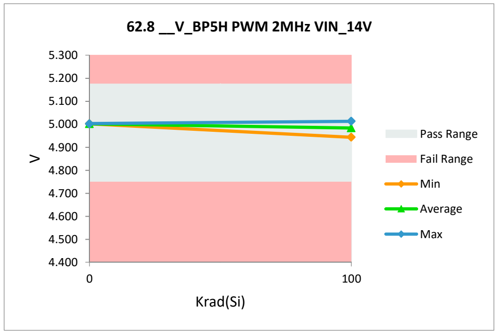


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.8 __V_BP5H PWM 2MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.000	5.001	0.001
0	2	5.002	5.002	0.000
100	23	4.990	4.959	-0.031
100	24	5.013	4.993	-0.020
100	25	4.993	4.985	-0.007
100	26	5.001	4.995	-0.006
100	27	5.001	4.943	-0.058
100	48u	4.998	5.007	0.009
100	49u	4.992	4.993	0.002
100	50u	5.017	5.012	-0.005
100	51u	5.002	4.978	-0.024
100	52u	4.994	4.974	-0.020
	Max	5.017	5.012	0.009
	Average	5.000	4.987	-0.013
	Min	4.990	4.943	-0.058
	Std Dev	0.008	0.020	0.018

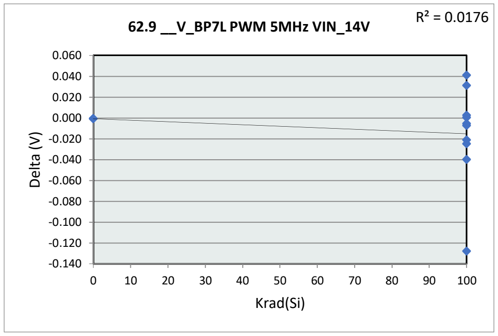


	62.8 __V_BP5H PWM 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.001	4.943
Average	5.002	4.984
Max	5.002	5.012
UL	5.175	5.175

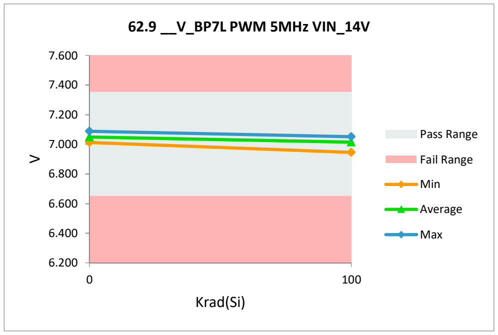


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.9 __V_BP7L PWM 5MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.013	7.012	-0.001
0	2	7.089	7.088	-0.001
100	23	6.998	7.029	0.031
100	24	7.047	7.006	-0.040
100	25	7.023	7.025	0.003
100	26	7.010	7.051	0.041
100	27	7.014	7.014	0.000
100	48u	7.017	6.992	-0.025
100	49u	7.054	7.046	-0.007
100	50u	7.024	7.003	-0.021
100	51u	7.042	7.037	-0.005
100	52u	7.073	6.945	-0.128
	Max	7.089	7.088	0.041
	Average	7.034	7.021	-0.013
	Min	6.998	6.945	-0.128
	Std Dev	0.027	0.035	0.042

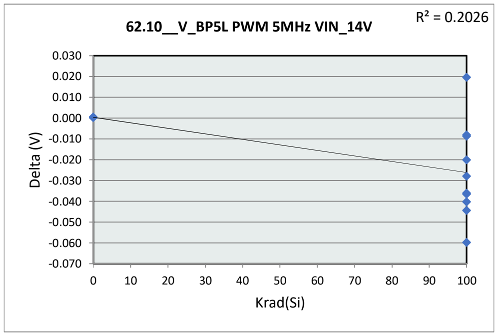


	62.9 __V_BP7L PWM 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.012	6.945
Average	7.050	7.015
Max	7.088	7.051
UL	7.350	7.350

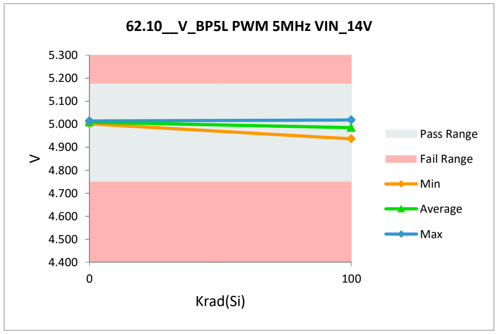


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.10__V_BP5L PWM 5MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.001	5.002	0.001
0	2	5.014	5.014	0.000
100	23	5.017	4.981	-0.036
100	24	5.018	4.982	-0.036
100	25	5.010	5.002	-0.008
100	26	4.990	5.010	0.020
100	27	5.009	4.968	-0.040
100	48u	5.030	4.985	-0.044
100	49u	5.016	4.996	-0.020
100	50u	5.027	5.018	-0.009
100	51u	5.004	4.976	-0.028
100	52u	4.996	4.936	-0.060
	Max	5.030	5.018	0.020
	Average	5.011	4.989	-0.022
	Min	4.990	4.936	-0.060
	Std Dev	0.012	0.023	0.023

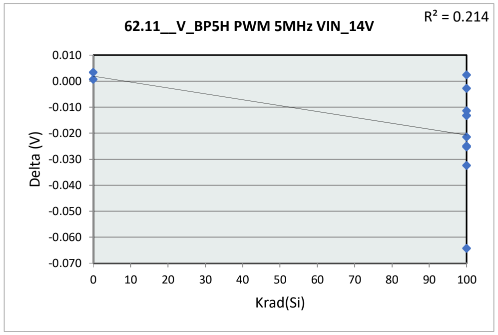


	62.10__V_BP5L PWM 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.002	4.936
Average	5.008	4.985
Max	5.014	5.018
UL	5.175	5.175

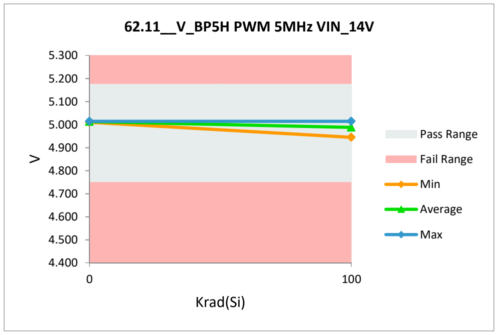


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.11__V_BP5H PWM 5MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.010	5.010	0.001
0	2	5.011	5.014	0.003
100	23	4.992	4.959	-0.032
100	24	5.018	4.997	-0.022
100	25	5.001	4.988	-0.013
100	26	5.010	4.997	-0.013
100	27	5.009	4.945	-0.064
100	48u	5.006	5.008	0.002
100	49u	5.000	4.997	-0.003
100	50u	5.025	5.014	-0.011
100	51u	5.012	4.987	-0.025
100	52u	5.005	4.979	-0.025
	Max	5.025	5.014	0.003
	Average	5.008	4.991	-0.017
	Min	4.992	4.945	-0.064
	Std Dev	0.009	0.022	0.019

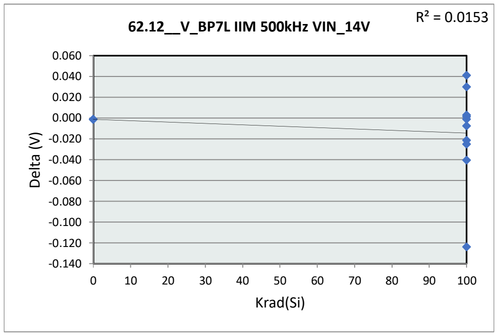


	62.11__V_BP5H PWM 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.010	4.945
Average	5.012	4.987
Max	5.014	5.014
UL	5.175	5.175

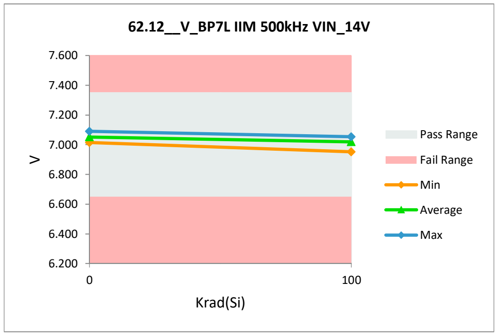


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.12__V_BP7L IIM 500kHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.015	7.014	-0.001
0	2	7.091	7.090	-0.001
100	23	7.001	7.031	0.030
100	24	7.049	7.009	-0.040
100	25	7.025	7.028	0.003
100	26	7.013	7.054	0.041
100	27	7.017	7.018	0.001
100	48u	7.020	6.995	-0.025
100	49u	7.056	7.049	-0.007
100	50u	7.027	7.006	-0.021
100	51u	7.045	7.044	-0.001
100	52u	7.075	6.951	-0.124
	Max	7.091	7.090	0.041
	Average	7.036	7.024	-0.012
	Min	7.001	6.951	-0.124
	Std Dev	0.027	0.035	0.042

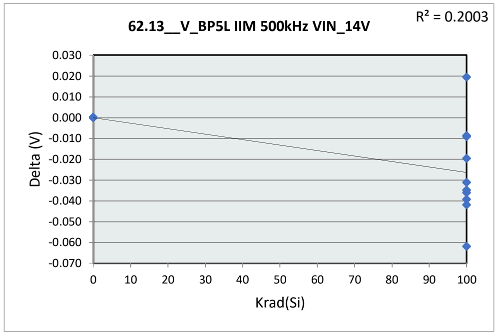


	62.12__V_BP7L IIM 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.014	6.951
Average	7.052	7.019
Max	7.090	7.054
UL	7.350	7.350

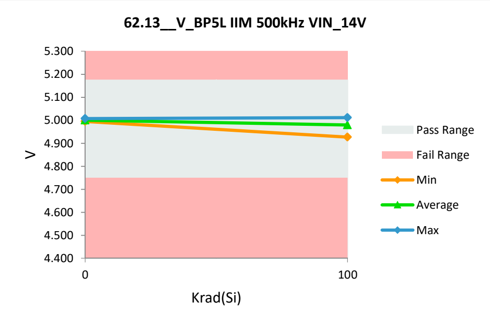


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.13__V_BP5L IIM 500kHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.994	4.995	0.000
0	2	5.007	5.007	0.000
100	23	5.011	4.975	-0.036
100	24	5.012	4.977	-0.035
100	25	5.003	4.994	-0.009
100	26	4.984	5.003	0.019
100	27	5.003	4.963	-0.039
100	48u	5.023	4.981	-0.042
100	49u	5.009	4.990	-0.020
100	50u	5.020	5.012	-0.009
100	51u	4.997	4.966	-0.031
100	52u	4.989	4.927	-0.062
	Max	5.023	5.012	0.019
	Average	5.004	4.982	-0.022
	Min	4.984	4.927	-0.062
	Std Dev	0.012	0.023	0.023

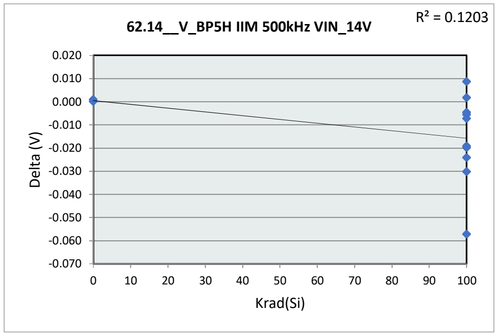


	62.13__V_BP5L IIM 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.995	4.927
Average	5.001	4.979
Max	5.007	5.012
UL	5.175	5.175

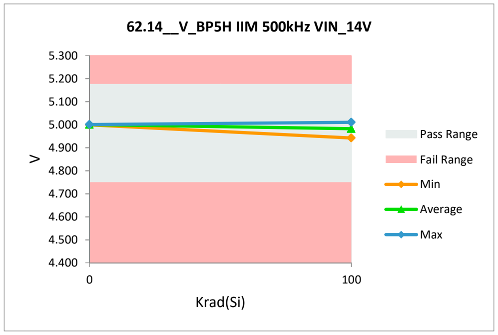


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.14__V_BP5H IIM 500kHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.998	4.999	0.001
0	2	5.000	5.000	0.000
100	23	4.988	4.957	-0.030
100	24	5.011	4.992	-0.019
100	25	4.991	4.984	-0.007
100	26	4.999	4.993	-0.006
100	27	4.999	4.941	-0.057
100	48u	4.996	5.004	0.009
100	49u	4.990	4.991	0.002
100	50u	5.015	5.010	-0.005
100	51u	5.000	4.976	-0.024
100	52u	4.992	4.972	-0.020
	Max	5.015	5.010	0.009
	Average	4.998	4.985	-0.013
	Min	4.988	4.941	-0.057
	Std Dev	0.008	0.020	0.018

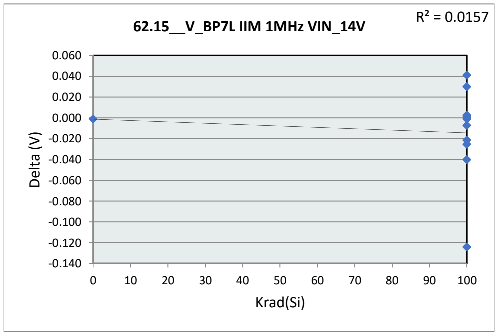


	62.14__V_BP5H IIM 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.999	4.941
Average	5.000	4.982
Max	5.000	5.010
UL	5.175	5.175

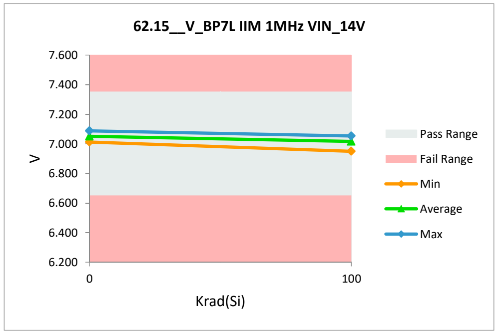


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.15__V_BP7L IIM 1MHz VIN_1		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.014	7.013	-0.001
0	2	7.090	7.089	-0.001
100	23	7.000	7.030	0.030
100	24	7.048	7.008	-0.040
100	25	7.024	7.027	0.003
100	26	7.011	7.053	0.041
100	27	7.016	7.017	0.001
100	48u	7.019	6.994	-0.025
100	49u	7.055	7.048	-0.007
100	50u	7.026	7.005	-0.021
100	51u	7.044	7.043	-0.001
100	52u	7.074	6.950	-0.124
	Max	7.090	7.089	0.041
	Average	7.035	7.023	-0.012
	Min	7.000	6.950	-0.124
	Std Dev	0.027	0.035	0.042

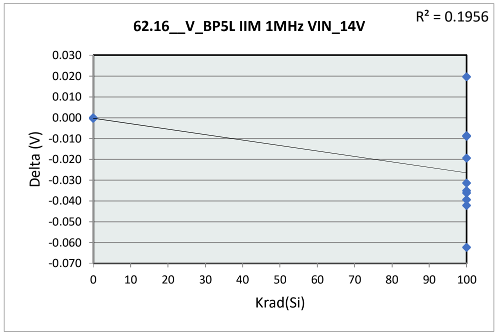


	62.15__V_BP7L IIM 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.013	6.950
Average	7.051	7.017
Max	7.089	7.053
UL	7.350	7.350

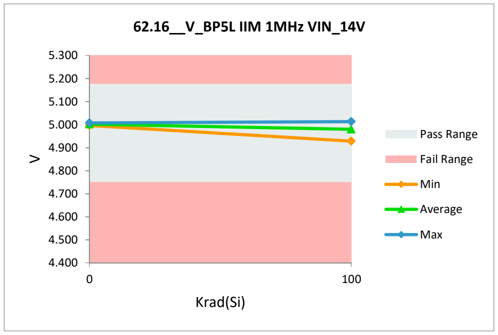


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.16__V_BP5L IIM 1MHz VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.996	4.996	0.000
0	2	5.008	5.008	-0.001
100	23	5.012	4.976	-0.036
100	24	5.013	4.978	-0.035
100	25	5.004	4.996	-0.009
100	26	4.985	5.004	0.020
100	27	5.004	4.964	-0.040
100	48u	5.024	4.982	-0.042
100	49u	5.010	4.991	-0.020
100	50u	5.022	5.013	-0.009
100	51u	4.998	4.967	-0.031
100	52u	4.990	4.928	-0.063
	Max	5.024	5.013	0.020
	Average	5.006	4.983	-0.022
	Min	4.985	4.928	-0.063
	Std Dev	0.012	0.024	0.023

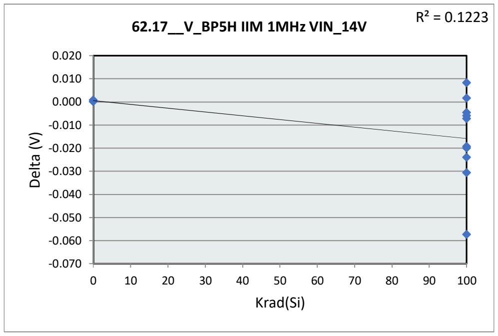


	62.16__V_BP5L IIM 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.996	4.928
Average	5.002	4.980
Max	5.008	5.013
UL	5.175	5.175

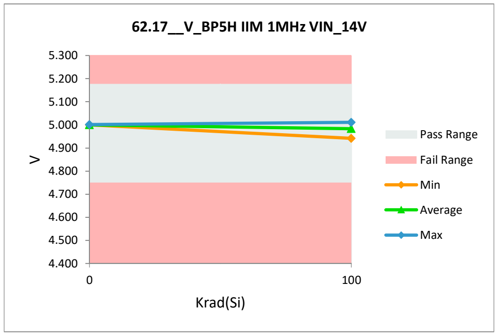


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.17__V_BP5H IIM 1MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.999	4.999	0.001
0	2	5.001	5.001	0.000
100	23	4.988	4.958	-0.031
100	24	5.012	4.992	-0.019
100	25	4.991	4.984	-0.007
100	26	4.999	4.993	-0.006
100	27	4.999	4.942	-0.057
100	48u	4.997	5.005	0.008
100	49u	4.990	4.992	0.002
100	50u	5.015	5.011	-0.004
100	51u	5.001	4.977	-0.024
100	52u	4.993	4.973	-0.020
	Max	5.015	5.011	0.008
	Average	4.999	4.986	-0.013
	Min	4.988	4.942	-0.057
	Std Dev	0.008	0.020	0.018

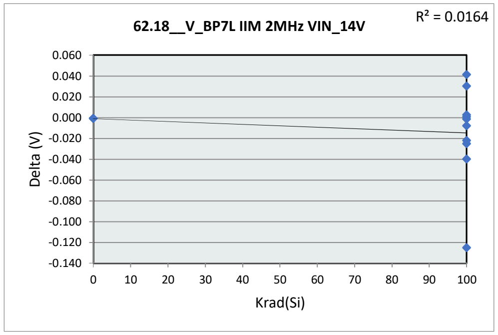


	62.17__V_BP5H IIM 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.000	4.942
Average	5.000	4.983
Max	5.001	5.011
UL	5.175	5.175

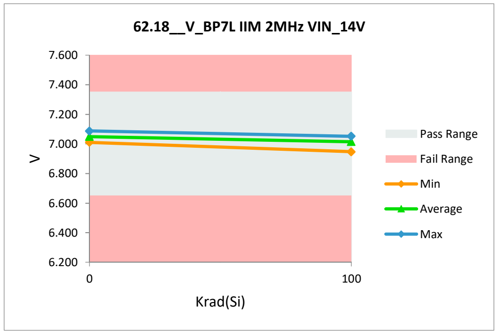


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.18__V_BP7L IIM 2MHz VIN_		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.012	7.011	-0.001
0	2	7.088	7.087	-0.001
100	23	6.998	7.028	0.030
100	24	7.046	7.006	-0.040
100	25	7.022	7.025	0.003
100	26	7.009	7.050	0.041
100	27	7.014	7.014	0.001
100	48u	7.017	6.992	-0.025
100	49u	7.053	7.045	-0.008
100	50u	7.024	7.002	-0.022
100	51u	7.042	7.041	-0.002
100	52u	7.072	6.947	-0.125
	Max	7.088	7.087	0.041
	Average	7.033	7.021	-0.012
	Min	6.998	6.947	-0.125
	Std Dev	0.027	0.035	0.042

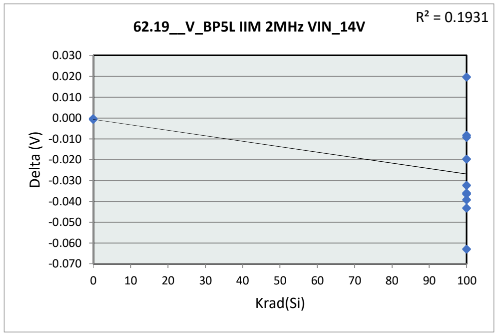


	62.18__V_BP7L IIM 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.011	6.947
Average	7.049	7.015
Max	7.087	7.051
UL	7.350	7.350

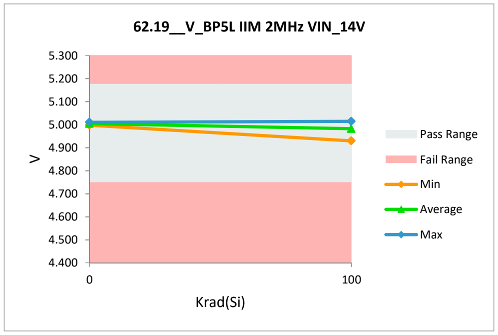


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.19__V_BP5L IIM 2MHz VIN_1		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.998	4.998	0.000
0	2	5.010	5.010	-0.001
100	23	5.015	4.978	-0.037
100	24	5.015	4.979	-0.036
100	25	5.006	4.998	-0.008
100	26	4.987	5.007	0.020
100	27	5.006	4.966	-0.039
100	48u	5.027	4.983	-0.043
100	49u	5.012	4.993	-0.020
100	50u	5.024	5.015	-0.009
100	51u	5.001	4.969	-0.032
100	52u	4.992	4.929	-0.063
	Max	5.027	5.015	0.020
	Average	5.008	4.985	-0.023
	Min	4.987	4.929	-0.063
	Std Dev	0.012	0.024	0.023

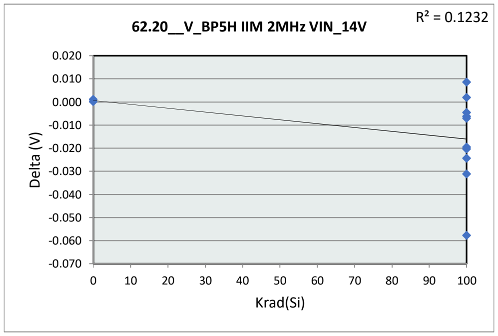


	62.19__V_BP5L IIM 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.998	4.929
Average	5.004	4.982
Max	5.010	5.015
UL	5.175	5.175

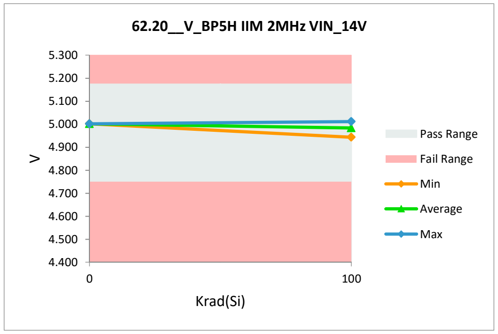


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.20__V_BP5H IIM 2MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.000	5.001	0.001
0	2	5.002	5.002	0.000
100	23	4.990	4.958	-0.031
100	24	5.013	4.993	-0.019
100	25	4.993	4.986	-0.007
100	26	5.001	4.994	-0.006
100	27	5.000	4.943	-0.058
100	48u	4.998	5.006	0.009
100	49u	4.992	4.994	0.002
100	50u	5.016	5.012	-0.005
100	51u	5.002	4.978	-0.024
100	52u	4.994	4.974	-0.020
	Max	5.016	5.012	0.009
	Average	5.000	4.987	-0.013
	Min	4.990	4.943	-0.058
	Std Dev	0.008	0.020	0.019

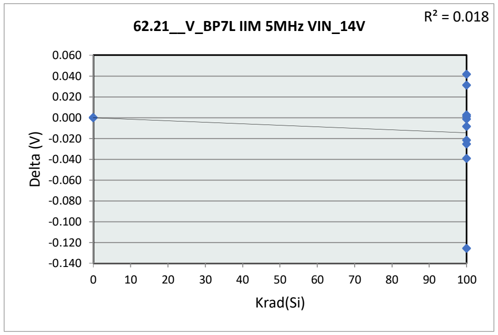


	62.20__V_BP5H IIM 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.001	4.943
Average	5.002	4.984
Max	5.002	5.012
UL	5.175	5.175

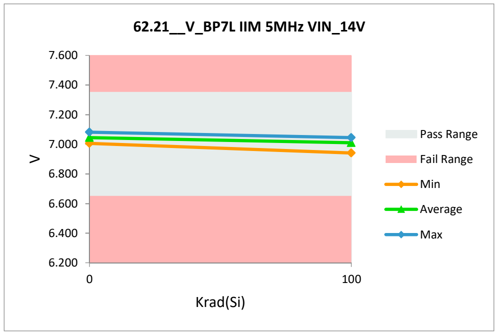


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.21__V_BP7L IIM 5MHz VIN_		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.007	7.007	0.000
0	2	7.083	7.083	0.000
100	23	6.992	7.023	0.031
100	24	7.041	7.001	-0.039
100	25	7.017	7.020	0.003
100	26	7.004	7.045	0.042
100	27	7.008	7.009	0.001
100	48u	7.012	6.986	-0.025
100	49u	7.048	7.039	-0.009
100	50u	7.018	6.997	-0.022
100	51u	7.037	7.035	-0.001
100	52u	7.067	6.941	-0.126
	Max	7.083	7.083	0.042
	Average	7.028	7.016	-0.012
	Min	6.992	6.941	-0.126
	Std Dev	0.027	0.035	0.042

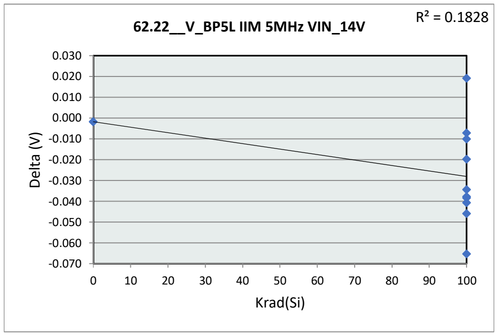


	62.21__V_BP7L IIM 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.007	6.941
Average	7.045	7.010
Max	7.083	7.045
UL	7.350	7.350

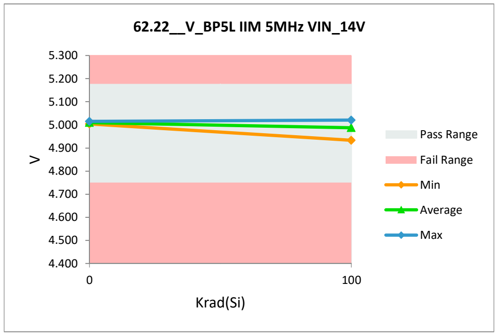


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.22__V_BP5L IIM 5MHz VIN_1		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.005	5.004	-0.002
0	2	5.017	5.016	-0.002
100	23	5.022	4.984	-0.038
100	24	5.022	4.984	-0.038
100	25	5.013	5.006	-0.007
100	26	4.994	5.013	0.019
100	27	5.012	4.971	-0.041
100	48u	5.033	4.988	-0.046
100	49u	5.019	4.999	-0.020
100	50u	5.031	5.021	-0.010
100	51u	5.008	4.974	-0.034
100	52u	4.999	4.934	-0.065
	Max	5.033	5.021	0.019
	Average	5.015	4.991	-0.024
	Min	4.994	4.934	-0.065
	Std Dev	0.012	0.024	0.024

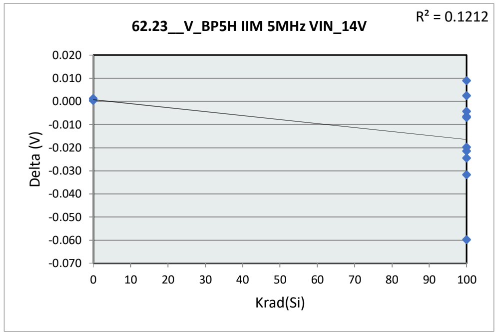


	62.22__V_BP5L IIM 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.004	4.934
Average	5.010	4.987
Max	5.016	5.021
UL	5.175	5.175

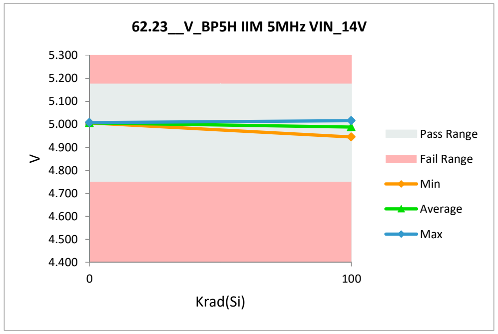


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		62.23__V_BP5H IIM 5MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	5.004	5.005	0.001
0	2	5.006	5.006	0.000
100	23	4.994	4.962	-0.032
100	24	5.017	4.997	-0.020
100	25	4.997	4.990	-0.007
100	26	5.005	4.998	-0.007
100	27	5.005	4.945	-0.060
100	48u	5.002	5.011	0.009
100	49u	4.996	4.998	0.002
100	50u	5.020	5.016	-0.004
100	51u	5.006	4.982	-0.025
100	52u	4.998	4.977	-0.022
	Max	5.020	5.016	0.009
	Average	5.004	4.991	-0.014
	Min	4.994	4.945	-0.060
	Std Dev	0.008	0.021	0.019

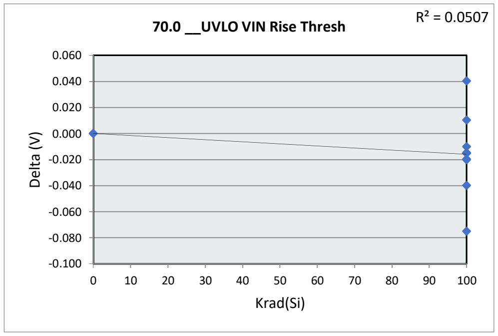


	62.23__V_BP5H IIM 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.005	4.945
Average	5.006	4.987
Max	5.006	5.016
UL	5.175	5.175

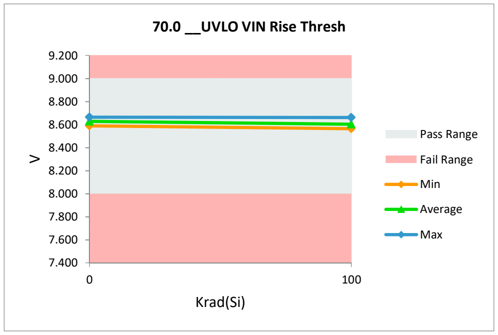


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		70.0 __UVLO VIN Rise Thresh		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		9	9	
Min Limit		8	8	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	8.590	8.590	0.000
0	2	8.665	8.665	0.000
100	23	8.550	8.590	0.040
100	24	8.580	8.565	-0.015
100	25	8.650	8.575	-0.075
100	26	8.620	8.600	-0.020
100	27	8.645	8.655	0.010
100	48u	8.610	8.590	-0.020
100	49u	8.675	8.660	-0.015
100	50u	8.630	8.615	-0.015
100	51u	8.635	8.595	-0.040
100	52u	8.595	8.585	-0.010
	Max	8.675	8.665	0.040
	Average	8.620	8.607	-0.013
	Min	8.550	8.565	-0.075
	Std Dev	0.037	0.034	0.028



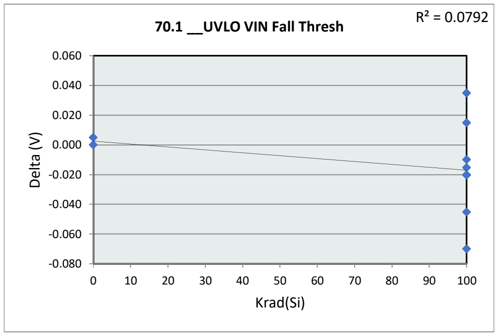
	70.0 __UVLO VIN Rise Thresh	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	V
Min Limit	8	V
Krad(Si)	0	100
LL	8.000	8.000
Min	8.590	8.565
Average	8.628	8.603
Max	8.665	8.660
UL	9.000	9.000



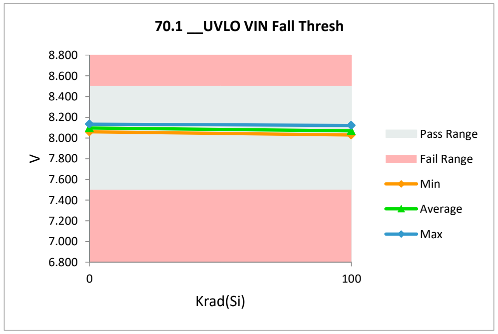
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	70.1 __UVLO VIN Fall Thresh	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	V	V
Max Limit	8.5	8.5
Min Limit	7.5	7.5

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	8.055	8.060	0.005
0	2	8.135	8.135	0.000
100	23	8.020	8.055	0.035
100	24	8.050	8.030	-0.020
100	25	8.115	8.045	-0.070
100	26	8.085	8.065	-0.020
100	27	8.105	8.120	0.015
100	48u	8.080	8.060	-0.020
100	49u	8.135	8.120	-0.015
100	50u	8.100	8.080	-0.020
100	51u	8.105	8.060	-0.045
100	52u	8.065	8.055	-0.010
	Max	8.135	8.135	0.035
	Average	8.088	8.074	-0.014
	Min	8.020	8.030	-0.070
	Std Dev	0.035	0.033	0.027

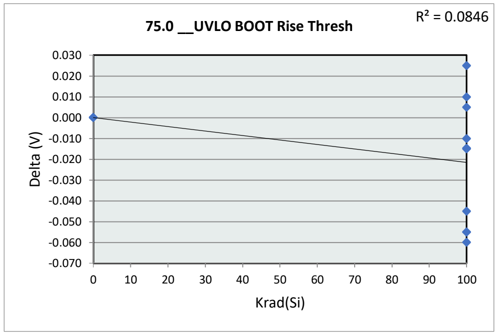


	70.1 __UVLO VIN Fall Thresh	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8.5	V
Min Limit	7.5	V
Krad(Si)	0	100
LL	7.500	7.500
Min	8.060	8.030
Average	8.098	8.069
Max	8.135	8.120
UL	8.500	8.500

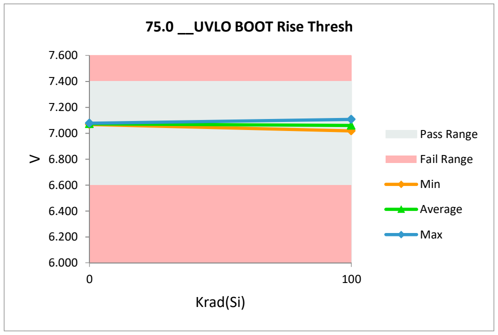


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		75.0 __UVLO BOOT Rise Thresh		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.4	7.4	
	Min Limit	6.6	6.6	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	7.068	7.068	0.000
0	2	7.077	7.077	0.000
100	23	7.098	7.043	-0.055
100	24	7.082	7.022	-0.060
100	25	7.102	7.108	0.005
100	26	7.048	7.032	-0.015
100	27	6.992	7.017	0.025
100	48u	7.082	7.068	-0.015
100	49u	7.068	7.057	-0.010
100	50u	7.102	7.057	-0.045
100	51u	7.093	7.102	0.010
100	52u	7.133	7.077	-0.055
	Max	7.133	7.108	0.025
	Average	7.079	7.061	-0.018
	Min	6.992	7.017	-0.060
	Std Dev	0.035	0.029	0.029

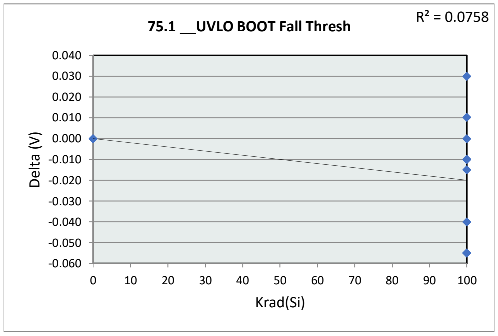


	75.0 __UVLO BOOT Rise Thresh	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.4	V
Min Limit	6.6	V
Krad(Si)	0	100
LL	6.600	6.600
Min	7.068	7.018
Average	7.073	7.058
Max	7.078	7.108
UL	7.400	7.400

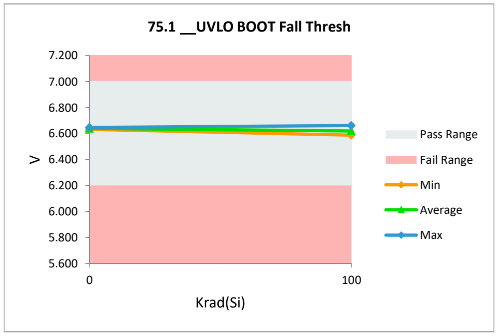


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		75.1 __UVLO BOOT Fall Thresh		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7	7	
Min Limit		6.2	6.2	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	6.633	6.633	0.000
0	2	6.648	6.648	0.000
100	23	6.663	6.608	-0.055
100	24	6.642	6.588	-0.055
100	25	6.663	6.663	0.000
100	26	6.608	6.597	-0.010
100	27	6.557	6.588	0.030
100	48u	6.642	6.633	-0.010
100	49u	6.628	6.613	-0.015
100	50u	6.657	6.617	-0.040
100	51u	6.652	6.663	0.010
100	52u	6.693	6.638	-0.055
	Max	6.693	6.663	0.030
	Average	6.640	6.624	-0.017
	Min	6.557	6.588	-0.055
	Std Dev	0.034	0.026	0.028



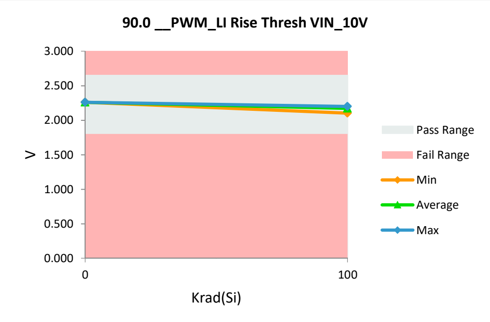
	75.1 __UVLO BOOT Fall Thresh	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7	V
Min Limit	6.2	V
Krad(Si)	0	100
LL	6.200	6.200
Min	6.633	6.588
Average	6.640	6.621
Max	6.648	6.663
UL	7.000	7.000



TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

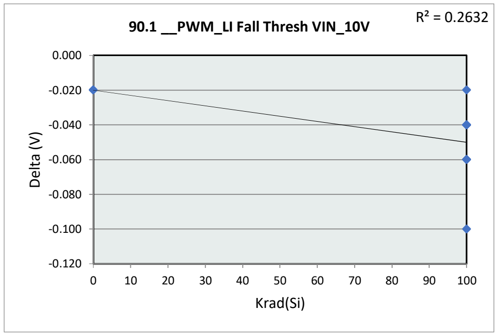
		90.0 __PWM_LI Rise Thresh VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	2.65	2.65	
	Min Limit	1.8	1.8	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.260	2.260	0.000
0	2	2.260	2.260	0.000
100	23	2.260	2.180	-0.080
100	24	2.260	2.180	-0.080
100	25	2.260	2.180	-0.080
100	26	2.240	2.200	-0.040
100	27	2.260	2.180	-0.080
100	48u	2.260	2.160	-0.100
100	49u	2.260	2.180	-0.080
100	50u	2.260	2.180	-0.080
100	51u	2.260	2.160	-0.100
100	52u	2.240	2.100	-0.140
	Max	2.260	2.260	0.000
	Average	2.257	2.185	-0.072
	Min	2.240	2.100	-0.140
	Std Dev	0.008	0.043	0.040

	90.0 __PWM_LI Rise Thresh VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.65	V
Min Limit	1.8	V
Krad(Si)	0	100
LL	1.800	1.800
Min	2.260	2.100
Average	2.260	2.170
Max	2.260	2.200
UL	2.650	2.650

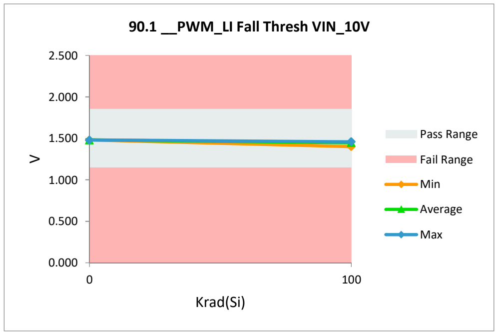


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		90.1 __PWM_LI Fall Thresh VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		1.85	1.85	
Min Limit		1.15	1.15	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.500	1.480	-0.020
0	2	1.500	1.480	-0.020
100	23	1.500	1.460	-0.040
100	24	1.500	1.460	-0.040
100	25	1.500	1.460	-0.040
100	26	1.480	1.460	-0.020
100	27	1.500	1.460	-0.040
100	48u	1.500	1.440	-0.060
100	49u	1.500	1.440	-0.060
100	50u	1.500	1.440	-0.060
100	51u	1.480	1.440	-0.040
100	52u	1.500	1.400	-0.100
	Max	1.500	1.480	-0.020
	Average	1.497	1.452	-0.045
	Min	1.480	1.400	-0.100
	Std Dev	0.008	0.022	0.023

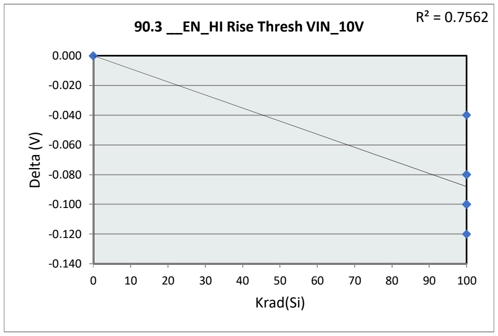


	90.1 __PWM_LI Fall Thresh VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.85	V
Min Limit	1.15	V
Krad(Si)	0	100
LL	1.150	1.150
Min	1.480	1.400
Average	1.480	1.446
Max	1.480	1.460
UL	1.850	1.850

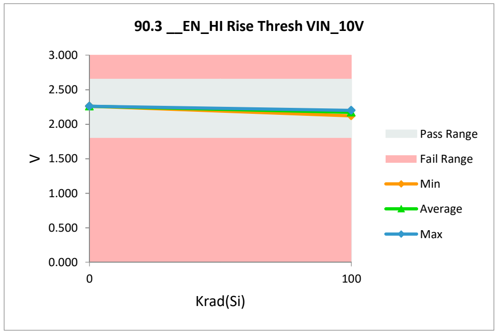


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		90.3 __EN_HI Rise Thresh VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		2.65	2.65	
Min Limit		1.8	1.8	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.260	2.260	0.000
0	2	2.260	2.260	0.000
100	23	2.260	2.180	-0.080
100	24	2.260	2.180	-0.080
100	25	2.260	2.180	-0.080
100	26	2.240	2.200	-0.040
100	27	2.260	2.160	-0.100
100	48u	2.260	2.160	-0.100
100	49u	2.260	2.180	-0.080
100	50u	2.280	2.180	-0.100
100	51u	2.260	2.160	-0.100
100	52u	2.240	2.120	-0.120
	Max	2.280	2.260	0.000
	Average	2.258	2.185	-0.073
	Min	2.240	2.120	-0.120
	Std Dev	0.010	0.040	0.039

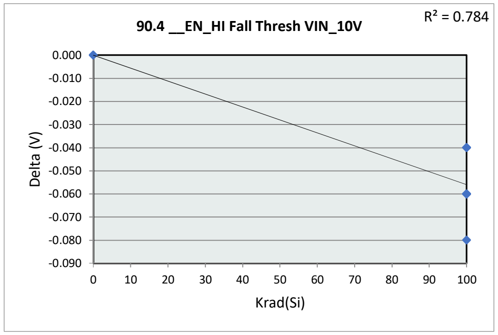


	90.3 __EN_HI Rise Thresh VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.65	V
Min Limit	1.8	V
Krad(Si)	0	100
LL	1.800	1.800
Min	2.260	2.120
Average	2.260	2.170
Max	2.260	2.200
UL	2.650	2.650

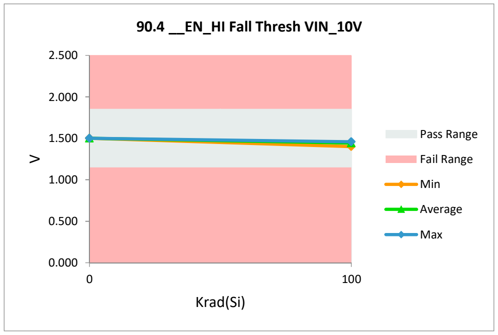


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		90.4 __EN_HI Fall Thresh VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		1.85	1.85	
Min Limit		1.15	1.15	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.500	1.500	0.000
0	2	1.500	1.500	0.000
100	23	1.500	1.440	-0.060
100	24	1.500	1.440	-0.060
100	25	1.500	1.460	-0.040
100	26	1.500	1.460	-0.040
100	27	1.500	1.440	-0.060
100	48u	1.500	1.440	-0.060
100	49u	1.500	1.460	-0.040
100	50u	1.500	1.440	-0.060
100	51u	1.500	1.440	-0.060
100	52u	1.480	1.400	-0.080
	Max	1.500	1.500	0.000
	Average	1.498	1.452	-0.047
	Min	1.480	1.400	-0.080
	Std Dev	0.006	0.028	0.025

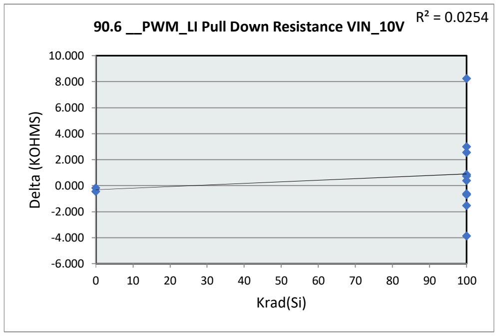


	90.4 __EN_HI Fall Thresh VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.85	V
Min Limit	1.15	V
Krad(Si)	0	100
LL	1.150	1.150
Min	1.500	1.400
Average	1.500	1.442
Max	1.500	1.460
UL	1.850	1.850

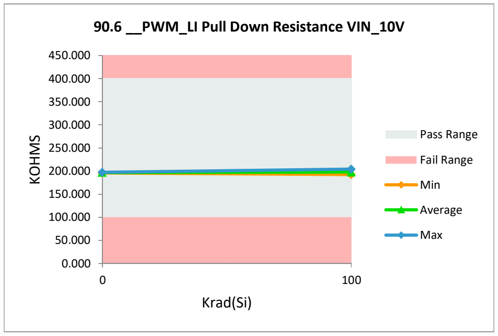


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		90.6 __PWM_LI Pull Down Resis		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		KOHMS	KOHMS	
Max Limit		400	400	
Min Limit		100	100	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	197.680	197.515	-0.166
0	2	196.427	195.977	-0.451
100	23	196.178	204.428	8.249
100	24	193.983	196.539	2.556
100	25	196.510	192.640	-3.870
100	26	195.693	194.154	-1.539
100	27	198.073	201.084	3.012
100	48u	201.100	201.959	0.859
100	49u	198.697	199.443	0.746
100	50u	195.764	195.063	-0.701
100	51u	196.685	196.073	-0.612
100	52u	195.240	195.642	0.402
	Max	201.100	204.428	8.249
	Average	196.836	197.543	0.707
	Min	193.983	192.640	-3.870
	Std Dev	1.853	3.490	2.978

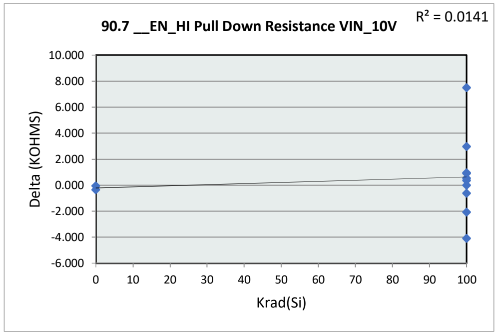


	90.6 __PWM_LI Pull Down Resistance VIN_	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	400	KOHMS
Min Limit	100	KOHMS
Krad(Si)	0	100
LL	100.000	100.000
Min	195.977	192.640
Average	196.746	197.703
Max	197.515	204.428
UL	400.000	400.000

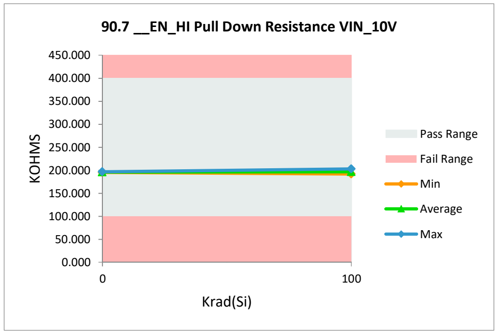


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		90.7 __EN_HI Pull Down Resista		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		KOHMS	KOHMS	
Max Limit		400	400	
Min Limit		100	100	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	196.734	196.676	-0.058
0	2	195.529	195.160	-0.370
100	23	195.550	203.052	7.502
100	24	193.495	196.470	2.975
100	25	195.996	191.908	-4.088
100	26	195.063	192.984	-2.079
100	27	199.004	199.940	0.936
100	48u	199.724	200.625	0.900
100	49u	197.805	198.341	0.535
100	50u	195.148	194.508	-0.640
100	51u	195.576	195.567	-0.009
100	52u	194.675	195.024	0.350
	Max	199.724	203.052	7.502
	Average	196.192	196.688	0.496
	Min	193.495	191.908	-4.088
	Std Dev	1.821	3.262	2.794



	90.7 __EN_HI Pull Down Resistance VIN_10	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	400	KOHMS
Min Limit	100	KOHMS
Krad(Si)	0	100
LL	100.000	100.000
Min	195.160	191.908
Average	195.918	196.842
Max	196.676	203.052
UL	400.000	400.000



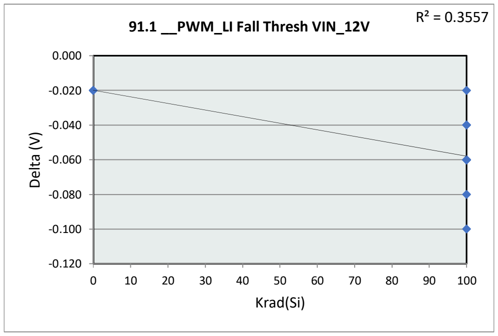
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		91.0 __PWM_LI Rise Thresh VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	2.65	2.65	
	Min Limit	1.8	1.8	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.260	2.260	0.000
0	2	2.260	2.260	0.000
100	23	2.240	2.180	-0.060
100	24	2.260	2.180	-0.080
100	25	2.260	2.180	-0.080
100	26	2.240	2.200	-0.040
100	27	2.260	2.180	-0.080
100	48u	2.260	2.160	-0.100
100	49u	2.260	2.180	-0.080
100	50u	2.260	2.180	-0.080
100	51u	2.260	2.160	-0.100
100	52u	2.240	2.100	-0.140
	Max	2.260	2.260	0.000
	Average	2.255	2.185	-0.070
	Min	2.240	2.100	-0.140
	Std Dev	0.009	0.043	0.040

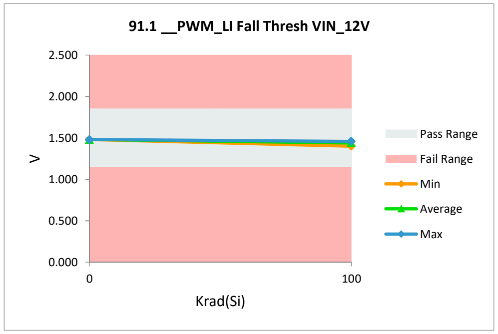
	91.0 __PWM_LI Rise Thresh VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.65	V
Min Limit	1.8	V
Krad(Si)	0	100
LL	1.800	1.800
Min	2.260	2.100
Average	2.260	2.170
Max	2.260	2.200
UL	2.650	2.650

TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		91.1 __PWM_LI Fall Thresh VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		1.85	1.85	
Min Limit		1.15	1.15	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.500	1.480	-0.020
0	2	1.500	1.480	-0.020
100	23	1.500	1.440	-0.060
100	24	1.500	1.440	-0.060
100	25	1.500	1.460	-0.040
100	26	1.480	1.460	-0.020
100	27	1.500	1.460	-0.040
100	48u	1.500	1.440	-0.060
100	49u	1.500	1.440	-0.060
100	50u	1.500	1.440	-0.060
100	51u	1.500	1.420	-0.080
100	52u	1.500	1.400	-0.100
	Max	1.500	1.480	-0.020
	Average	1.498	1.447	-0.052
	Min	1.480	1.400	-0.100
	Std Dev	0.006	0.023	0.025

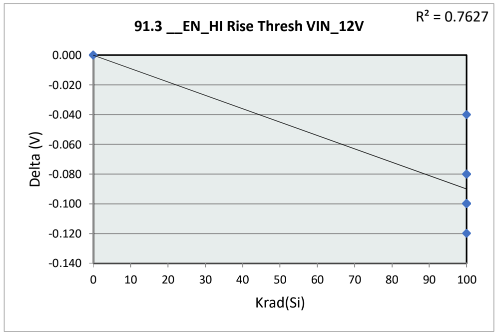


	91.1 __PWM_LI Fall Thresh VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.85	V
Min Limit	1.15	V
Krad(Si)	0	100
LL	1.150	1.150
Min	1.480	1.400
Average	1.480	1.440
Max	1.480	1.460
UL	1.850	1.850

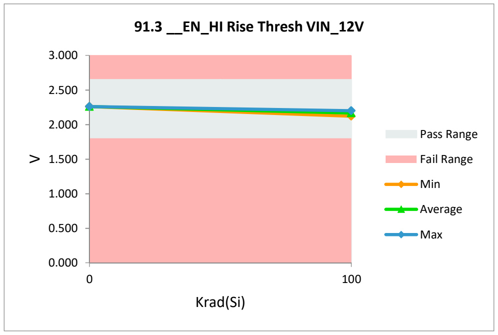


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		91.3 __EN_HI Rise Thresh VIN_		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		2.65	2.65	
Min Limit		1.8	1.8	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.260	2.260	0.000
0	2	2.260	2.260	0.000
100	23	2.260	2.160	-0.100
100	24	2.260	2.180	-0.080
100	25	2.260	2.180	-0.080
100	26	2.240	2.200	-0.040
100	27	2.260	2.160	-0.100
100	48u	2.260	2.160	-0.100
100	49u	2.260	2.180	-0.080
100	50u	2.280	2.180	-0.100
100	51u	2.260	2.160	-0.100
100	52u	2.240	2.120	-0.120
	Max	2.280	2.260	0.000
	Average	2.258	2.183	-0.075
	Min	2.240	2.120	-0.120
	Std Dev	0.010	0.041	0.040

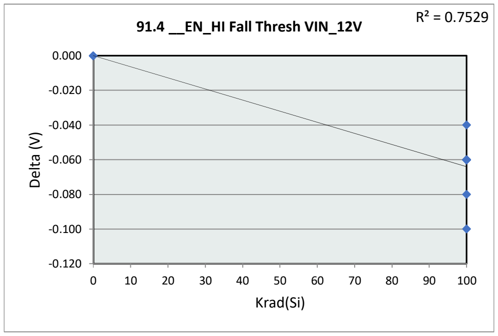


	91.3 __EN_HI Rise Thresh VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.65	V
Min Limit	1.8	V
Krad(Si)	0	100
LL	1.800	1.800
Min	2.260	2.120
Average	2.260	2.168
Max	2.260	2.200
UL	2.650	2.650

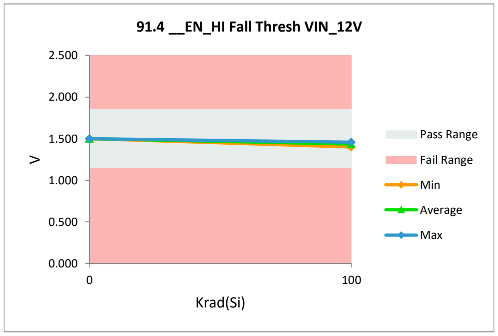


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		91.4 __EN_HI Fall Thresh VIN_1		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	1.85	1.85	
	Min Limit	1.15	1.15	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.500	1.500	0.000
0	2	1.500	1.500	0.000
100	23	1.500	1.440	-0.060
100	24	1.500	1.440	-0.060
100	25	1.500	1.440	-0.060
100	26	1.500	1.460	-0.040
100	27	1.500	1.440	-0.060
100	48u	1.500	1.440	-0.060
100	49u	1.500	1.440	-0.060
100	50u	1.500	1.440	-0.060
100	51u	1.500	1.420	-0.080
100	52u	1.500	1.400	-0.100
	Max	1.500	1.500	0.000
	Average	1.500	1.447	-0.053
	Min	1.500	1.400	-0.100
	Std Dev	0.000	0.029	0.029

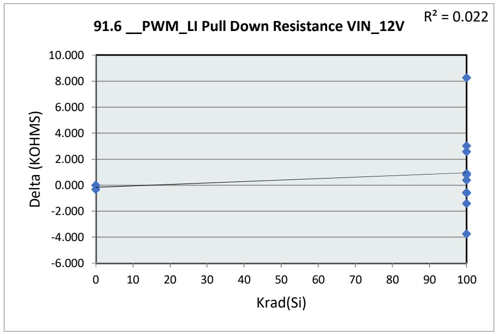


	91.4 __EN_HI Fall Thresh VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.85	V
Min Limit	1.15	V
Krad(Si)	0	100
LL	1.150	1.150
Min	1.500	1.400
Average	1.500	1.436
Max	1.500	1.460
UL	1.850	1.850

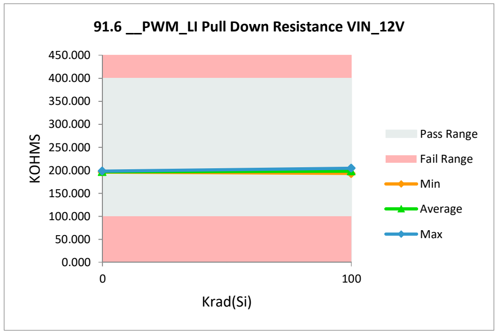


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		91.6 __PWM_LI Pull Down Resis		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		KOHMS	KOHMS	
Max Limit		400	400	
Min Limit		100	100	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	197.728	197.721	-0.007
0	2	196.484	196.160	-0.324
100	23	196.249	204.513	8.264
100	24	194.040	196.618	2.578
100	25	196.566	192.810	-3.756
100	26	195.767	194.349	-1.417
100	27	198.150	201.173	3.024
100	48u	201.151	202.036	0.885
100	49u	198.754	199.542	0.788
100	50u	195.819	195.242	-0.577
100	51u	196.746	196.132	-0.614
100	52u	195.305	195.696	0.391
	Max	201.151	204.513	8.264
	Average	196.897	197.666	0.770
	Min	194.040	192.810	-3.756
	Std Dev	1.850	3.462	2.946



	91.6 __PWM_LI Pull Down Resistance VIN_	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	400	KOHMS
Min Limit	100	KOHMS
Krad(Si)	0	100
LL	100.000	100.000
Min	196.160	192.810
Average	196.941	197.811
Max	197.722	204.513
UL	400.000	400.000



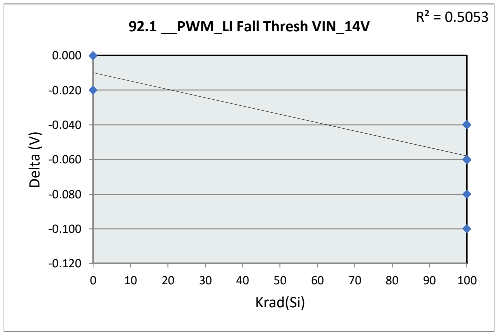
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		92.0 __PWM_LI Rise Thresh VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		2.65	2.65	
Min Limit		1.8	1.8	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.260	2.260	0.000
0	2	2.260	2.260	0.000
100	23	2.260	2.180	-0.080
100	24	2.260	2.180	-0.080
100	25	2.260	2.180	-0.080
100	26	2.240	2.200	-0.040
100	27	2.260	2.180	-0.080
100	48u	2.260	2.160	-0.100
100	49u	2.260	2.180	-0.080
100	50u	2.280	2.180	-0.100
100	51u	2.260	2.160	-0.100
100	52u	2.240	2.100	-0.140
	Max	2.280	2.260	0.000
	Average	2.258	2.185	-0.073
	Min	2.240	2.100	-0.140
	Std Dev	0.010	0.043	0.041

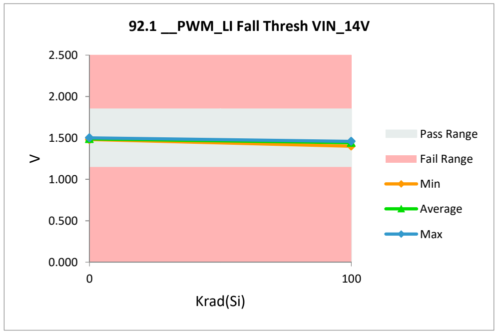
	92.0 __PWM_LI Rise Thresh VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.65	V
Min Limit	1.8	V
Krad(Si)	0	100
LL	1.800	1.800
Min	2.260	2.100
Average	2.260	2.170
Max	2.260	2.200
UL	2.650	2.650

TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		92.1 __PWM_LI Fall Thresh VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	1.85	1.85	
	Min Limit	1.15	1.15	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.500	1.480	-0.020
0	2	1.500	1.500	0.000
100	23	1.500	1.460	-0.040
100	24	1.500	1.440	-0.060
100	25	1.500	1.460	-0.040
100	26	1.500	1.460	-0.040
100	27	1.500	1.460	-0.040
100	48u	1.500	1.440	-0.060
100	49u	1.500	1.440	-0.060
100	50u	1.500	1.440	-0.060
100	51u	1.500	1.420	-0.080
100	52u	1.500	1.400	-0.100
	Max	1.500	1.500	0.000
	Average	1.500	1.450	-0.050
	Min	1.500	1.400	-0.100
	Std Dev	0.000	0.026	0.026

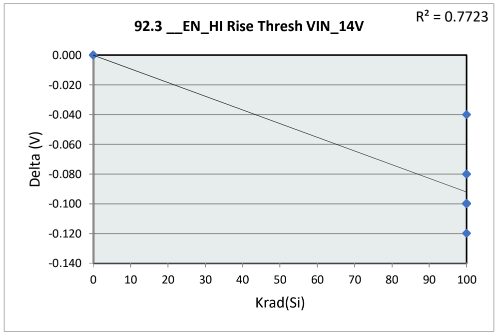


	92.1 __PWM_LI Fall Thresh VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.85	V
Min Limit	1.15	V
Krad(Si)	0	100
LL	1.150	1.150
Min	1.480	1.400
Average	1.490	1.442
Max	1.500	1.460
UL	1.850	1.850

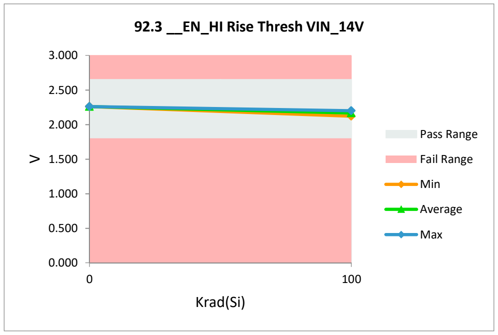


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		92.3 __EN_HI Rise Thresh VIN_		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		2.65	2.65	
Min Limit		1.8	1.8	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.260	2.260	0.000
0	2	2.260	2.260	0.000
100	23	2.260	2.160	-0.100
100	24	2.260	2.180	-0.080
100	25	2.260	2.180	-0.080
100	26	2.240	2.200	-0.040
100	27	2.260	2.160	-0.100
100	48u	2.260	2.160	-0.100
100	49u	2.280	2.180	-0.100
100	50u	2.280	2.180	-0.100
100	51u	2.260	2.160	-0.100
100	52u	2.240	2.120	-0.120
	Max	2.280	2.260	0.000
	Average	2.260	2.183	-0.077
	Min	2.240	2.120	-0.120
	Std Dev	0.012	0.041	0.041

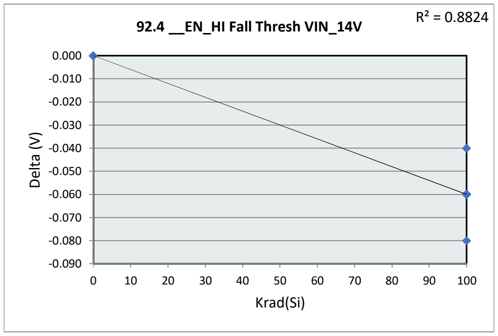


	92.3 __EN_HI Rise Thresh VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.65	V
Min Limit	1.8	V
Krad(Si)	0	100
LL	1.800	1.800
Min	2.260	2.120
Average	2.260	2.168
Max	2.260	2.200
UL	2.650	2.650

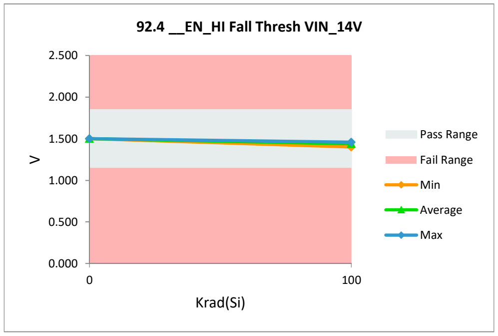


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		92.4 __EN_HI Fall Thresh VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		1.85	1.85	
Min Limit		1.15	1.15	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.500	1.500	0.000
0	2	1.500	1.500	0.000
100	23	1.500	1.440	-0.060
100	24	1.500	1.440	-0.060
100	25	1.500	1.440	-0.060
100	26	1.500	1.460	-0.040
100	27	1.500	1.440	-0.060
100	48u	1.500	1.440	-0.060
100	49u	1.500	1.440	-0.060
100	50u	1.500	1.440	-0.060
100	51u	1.500	1.440	-0.060
100	52u	1.480	1.400	-0.080
	Max	1.500	1.500	0.000
	Average	1.498	1.448	-0.050
	Min	1.480	1.400	-0.080
	Std Dev	0.006	0.028	0.025

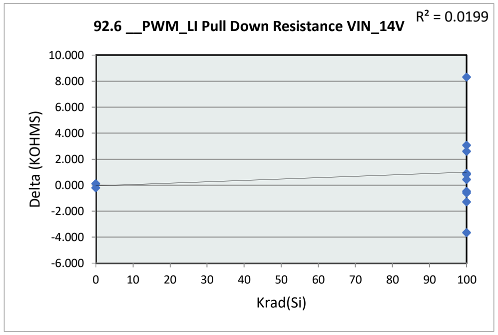


	92.4 __EN_HI Fall Thresh VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.85	V
Min Limit	1.15	V
Krad(Si)	0	100
LL	1.150	1.150
Min	1.500	1.400
Average	1.500	1.438
Max	1.500	1.460
UL	1.850	1.850

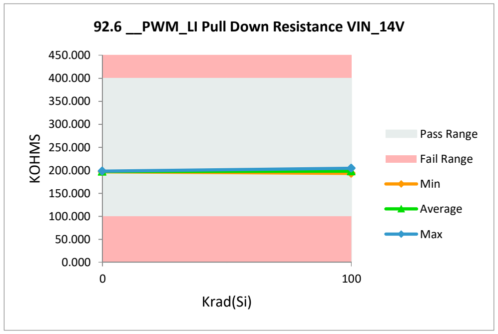


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		92.6 __PWM_LI Pull Down Resis		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	KOHMS	KOHMS	
	Max Limit	400	400	
	Min Limit	100	100	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	197.791	197.894	0.103
0	2	196.529	196.317	-0.212
100	23	196.275	204.566	8.291
100	24	194.077	196.678	2.600
100	25	196.617	192.969	-3.647
100	26	195.816	194.517	-1.299
100	27	198.177	201.247	3.069
100	48u	201.196	202.081	0.885
100	49u	198.808	199.621	0.813
100	50u	195.876	195.406	-0.470
100	51u	196.810	196.200	-0.609
100	52u	195.329	195.755	0.426
	Max	201.196	204.566	8.291
	Average	196.942	197.771	0.829
	Min	194.077	192.969	-3.647
	Std Dev	1.853	3.429	2.922

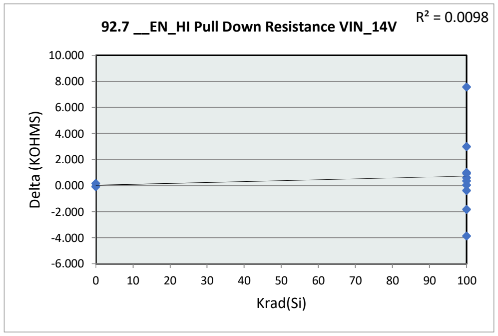


	92.6 __PWM_LI Pull Down Resistance VIN_	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	400	KOHMS
Min Limit	100	KOHMS
Krad(Si)	0	100
LL	100.000	100.000
Min	196.317	192.969
Average	197.106	197.904
Max	197.894	204.566
UL	400.000	400.000

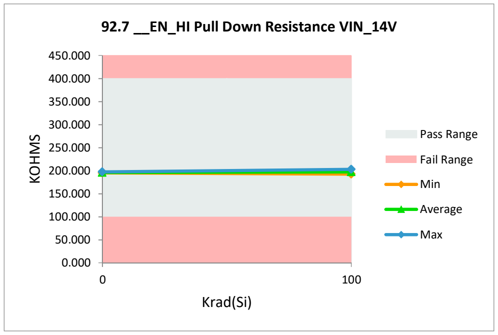


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		92.7 __EN_HI Pull Down Resista		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	KOHMS	KOHMS	
	Max Limit	400	400	
	Min Limit	100	100	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	196.848	197.016	0.168
0	2	195.619	195.523	-0.097
100	23	195.651	203.206	7.555
100	24	193.620	196.601	2.982
100	25	196.121	192.239	-3.882
100	26	195.178	193.355	-1.824
100	27	199.107	200.095	0.988
100	48u	199.809	200.726	0.917
100	49u	197.936	198.539	0.602
100	50u	195.268	194.877	-0.392
100	51u	195.684	195.708	0.024
100	52u	194.768	195.128	0.360
	Max	199.809	203.206	7.555
	Average	196.301	196.918	0.617
	Min	193.620	192.239	-3.882
	Std Dev	1.817	3.194	2.735

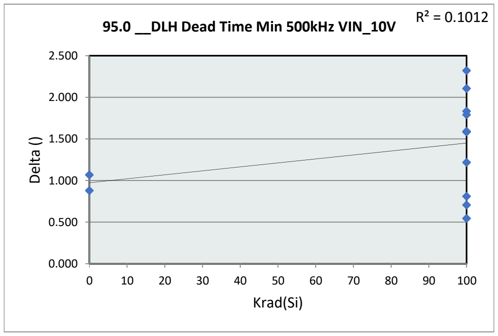


	92.7 __EN_HI Pull Down Resistance VIN_14	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	400	KOHMS
Min Limit	100	KOHMS
Krad(Si)	0	100
LL	100.000	100.000
Min	195.523	192.239
Average	196.270	197.047
Max	197.016	203.206
UL	400.000	400.000

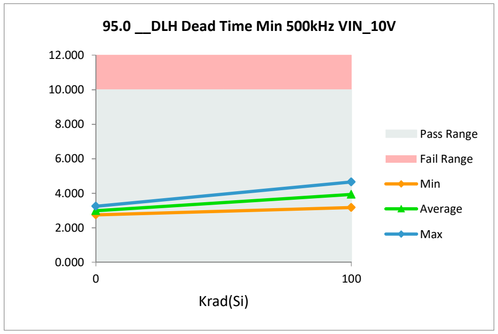


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.0 __DLH Dead Time Min 500k		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	10	10	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.356	3.236	0.880
0	2	1.668	2.738	1.070
100	23	2.944	3.651	0.707
100	24	3.407	3.950	0.543
100	25	2.452	4.287	1.835
100	26	1.992	3.585	1.592
100	27	2.542	4.650	2.107
100	48u	2.411	3.995	1.584
100	49u	2.358	3.167	0.809
100	50u	2.349	4.139	1.790
100	51u	2.504	3.721	1.217
100	52u	1.902	4.222	2.321
	Max	3.407	4.650	2.321
	Average	2.407	3.778	1.371
	Min	1.668	2.738	0.543
	Std Dev	0.457	0.542	0.582

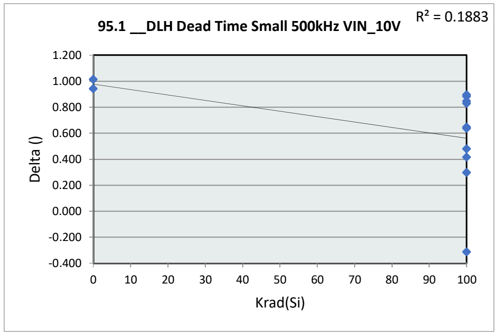


	95.0 __DLH Dead Time Min 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	2.738	3.167
Average	2.987	3.937
Max	3.236	4.650
UL	10.000	10.000

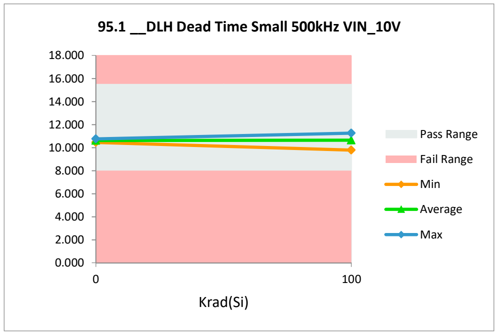


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.1 __DLH Dead Time Small 50		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	15.5	15.5	
	Min Limit	8	8	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	9.813	10.755	0.943
0	2	9.433	10.446	1.013
100	23	10.075	10.490	0.414
100	24	10.578	10.876	0.298
100	25	10.104	10.932	0.828
100	26	9.740	10.387	0.647
100	27	10.381	11.264	0.883
100	48u	10.106	10.584	0.479
100	49u	10.099	9.786	-0.313
100	50u	10.016	10.862	0.847
100	51u	10.014	10.651	0.637
100	52u	9.738	10.633	0.895
	Max	10.578	11.264	1.013
	Average	10.008	10.639	0.631
	Min	9.433	9.786	-0.313
	Std Dev	0.303	0.363	0.373

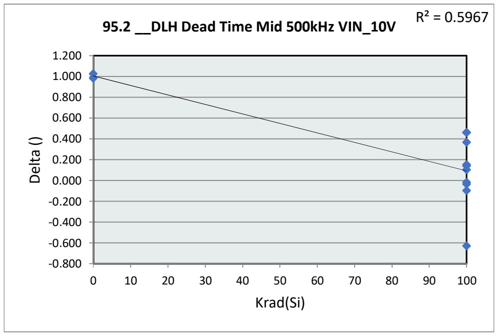


	95.1 __DLH Dead Time Small 500kHz VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.446	9.786
Average	10.601	10.647
Max	10.755	11.264
UL	15.500	15.500

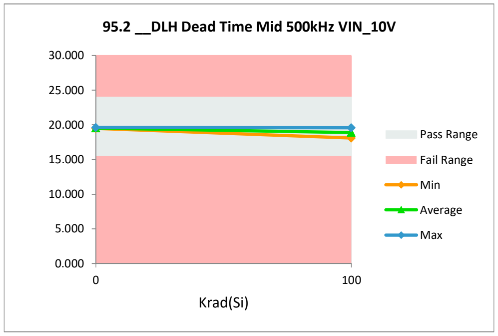


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.2 __DLH Dead Time Mid 500k		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	24	24	
	Min Limit	15.5	15.5	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.581	19.606	1.025
0	2	18.521	19.505	0.984
100	23	18.282	18.743	0.461
100	24	18.861	19.015	0.154
100	25	19.112	19.096	-0.015
100	26	18.662	18.767	0.104
100	27	19.136	19.601	0.464
100	48u	18.721	18.624	-0.097
100	49u	18.734	18.107	-0.627
100	50u	18.695	19.063	0.368
100	51u	19.063	19.202	0.139
100	52u	18.913	18.879	-0.035
	Max	19.136	19.606	1.025
	Average	18.773	19.017	0.244
	Min	18.282	18.107	-0.627
	Std Dev	0.256	0.438	0.460

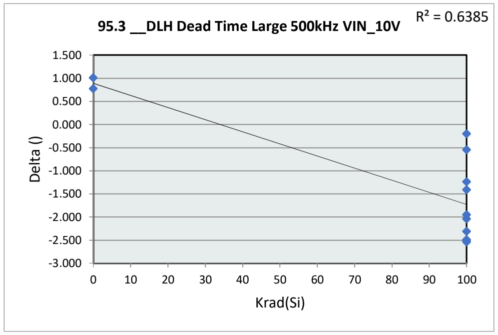


	95.2 __DLH Dead Time Mid 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	19.505	18.107
Average	19.555	18.910
Max	19.606	19.601
UL	24.000	24.000

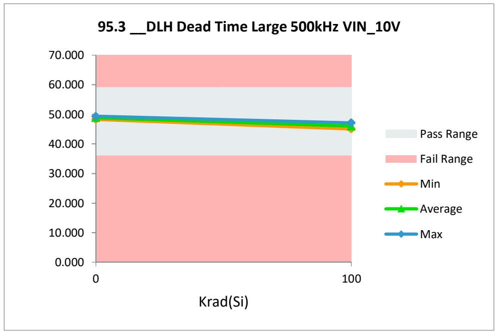


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.3 __DLH Dead Time Large 50		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	59	59	
	Min Limit	36	36	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	47.520	48.292	0.772
0	2	48.312	49.321	1.009
100	23	45.560	45.356	-0.204
100	24	46.424	45.878	-0.546
100	25	48.523	45.993	-2.530
100	26	48.461	46.151	-2.310
100	27	48.294	46.882	-1.413
100	48u	47.391	45.350	-2.041
100	49u	47.605	45.062	-2.543
100	50u	47.677	45.725	-1.951
100	51u	48.352	47.111	-1.242
100	52u	48.730	46.235	-2.495
	Max	48.730	49.321	1.009
	Average	47.737	46.446	-1.291
	Min	45.560	45.062	-2.543
	Std Dev	0.944	1.272	1.275

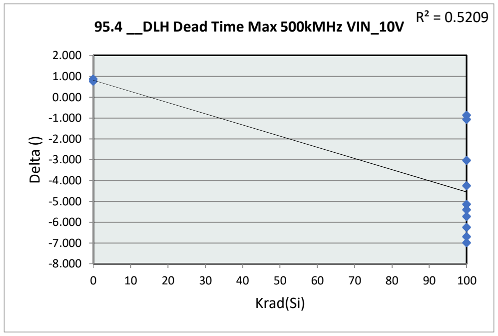


	95.3 __DLH Dead Time Large 500kHz VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	48.292	45.062
Average	48.806	45.974
Max	49.321	47.111
UL	59.000	59.000

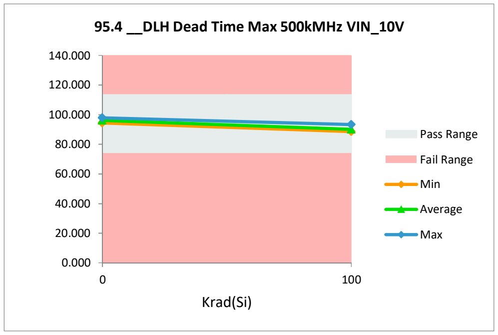


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.4 __DLH Dead Time Max 500k		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	113.5	113.5	
	Min Limit	74	74	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	93.582	94.444	0.862
0	2	97.197	97.955	0.758
100	23	89.442	88.571	-0.872
100	24	91.022	89.950	-1.073
100	25	96.344	90.090	-6.255
100	26	96.950	90.239	-6.711
100	27	95.330	91.072	-4.258
100	48u	94.143	88.732	-5.411
100	49u	94.795	89.054	-5.741
100	50u	94.306	89.150	-5.156
100	51u	96.298	93.261	-3.037
100	52u	97.949	90.959	-6.989
	Max	97.949	97.955	0.862
	Average	94.780	91.123	-3.657
	Min	89.442	88.571	-6.989
	Std Dev	2.528	2.795	2.891

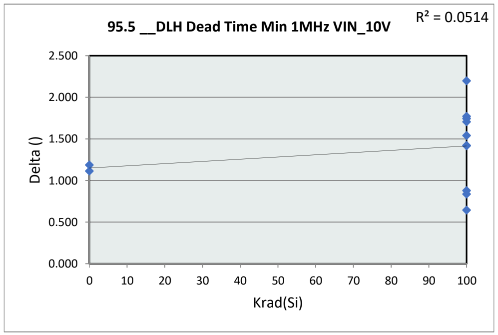


	95.4 __DLH Dead Time Max 500kMHz VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	94.444	88.571
Average	96.200	90.108
Max	97.955	93.261
UL	113.500	113.500

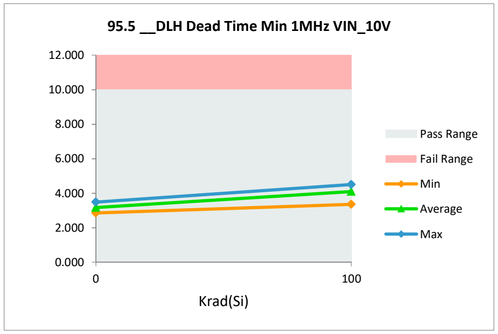


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.5 __DLH Dead Time Min 1MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.300	3.488	1.188
0	2	1.736	2.849	1.114
100	23	2.994	3.873	0.879
100	24	3.457	4.295	0.838
100	25	2.649	4.394	1.746
100	26	2.253	3.795	1.542
100	27	2.804	4.511	1.707
100	48u	2.691	4.109	1.419
100	49u	2.709	3.352	0.643
100	50u	2.527	4.298	1.771
100	51u	2.525	3.945	1.421
100	52u	2.141	4.337	2.197
	Max	3.457	4.511	2.197
	Average	2.565	3.937	1.372
	Min	1.736	2.849	0.643
	Std Dev	0.439	0.499	0.456

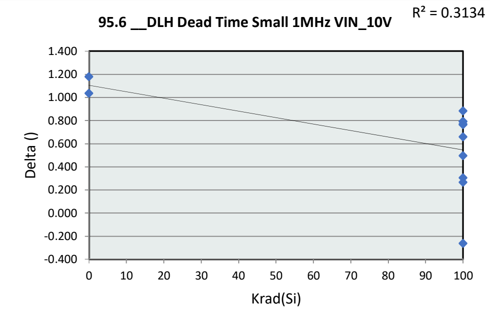


	95.5 __DLH Dead Time Min 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	2.849	3.352
Average	3.169	4.091
Max	3.488	4.511
UL	10.000	10.000

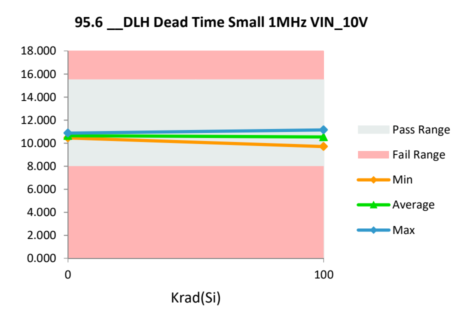


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.6 __DLH Dead Time Small 1M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		15.5	15.5	
Min Limit		8	8	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	9.691	10.868	1.178
0	2	9.401	10.434	1.034
100	23	10.034	10.300	0.266
100	24	10.283	10.778	0.494
100	25	10.114	10.774	0.659
100	26	9.561	10.351	0.790
100	27	10.273	11.155	0.882
100	48u	10.034	10.339	0.304
100	49u	9.964	9.701	-0.263
100	50u	9.956	10.720	0.764
100	51u	9.898	10.689	0.792
100	52u	9.716	10.484	0.768
	Max	10.283	11.155	1.178
	Average	9.910	10.549	0.639
	Min	9.401	9.701	-0.263
	Std Dev	0.272	0.370	0.390

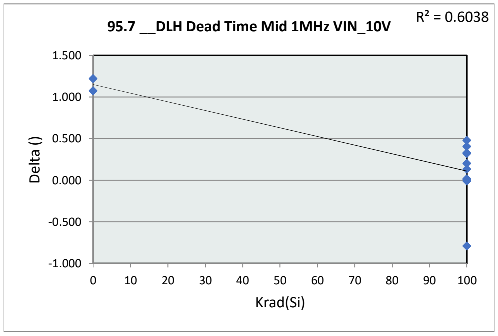


	95.6 __DLH Dead Time Small 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.434	9.701
Average	10.651	10.529
Max	10.868	11.155
UL	15.500	15.500

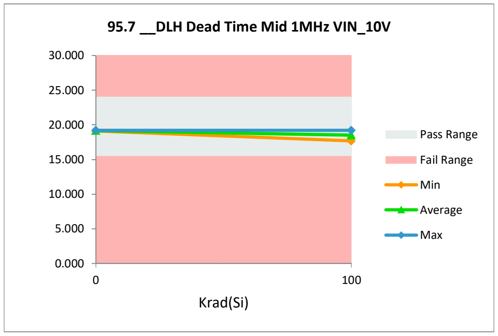


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.7 __DLH Dead Time Mid 1MHz		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	24	24	
	Min Limit	15.5	15.5	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	17.993	19.215	1.223
0	2	18.025	19.101	1.076
100	23	17.892	18.300	0.407
100	24	18.229	18.708	0.479
100	25	18.618	18.628	0.010
100	26	18.220	18.352	0.132
100	27	18.882	19.202	0.320
100	48u	18.430	18.422	-0.009
100	49u	18.487	17.696	-0.791
100	50u	18.443	18.646	0.204
100	51u	18.565	18.894	0.329
100	52u	18.396	18.414	0.018
	Max	18.882	19.215	1.223
	Average	18.348	18.632	0.283
	Min	17.892	17.696	-0.791
	Std Dev	0.288	0.439	0.521

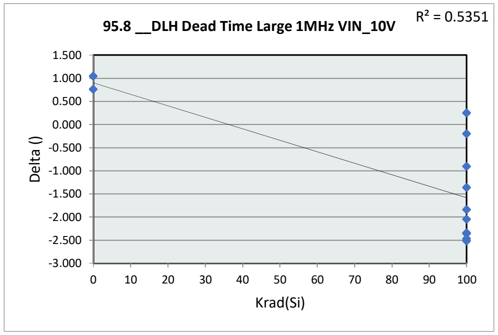


	95.7 __DLH Dead Time Mid 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	19.101	17.696
Average	19.158	18.526
Max	19.215	19.203
UL	24.000	24.000

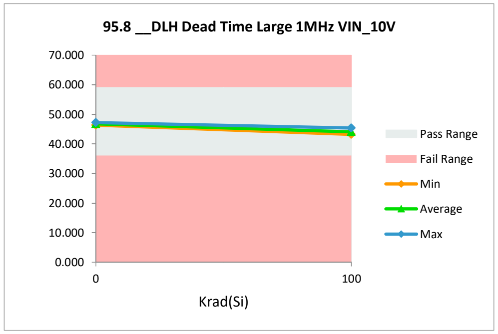


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.8 __DLH Dead Time Large 1M		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	59	59	
	Min Limit	36	36	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	45.620	46.379	0.759
0	2	46.210	47.253	1.044
100	23	43.327	43.572	0.245
100	24	44.369	44.165	-0.204
100	25	46.471	44.123	-2.347
100	26	46.412	44.054	-2.358
100	27	46.374	45.009	-1.365
100	48u	45.489	43.438	-2.051
100	49u	45.688	43.214	-2.474
100	50u	45.648	43.807	-1.840
100	51u	46.301	45.394	-0.907
100	52u	46.796	44.273	-2.523
	Max	46.796	47.253	1.044
	Average	45.725	44.557	-1.169
	Min	43.327	43.214	-2.523
	Std Dev	0.992	1.234	1.322

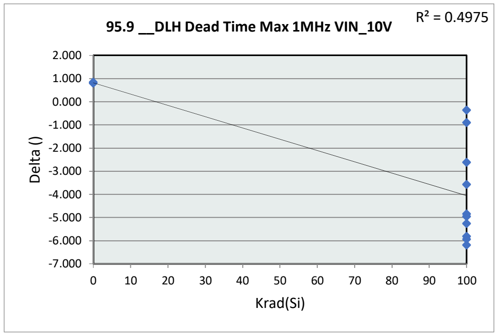


	95.8 __DLH Dead Time Large 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	46.379	43.214
Average	46.816	44.105
Max	47.253	45.394
UL	59.000	59.000

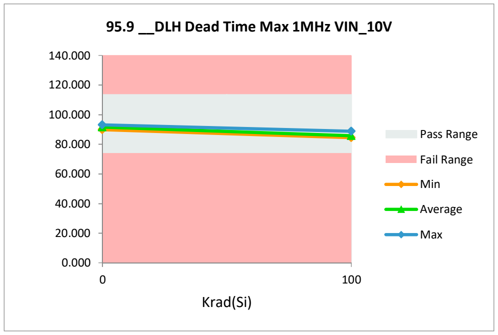


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.9 __DLH Dead Time Max 1MH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	113.5	113.5	
	Min Limit	74	74	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	89.098	89.939	0.841
0	2	92.386	93.183	0.797
100	23	84.904	84.542	-0.363
100	24	86.695	85.782	-0.912
100	25	91.745	85.925	-5.820
100	26	91.869	85.926	-5.943
100	27	90.618	87.037	-3.581
100	48u	89.444	84.486	-4.958
100	49u	89.915	84.642	-5.273
100	50u	89.598	84.743	-4.855
100	51u	91.497	88.869	-2.628
100	52u	93.076	86.884	-6.191
	Max	93.076	93.183	0.841
	Average	90.070	86.830	-3.240
	Min	84.904	84.486	-6.191
	Std Dev	2.382	2.643	2.688

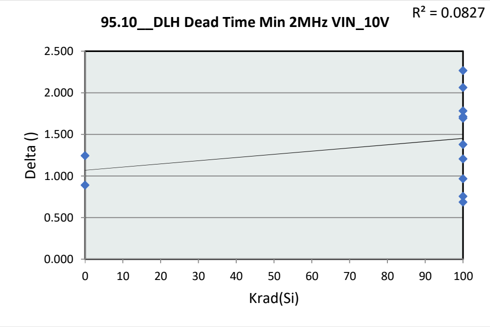


	95.9 __DLH Dead Time Max 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	89.939	84.486
Average	91.561	85.884
Max	93.183	88.869
UL	113.500	113.500

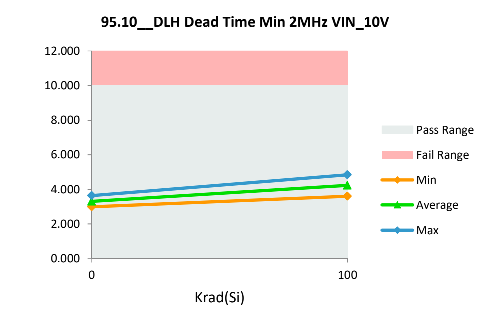


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.10__DLH Dead Time Min 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.383	3.630	1.247
0	2	2.085	2.978	0.892
100	23	3.265	4.022	0.757
100	24	3.609	4.297	0.688
100	25	2.651	4.432	1.781
100	26	2.247	3.940	1.693
100	27	2.768	4.834	2.066
100	48u	2.821	4.029	1.208
100	49u	2.626	3.594	0.968
100	50u	2.646	4.359	1.713
100	51u	2.690	4.071	1.381
100	52u	2.342	4.609	2.267
	Max	3.609	4.834	2.267
	Average	2.678	4.066	1.388
	Min	2.085	2.978	0.688
	Std Dev	0.424	0.502	0.518



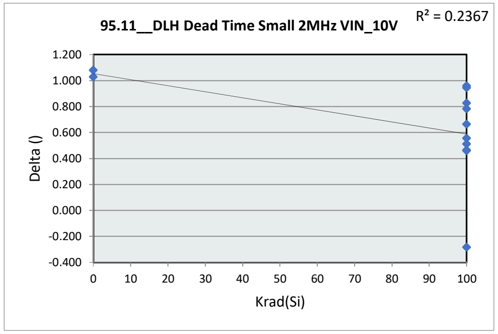
	95.10__DLH Dead Time Min 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	2.978	3.594
Average	3.304	4.219
Max	3.630	4.834
UL	10.000	10.000



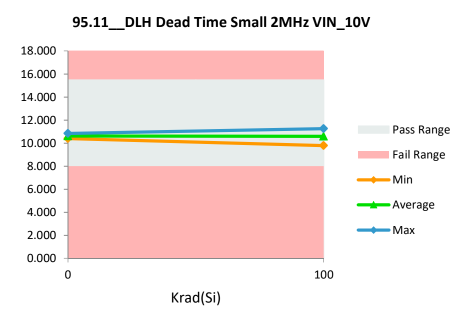
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	95.11__DLH Dead Time Small 2M	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	15.5	15.5
Min Limit	8	8

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	9.753	10.833	1.080
0	2	9.357	10.384	1.027
100	23	9.948	10.407	0.459
100	24	10.340	10.805	0.464
100	25	10.114	10.896	0.782
100	26	9.532	10.357	0.825
100	27	10.316	11.261	0.945
100	48u	9.934	10.444	0.510
100	49u	10.056	9.772	-0.284
100	50u	9.981	10.643	0.663
100	51u	9.951	10.508	0.556
100	52u	9.681	10.639	0.958
	Max	10.340	11.261	1.080
	Average	9.914	10.579	0.665
	Min	9.357	9.772	-0.284
	Std Dev	0.293	0.367	0.372

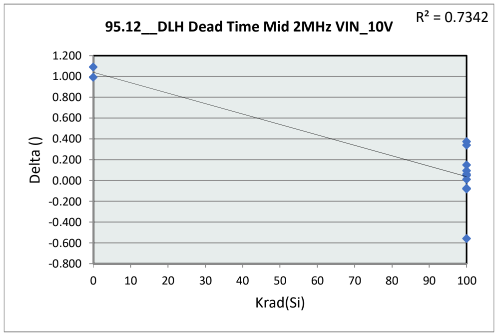


	95.11__DLH Dead Time Small 2MHz VIN_10	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.384	9.772
Average	10.608	10.573
Max	10.833	11.261
UL	15.500	15.500

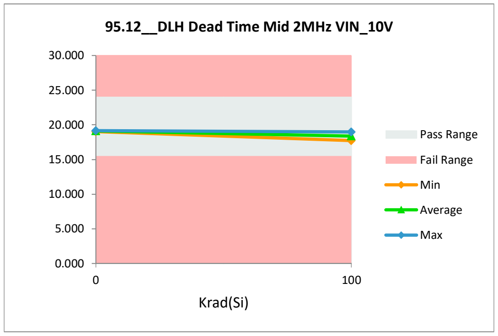


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.12__DLH Dead Time Mid 2MH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	24	24	
	Min Limit	15.5	15.5	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.051	19.043	0.992
0	2	18.076	19.165	1.090
100	23	17.764	18.138	0.373
100	24	18.427	18.437	0.010
100	25	18.427	18.575	0.148
100	26	18.269	18.188	-0.081
100	27	18.654	18.996	0.342
100	48u	18.183	18.278	0.095
100	49u	18.307	17.750	-0.558
100	50u	18.360	18.421	0.062
100	51u	18.547	18.595	0.049
100	52u	18.282	18.206	-0.076
	Max	18.654	19.165	1.090
	Average	18.279	18.483	0.204
	Min	17.764	17.750	-0.558
	Std Dev	0.240	0.419	0.456



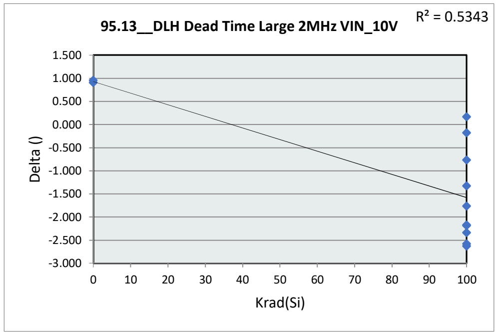
	95.12__DLH Dead Time Mid 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	19.043	17.750
Average	19.104	18.358
Max	19.165	18.996
UL	24.000	24.000



TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

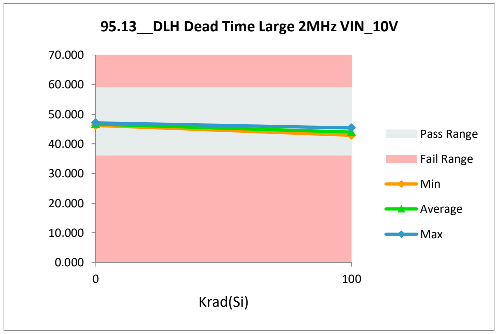
95.13__DLH Dead Time Large 2M

	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	59	59	
	Min Limit	36	36	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	45.322	46.228	0.905
0	2	46.138	47.093	0.955
100	23	43.381	43.542	0.161
100	24	44.106	43.923	-0.184
100	25	46.307	44.134	-2.173
100	26	46.175	43.988	-2.187
100	27	46.205	44.876	-1.329
100	48u	45.535	43.192	-2.344
100	49u	45.573	42.943	-2.630
100	50u	45.529	43.765	-1.764
100	51u	46.111	45.344	-0.768
100	52u	46.794	44.208	-2.586
	Max	46.794	47.093	0.955
	Average	45.598	44.436	-1.162
	Min	43.381	42.943	-2.630
	Std Dev	0.973	1.240	1.337



95.13__DLH Dead Time Large 2MHz VIN_10

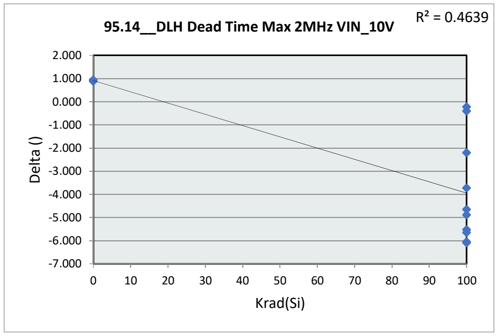
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	46.228	42.943
Average	46.661	43.991
Max	47.094	45.344
UL	59.000	59.000



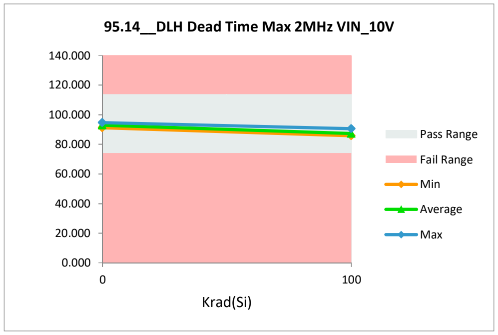
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	95.14__DLH Dead Time Max 2MH	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	113.5	113.5
Min Limit	74	74

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	90.349	91.287	0.938
0	2	93.761	94.644	0.883
100	23	85.967	85.742	-0.225
100	24	87.640	87.238	-0.401
100	25	93.028	87.374	-5.654
100	26	93.347	87.245	-6.101
100	27	92.036	88.311	-3.725
100	48u	90.663	85.772	-4.891
100	49u	91.391	85.868	-5.524
100	50u	90.868	86.216	-4.652
100	51u	92.766	90.559	-2.207
100	52u	94.466	88.410	-6.056
	Max	94.466	94.644	0.938
	Average	91.357	88.222	-3.135
	Min	85.967	85.742	-6.101
	Std Dev	2.509	2.705	2.774

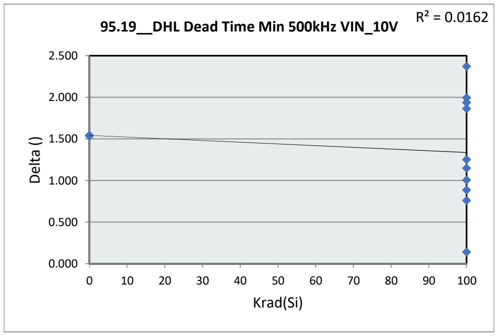


	95.14__DLH Dead Time Max 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	91.287	85.742
Average	92.965	87.274
Max	94.644	90.559
UL	113.500	113.500

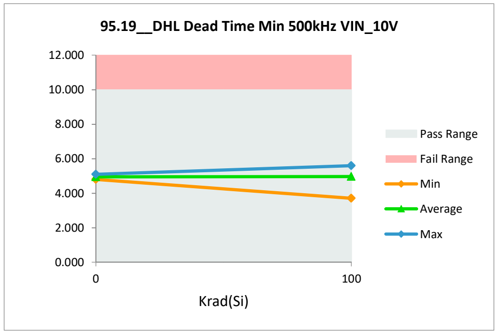


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.19__DHL Dead Time Min 500		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.257	4.795	1.538
0	2	3.540	5.087	1.547
100	23	3.126	5.063	1.938
100	24	3.059	5.431	2.372
100	25	3.806	4.813	1.007
100	26	3.914	4.800	0.887
100	27	3.849	5.102	1.253
100	48u	3.510	5.374	1.864
100	49u	3.569	3.712	0.143
100	50u	3.521	4.670	1.149
100	51u	3.602	5.597	1.995
100	52u	4.378	5.137	0.759
	Max	4.378	5.597	2.372
	Average	3.594	4.965	1.371
	Min	3.059	3.712	0.143
	Std Dev	0.364	0.486	0.627

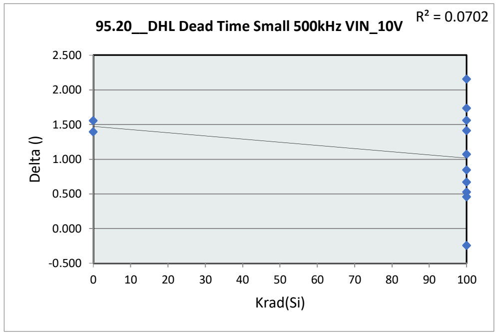


	95.19__DHL Dead Time Min 500kHz VIN_10	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.795	3.712
Average	4.941	4.970
Max	5.087	5.598
UL	10.000	10.000

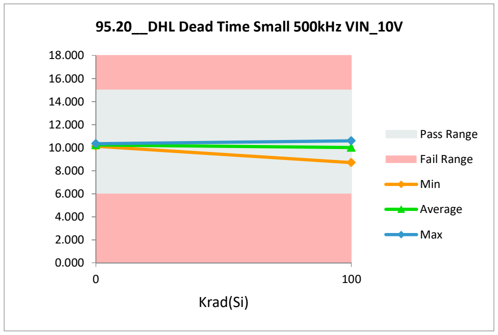


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.20__DHL Dead Time Small 50		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		15	15	
Min Limit		6	6	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	8.726	10.119	1.392
0	2	8.780	10.332	1.552
100	23	8.547	10.105	1.558
100	24	8.409	10.561	2.153
100	25	9.300	9.970	0.670
100	26	9.233	9.757	0.525
100	27	9.196	10.266	1.071
100	48u	9.178	10.589	1.410
100	49u	8.939	8.694	-0.245
100	50u	8.840	9.684	0.844
100	51u	8.797	10.530	1.733
100	52u	9.469	9.923	0.454
	Max	9.469	10.589	2.153
	Average	8.951	10.044	1.093
	Min	8.409	8.694	-0.245
	Std Dev	0.324	0.522	0.668

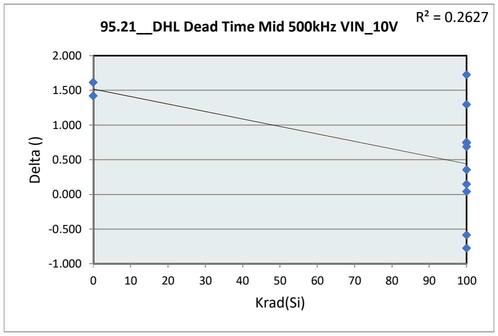


95.20__DHL Dead Time Small 500kHz VIN_1		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.119	8.694
Average	10.225	10.008
Max	10.332	10.589
UL	15.000	15.000

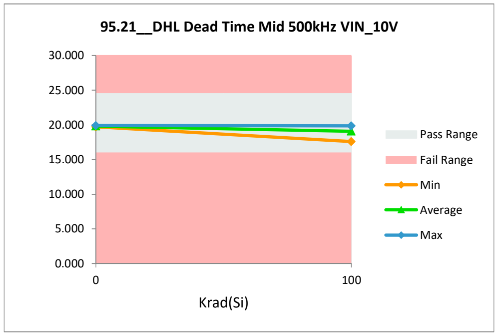


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.21__DHL Dead Time Mid 500		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24.5	24.5	
Min Limit		16	16	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.306	19.923	1.616
0	2	18.280	19.700	1.420
100	23	18.200	19.497	1.297
100	24	18.044	19.771	1.727
100	25	18.973	19.013	0.040
100	26	18.571	18.927	0.356
100	27	18.882	19.635	0.753
100	48u	19.189	19.878	0.689
100	49u	18.348	17.573	-0.775
100	50u	18.533	18.680	0.146
100	51u	18.659	19.404	0.745
100	52u	19.091	18.507	-0.584
	Max	19.189	19.923	1.727
	Average	18.590	19.209	0.619
	Min	18.044	17.573	-0.775
	Std Dev	0.374	0.699	0.819

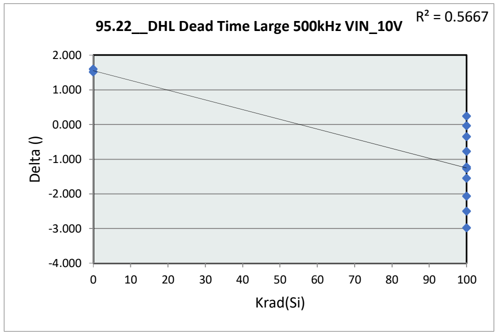


	95.21__DHL Dead Time Mid 500kHz VIN_10	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	19.700	17.573
Average	19.811	19.089
Max	19.923	19.878
UL	24.500	24.500

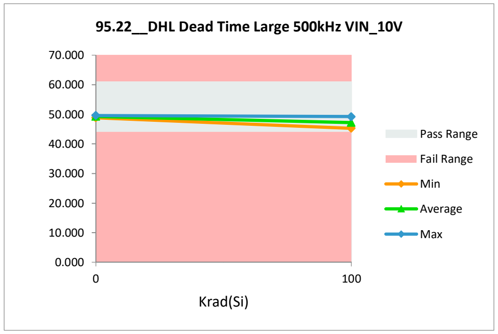


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.22__DHL Dead Time Large 50		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		61	61	
Min Limit		44	44	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	48.050	49.642	1.592
0	2	47.298	48.811	1.513
100	23	48.180	48.416	0.236
100	24	48.099	47.747	-0.352
100	25	49.071	47.007	-2.065
100	26	47.816	47.040	-0.776
100	27	48.503	48.468	-0.035
100	48u	50.441	49.214	-1.227
100	49u	47.844	45.342	-2.503
100	50u	48.171	46.617	-1.554
100	51u	48.207	46.928	-1.279
100	52u	48.243	45.264	-2.979
	Max	50.441	49.642	1.592
	Average	48.327	47.541	-0.786
	Min	47.298	45.264	-2.979
	Std Dev	0.786	1.423	1.451

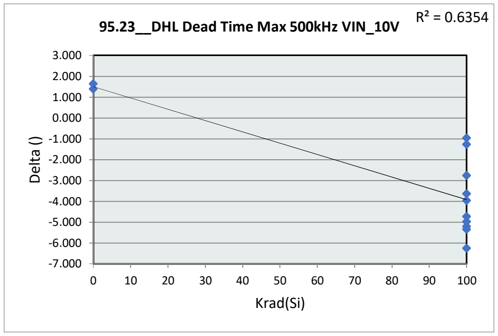

95.22__DHL Dead Time Large 500kHz VIN_10V

	95.22__DHL Dead Time Large 500kHz VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	48.811	45.264
Average	49.227	47.204
Max	49.642	49.214
UL	61.000	61.000

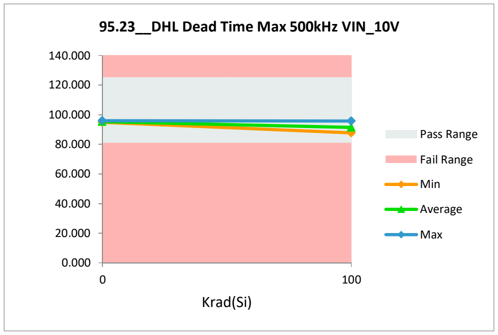

95.22__DHL Dead Time Large 500kHz VIN_10V

TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.23__DHL Dead Time Max 500		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	125	125	
	Min Limit	81	81	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	94.307	95.937	1.630
0	2	93.453	94.833	1.380
100	23	94.902	93.625	-1.277
100	24	95.285	91.634	-3.650
100	25	96.200	90.846	-5.354
100	26	93.676	90.909	-2.767
100	27	95.024	94.053	-0.971
100	48u	99.722	95.749	-3.973
100	49u	94.009	88.794	-5.215
100	50u	94.888	89.904	-4.984
100	51u	94.724	89.984	-4.739
100	52u	93.978	87.716	-6.261
	Max	99.722	95.937	1.630
	Average	95.014	91.999	-3.015
	Min	93.453	87.716	-6.261
	Std Dev	1.667	2.766	2.649

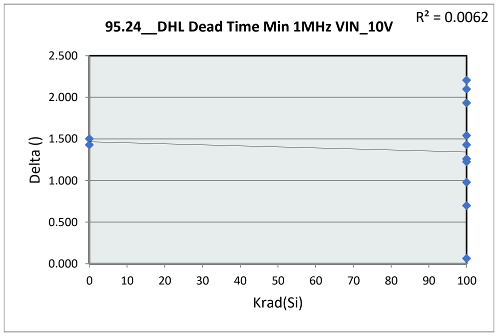


	95.23__DHL Dead Time Max 500kHz VIN_10	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	94.833	87.717
Average	95.385	91.321
Max	95.937	95.749
UL	125.000	125.000

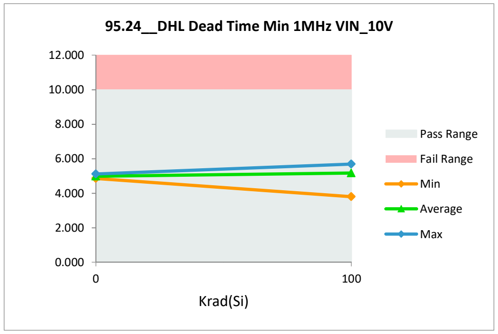


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.24__DHL Dead Time Min 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.351	4.853	1.502
0	2	3.678	5.106	1.428
100	23	3.167	5.266	2.099
100	24	3.356	5.563	2.207
100	25	3.954	5.383	1.429
100	26	4.186	4.883	0.697
100	27	3.985	5.209	1.224
100	48u	3.868	5.408	1.539
100	49u	3.736	3.802	0.066
100	50u	3.821	5.081	1.259
100	51u	3.748	5.682	1.934
100	52u	4.424	5.403	0.979
	Max	4.424	5.682	2.207
	Average	3.773	5.137	1.364
	Min	3.167	3.802	0.066
	Std Dev	0.358	0.490	0.599



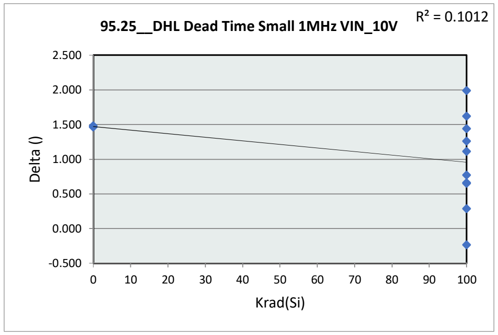
	95.24__DHL Dead Time Min 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.853	3.802
Average	4.979	5.168
Max	5.106	5.682
UL	10.000	10.000



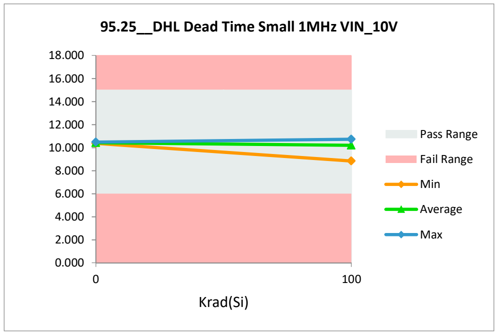
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	95.25__DHL Dead Time Small 1M	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	15	15
Min Limit	6	6

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	8.883	10.361	1.478
0	2	9.016	10.480	1.464
100	23	8.744	10.365	1.621
100	24	8.741	10.729	1.988
100	25	9.502	10.163	0.661
100	26	9.337	9.987	0.651
100	27	9.443	10.554	1.111
100	48u	9.422	10.682	1.259
100	49u	9.071	8.835	-0.236
100	50u	9.298	10.069	0.771
100	51u	9.234	10.675	1.441
100	52u	9.754	10.040	0.286
	Max	9.754	10.729	1.988
	Average	9.204	10.245	1.041
	Min	8.741	8.835	-0.236
	Std Dev	0.317	0.515	0.631

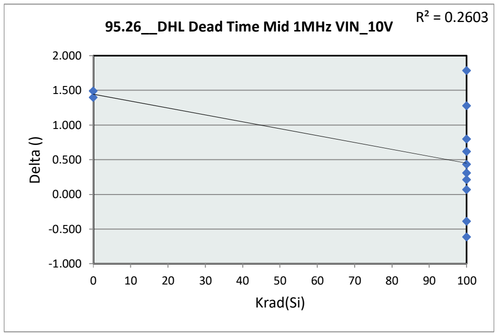


	95.25__DHL Dead Time Small 1MHz VIN_10	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.361	8.835
Average	10.420	10.210
Max	10.480	10.729
UL	15.000	15.000

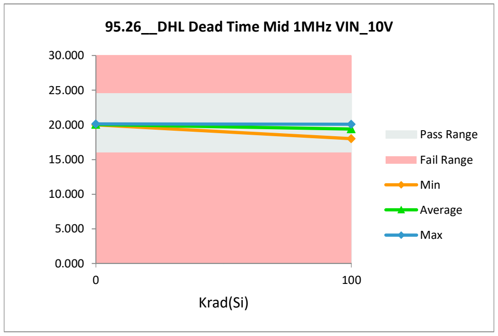


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.26__DHL Dead Time Mid 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24.5	24.5	
Min Limit		16	16	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.743	20.142	1.400
0	2	18.496	19.984	1.488
100	23	18.476	19.753	1.277
100	24	18.313	20.097	1.784
100	25	19.263	19.331	0.067
100	26	18.945	19.253	0.307
100	27	19.202	19.822	0.620
100	48u	19.622	20.055	0.433
100	49u	18.613	17.998	-0.615
100	50u	18.799	19.010	0.210
100	51u	18.866	19.666	0.800
100	52u	19.167	18.778	-0.389
	Max	19.622	20.142	1.784
	Average	18.875	19.491	0.615
	Min	18.313	17.998	-0.615
	Std Dev	0.383	0.648	0.759

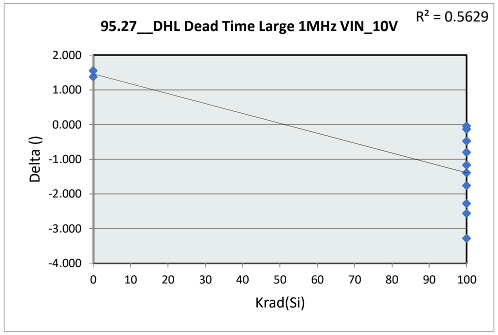


	95.26__DHL Dead Time Mid 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	19.984	17.998
Average	20.063	19.376
Max	20.142	20.097
UL	24.500	24.500

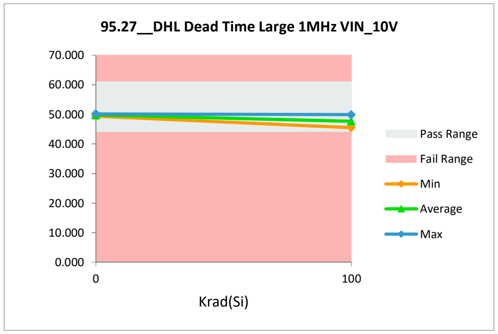


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.27__DHL Dead Time Large 1M		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	61	61	
	Min Limit	44	44	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	48.635	50.179	1.544
0	2	47.960	49.331	1.371
100	23	48.797	48.658	-0.139
100	24	48.609	48.130	-0.479
100	25	49.563	47.281	-2.281
100	26	48.353	47.550	-0.803
100	27	48.998	48.950	-0.048
100	48u	51.033	49.862	-1.171
100	49u	48.411	45.846	-2.564
100	50u	48.724	46.963	-1.761
100	51u	48.811	47.416	-1.395
100	52u	48.767	45.481	-3.286
	Max	51.033	50.179	1.544
	Average	48.888	47.971	-0.918
	Min	47.960	45.481	-3.286
	Std Dev	0.777	1.491	1.479

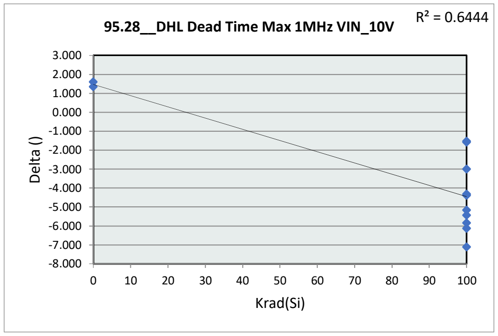


	95.27__DHL Dead Time Large 1MHz VIN_10	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	49.331	45.481
Average	49.755	47.614
Max	50.179	49.862
UL	61.000	61.000

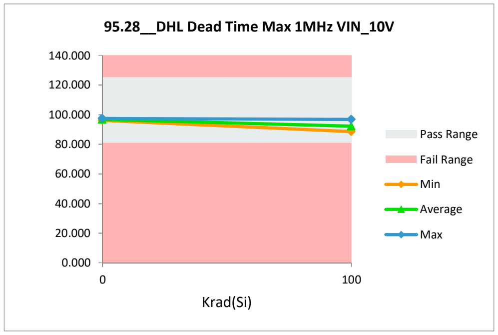


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.28__DHL Dead Time Max 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		125	125	
Min Limit		81	81	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	95.817	97.413	1.596
0	2	94.870	96.209	1.340
100	23	96.229	94.646	-1.583
100	24	96.840	92.511	-4.329
100	25	97.842	91.700	-6.142
100	26	94.984	91.973	-3.010
100	27	96.541	95.011	-1.530
100	48u	101.290	96.895	-4.395
100	49u	95.555	89.703	-5.852
100	50u	96.348	90.913	-5.435
100	51u	96.223	91.045	-5.178
100	52u	95.647	88.534	-7.113
	Max	101.290	97.413	1.596
	Average	96.515	93.046	-3.469
	Min	94.870	88.534	-7.113
	Std Dev	1.708	2.918	2.873

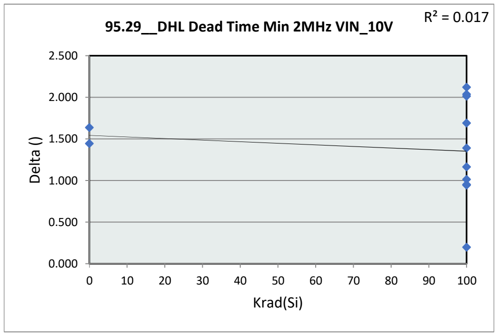


	95.28__DHL Dead Time Max 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	96.209	88.534
Average	96.811	92.293
Max	97.413	96.895
UL	125.000	125.000

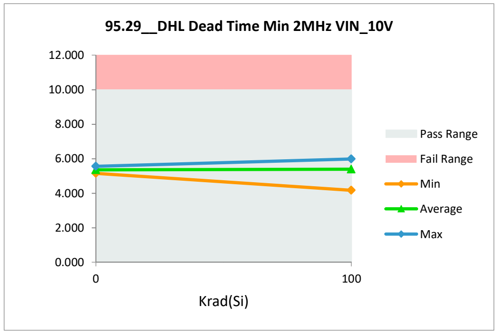


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.29__DHL Dead Time Min 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.711	5.157	1.446
0	2	3.926	5.563	1.637
100	23	3.594	5.286	1.692
100	24	3.561	5.682	2.120
100	25	4.320	5.271	0.951
100	26	4.240	5.183	0.943
100	27	4.207	5.599	1.391
100	48u	3.913	5.928	2.015
100	49u	3.972	4.171	0.199
100	50u	4.044	5.210	1.165
100	51u	3.953	5.988	2.035
100	52u	4.643	5.657	1.014
	Max	4.643	5.988	2.120
	Average	4.007	5.391	1.384
	Min	3.561	4.171	0.199
	Std Dev	0.313	0.478	0.564

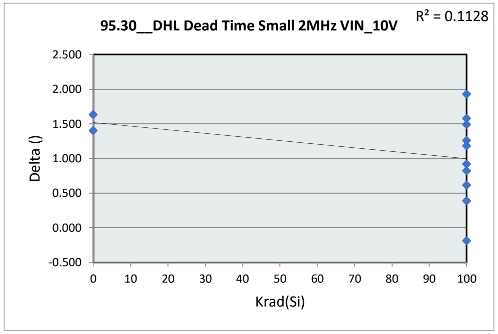


	95.29__DHL Dead Time Min 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.157	4.171
Average	5.360	5.397
Max	5.563	5.988
UL	10.000	10.000

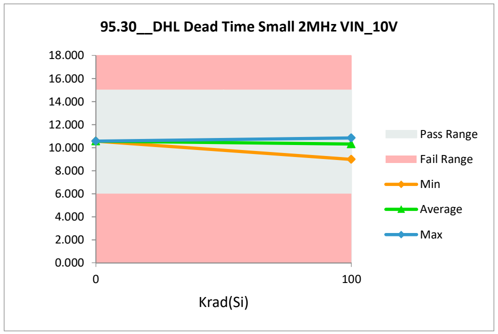


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.30__DHL Dead Time Small 2M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		15	15	
Min Limit		6	6	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	8.924	10.557	1.633
0	2	9.149	10.551	1.403
100	23	8.803	10.379	1.576
100	24	8.851	10.781	1.930
100	25	9.528	10.351	0.823
100	26	9.514	10.129	0.615
100	27	9.586	10.765	1.179
100	48u	9.479	10.738	1.258
100	49u	9.164	8.975	-0.189
100	50u	9.194	10.111	0.917
100	51u	9.352	10.842	1.490
100	52u	9.733	10.118	0.385
	Max	9.733	10.842	1.930
	Average	9.273	10.358	1.085
	Min	8.803	8.975	-0.189
	Std Dev	0.307	0.512	0.602

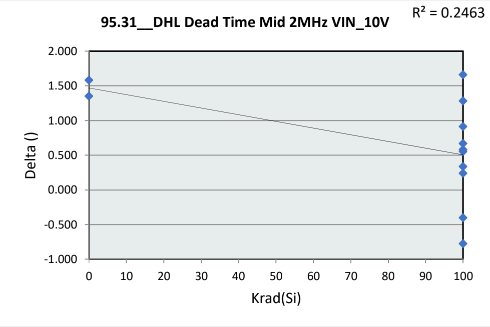


	95.30__DHL Dead Time Small 2MHz VIN_10	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.551	8.975
Average	10.554	10.319
Max	10.557	10.842
UL	15.000	15.000

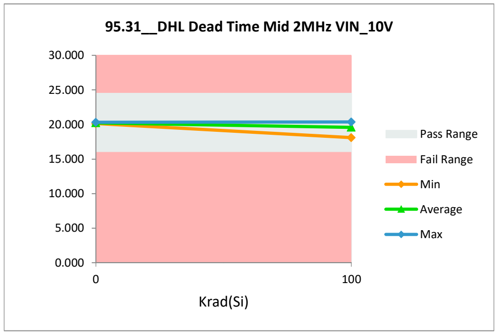


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.31__DHL Dead Time Mid 2MH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	24.5	24.5	
	Min Limit	16	16	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.724	20.309	1.585
0	2	18.790	20.141	1.352
100	23	18.617	19.899	1.281
100	24	18.525	20.185	1.660
100	25	19.261	19.501	0.240
100	26	18.982	19.535	0.553
100	27	19.454	20.035	0.582
100	48u	19.679	20.347	0.668
100	49u	18.858	18.083	-0.775
100	50u	18.865	19.204	0.339
100	51u	19.023	19.938	0.914
100	52u	19.376	18.975	-0.402
	Max	19.679	20.347	1.660
	Average	19.013	19.679	0.666
	Min	18.525	18.083	-0.775
	Std Dev	0.357	0.666	0.755

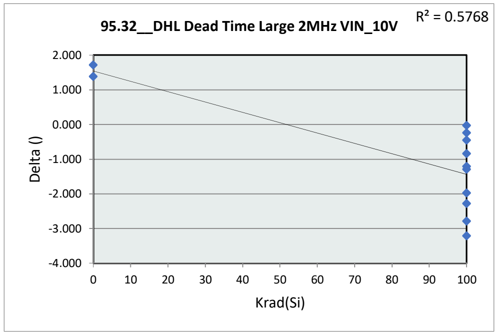


	95.31__DHL Dead Time Mid 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	20.141	18.083
Average	20.225	19.570
Max	20.309	20.347
UL	24.500	24.500

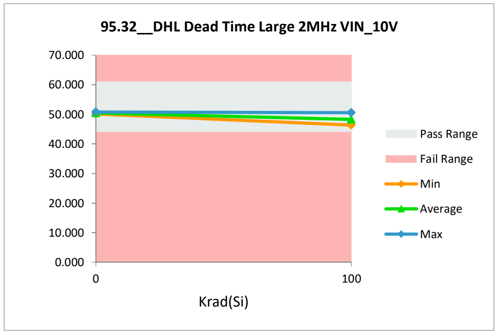


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		95.32__DHL Dead Time Large 2M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		61	61	
Min Limit		44	44	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	49.382	50.761	1.379
0	2	48.448	50.160	1.712
100	23	49.611	49.371	-0.240
100	24	49.343	48.887	-0.455
100	25	50.375	48.091	-2.284
100	26	49.103	48.260	-0.843
100	27	49.677	49.646	-0.030
100	48u	51.891	50.596	-1.295
100	49u	49.266	46.479	-2.788
100	50u	49.464	47.487	-1.976
100	51u	49.367	48.156	-1.211
100	52u	49.553	46.335	-3.218
	Max	51.891	50.761	1.712
	Average	49.623	48.686	-0.937
	Min	48.448	46.335	-3.218
	Std Dev	0.838	1.483	1.527



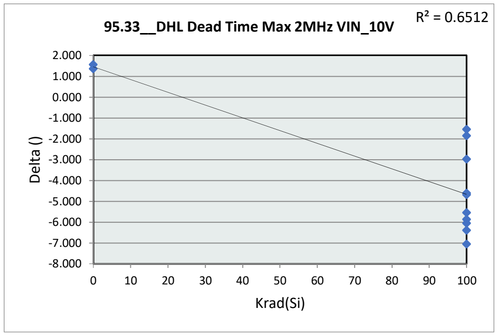
	95.32__DHL Dead Time Large 2MHz VIN_10	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	50.160	46.336
Average	50.460	48.331
Max	50.761	50.596
UL	61.000	61.000



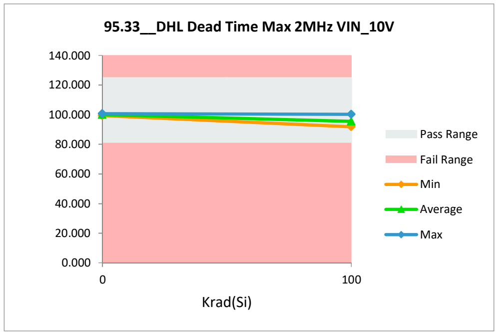
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	95.33__DHL Dead Time Max 2MH	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	125	125
Min Limit	81	81

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	99.172	100.720	1.548
0	2	98.032	99.380	1.348
100	23	99.648	97.788	-1.860
100	24	100.234	95.547	-4.687
100	25	101.318	94.915	-6.402
100	26	98.187	95.202	-2.986
100	27	99.883	98.330	-1.553
100	48u	104.972	100.359	-4.613
100	49u	98.803	92.739	-6.064
100	50u	99.711	94.167	-5.544
100	51u	99.634	93.765	-5.869
100	52u	98.814	91.749	-7.065
	Max	104.972	100.720	1.548
	Average	99.867	96.222	-3.646
	Min	98.032	91.749	-7.065
	Std Dev	1.842	3.012	2.949

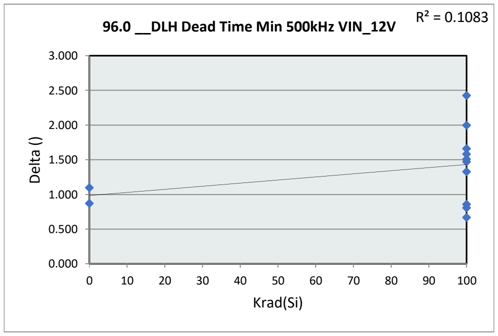


	95.33__DHL Dead Time Max 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	99.380	91.749
Average	100.050	95.456
Max	100.721	100.359
UL	125.000	125.000

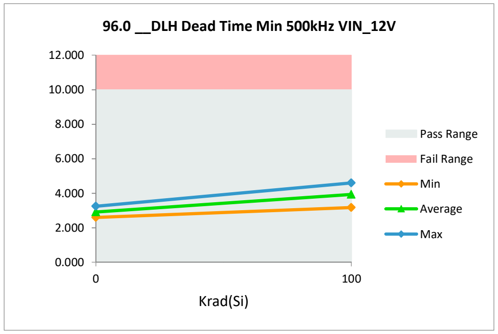


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.0 __DLH Dead Time Min 500k		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	10	10	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.146	3.243	1.097
0	2	1.722	2.594	0.872
100	23	3.003	3.673	0.670
100	24	3.207	4.012	0.806
100	25	2.567	4.151	1.584
100	26	2.066	3.572	1.506
100	27	2.588	4.587	1.999
100	48u	2.526	3.998	1.472
100	49u	2.308	3.164	0.857
100	50u	2.428	4.088	1.660
100	51u	2.416	3.744	1.329
100	52u	1.807	4.231	2.424
	Max	3.207	4.587	2.424
	Average	2.399	3.755	1.356
	Min	1.722	2.594	0.670
	Std Dev	0.436	0.549	0.527

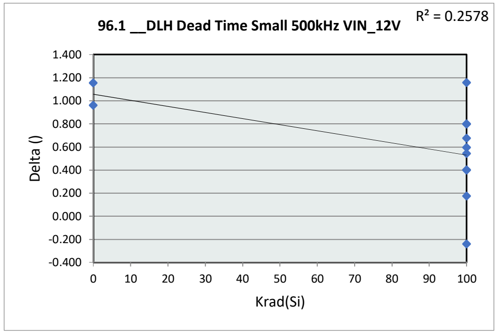


	96.0 __DLH Dead Time Min 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	2.594	3.165
Average	2.918	3.922
Max	3.243	4.587
UL	10.000	10.000

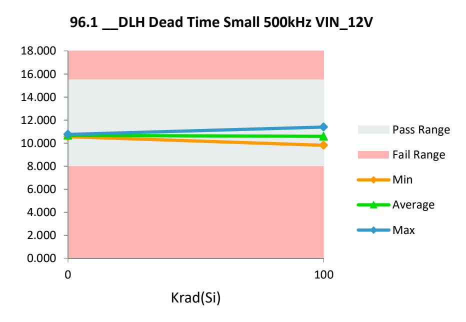


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.1 __DLH Dead Time Small 50		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		15.5	15.5	
Min Limit		8	8	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	9.801	10.762	0.961
0	2	9.406	10.558	1.153
100	23	10.037	10.436	0.399
100	24	10.488	10.662	0.174
100	25	10.162	10.757	0.595
100	26	9.708	10.384	0.676
100	27	10.246	11.401	1.156
100	48u	9.989	10.389	0.400
100	49u	10.046	9.804	-0.242
100	50u	10.020	10.818	0.799
100	51u	10.024	10.566	0.541
100	52u	9.787	10.582	0.795
	Max	10.488	11.401	1.156
	Average	9.976	10.593	0.617
	Min	9.406	9.804	-0.242
	Std Dev	0.277	0.369	0.404

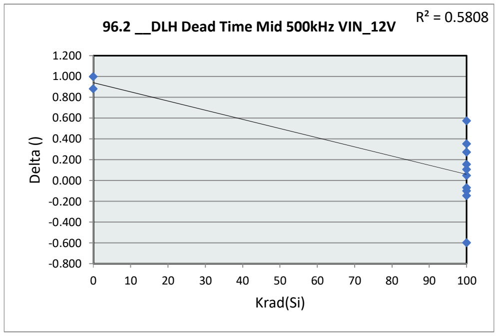


	96.1 __DLH Dead Time Small 500kHz VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.558	9.804
Average	10.660	10.580
Max	10.762	11.402
UL	15.500	15.500

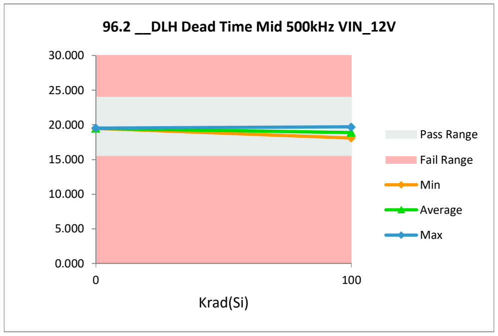


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.2 __DLH Dead Time Mid 500k		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24	24	
Min Limit		15.5	15.5	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.540	19.539	1.000
0	2	18.586	19.466	0.881
100	23	18.310	18.662	0.352
100	24	18.791	18.898	0.106
100	25	19.146	19.000	-0.146
100	26	18.811	18.712	-0.098
100	27	19.121	19.696	0.575
100	48u	18.825	18.757	-0.069
100	49u	18.686	18.087	-0.599
100	50u	18.913	19.067	0.155
100	51u	18.893	19.167	0.274
100	52u	18.750	18.799	0.049
	Max	19.146	19.696	1.000
	Average	18.781	18.988	0.207
	Min	18.310	18.087	-0.599
	Std Dev	0.235	0.443	0.450

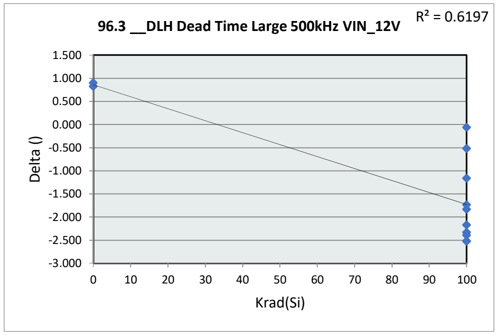


	96.2 __DLH Dead Time Mid 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	19.466	18.087
Average	19.503	18.884
Max	19.540	19.696
UL	24.000	24.000

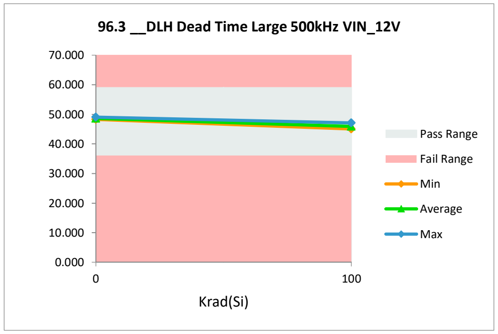


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	96.3 __DLH Dead Time Large 50			
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		59	59	
Min Limit		36	36	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	47.434	48.255	0.820
0	2	48.174	49.075	0.901
100	23	45.474	45.414	-0.061
100	24	46.353	45.834	-0.519
100	25	48.531	46.135	-2.396
100	26	48.336	46.000	-2.336
100	27	48.438	46.697	-1.741
100	48u	47.354	45.178	-2.176
100	49u	47.553	45.034	-2.519
100	50u	47.549	45.715	-1.834
100	51u	48.256	47.090	-1.166
100	52u	48.572	46.047	-2.526
	Max	48.572	49.075	0.901
	Average	47.669	46.373	-1.296
	Min	45.474	45.034	-2.526
	Std Dev	0.950	1.229	1.280

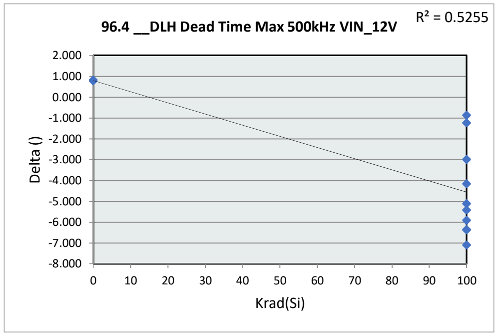


	96.3 __DLH Dead Time Large 500kHz VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	48.255	45.034
Average	48.665	45.914
Max	49.075	47.090
UL	59.000	59.000

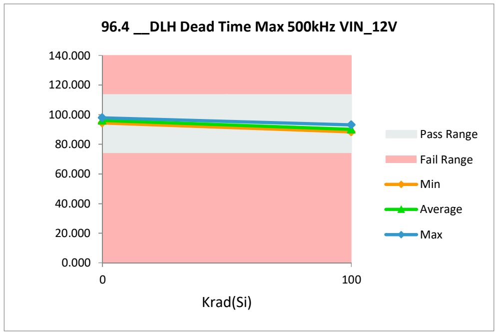


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.4 __DLH Dead Time Max 500k		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		113.5	113.5	
Min Limit		74	74	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	93.669	94.442	0.773
0	2	97.090	97.907	0.817
100	23	89.300	88.418	-0.882
100	24	91.169	89.932	-1.237
100	25	96.399	90.038	-6.361
100	26	96.778	90.394	-6.384
100	27	95.179	91.017	-4.162
100	48u	93.921	88.494	-5.427
100	49u	94.705	88.779	-5.926
100	50u	94.202	89.076	-5.127
100	51u	96.174	93.177	-2.997
100	52u	97.927	90.816	-7.111
	Max	97.927	97.907	0.817
	Average	94.709	91.041	-3.669
	Min	89.300	88.418	-7.111
	Std Dev	2.509	2.834	2.876



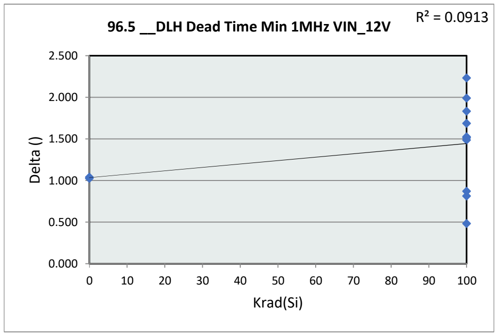
	96.4 __DLH Dead Time Max 500kHz VIN_12	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	94.442	88.418
Average	96.174	90.014
Max	97.907	93.177
UL	113.500	113.500



TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

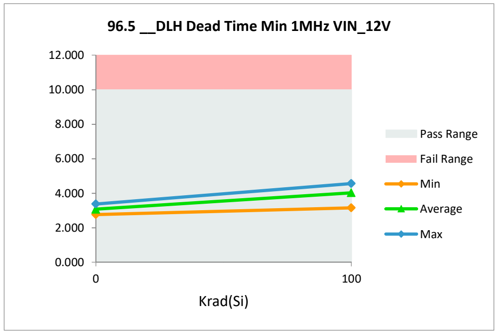
96.5 __DLH Dead Time Min 1MHz

Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	**Serial #**	**Pre_6015**	**Post_6015**	**Delta**
0	1	2.348	3.374	1.026
0	2	1.722	2.763	1.041
100	23	3.009	3.880	0.871
100	24	3.354	4.166	0.812
100	25	2.585	4.110	1.525
100	26	1.998	3.687	1.689
100	27	2.730	4.564	1.835
100	48u	2.575	4.062	1.488
100	49u	2.658	3.143	0.485
100	50u	2.392	4.383	1.991
100	51u	2.372	3.886	1.514
100	52u	2.170	4.404	2.233
	Max	3.354	4.564	2.233
	Average	2.493	3.869	1.376
	Min	1.722	2.763	0.485
	Std Dev	0.437	0.543	0.529



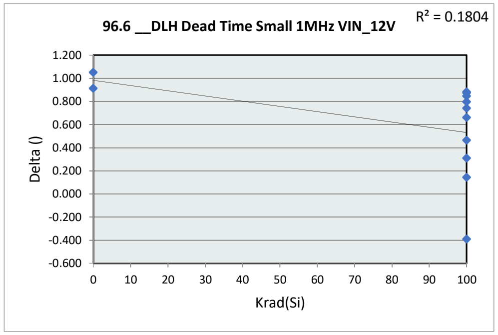
96.5 __DLH Dead Time Min 1MHz VIN_12V

Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	**0**	**100**
LL	0.000	0.000
Min	2.763	3.143
Average	3.068	4.029
Max	3.374	4.565
UL	10.000	10.000

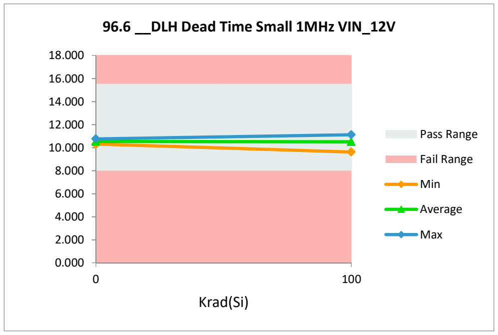


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.6 __DLH Dead Time Small 1M		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	15.5	15.5	
	Min Limit	8	8	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	9.703	10.755	1.052
0	2	9.383	10.295	0.912
100	23	9.979	10.443	0.464
100	24	10.382	10.525	0.142
100	25	10.039	10.778	0.739
100	26	9.601	10.483	0.882
100	27	10.257	11.103	0.846
100	48u	9.969	10.277	0.308
100	49u	10.016	9.626	-0.391
100	50u	9.913	10.708	0.795
100	51u	9.921	10.580	0.659
100	52u	9.688	10.562	0.874
	Max	10.382	11.103	1.052
	Average	9.904	10.511	0.607
	Min	9.383	9.626	-0.391
	Std Dev	0.277	0.359	0.412

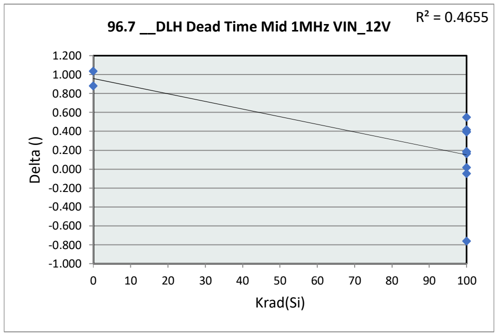


	96.6 __DLH Dead Time Small 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.295	9.626
Average	10.525	10.509
Max	10.755	11.103
UL	15.500	15.500

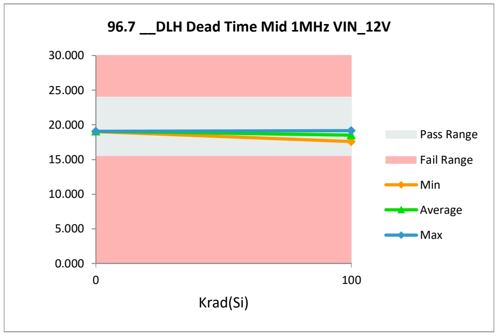


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.7 __DLH Dead Time Mid 1MHz		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	24	24	
	Min Limit	15.5	15.5	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.209	19.090	0.881
0	2	18.013	19.048	1.035
100	23	17.854	18.403	0.549
100	24	18.377	18.770	0.393
100	25	18.549	18.733	0.184
100	26	18.232	18.417	0.185
100	27	18.760	19.176	0.416
100	48u	18.279	18.234	-0.045
100	49u	18.348	17.587	-0.761
100	50u	18.436	18.598	0.162
100	51u	18.347	18.745	0.398
100	52u	18.359	18.378	0.019
	Max	18.760	19.176	1.035
	Average	18.314	18.598	0.285
	Min	17.854	17.587	-0.761
	Std Dev	0.233	0.439	0.461

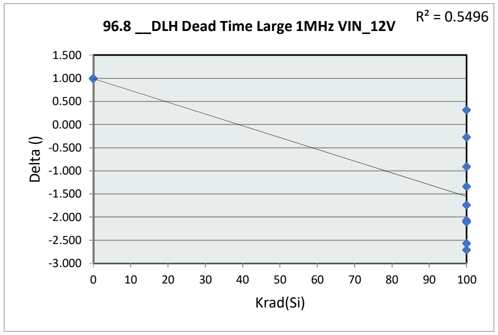


	96.7 __DLH Dead Time Mid 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	19.048	17.587
Average	19.069	18.504
Max	19.090	19.176
UL	24.000	24.000

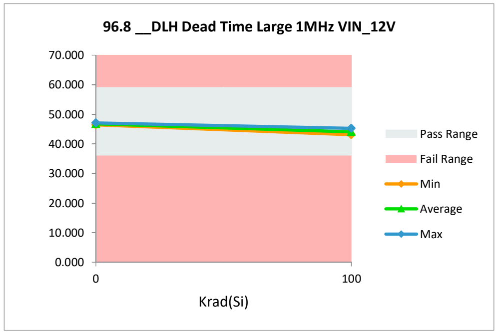


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.8 __DLH Dead Time Large 1M		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	59	59	
	Min Limit	36	36	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	45.515	46.503	0.988
0	2	46.127	47.122	0.996
100	23	43.321	43.630	0.309
100	24	44.230	43.949	-0.281
100	25	46.370	44.256	-2.115
100	26	46.243	44.163	-2.080
100	27	46.215	44.873	-1.342
100	48u	45.548	43.445	-2.103
100	49u	45.835	43.119	-2.716
100	50u	45.600	43.852	-1.748
100	51u	46.191	45.275	-0.916
100	52u	46.800	44.221	-2.579
	Max	46.800	47.122	0.996
	Average	45.666	44.534	-1.132
	Min	43.321	43.119	-2.716
	Std Dev	0.979	1.220	1.338

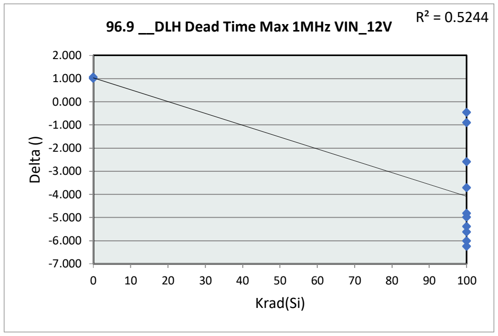


	96.8 __DLH Dead Time Large 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	46.503	43.120
Average	46.813	44.078
Max	47.122	45.275
UL	59.000	59.000

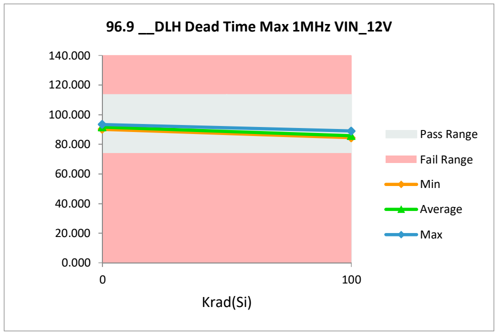


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.9 __DLH Dead Time Max 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		113.5	113.5	
Min Limit		74	74	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	89.049	90.104	1.055
0	2	92.298	93.307	1.009
100	23	84.857	84.390	-0.467
100	24	86.527	85.619	-0.907
100	25	91.617	85.988	-5.629
100	26	92.010	85.990	-6.020
100	27	90.605	86.896	-3.710
100	48u	89.447	84.458	-4.989
100	49u	89.958	84.562	-5.396
100	50u	89.665	84.844	-4.821
100	51u	91.518	88.928	-2.590
100	52u	92.939	86.685	-6.254
	Max	92.939	93.307	1.055
	Average	90.041	86.814	-3.227
	Min	84.857	84.390	-6.254
	Std Dev	2.394	2.708	2.747

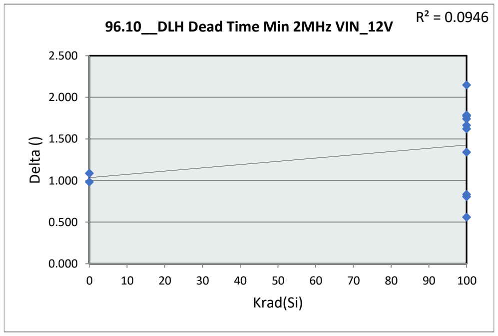


	96.9 __DLH Dead Time Max 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	90.104	84.390
Average	91.705	85.836
Max	93.307	88.928
UL	113.500	113.500

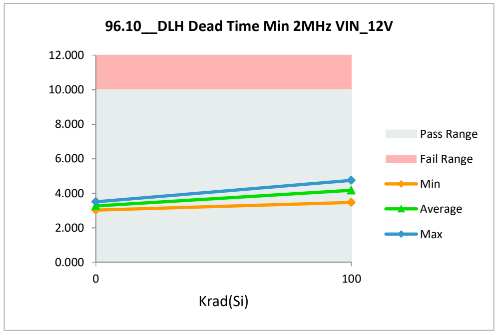


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.10__DLH Dead Time Min 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.411	3.497	1.086
0	2	2.044	3.027	0.983
100	23	3.053	3.860	0.807
100	24	3.391	4.224	0.833
100	25	2.718	4.460	1.742
100	26	2.167	3.954	1.788
100	27	2.970	4.747	1.777
100	48u	2.679	4.300	1.622
100	49u	2.910	3.470	0.560
100	50u	2.628	4.293	1.666
100	51u	2.645	3.984	1.339
100	52u	2.183	4.330	2.147
	Max	3.391	4.747	2.147
	Average	2.650	4.012	1.362
	Min	2.044	3.027	0.560
	Std Dev	0.400	0.487	0.498

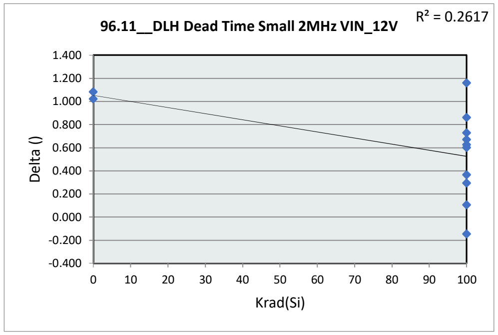


	96.10__DLH Dead Time Min 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	3.027	3.470
Average	3.262	4.162
Max	3.497	4.747
UL	10.000	10.000

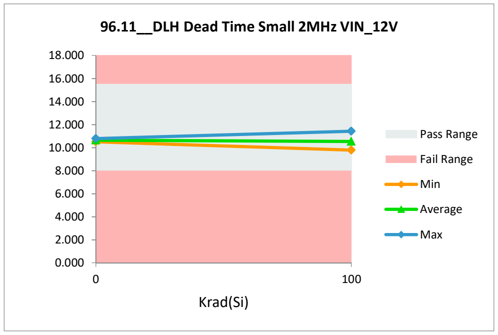


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.11__DLH Dead Time Small 2M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		15.5	15.5	
Min Limit		8	8	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	9.758	10.781	1.022
0	2	9.427	10.509	1.082
100	23	10.017	10.309	0.293
100	24	10.405	10.508	0.104
100	25	10.086	10.757	0.670
100	26	9.631	10.491	0.860
100	27	10.248	11.407	1.159
100	48u	10.039	10.404	0.365
100	49u	9.934	9.785	-0.149
100	50u	9.999	10.727	0.728
100	51u	9.948	10.548	0.600
100	52u	9.742	10.367	0.625
	Max	10.405	11.407	1.159
	Average	9.936	10.549	0.613
	Min	9.427	9.785	-0.149
	Std Dev	0.267	0.377	0.401



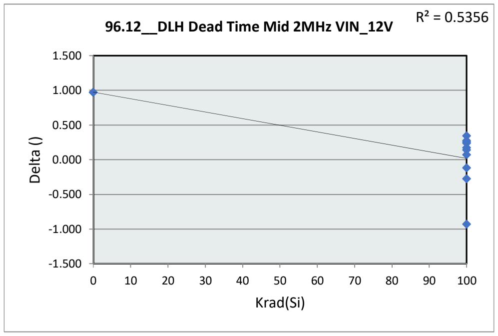
	96.11__DLH Dead Time Small 2MHz VIN_12	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.509	9.785
Average	10.645	10.530
Max	10.781	11.407
UL	15.500	15.500



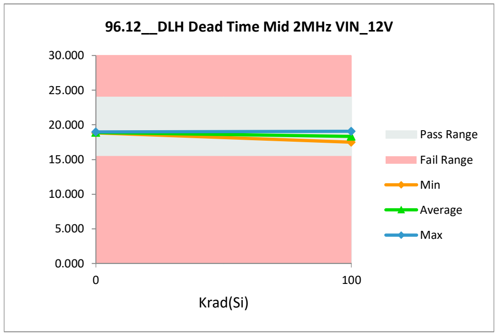
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	96.12__DLH Dead Time Mid 2MH	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	24	24
Min Limit	15.5	15.5

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	17.997	18.971	0.974
0	2	17.874	18.847	0.973
100	23	17.830	18.085	0.256
100	24	18.367	18.438	0.071
100	25	18.405	18.547	0.142
100	26	18.151	18.326	0.175
100	27	18.806	19.081	0.275
100	48u	18.293	18.020	-0.272
100	49u	18.407	17.479	-0.928
100	50u	18.260	18.497	0.237
100	51u	18.452	18.799	0.346
100	52u	18.367	18.250	-0.117
	Max	18.806	19.081	0.974
	Average	18.267	18.445	0.178
	Min	17.830	17.479	-0.928
	Std Dev	0.273	0.455	0.508



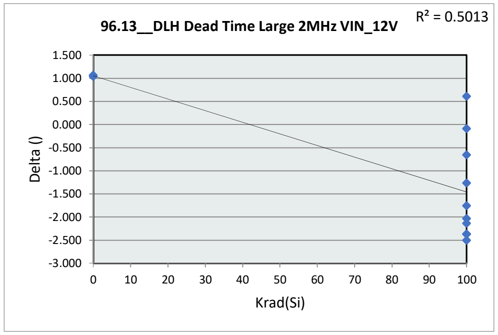
	96.12__DLH Dead Time Mid 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	18.847	17.479
Average	18.909	18.352
Max	18.971	19.082
UL	24.000	24.000



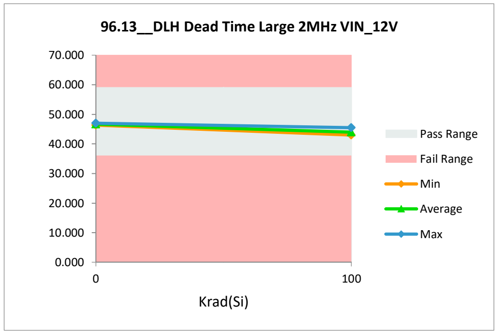
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	96.13__DLH Dead Time Large 2M	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	59	59
Min Limit	36	36

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	45.264	46.332	1.067
0	2	46.014	47.052	1.039
100	23	42.935	43.544	0.609
100	24	44.050	43.958	-0.091
100	25	46.448	44.078	-2.370
100	26	46.102	44.066	-2.035
100	27	46.172	44.902	-1.270
100	48u	45.362	43.225	-2.138
100	49u	45.532	43.028	-2.504
100	50u	45.426	43.666	-1.760
100	51u	46.117	45.458	-0.659
100	52u	46.604	44.227	-2.376
	Max	46.604	47.052	1.067
	Average	45.502	44.461	-1.041
	Min	42.935	43.028	-2.504
	Std Dev	1.059	1.246	1.381

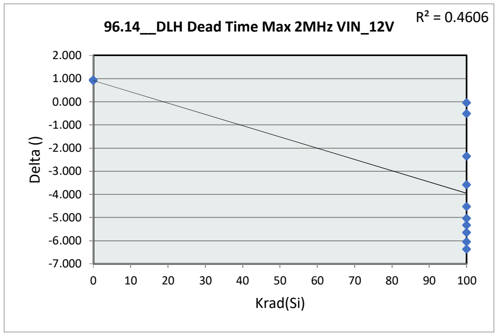


	96.13__DLH Dead Time Large 2MHz VIN_12	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	46.332	43.028
Average	46.692	44.015
Max	47.052	45.458
UL	59.000	59.000

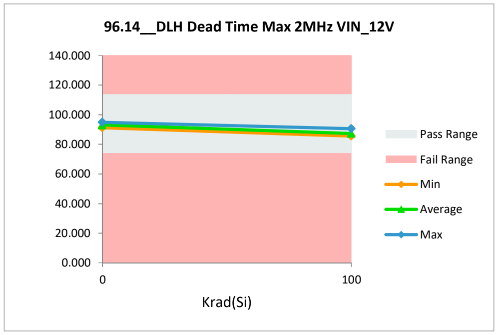


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.14__DLH Dead Time Max 2MH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	113.5	113.5	
	Min Limit	74	74	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	90.385	91.287	0.901
0	2	93.837	94.767	0.929
100	23	85.950	85.897	-0.053
100	24	87.660	87.143	-0.517
100	25	92.996	87.348	-5.648
100	26	93.413	87.363	-6.050
100	27	91.810	88.214	-3.596
100	48u	90.633	85.582	-5.051
100	49u	91.099	85.761	-5.337
100	50u	90.819	86.286	-4.532
100	51u	92.822	90.458	-2.364
100	52u	94.595	88.222	-6.373
	Max	94.595	94.767	0.929
	Average	91.335	88.194	-3.141
	Min	85.950	85.582	-6.373
	Std Dev	2.534	2.731	2.792

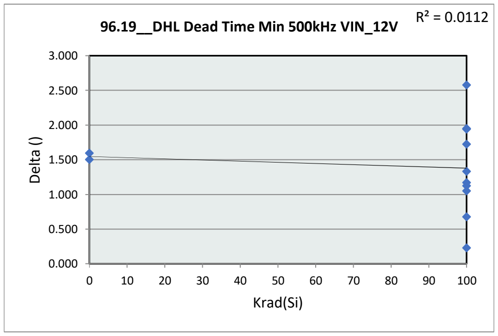


	96.14__DLH Dead Time Max 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	91.287	85.582
Average	93.027	87.227
Max	94.767	90.458
UL	113.500	113.500

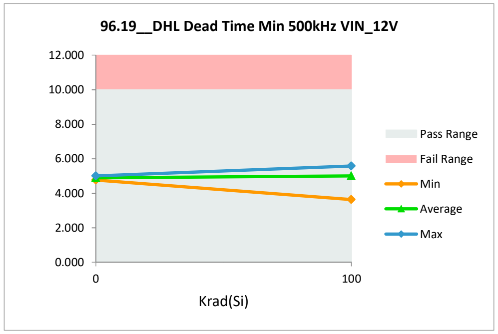


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.19__DHL Dead Time Min 500		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	10	10	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.173	4.767	1.593
0	2	3.504	5.006	1.502
100	23	3.118	5.060	1.942
100	24	2.972	5.548	2.576
100	25	3.897	4.946	1.049
100	26	4.060	4.737	0.677
100	27	3.876	5.045	1.170
100	48u	3.529	5.254	1.725
100	49u	3.405	3.636	0.231
100	50u	3.592	4.717	1.125
100	51u	3.625	5.576	1.951
100	52u	4.150	5.484	1.334
	Max	4.150	5.576	2.576
	Average	3.575	4.981	1.406
	Min	2.972	3.636	0.231
	Std Dev	0.373	0.522	0.624

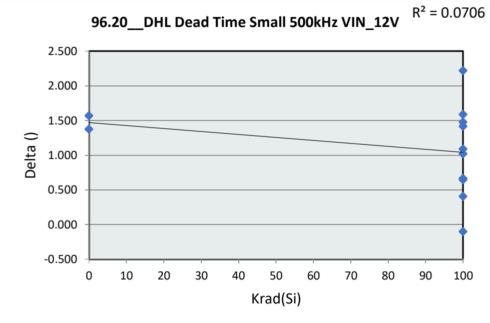


96.19__DHL Dead Time Min 500kHz VIN_12		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.767	3.636
Average	4.886	5.000
Max	5.006	5.576
UL	10.000	10.000

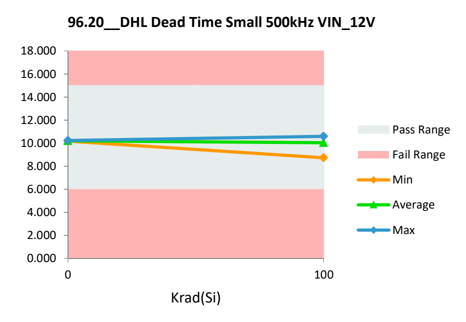


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.20__DHL Dead Time Small 50		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		15	15	
Min Limit		6	6	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	8.606	10.175	1.569
0	2	8.840	10.214	1.373
100	23	8.600	10.188	1.589
100	24	8.370	10.587	2.218
100	25	9.342	9.986	0.644
100	26	9.070	9.736	0.666
100	27	9.211	10.299	1.088
100	48u	9.119	10.536	1.417
100	49u	8.818	8.714	-0.104
100	50u	8.798	9.816	1.018
100	51u	9.009	10.484	1.475
100	52u	9.566	9.972	0.405
	Max	9.566	10.587	2.218
	Average	8.946	10.059	1.113
	Min	8.370	8.714	-0.104
	Std Dev	0.341	0.503	0.629

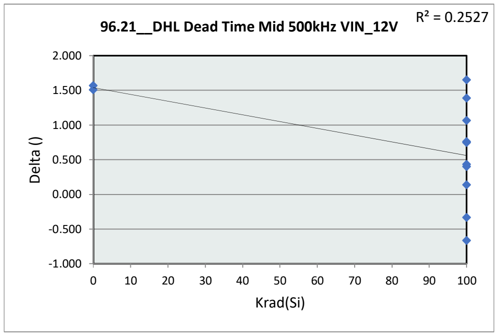


	96.20__DHL Dead Time Small 500kHz VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.175	8.714
Average	10.194	10.032
Max	10.214	10.588
UL	15.000	15.000

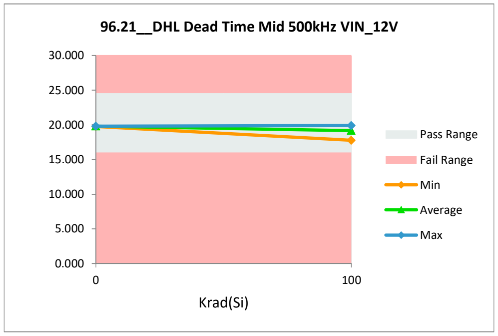


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.21__DHL Dead Time Mid 500		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24.5	24.5	
Min Limit		16	16	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.315	19.822	1.507
0	2	18.206	19.774	1.569
100	23	18.150	19.536	1.387
100	24	18.017	19.668	1.651
100	25	18.968	19.105	0.137
100	26	18.497	18.897	0.400
100	27	18.756	19.503	0.747
100	48u	19.147	19.908	0.761
100	49u	18.429	17.763	-0.666
100	50u	18.545	18.981	0.436
100	51u	18.463	19.530	1.067
100	52u	18.991	18.661	-0.330
	Max	19.147	19.908	1.651
	Average	18.540	19.262	0.722
	Min	18.017	17.763	-0.666
	Std Dev	0.358	0.618	0.758

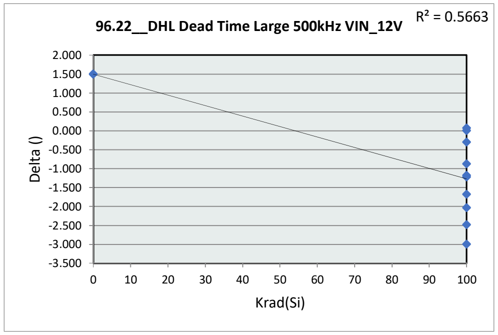


	96.21__DHL Dead Time Mid 500kHz VIN_12	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	19.774	17.763
Average	19.798	19.155
Max	19.822	19.908
UL	24.500	24.500

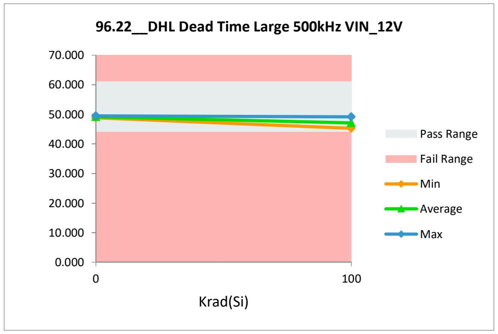


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.22__DHL Dead Time Large 50		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	61	61	
	Min Limit	44	44	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	48.017	49.516	1.500
0	2	47.343	48.837	1.494
100	23	48.176	48.251	0.076
100	24	48.031	47.734	-0.297
100	25	48.977	46.939	-2.038
100	26	47.883	47.005	-0.878
100	27	48.465	48.470	0.006
100	48u	50.387	49.210	-1.177
100	49u	47.703	45.223	-2.480
100	50u	48.215	46.531	-1.683
100	51u	48.190	46.969	-1.221
100	52u	48.227	45.227	-3.000
	Max	50.387	49.516	1.500
	Average	48.301	47.493	-0.808
	Min	47.343	45.223	-3.000
	Std Dev	0.767	1.429	1.431

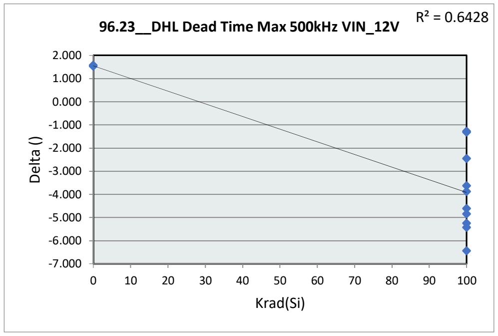


	96.22__DHL Dead Time Large 500kHz VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	48.837	45.223
Average	49.177	47.156
Max	49.516	49.210
UL	61.000	61.000

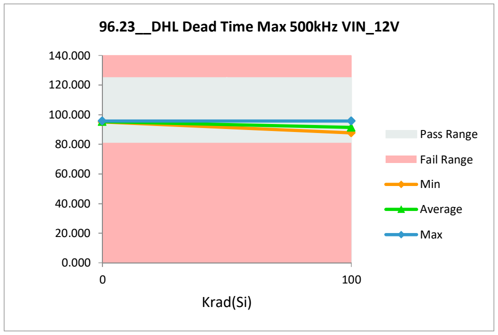


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.23__DHL Dead Time Max 500		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		125	125	
Min Limit		81	81	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	94.247	95.784	1.536
0	2	93.406	94.979	1.574
100	23	94.858	93.543	-1.315
100	24	95.239	91.599	-3.640
100	25	96.268	90.833	-5.435
100	26	93.661	91.204	-2.458
100	27	95.033	93.748	-1.285
100	48u	99.614	95.735	-3.879
100	49u	93.923	88.666	-5.257
100	50u	94.781	89.927	-4.854
100	51u	94.840	90.230	-4.610
100	52u	94.199	87.758	-6.440
	Max	99.614	95.784	1.574
	Average	95.006	92.000	-3.005
	Min	93.406	87.758	-6.440
	Std Dev	1.645	2.718	2.657

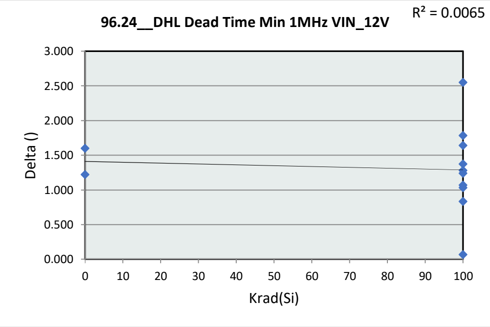


	96.23__DHL Dead Time Max 500kHz VIN_12	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	94.979	87.758
Average	95.381	91.324
Max	95.784	95.735
UL	125.000	125.000

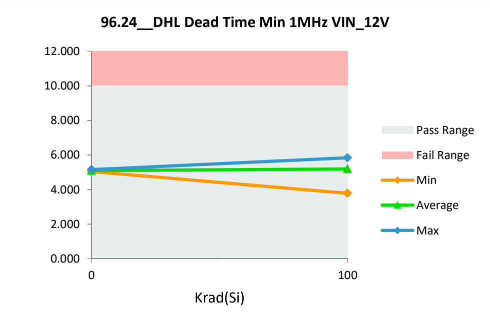


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.24__DHL Dead Time Min 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.431	5.032	1.601
0	2	3.931	5.151	1.220
100	23	3.534	5.177	1.643
100	24	3.283	5.831	2.548
100	25	4.169	5.239	1.069
100	26	4.150	4.982	0.832
100	27	4.042	5.282	1.240
100	48u	3.993	5.367	1.375
100	49u	3.705	3.773	0.067
100	50u	3.639	4.921	1.282
100	51u	3.913	5.700	1.786
100	52u	4.555	5.589	1.034
	Max	4.555	5.831	2.548
	Average	3.862	5.170	1.308
	Min	3.283	3.773	0.067
	Std Dev	0.359	0.524	0.594

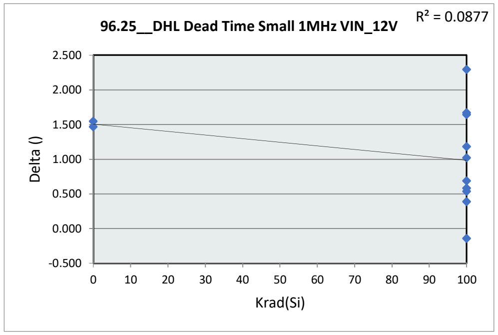


	96.24__DHL Dead Time Min 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.032	3.773
Average	5.091	5.186
Max	5.151	5.831
UL	10.000	10.000

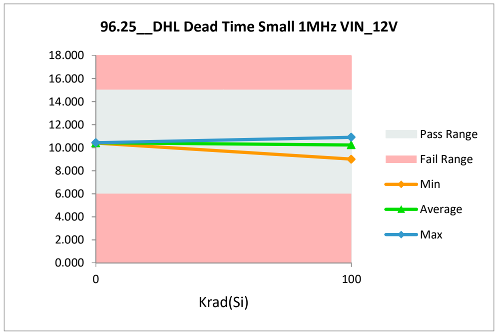


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.25__DHL Dead Time Small 1M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		15	15	
Min Limit		6	6	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	8.856	10.402	1.545
0	2	8.940	10.409	1.469
100	23	8.770	10.439	1.668
100	24	8.603	10.894	2.291
100	25	9.452	10.140	0.688
100	26	9.362	9.895	0.533
100	27	9.439	10.458	1.019
100	48u	9.473	10.653	1.181
100	49u	9.133	8.990	-0.143
100	50u	9.352	9.934	0.583
100	51u	9.073	10.715	1.642
100	52u	9.725	10.111	0.386
	Max	9.725	10.894	2.291
	Average	9.182	10.253	1.072
	Min	8.603	8.990	-0.143
	Std Dev	0.339	0.501	0.687

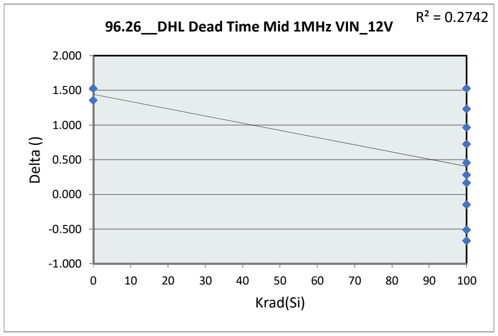


	96.25__DHL Dead Time Small 1MHz VIN_12	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.402	8.990
Average	10.405	10.223
Max	10.409	10.894
UL	15.000	15.000

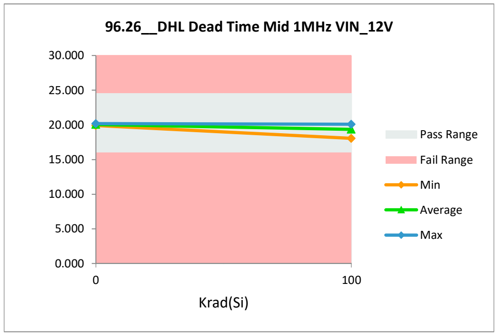


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.26__DHL Dead Time Mid 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24.5	24.5	
Min Limit		16	16	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.673	20.201	1.528
0	2	18.553	19.908	1.355
100	23	18.540	19.772	1.232
100	24	18.352	19.881	1.529
100	25	19.360	19.214	-0.146
100	26	18.834	18.999	0.165
100	27	19.150	19.876	0.726
100	48u	19.650	20.107	0.456
100	49u	18.712	18.041	-0.671
100	50u	18.849	19.132	0.283
100	51u	18.840	19.806	0.966
100	52u	19.313	18.801	-0.512
	Max	19.650	20.201	1.529
	Average	18.902	19.478	0.576
	Min	18.352	18.041	-0.671
	Std Dev	0.388	0.644	0.772



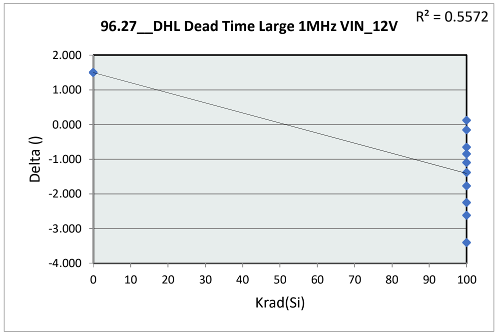
	96.26__DHL Dead Time Mid 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	19.908	18.041
Average	20.054	19.363
Max	20.201	20.107
UL	24.500	24.500



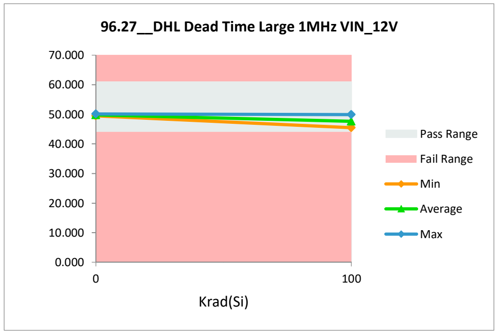
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	96.27__DHL Dead Time Large 1M	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	61	61
Min Limit	44	44

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	48.640	50.132	1.492
0	2	47.945	49.450	1.505
100	23	48.635	48.750	0.115
100	24	48.647	47.994	-0.653
100	25	49.680	47.426	-2.254
100	26	48.377	47.524	-0.853
100	27	48.986	48.829	-0.157
100	48u	50.995	49.899	-1.096
100	49u	48.425	45.800	-2.625
100	50u	48.740	46.971	-1.769
100	51u	48.744	47.354	-1.390
100	52u	48.901	45.490	-3.411
	Max	50.995	50.132	1.505
	Average	48.893	47.968	-0.925
	Min	47.945	45.490	-3.411
	Std Dev	0.779	1.497	1.516

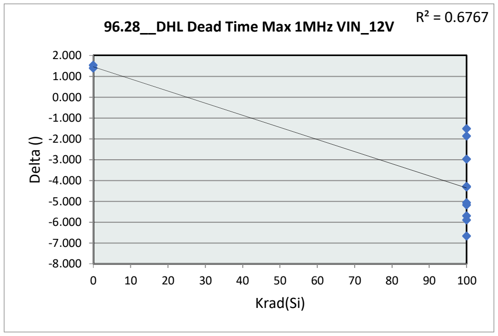


	96.27__DHL Dead Time Large 1MHz VIN_12	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	49.450	45.490
Average	49.791	47.604
Max	50.132	49.899
UL	61.000	61.000

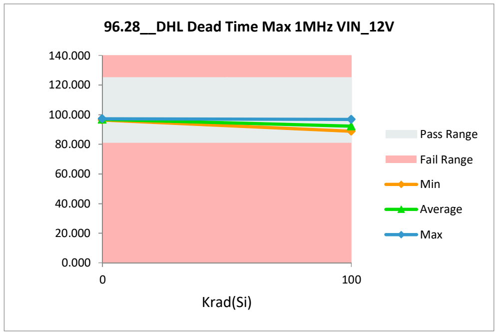


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.28__DHL Dead Time Max 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		125	125	
Min Limit		81	81	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	95.794	97.176	1.382
0	2	94.775	96.293	1.518
100	23	96.371	94.497	-1.874
100	24	96.733	92.407	-4.326
100	25	97.758	91.856	-5.902
100	26	95.072	92.084	-2.988
100	27	96.509	94.986	-1.523
100	48u	101.174	96.888	-4.286
100	49u	95.381	89.681	-5.700
100	50u	96.191	91.111	-5.080
100	51u	96.192	91.005	-5.187
100	52u	95.410	88.744	-6.666
	Max	101.174	97.176	1.518
	Average	96.447	93.061	-3.386
	Min	94.775	88.744	-6.666
	Std Dev	1.695	2.840	2.746

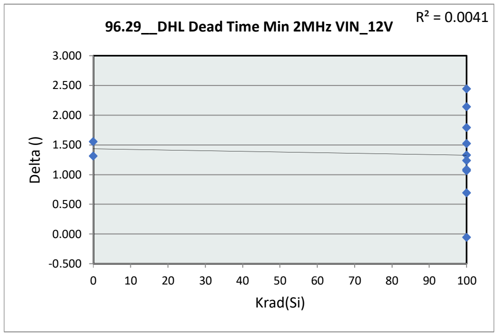


96.28__DHL Dead Time Max 1MHz VIN_12V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	96.293	88.744
Average	96.735	92.326
Max	97.176	96.888
UL	125.000	125.000

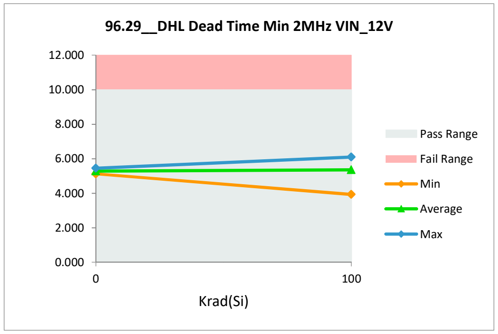


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.29__DHL Dead Time Min 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.811	5.123	1.312
0	2	3.890	5.443	1.553
100	23	3.700	5.223	1.523
100	24	3.463	5.907	2.444
100	25	4.226	5.462	1.236
100	26	4.295	4.989	0.694
100	27	4.286	5.373	1.087
100	48u	3.970	5.762	1.792
100	49u	3.977	3.924	-0.053
100	50u	3.816	5.145	1.329
100	51u	3.947	6.091	2.144
100	52u	4.556	5.620	1.064
	Max	4.556	6.091	2.444
	Average	3.995	5.338	1.344
	Min	3.463	3.924	-0.053
	Std Dev	0.300	0.556	0.651

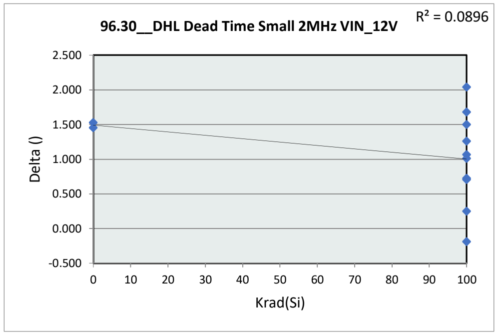


	96.29__DHL Dead Time Min 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.123	3.924
Average	5.283	5.349
Max	5.443	6.091
UL	10.000	10.000

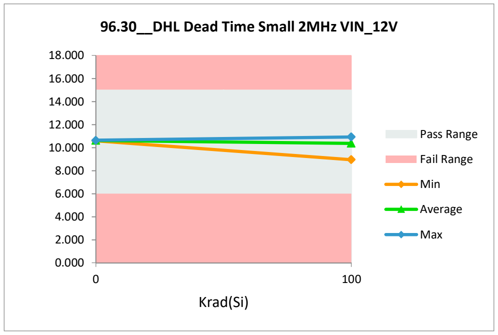


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.30__DHL Dead Time Small 2M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		15	15	
Min Limit		6	6	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	9.102	10.628	1.526
0	2	9.143	10.598	1.454
100	23	8.904	10.581	1.677
100	24	8.878	10.917	2.039
100	25	9.615	10.340	0.725
100	26	9.479	10.186	0.707
100	27	9.475	10.541	1.066
100	48u	9.622	10.882	1.260
100	49u	9.138	8.949	-0.189
100	50u	9.321	10.331	1.010
100	51u	9.279	10.776	1.497
100	52u	9.955	10.204	0.249
	Max	9.955	10.917	2.039
	Average	9.326	10.411	1.085
	Min	8.878	8.949	-0.189
	Std Dev	0.318	0.520	0.632

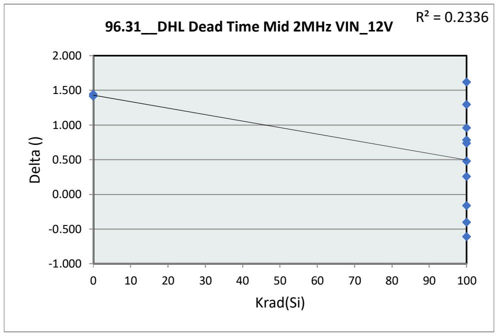


	96.30__DHL Dead Time Small 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.598	8.949
Average	10.613	10.371
Max	10.628	10.917
UL	15.000	15.000

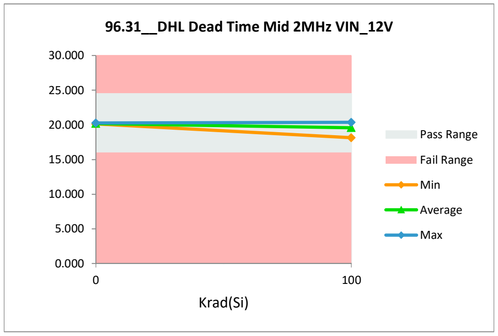


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.31__DHL Dead Time Mid 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24.5	24.5	
Min Limit		16	16	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.842	20.257	1.416
0	2	18.704	20.149	1.445
100	23	18.624	19.921	1.297
100	24	18.476	20.093	1.617
100	25	19.527	19.365	-0.162
100	26	18.923	19.401	0.478
100	27	19.344	20.130	0.786
100	48u	19.607	20.344	0.737
100	49u	18.768	18.159	-0.609
100	50u	19.093	19.350	0.258
100	51u	18.962	19.923	0.961
100	52u	19.393	18.993	-0.400
	Max	19.607	20.344	1.617
	Average	19.022	19.674	0.652
	Min	18.476	18.159	-0.609
	Std Dev	0.371	0.643	0.752

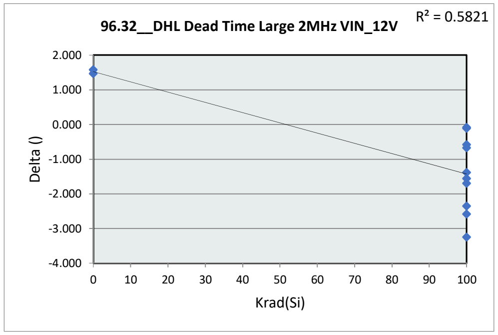


	96.31__DHL Dead Time Mid 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	20.149	18.159
Average	20.203	19.568
Max	20.257	20.344
UL	24.500	24.500

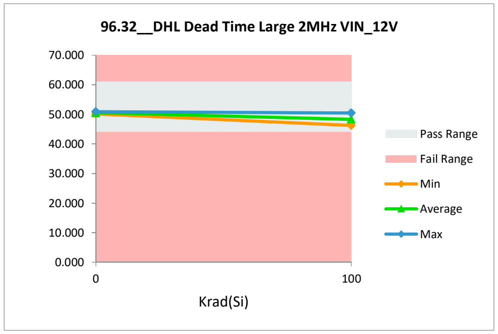


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.32__DHL Dead Time Large 2M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		61	61	
Min Limit		44	44	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	49.299	50.875	1.576
0	2	48.679	50.146	1.467
100	23	49.405	49.292	-0.113
100	24	49.367	48.780	-0.587
100	25	50.269	47.917	-2.352
100	26	49.028	48.356	-0.672
100	27	49.840	49.756	-0.083
100	48u	51.879	50.497	-1.382
100	49u	49.084	46.501	-2.584
100	50u	49.392	47.689	-1.703
100	51u	49.433	47.876	-1.557
100	52u	49.456	46.210	-3.246
	Max	51.879	50.875	1.576
	Average	49.594	48.658	-0.936
	Min	48.679	46.210	-3.246
	Std Dev	0.821	1.507	1.505

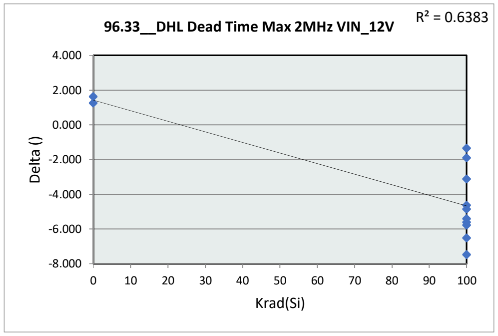


	96.32__DHL Dead Time Large 2MHz VIN_12	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	50.146	46.210
Average	50.511	48.288
Max	50.875	50.497
UL	61.000	61.000

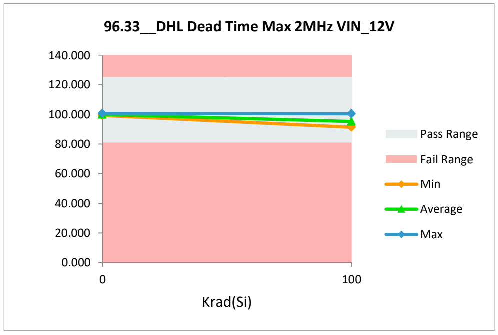


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		96.33__DHL Dead Time Max 2MH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	125	125	
	Min Limit	81	81	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	99.048	100.662	1.614
0	2	98.127	99.371	1.244
100	23	99.598	97.688	-1.910
100	24	100.159	95.308	-4.850
100	25	101.286	94.772	-6.514
100	26	98.224	95.105	-3.119
100	27	99.839	98.484	-1.354
100	48u	105.020	100.378	-4.642
100	49u	98.557	92.783	-5.774
100	50u	99.642	94.225	-5.417
100	51u	99.447	93.825	-5.621
100	52u	98.850	91.367	-7.483
	Max	105.020	100.662	1.614
	Average	99.816	96.164	-3.652
	Min	98.127	91.367	-7.483
	Std Dev	1.860	3.067	2.971

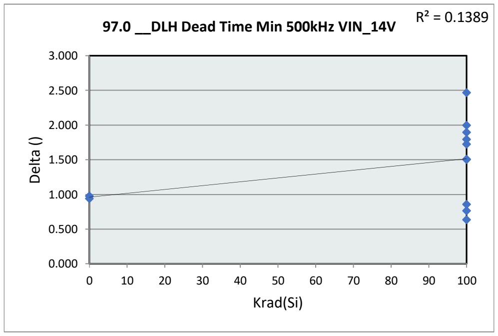


	96.33__DHL Dead Time Max 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	99.371	91.367
Average	100.017	95.394
Max	100.662	100.378
UL	125.000	125.000

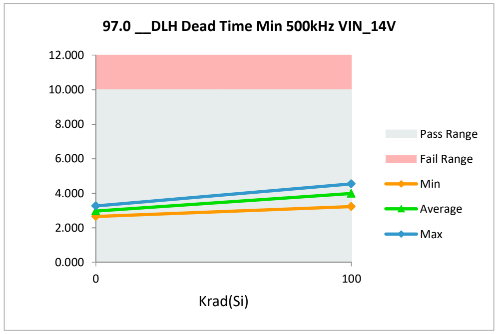


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.0 __DLH Dead Time Min 500k		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.283	3.260	0.977
0	2	1.717	2.660	0.942
100	23	2.968	3.603	0.635
100	24	3.246	4.102	0.856
100	25	2.553	4.277	1.724
100	26	1.919	3.714	1.795
100	27	2.549	4.545	1.997
100	48u	2.451	3.955	1.505
100	49u	2.462	3.225	0.763
100	50u	2.271	4.165	1.895
100	51u	2.393	3.900	1.507
100	52u	1.839	4.305	2.465
	Max	3.246	4.545	2.465
	Average	2.388	3.809	1.422
	Min	1.717	2.660	0.635
	Std Dev	0.440	0.545	0.579

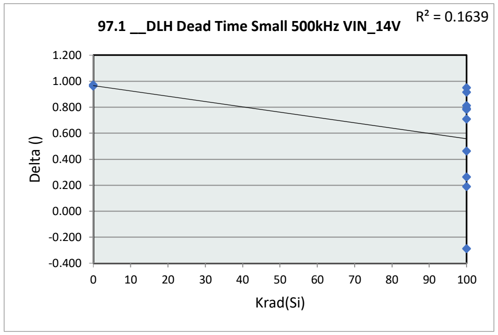


	97.0 __DLH Dead Time Min 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	2.660	3.225
Average	2.960	3.979
Max	3.260	4.545
UL	10.000	10.000

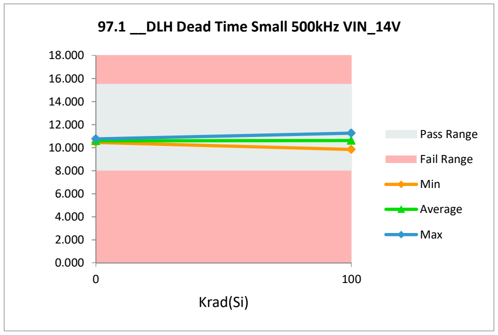


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.1 __DLH Dead Time Small 50		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	15.5	15.5	
	Min Limit	8	8	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	9.787	10.750	0.962
0	2	9.466	10.436	0.970
100	23	10.068	10.331	0.263
100	24	10.533	10.721	0.188
100	25	10.105	10.894	0.789
100	26	9.628	10.578	0.950
100	27	10.347	11.262	0.915
100	48u	10.054	10.515	0.461
100	49u	10.112	9.824	-0.288
100	50u	10.018	10.799	0.781
100	51u	10.007	10.713	0.707
100	52u	9.782	10.593	0.811
	Max	10.533	11.262	0.970
	Average	9.992	10.618	0.626
	Min	9.466	9.824	-0.288
	Std Dev	0.294	0.346	0.393

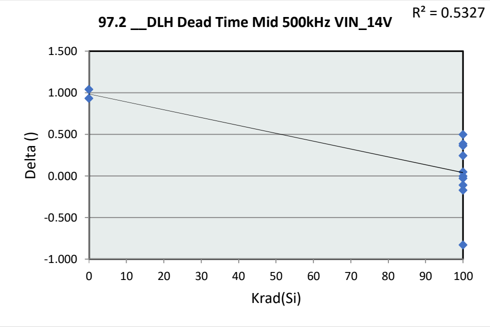


	97.1 __DLH Dead Time Small 500kHz VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.436	9.824
Average	10.593	10.623
Max	10.750	11.262
UL	15.500	15.500

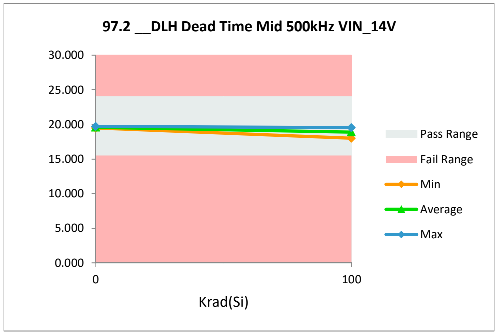


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.2 __DLH Dead Time Mid 500k		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24	24	
Min Limit		15.5	15.5	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.665	19.705	1.040
0	2	18.565	19.497	0.932
100	23	18.285	18.783	0.498
100	24	18.894	18.893	-0.001
100	25	19.099	19.072	-0.027
100	26	18.733	18.779	0.047
100	27	19.154	19.542	0.387
100	48u	18.717	18.547	-0.171
100	49u	18.841	18.015	-0.826
100	50u	18.803	19.046	0.243
100	51u	18.861	19.225	0.364
100	52u	18.856	18.748	-0.108
	Max	19.154	19.705	1.040
	Average	18.790	18.988	0.198
	Min	18.285	18.015	-0.826
	Std Dev	0.230	0.471	0.504

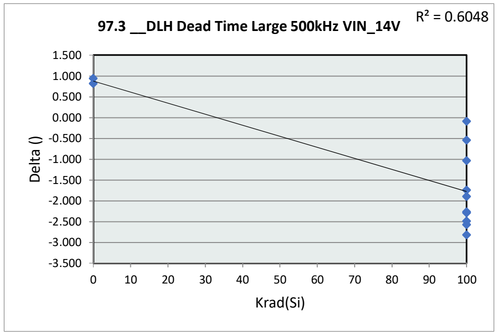


	97.2 __DLH Dead Time Mid 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	19.497	18.015
Average	19.601	18.865
Max	19.705	19.542
UL	24.000	24.000

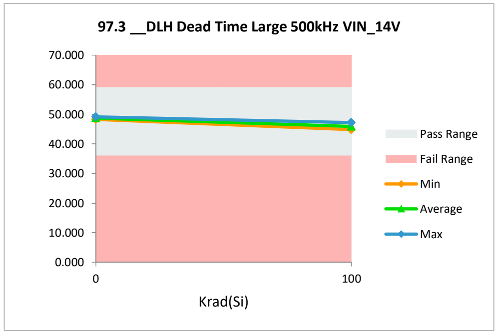


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.3 __DLH Dead Time Large 50		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		59	59	
Min Limit		36	36	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	47.517	48.332	0.815
0	2	48.182	49.122	0.940
100	23	45.446	45.351	-0.094
100	24	46.307	45.763	-0.544
100	25	48.542	46.051	-2.491
100	26	48.283	46.014	-2.268
100	27	48.369	46.625	-1.744
100	48u	47.377	45.084	-2.293
100	49u	47.707	44.888	-2.819
100	50u	47.610	45.712	-1.897
100	51u	48.238	47.204	-1.034
100	52u	48.590	46.014	-2.576
	Max	48.590	49.122	0.940
	Average	47.681	46.347	-1.334
	Min	45.446	44.888	-2.819
	Std Dev	0.952	1.287	1.328



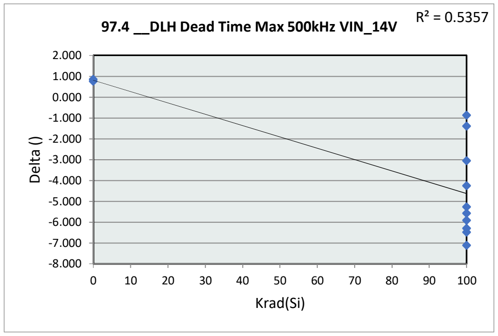
	97.3 __DLH Dead Time Large 500kHz VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	48.332	44.888
Average	48.727	45.871
Max	49.122	47.204
UL	59.000	59.000



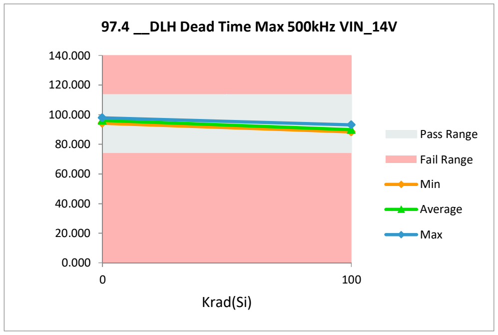
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	97.4 __DLH Dead Time Max 500k	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	113.5	113.5
Min Limit	74	74

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	93.518	94.276	0.758
0	2	97.044	97.893	0.848
100	23	89.387	88.505	-0.882
100	24	90.983	89.591	-1.391
100	25	96.376	90.069	-6.307
100	26	96.678	90.189	-6.489
100	27	95.253	90.996	-4.257
100	48u	94.064	88.479	-5.586
100	49u	94.662	88.738	-5.924
100	50u	94.311	89.042	-5.269
100	51u	96.141	93.077	-3.064
100	52u	97.950	90.824	-7.126
	Max	97.950	97.893	0.848
	Average	94.697	90.973	-3.724
	Min	89.387	88.479	-7.126
	Std Dev	2.507	2.822	2.889

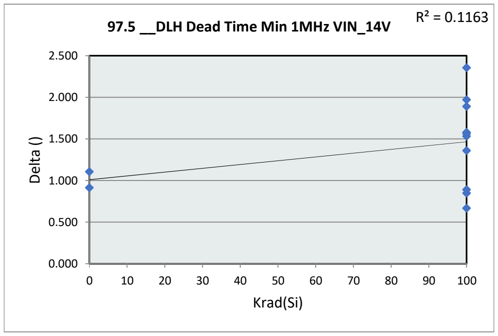


	97.4 __DLH Dead Time Max 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	94.276	88.479
Average	96.084	89.951
Max	97.893	93.077
UL	113.500	113.500

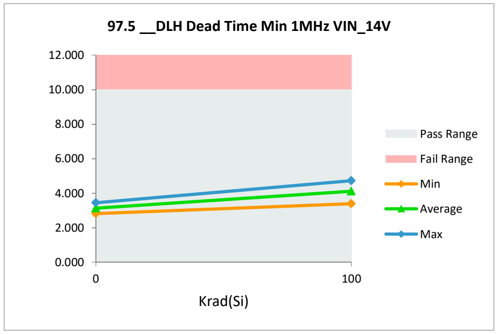


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.5 __DLH Dead Time Min 1MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.523	3.439	0.916
0	2	1.706	2.810	1.105
100	23	3.051	3.899	0.848
100	24	3.331	4.223	0.892
100	25	2.708	4.285	1.578
100	26	2.275	3.839	1.564
100	27	2.758	4.729	1.971
100	48u	2.589	4.124	1.535
100	49u	2.721	3.390	0.669
100	50u	2.481	4.371	1.890
100	51u	2.497	3.856	1.359
100	52u	2.048	4.406	2.358
	Max	3.331	4.729	2.358
	Average	2.557	3.948	1.390
	Min	1.706	2.810	0.669
	Std Dev	0.427	0.531	0.521

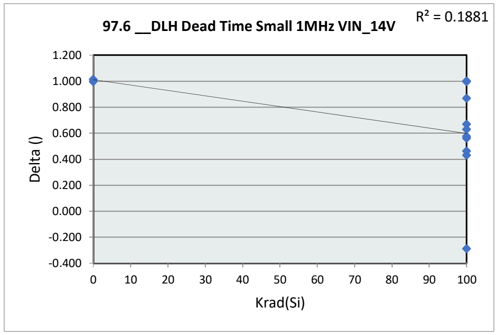


97.5 __DLH Dead Time Min 1MHz VIN_14V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	2.810	3.390
Average	3.125	4.112
Max	3.439	4.729
UL	10.000	10.000

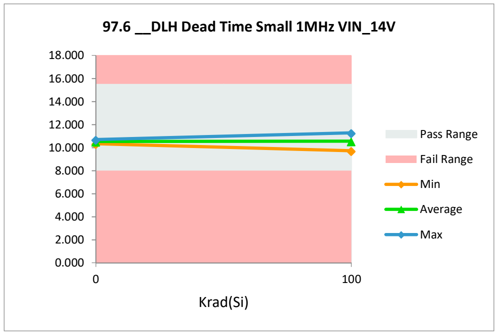


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.6 __DLH Dead Time Small 1M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		15.5	15.5	
Min Limit		8	8	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	9.705	10.709	1.003
0	2	9.330	10.349	1.020
100	23	9.925	10.492	0.567
100	24	10.298	10.736	0.438
100	25	10.091	10.675	0.583
100	26	9.450	10.458	1.007
100	27	10.266	11.269	1.003
100	48u	9.986	10.455	0.469
100	49u	10.004	9.723	-0.281
100	50u	9.985	10.861	0.876
100	51u	9.875	10.513	0.638
100	52u	9.744	10.419	0.675
	Max	10.298	11.269	1.020
	Average	9.888	10.555	0.667
	Min	9.330	9.723	-0.281
	Std Dev	0.293	0.363	0.371

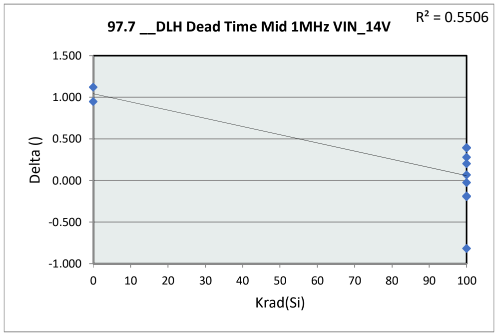


	97.6 __DLH Dead Time Small 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.350	9.723
Average	10.529	10.560
Max	10.709	11.269
UL	15.500	15.500

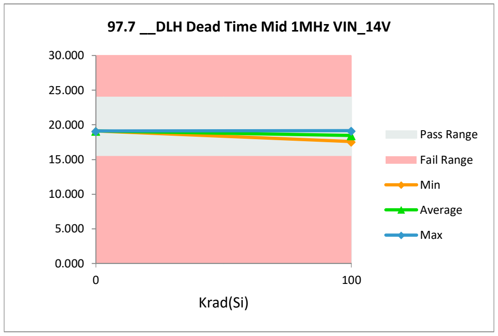


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.7 __DLH Dead Time Mid 1MHz		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	24	24	
	Min Limit	15.5	15.5	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.143	19.098	0.955
0	2	17.984	19.115	1.131
100	23	17.973	18.372	0.399
100	24	18.490	18.475	-0.015
100	25	18.732	18.552	-0.180
100	26	18.232	18.306	0.074
100	27	18.779	19.183	0.404
100	48u	18.315	18.128	-0.187
100	49u	18.414	17.606	-0.808
100	50u	18.374	18.775	0.401
100	51u	18.521	18.729	0.208
100	52u	18.314	18.601	0.288
	Max	18.779	19.183	1.131
	Average	18.356	18.578	0.222
	Min	17.973	17.606	-0.808
	Std Dev	0.255	0.453	0.516

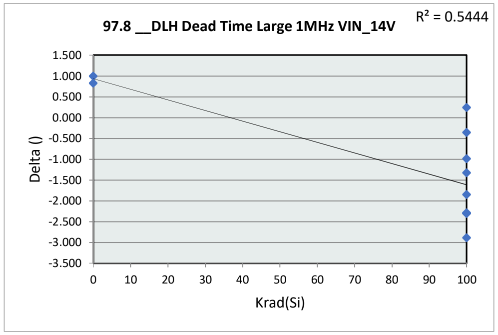


	97.7 __DLH Dead Time Mid 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	19.098	17.606
Average	19.106	18.473
Max	19.115	19.183
UL	24.000	24.000

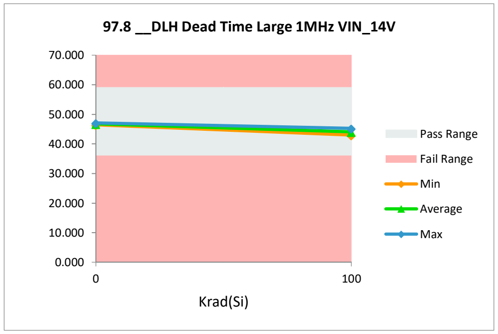


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.8 __DLH Dead Time Large 1M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		59	59	
Min Limit		36	36	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	45.601	46.446	0.845
0	2	46.073	47.092	1.019
100	23	43.383	43.646	0.263
100	24	44.288	43.951	-0.338
100	25	46.521	44.248	-2.273
100	26	46.394	44.113	-2.282
100	27	46.235	44.925	-1.310
100	48u	45.509	43.242	-2.267
100	49u	45.840	42.973	-2.867
100	50u	45.702	43.874	-1.827
100	51u	46.257	45.292	-0.965
100	52u	46.592	44.312	-2.280
	Max	46.592	47.092	1.019
	Average	45.700	44.509	-1.190
	Min	43.383	42.973	-2.867
	Std Dev	0.959	1.239	1.344

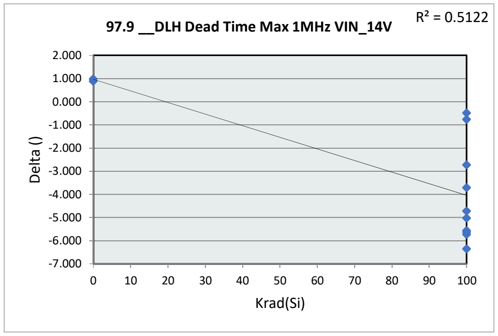


	97.8 __DLH Dead Time Large 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	46.446	42.973
Average	46.769	44.057
Max	47.092	45.292
UL	59.000	59.000

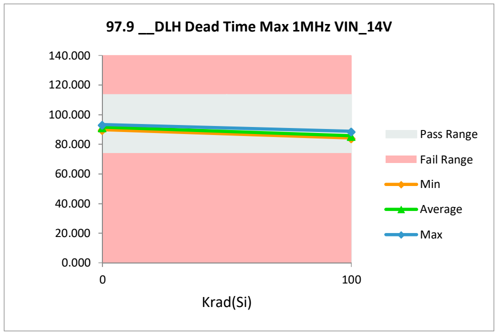


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.9 __DLH Dead Time Max 1MH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	113.5	113.5	
	Min Limit	74	74	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	88.905	89.923	1.018
0	2	92.330	93.248	0.918
100	23	84.773	84.329	-0.444
100	24	86.416	85.684	-0.732
100	25	91.501	85.896	-5.605
100	26	91.799	86.104	-5.695
100	27	90.579	86.906	-3.673
100	48u	89.377	84.394	-4.983
100	49u	89.838	84.305	-5.533
100	50u	89.570	84.890	-4.680
100	51u	91.409	88.716	-2.693
100	52u	93.031	86.707	-6.324
	Max	93.031	93.248	1.018
	Average	89.961	86.758	-3.202
	Min	84.773	84.305	-6.324
	Std Dev	2.419	2.685	2.722

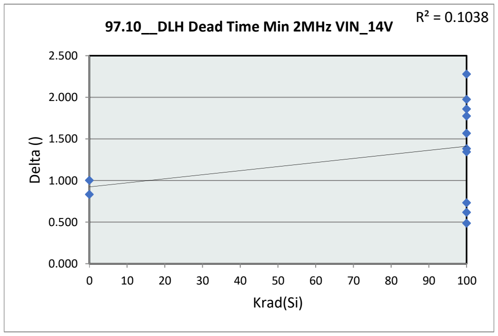


	97.9 __DLH Dead Time Max 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	89.923	84.305
Average	91.585	85.793
Max	93.248	88.716
UL	113.500	113.500

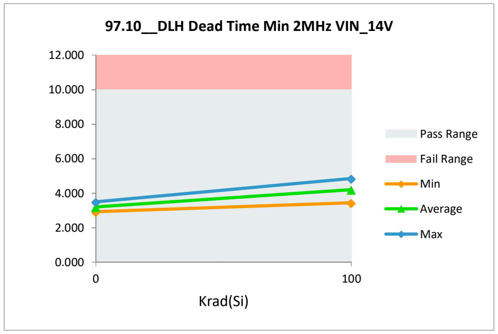


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.10__DLH Dead Time Min 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.485	3.496	1.011
0	2	2.092	2.932	0.839
100	23	3.289	3.916	0.627
100	24	3.624	4.120	0.496
100	25	2.875	4.450	1.575
100	26	2.213	3.997	1.784
100	27	2.867	4.851	1.984
100	48u	2.858	4.210	1.352
100	49u	2.705	3.447	0.742
100	50u	2.695	4.562	1.866
100	51u	2.548	3.940	1.392
100	52u	2.295	4.582	2.288
	Max	3.624	4.851	2.288
	Average	2.712	4.042	1.330
	Min	2.092	2.932	0.496
	Std Dev	0.439	0.550	0.586



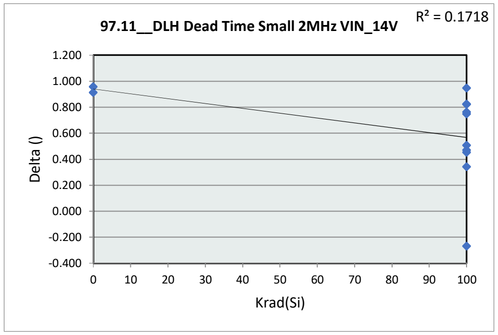
	97.10__DLH Dead Time Min 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	2.932	3.447
Average	3.214	4.207
Max	3.496	4.851
UL	10.000	10.000



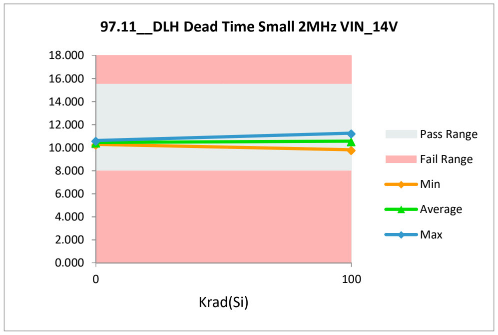
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	97.11__DLH Dead Time Small 2M	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	15.5	15.5
Min Limit	8	8

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	9.653	10.617	0.964
0	2	9.350	10.268	0.918
100	23	9.908	10.257	0.349
100	24	10.278	10.792	0.514
100	25	10.016	10.785	0.770
100	26	9.643	10.475	0.832
100	27	10.295	11.249	0.954
100	48u	9.957	10.416	0.458
100	49u	10.070	9.809	-0.261
100	50u	9.930	10.759	0.829
100	51u	9.972	10.448	0.477
100	52u	9.775	10.528	0.753
	Max	10.295	11.249	0.964
	Average	9.904	10.534	0.630
	Min	9.350	9.809	-0.261
	Std Dev	0.269	0.356	0.351

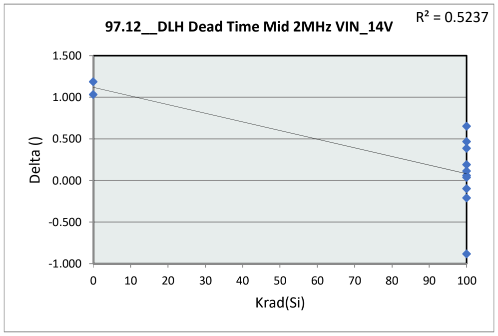


	97.11__DLH Dead Time Small 2MHz VIN_14	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.268	9.809
Average	10.443	10.552
Max	10.617	11.249
UL	15.500	15.500

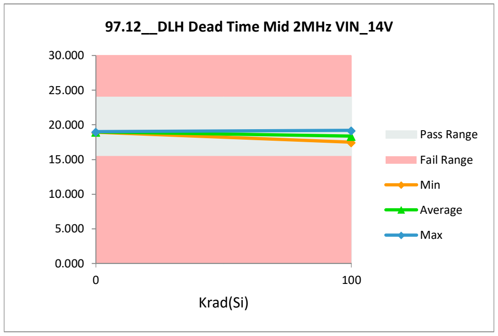


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.12__DLH Dead Time Mid 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24	24	
Min Limit		15.5	15.5	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	17.842	19.037	1.195
0	2	17.890	18.932	1.042
100	23	17.733	18.209	0.475
100	24	18.390	18.434	0.045
100	25	18.441	18.508	0.067
100	26	18.069	18.190	0.120
100	27	18.574	19.233	0.659
100	48u	18.189	18.101	-0.088
100	49u	18.383	17.510	-0.873
100	50u	18.426	18.626	0.200
100	51u	18.289	18.685	0.396
100	52u	18.436	18.237	-0.200
	Max	18.574	19.233	1.195
	Average	18.222	18.475	0.253
	Min	17.733	17.510	-0.873
	Std Dev	0.276	0.472	0.559

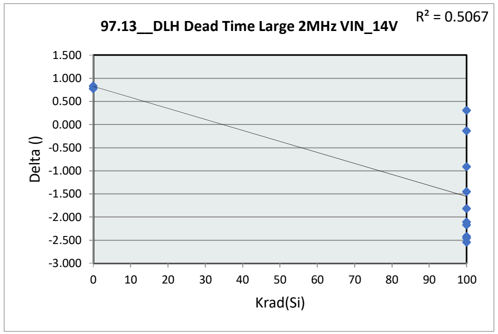


	97.12__DLH Dead Time Mid 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	18.932	17.510
Average	18.985	18.373
Max	19.037	19.233
UL	24.000	24.000

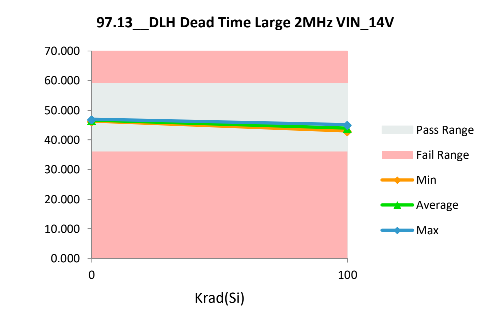


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.13__DLH Dead Time Large 2M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		59	59	
Min Limit		36	36	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	45.511	46.363	0.851
0	2	46.246	47.041	0.795
100	23	43.345	43.667	0.322
100	24	44.011	43.889	-0.123
100	25	46.486	44.086	-2.401
100	26	46.170	44.015	-2.155
100	27	46.292	44.859	-1.433
100	48u	45.551	43.458	-2.093
100	49u	45.576	43.050	-2.526
100	50u	45.523	43.720	-1.803
100	51u	46.101	45.204	-0.896
100	52u	46.607	44.168	-2.439
	Max	46.607	47.041	0.851
	Average	45.618	44.460	-1.158
	Min	43.345	43.050	-2.526
	Std Dev	0.995	1.203	1.300

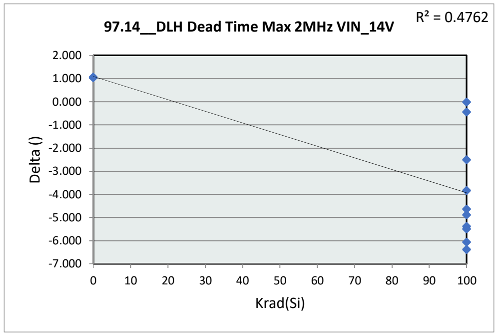


	97.13__DLH Dead Time Large 2MHz VIN_14	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	46.363	43.050
Average	46.702	44.011
Max	47.041	45.204
UL	59.000	59.000

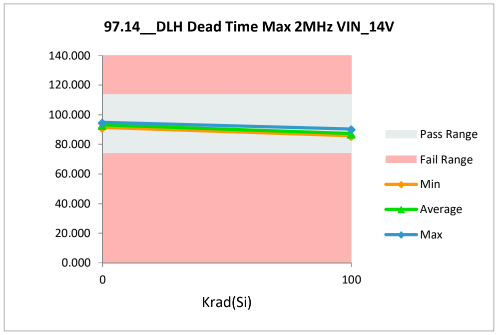


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.14__DLH Dead Time Max 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		113.5	113.5	
Min Limit		74	74	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	90.321	91.393	1.072
0	2	93.654	94.760	1.106
100	23	85.805	85.829	0.025
100	24	87.479	87.075	-0.404
100	25	92.836	87.378	-5.458
100	26	93.438	87.413	-6.024
100	27	91.961	88.163	-3.798
100	48u	90.562	85.715	-4.847
100	49u	91.202	85.848	-5.354
100	50u	90.774	86.177	-4.597
100	51u	92.839	90.373	-2.465
100	52u	94.386	88.037	-6.349
	Max	94.386	94.760	1.106
	Average	91.271	88.180	-3.091
	Min	85.805	85.715	-6.349
	Std Dev	2.547	2.730	2.829

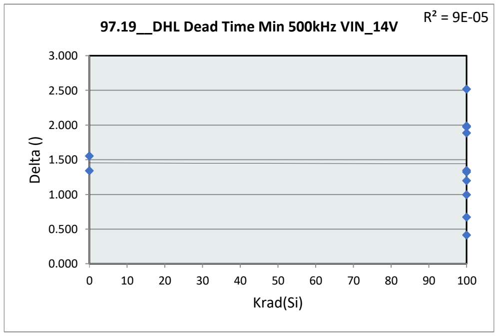


	97.14__DLH Dead Time Max 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	91.393	85.715
Average	93.076	87.201
Max	94.760	90.373
UL	113.500	113.500

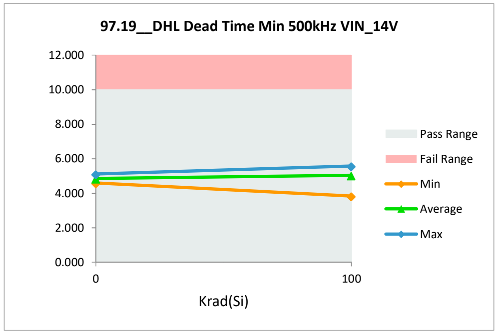


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.19__DHL Dead Time Min 500		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.256	4.604	1.349
0	2	3.561	5.123	1.562
100	23	3.008	4.991	1.983
100	24	3.040	5.566	2.526
100	25	3.858	5.190	1.332
100	26	3.820	4.504	0.684
100	27	3.819	5.174	1.355
100	48u	3.652	5.546	1.894
100	49u	3.422	3.845	0.423
100	50u	3.579	4.787	1.208
100	51u	3.576	5.574	1.997
100	52u	4.283	5.287	1.004
	Max	4.283	5.574	2.526
	Average	3.573	5.016	1.443
	Min	3.008	3.845	0.423
	Std Dev	0.362	0.513	0.594



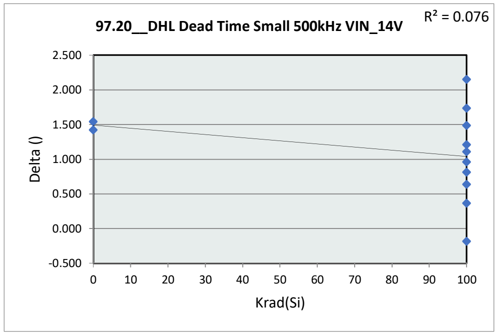
	97.19__DHL Dead Time Min 500kHz VIN_14	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.604	3.845
Average	4.863	5.047
Max	5.123	5.574
UL	10.000	10.000



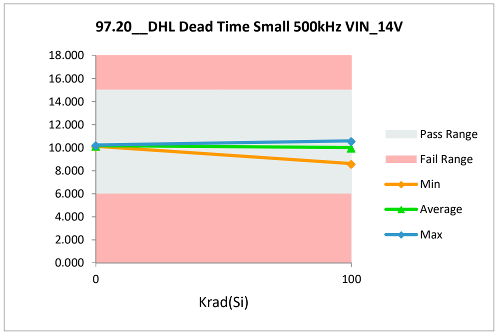
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	97.20__DHL Dead Time Small 50	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	15	15
Min Limit	6	6

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	8.569	10.122	1.553
0	2	8.796	10.228	1.432
100	23	8.396	10.145	1.749
100	24	8.413	10.576	2.163
100	25	9.148	9.972	0.824
100	26	9.059	9.709	0.650
100	27	9.066	10.188	1.122
100	48u	9.338	10.561	1.223
100	49u	8.778	8.605	-0.173
100	50u	8.862	9.833	0.971
100	51u	9.040	10.541	1.501
100	52u	9.490	9.870	0.380
	Max	9.490	10.576	2.163
	Average	8.913	10.029	1.116
	Min	8.396	8.605	-0.173
	Std Dev	0.344	0.533	0.638

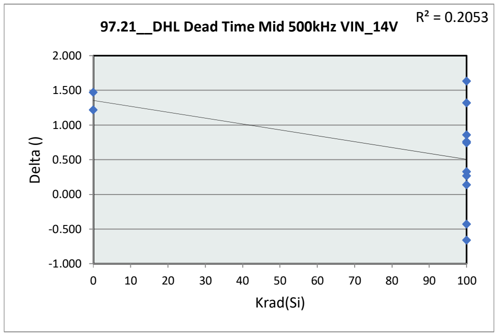


	97.20__DHL Dead Time Small 500kHz VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.122	8.605
Average	10.175	10.000
Max	10.228	10.576
UL	15.000	15.000

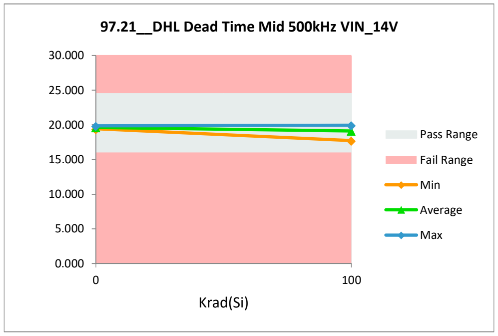


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.21__DHL Dead Time Mid 500		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	24.5	24.5	
	Min Limit	16	16	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.389	19.872	1.483
0	2	18.192	19.419	1.227
100	23	18.090	19.419	1.329
100	24	17.981	19.622	1.641
100	25	18.986	19.133	0.147
100	26	18.558	18.836	0.278
100	27	18.772	19.522	0.750
100	48u	19.195	19.968	0.772
100	49u	18.366	17.716	-0.650
100	50u	18.560	18.899	0.339
100	51u	18.661	19.526	0.865
100	52u	19.053	18.635	-0.418
	Max	19.195	19.968	1.641
	Average	18.567	19.214	0.647
	Min	17.981	17.716	-0.650
	Std Dev	0.386	0.623	0.730



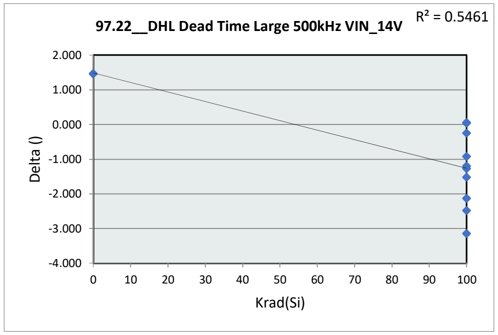
	97.21__DHL Dead Time Mid 500kHz VIN_14	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	19.419	17.716
Average	19.645	19.128
Max	19.872	19.968
UL	24.500	24.500



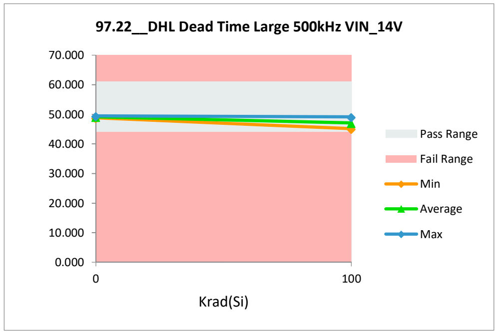
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	97.22__DHL Dead Time Large 50	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	61	61
Min Limit	44	44

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	48.036	49.525	1.489
0	2	47.369	48.850	1.482
100	23	48.150	48.231	0.081
100	24	48.040	47.812	-0.228
100	25	49.020	46.913	-2.107
100	26	47.857	46.963	-0.894
100	27	48.383	48.444	0.061
100	48u	50.366	49.194	-1.172
100	49u	47.803	45.343	-2.460
100	50u	48.056	46.559	-1.496
100	51u	48.154	46.906	-1.248
100	52u	48.293	45.170	-3.122
	Max	50.366	49.525	1.489
	Average	48.294	47.493	-0.801
	Min	47.369	45.170	-3.122
	Std Dev	0.759	1.423	1.445



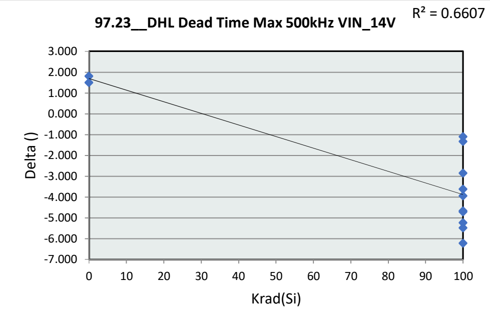
	97.22__DHL Dead Time Large 500kHz VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	48.850	45.170
Average	49.188	47.154
Max	49.525	49.194
UL	61.000	61.000



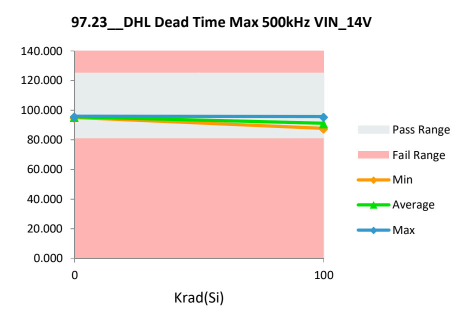
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	97.23__DHL Dead Time Max 500	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	125	125
Min Limit	81	81

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	94.085	95.936	1.852
0	2	93.441	94.977	1.536
100	23	94.873	93.584	-1.289
100	24	95.208	91.625	-3.583
100	25	96.174	90.727	-5.447
100	26	93.648	90.842	-2.806
100	27	94.893	93.826	-1.067
100	48u	99.533	95.634	-3.900
100	49u	93.904	88.715	-5.189
100	50u	94.661	89.980	-4.681
100	51u	94.685	90.059	-4.626
100	52u	93.944	87.769	-6.176
	Max	99.533	95.936	1.852
	Average	94.921	91.973	-2.948
	Min	93.441	87.769	-6.176
	Std Dev	1.639	2.748	2.667

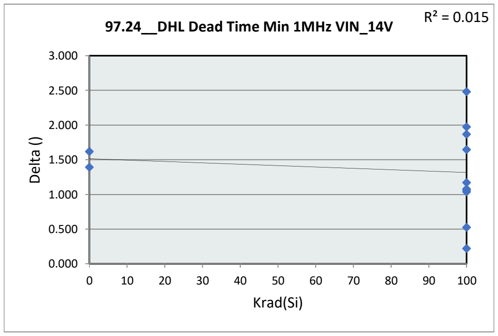


	97.23__DHL Dead Time Max 500kHz VIN_14	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	94.977	87.769
Average	95.457	91.276
Max	95.936	95.634
UL	125.000	125.000

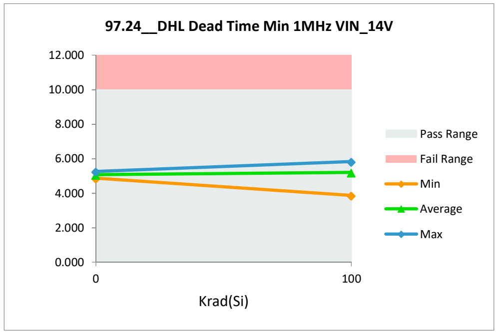


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.24__DHL Dead Time Min 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.473	4.873	1.400
0	2	3.645	5.270	1.626
100	23	3.419	5.295	1.876
100	24	3.305	5.793	2.489
100	25	4.106	5.151	1.045
100	26	4.187	4.722	0.535
100	27	4.116	5.205	1.090
100	48u	3.930	5.586	1.656
100	49u	3.644	3.876	0.231
100	50u	3.767	4.947	1.181
100	51u	3.857	5.838	1.981
100	52u	4.535	5.605	1.070
	Max	4.535	5.838	2.489
	Average	3.832	5.180	1.348
	Min	3.305	3.876	0.231
	Std Dev	0.362	0.542	0.627

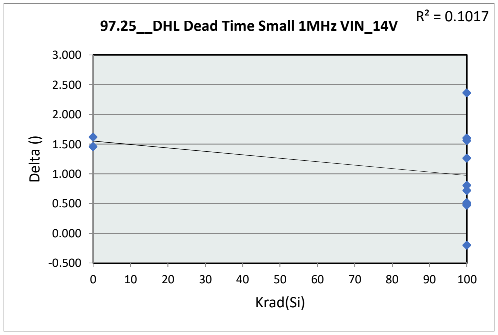


	97.24__DHL Dead Time Min 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.873	3.876
Average	5.072	5.202
Max	5.270	5.838
UL	10.000	10.000

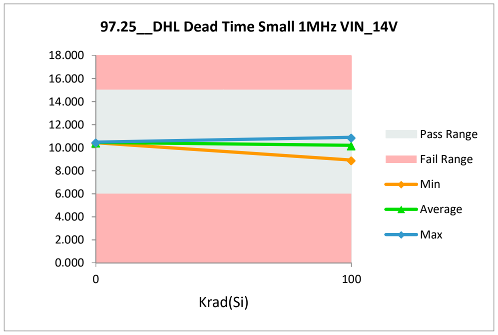


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.25__DHL Dead Time Small 1M		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	15	15	
	Min Limit	6	6	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	8.799	10.431	1.632
0	2	9.005	10.476	1.471
100	23	8.741	10.357	1.616
100	24	8.523	10.898	2.375
100	25	9.519	10.049	0.530
100	26	9.432	9.936	0.504
100	27	9.577	10.396	0.819
100	48u	9.352	10.631	1.279
100	49u	9.103	8.916	-0.187
100	50u	9.264	10.000	0.736
100	51u	9.097	10.674	1.576
100	52u	9.674	10.159	0.485
	Max	9.674	10.898	2.375
	Average	9.174	10.244	1.070
	Min	8.523	8.916	-0.187
	Std Dev	0.361	0.509	0.706

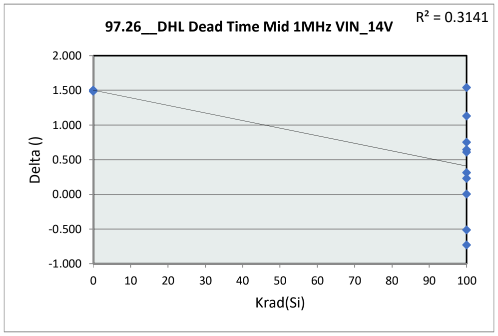


97.25__DHL Dead Time Small 1MHz VIN_14V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.431	8.916
Average	10.454	10.202
Max	10.476	10.898
UL	15.000	15.000

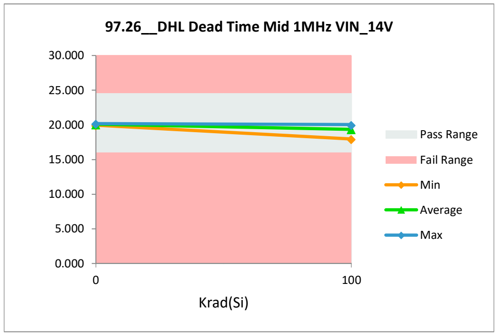


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.26__DHL Dead Time Mid 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24.5	24.5	
Min Limit		16	16	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.674	20.167	1.493
0	2	18.451	19.963	1.512
100	23	18.560	19.702	1.141
100	24	18.471	20.020	1.549
100	25	19.343	19.358	0.014
100	26	18.847	19.085	0.238
100	27	19.144	19.905	0.761
100	48u	19.390	20.007	0.617
100	49u	18.675	17.955	-0.720
100	50u	18.792	19.117	0.324
100	51u	18.977	19.630	0.653
100	52u	19.281	18.776	-0.505
	Max	19.390	20.167	1.549
	Average	18.884	19.474	0.590
	Min	18.451	17.955	-0.720
	Std Dev	0.339	0.650	0.761

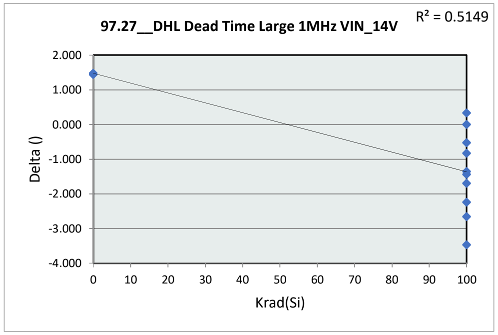


	97.26__DHL Dead Time Mid 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	19.963	17.955
Average	20.065	19.355
Max	20.167	20.020
UL	24.500	24.500

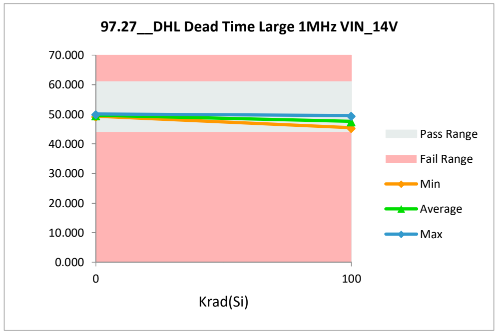


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.27__DHL Dead Time Large 1M		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	61	61	
	Min Limit	44	44	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	48.625	50.089	1.464
0	2	47.911	49.409	1.498
100	23	48.729	48.750	0.021
100	24	48.626	48.124	-0.502
100	25	49.635	47.421	-2.214
100	26	48.298	47.493	-0.805
100	27	48.717	49.079	0.362
100	48u	50.993	49.579	-1.415
100	49u	48.347	45.710	-2.636
100	50u	48.628	46.958	-1.669
100	51u	48.746	47.411	-1.334
100	52u	48.937	45.497	-3.440
	Max	50.993	50.089	1.498
	Average	48.849	47.960	-0.889
	Min	47.911	45.497	-3.440
	Std Dev	0.789	1.480	1.543

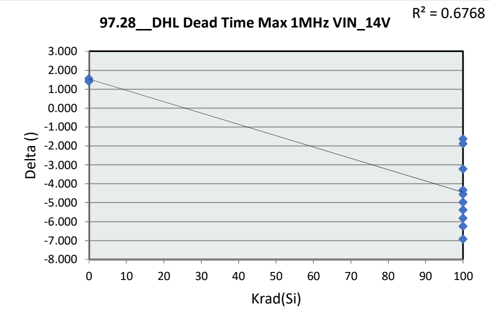


	97.27__DHL Dead Time Large 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	49.409	45.497
Average	49.749	47.602
Max	50.089	49.579
UL	61.000	61.000

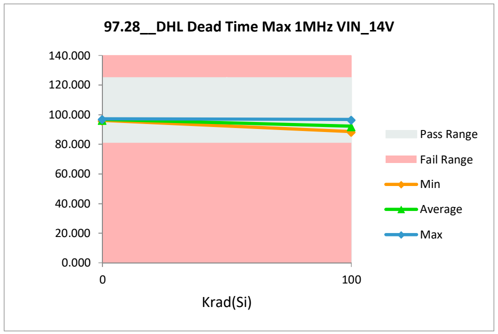


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.28__DHL Dead Time Max 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		125	125	
Min Limit		81	81	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	95.633	97.227	1.594
0	2	94.702	96.170	1.468
100	23	96.315	94.483	-1.832
100	24	96.529	92.245	-4.284
100	25	97.767	91.559	-6.208
100	26	95.075	91.896	-3.178
100	27	96.424	94.843	-1.581
100	48u	101.295	96.780	-4.515
100	49u	95.385	89.606	-5.778
100	50u	96.186	90.840	-5.346
100	51u	96.004	91.078	-4.925
100	52u	95.388	88.517	-6.871
	Max	101.295	97.227	1.594
	Average	96.392	92.937	-3.455
	Min	94.702	88.517	-6.871
	Std Dev	1.741	2.886	2.831

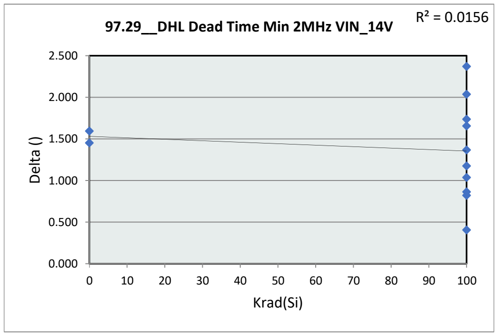


	97.28__DHL Dead Time Max 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	96.170	88.517
Average	96.699	92.185
Max	97.227	96.780
UL	125.000	125.000

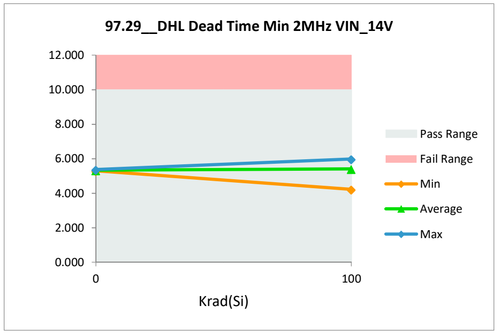


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.29__DHL Dead Time Min 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.693	5.297	1.604
0	2	3.911	5.372	1.461
100	23	3.598	5.260	1.663
100	24	3.595	5.975	2.380
100	25	4.446	5.276	0.830
100	26	4.257	5.130	0.873
100	27	4.185	5.230	1.045
100	48u	3.935	5.979	2.044
100	49u	3.808	4.220	0.413
100	50u	3.944	5.319	1.375
100	51u	4.095	5.840	1.745
100	52u	4.607	5.791	1.184
	Max	4.607	5.979	2.380
	Average	4.006	5.391	1.385
	Min	3.595	4.220	0.413
	Std Dev	0.323	0.482	0.552

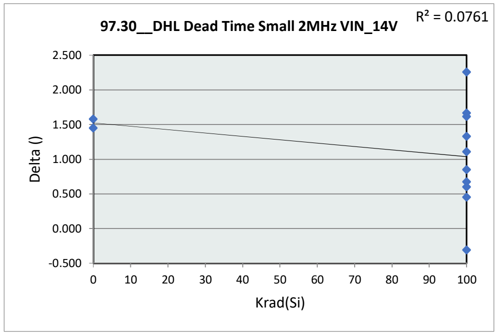


	97.29__DHL Dead Time Min 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.297	4.221
Average	5.334	5.402
Max	5.372	5.979
UL	10.000	10.000

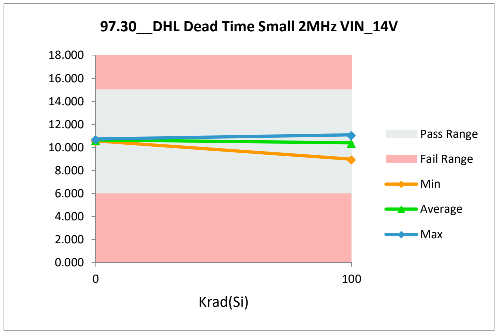


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.30__DHL Dead Time Small 2M		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	15	15	
	Min Limit	6	6	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	9.087	10.548	1.461
0	2	9.146	10.736	1.590
100	23	8.869	10.498	1.629
100	24	8.823	11.090	2.267
100	25	9.579	10.264	0.686
100	26	9.496	10.108	0.612
100	27	9.518	10.638	1.119
100	48u	9.534	10.877	1.343
100	49u	9.269	8.973	-0.296
100	50u	9.374	10.237	0.863
100	51u	9.212	10.892	1.681
100	52u	9.779	10.245	0.466
	Max	9.779	11.090	2.267
	Average	9.307	10.426	1.118
	Min	8.823	8.973	-0.296
	Std Dev	0.293	0.550	0.689

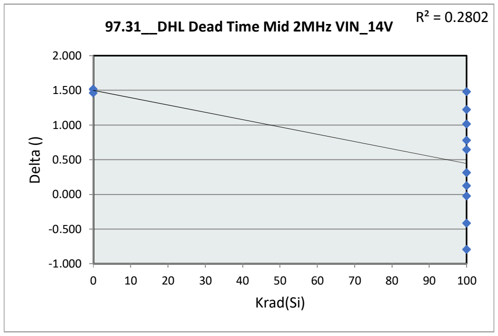


97.30__DHL Dead Time Small 2MHz VIN_14		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.548	8.973
Average	10.642	10.382
Max	10.736	11.090
UL	15.000	15.000

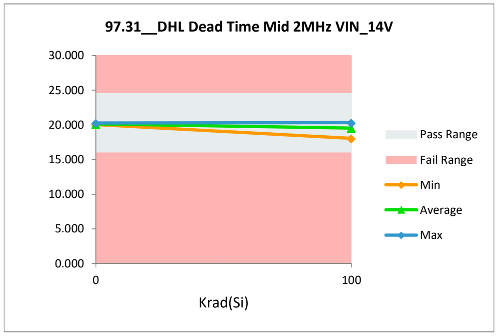


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.31__DHL Dead Time Mid 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24.5	24.5	
Min Limit		16	16	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	18.784	20.255	1.471
0	2	18.524	20.052	1.528
100	23	18.665	19.898	1.233
100	24	18.587	20.077	1.491
100	25	19.408	19.392	-0.016
100	26	18.967	19.099	0.132
100	27	19.286	20.073	0.787
100	48u	19.671	20.327	0.655
100	49u	18.820	18.035	-0.785
100	50u	19.004	19.325	0.321
100	51u	18.955	19.978	1.023
100	52u	19.320	18.916	-0.404
	Max	19.671	20.327	1.528
	Average	18.999	19.619	0.620
	Min	18.524	18.035	-0.785
	Std Dev	0.356	0.683	0.776

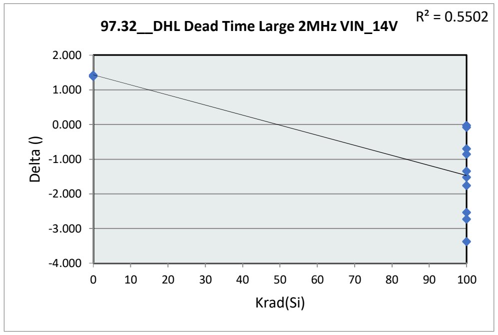


	97.31__DHL Dead Time Mid 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	20.052	18.035
Average	20.153	19.512
Max	20.255	20.327
UL	24.500	24.500

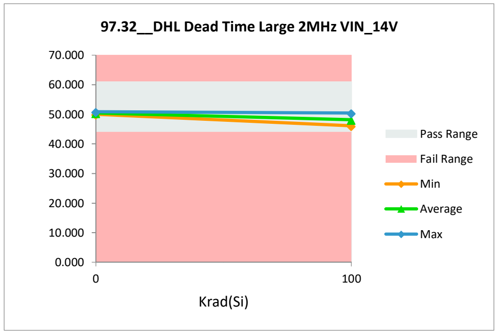


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.32__DHL Dead Time Large 2M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		61	61	
Min Limit		44	44	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	49.419	50.867	1.448
0	2	48.607	50.017	1.410
100	23	49.391	49.334	-0.057
100	24	49.310	48.631	-0.678
100	25	50.460	47.949	-2.511
100	26	49.007	48.177	-0.830
100	27	49.690	49.690	0.000
100	48u	51.797	50.474	-1.323
100	49u	49.045	46.342	-2.702
100	50u	49.334	47.595	-1.739
100	51u	49.457	47.959	-1.498
100	52u	49.447	46.092	-3.355
	Max	51.797	50.867	1.448
	Average	49.580	48.594	-0.986
	Min	48.607	46.092	-3.355
	Std Dev	0.825	1.531	1.521

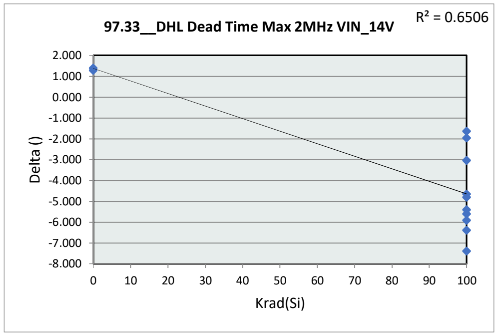


	97.32__DHL Dead Time Large 2MHz VIN_14	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	50.017	46.092
Average	50.442	48.224
Max	50.867	50.474
UL	61.000	61.000

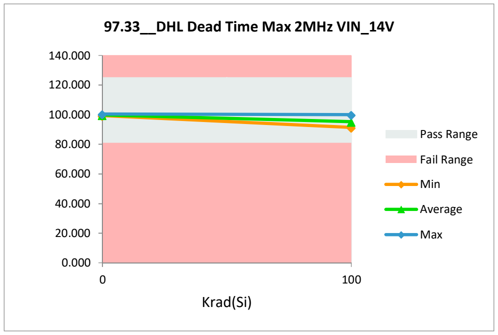


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		97.33__DHL Dead Time Max 2MH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	125	125	
	Min Limit	81	81	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	99.058	100.387	1.329
0	2	97.919	99.356	1.437
100	23	99.508	97.580	-1.929
100	24	99.944	95.334	-4.610
100	25	101.076	94.728	-6.347
100	26	98.129	95.126	-3.003
100	27	99.855	98.257	-1.599
100	48u	104.806	100.032	-4.774
100	49u	98.510	92.631	-5.880
100	50u	99.529	94.164	-5.365
100	51u	99.448	93.875	-5.573
100	52u	98.690	91.340	-7.350
	Max	104.806	100.387	1.437
	Average	99.706	96.067	-3.639
	Min	97.919	91.340	-7.350
	Std Dev	1.826	2.986	2.908

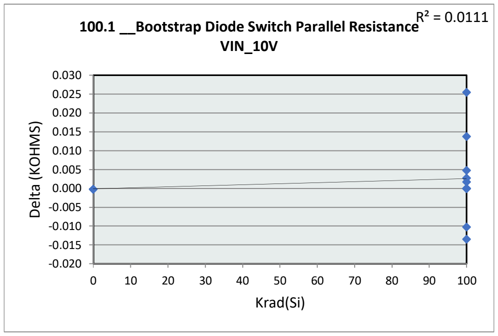


	97.33__DHL Dead Time Max 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	99.357	91.340
Average	99.872	95.306
Max	100.387	100.032
UL	125.000	125.000

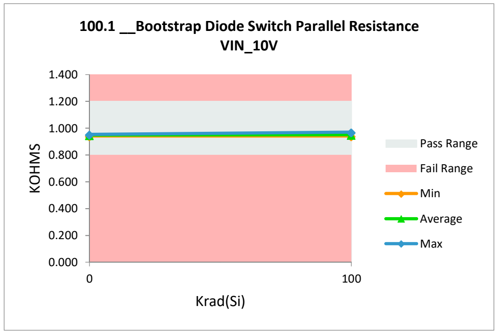


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		100.1 __Bootstrap Diode Switch		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		KOHMS	KOHMS	
Max Limit		1.2	1.2	
Min Limit		0.8	0.8	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	0.943	0.943	0.000
0	2	0.954	0.954	0.000
100	23	0.946	0.971	0.026
100	24	0.955	0.945	-0.010
100	25	0.945	0.947	0.003
100	26	0.955	0.942	-0.013
100	27	0.945	0.959	0.014
100	48u	0.960	0.960	0.000
100	49u	0.946	0.946	0.000
100	50u	0.943	0.943	0.000
100	51u	0.945	0.949	0.005
100	52u	0.949	0.951	0.002
	Max	0.960	0.971	0.026
	Average	0.949	0.951	0.002
	Min	0.943	0.942	-0.013
	Std Dev	0.006	0.009	0.010



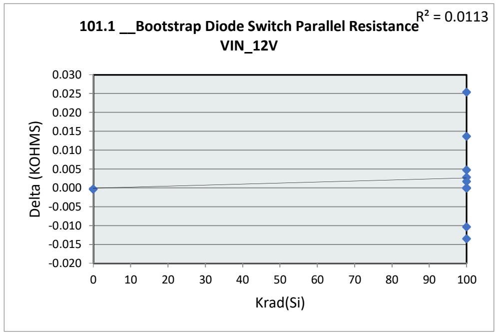
	100.1 __Bootstrap Diode Switch Parallel Res	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.2	KOHMS
Min Limit	0.8	KOHMS
Krad(Si)	0	100
LL	0.800	0.800
Min	0.943	0.942
Average	0.949	0.951
Max	0.954	0.972
UL	1.200	1.200



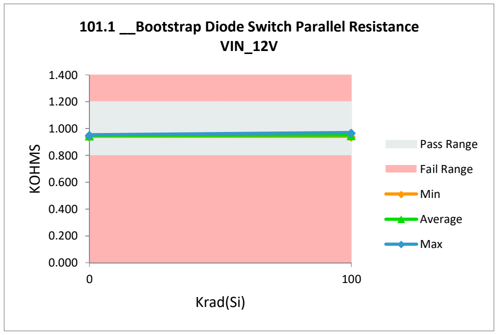
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	101.1 __Bootstrap Diode Switch	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	KOHMS	KOHMS
Max Limit	1.2	1.2
Min Limit	0.8	0.8

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	0.943	0.943	0.000
0	2	0.955	0.955	0.000
100	23	0.946	0.972	0.026
100	24	0.955	0.945	-0.010
100	25	0.945	0.948	0.003
100	26	0.955	0.942	-0.013
100	27	0.945	0.959	0.014
100	48u	0.960	0.960	0.000
100	49u	0.947	0.947	0.000
100	50u	0.943	0.943	0.000
100	51u	0.945	0.950	0.005
100	52u	0.949	0.951	0.002
	Max	0.960	0.972	0.026
	Average	0.949	0.951	0.002
	Min	0.943	0.942	-0.013
	Std Dev	0.006	0.009	0.010

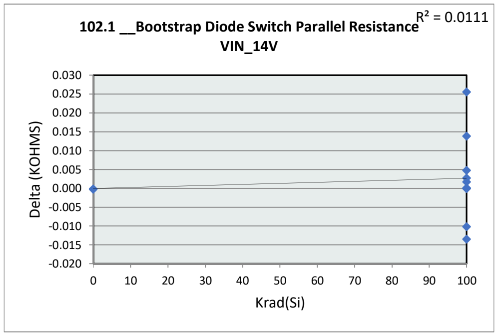


	101.1 __Bootstrap Diode Switch Parallel Res	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.2	KOHMS
Min Limit	0.8	KOHMS
Krad(Si)	0	100
LL	0.800	0.800
Min	0.943	0.942
Average	0.949	0.952
Max	0.955	0.972
UL	1.200	1.200

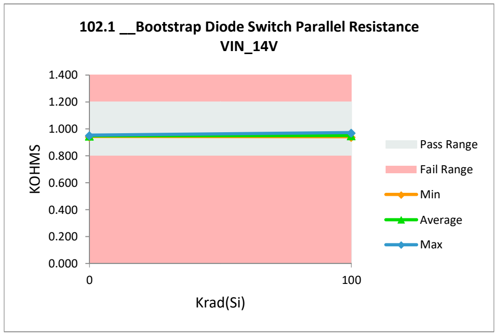


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		102.1 __Bootstrap Diode Switch		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		KOHMS	KOHMS	
Max Limit		1.2	1.2	
Min Limit		0.8	0.8	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	0.943	0.943	0.000
0	2	0.955	0.955	0.000
100	23	0.946	0.972	0.026
100	24	0.955	0.945	-0.010
100	25	0.945	0.948	0.003
100	26	0.955	0.942	-0.013
100	27	0.945	0.959	0.014
100	48u	0.960	0.961	0.000
100	49u	0.947	0.947	0.000
100	50u	0.943	0.944	0.000
100	51u	0.945	0.950	0.005
100	52u	0.950	0.951	0.002
	Max	0.960	0.972	0.026
	Average	0.949	0.951	0.002
	Min	0.943	0.942	-0.013
	Std Dev	0.006	0.009	0.010

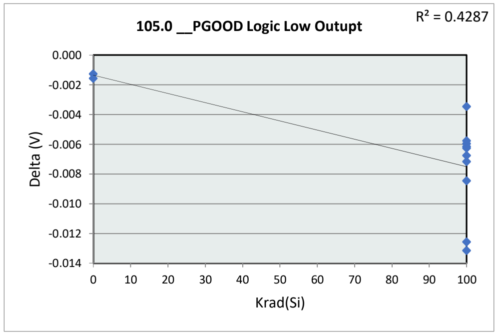


	102.1 __Bootstrap Diode Switch Parallel Res	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.2	KOHMS
Min Limit	0.8	KOHMS
Krad(Si)	0	100
LL	0.800	0.800
Min	0.943	0.942
Average	0.949	0.952
Max	0.955	0.972
UL	1.200	1.200

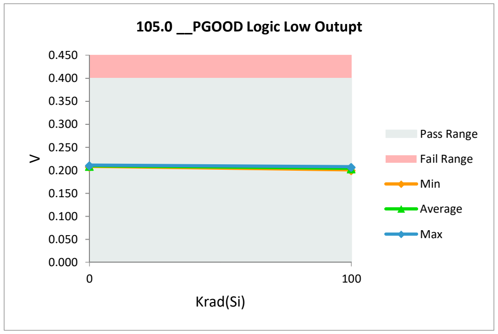


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		105.0 __PGOOD Logic Low Outu		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	0.4	0.4	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	0.210	0.209	-0.001
0	2	0.213	0.211	-0.001
100	23	0.214	0.201	-0.013
100	24	0.212	0.205	-0.007
100	25	0.216	0.207	-0.008
100	26	0.213	0.206	-0.007
100	27	0.215	0.203	-0.013
100	48u	0.210	0.205	-0.006
100	49u	0.211	0.205	-0.006
100	50u	0.208	0.202	-0.006
100	51u	0.211	0.205	-0.006
100	52u	0.211	0.208	-0.003
	Max	0.216	0.211	-0.001
	Average	0.212	0.206	-0.006
	Min	0.208	0.201	-0.013
	Std Dev	0.002	0.003	0.004

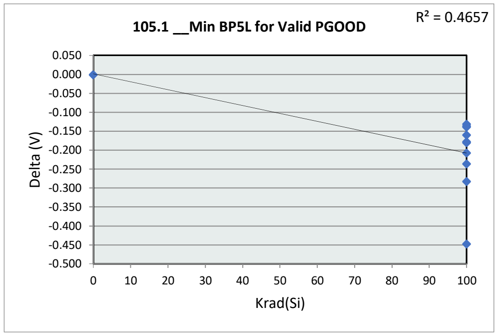


	105.0 __PGOOD Logic Low Outupt	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.4	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.209	0.201
Average	0.210	0.205
Max	0.211	0.208
UL	0.400	0.400

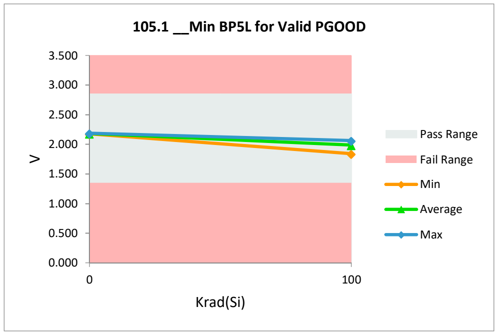


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		105.1 __Min BP5L for Valid PGO		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	2.85	2.85	
	Min Limit	1.35	1.35	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.174	2.175	0.001
0	2	2.185	2.186	0.001
100	23	2.287	1.842	-0.445
100	24	2.198	2.040	-0.158
100	25	2.254	2.020	-0.234
100	26	2.202	2.026	-0.176
100	27	2.194	1.914	-0.281
100	48u	2.094	1.957	-0.137
100	49u	2.172	2.037	-0.135
100	50u	2.123	1.994	-0.129
100	51u	2.243	2.064	-0.179
100	52u	2.183	1.977	-0.206
	Max	2.287	2.186	0.001
	Average	2.192	2.019	-0.173
	Min	2.094	1.842	-0.445
	Std Dev	0.053	0.097	0.119



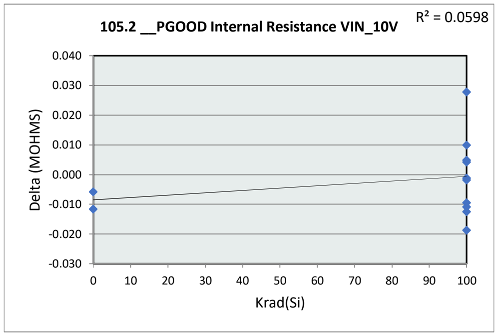
	105.1 __Min BP5L for Valid PGOOD	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.85	V
Min Limit	1.35	V
Krad(Si)	0	100
LL	1.350	1.350
Min	2.175	1.842
Average	2.180	1.987
Max	2.186	2.064
UL	2.850	2.850



TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

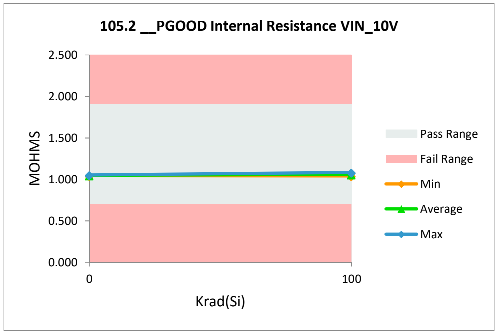
105.2 __PGOOD Internal Resista

Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		MOHMS	MOHMS	
Max Limit		1.9	1.9	
Min Limit		0.7	0.7	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.051	1.046	-0.006
0	2	1.065	1.054	-0.011
100	23	1.055	1.083	0.028
100	24	1.057	1.067	0.010
100	25	1.045	1.043	-0.002
100	26	1.054	1.044	-0.011
100	27	1.053	1.058	0.005
100	48u	1.093	1.084	-0.009
100	49u	1.073	1.061	-0.012
100	50u	1.058	1.057	-0.001
100	51u	1.052	1.056	0.004
100	52u	1.065	1.046	-0.018
	Max	1.093	1.084	0.028
	Average	1.060	1.058	-0.002
	Min	1.045	1.043	-0.018
	Std Dev	0.013	0.014	0.013



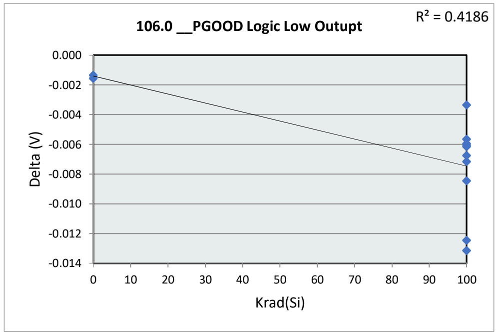
105.2 __PGOOD Internal Resistance VIN_10

Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.9	MOHMS
Min Limit	0.7	MOHMS
Krad(Si)	0	100
LL	0.700	0.700
Min	1.046	1.043
Average	1.050	1.060
Max	1.054	1.084
UL	1.900	1.900

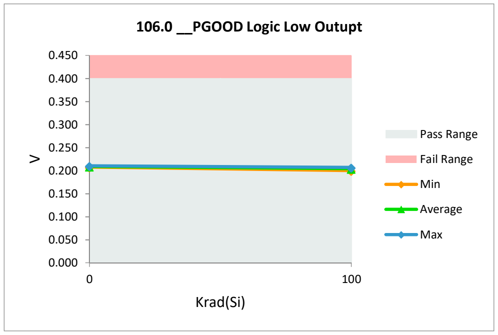


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		106.0 __PGOOD Logic Low Outu		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		0.4	0.4	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	0.209	0.208	-0.001
0	2	0.212	0.211	-0.001
100	23	0.213	0.200	-0.013
100	24	0.211	0.204	-0.007
100	25	0.215	0.206	-0.008
100	26	0.212	0.205	-0.007
100	27	0.214	0.202	-0.012
100	48u	0.209	0.204	-0.006
100	49u	0.210	0.204	-0.006
100	50u	0.208	0.202	-0.006
100	51u	0.211	0.205	-0.006
100	52u	0.211	0.207	-0.003
	Max	0.215	0.211	-0.001
	Average	0.211	0.205	-0.006
	Min	0.208	0.200	-0.013
	Std Dev	0.002	0.003	0.004

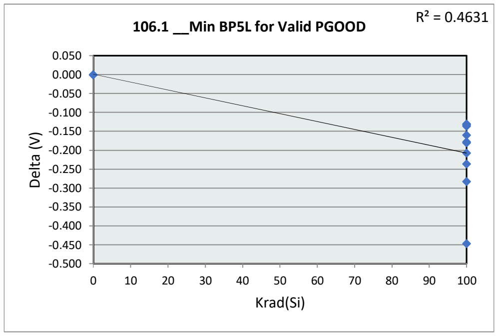


	106.0 __PGOOD Logic Low Outupt	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.4	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.208	0.200
Average	0.209	0.204
Max	0.211	0.207
UL	0.400	0.400

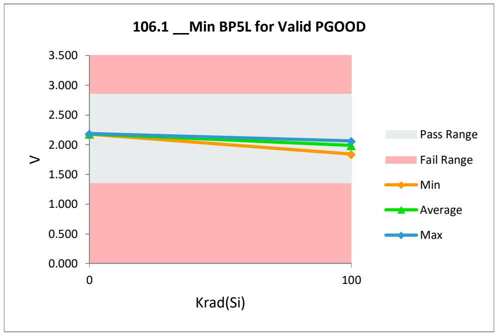


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		106.1 __Min BP5L for Valid PGO		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		2.85	2.85	
Min Limit		1.35	1.35	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.174	2.175	0.001
0	2	2.185	2.186	0.001
100	23	2.287	1.842	-0.445
100	24	2.199	2.040	-0.159
100	25	2.254	2.020	-0.234
100	26	2.203	2.027	-0.176
100	27	2.195	1.914	-0.281
100	48u	2.094	1.962	-0.132
100	49u	2.172	2.037	-0.135
100	50u	2.123	1.994	-0.129
100	51u	2.243	2.064	-0.179
100	52u	2.183	1.978	-0.206
	Max	2.287	2.186	0.001
	Average	2.193	2.020	-0.173
	Min	2.094	1.842	-0.445
	Std Dev	0.053	0.097	0.119



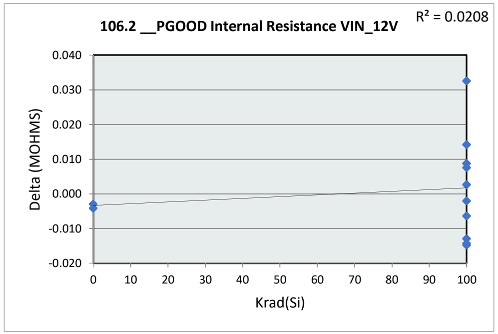
	106.1 __Min BP5L for Valid PGOOD	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.85	V
Min Limit	1.35	V
Krad(Si)	0	100
LL	1.350	1.350
Min	2.175	1.842
Average	2.181	1.988
Max	2.186	2.064
UL	2.850	2.850



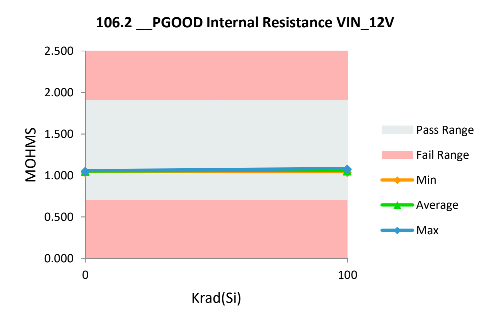
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	106.2 __PGOOD Internal Resista	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	MOHMS	MOHMS
Max Limit	1.9	1.9
Min Limit	0.7	0.7

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.049	1.046	-0.003
0	2	1.063	1.059	-0.004
100	23	1.052	1.085	0.033
100	24	1.061	1.069	0.008
100	25	1.043	1.046	0.003
100	26	1.059	1.045	-0.014
100	27	1.050	1.059	0.009
100	48u	1.097	1.083	-0.014
100	49u	1.071	1.065	-0.006
100	50u	1.057	1.056	-0.002
100	51u	1.049	1.064	0.014
100	52u	1.065	1.053	-0.013
	Max	1.097	1.085	0.033
	Average	1.060	1.061	0.001
	Min	1.043	1.045	-0.014
	Std Dev	0.014	0.013	0.014

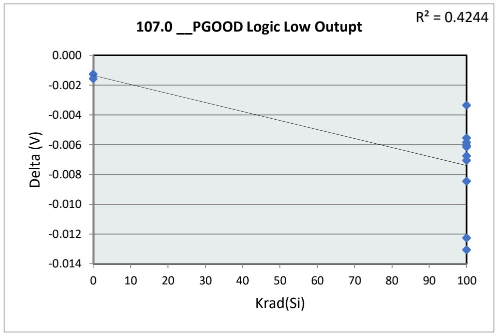


	106.2 __PGOOD Internal Resistance VIN_12	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.9	MOHMS
Min Limit	0.7	MOHMS
Krad(Si)	0	100
LL	0.700	0.700
Min	1.046	1.045
Average	1.053	1.062
Max	1.059	1.085
UL	1.900	1.900

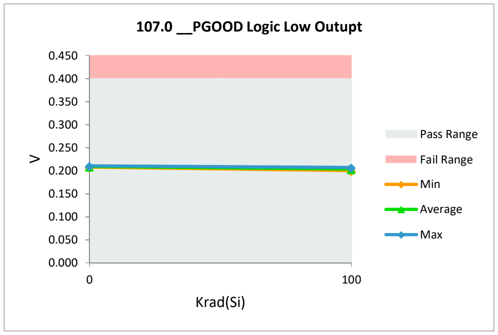


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		107.0 __PGOOD Logic Low Outu		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		0.4	0.4	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	0.209	0.208	-0.001
0	2	0.212	0.210	-0.001
100	23	0.213	0.200	-0.013
100	24	0.211	0.204	-0.007
100	25	0.215	0.206	-0.008
100	26	0.212	0.205	-0.007
100	27	0.214	0.202	-0.012
100	48u	0.209	0.204	-0.005
100	49u	0.210	0.204	-0.006
100	50u	0.207	0.201	-0.006
100	51u	0.210	0.204	-0.006
100	52u	0.210	0.207	-0.003
	Max	0.215	0.210	-0.001
	Average	0.211	0.205	-0.006
	Min	0.207	0.200	-0.013
	Std Dev	0.002	0.003	0.004

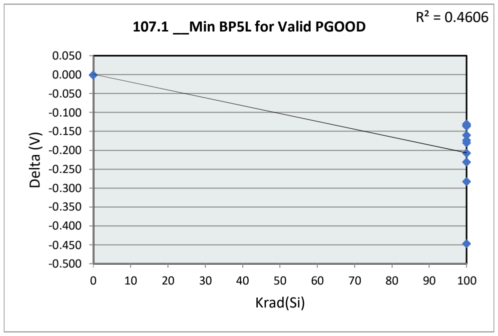


	107.0 __PGOOD Logic Low Outupt	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.4	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.208	0.200
Average	0.209	0.204
Max	0.210	0.207
UL	0.400	0.400

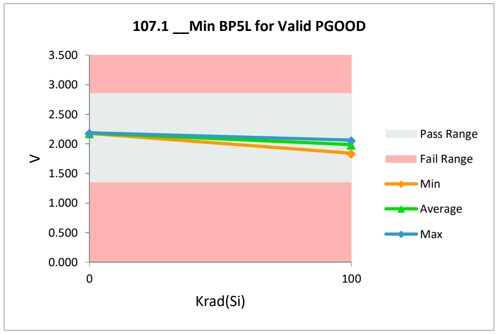


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		107.1 __Min BP5L for Valid PGOO		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		2.85	2.85	
Min Limit		1.35	1.35	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	2.174	2.175	0.001
0	2	2.185	2.186	0.001
100	23	2.288	1.842	-0.445
100	24	2.199	2.040	-0.159
100	25	2.254	2.025	-0.229
100	26	2.203	2.031	-0.172
100	27	2.195	1.914	-0.281
100	48u	2.095	1.963	-0.132
100	49u	2.172	2.037	-0.135
100	50u	2.123	1.994	-0.129
100	51u	2.243	2.064	-0.179
100	52u	2.184	1.977	-0.206
	Max	2.288	2.186	0.001
	Average	2.193	2.021	-0.172
	Min	2.095	1.842	-0.445
	Std Dev	0.053	0.097	0.119

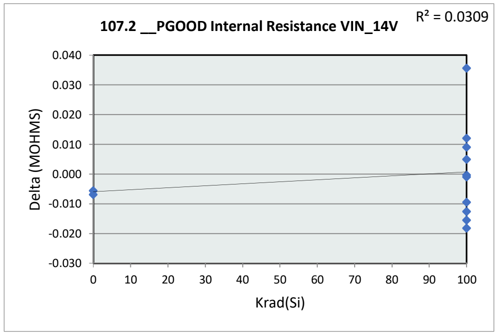


	107.1 __Min BP5L for Valid PGOOD	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.85	V
Min Limit	1.35	V
Krad(Si)	0	100
LL	1.350	1.350
Min	2.175	1.842
Average	2.181	1.989
Max	2.186	2.064
UL	2.850	2.850

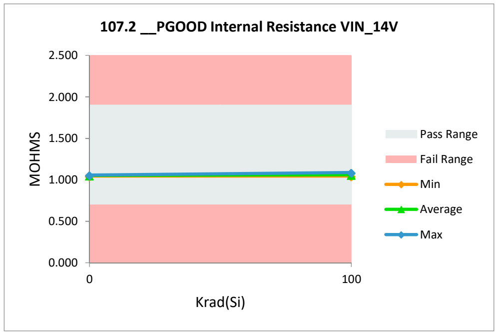


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		107.2 __PGOOD Internal Resista		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		MOHMS	MOHMS	
Max Limit		1.9	1.9	
Min Limit		0.7	0.7	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.052	1.047	-0.005
0	2	1.064	1.058	-0.007
100	23	1.054	1.090	0.036
100	24	1.057	1.070	0.012
100	25	1.048	1.047	-0.001
100	26	1.062	1.046	-0.015
100	27	1.051	1.061	0.009
100	48u	1.095	1.086	-0.009
100	49u	1.076	1.064	-0.012
100	50u	1.059	1.059	0.000
100	51u	1.054	1.059	0.005
100	52u	1.066	1.049	-0.018
	Max	1.095	1.090	0.036
	Average	1.062	1.061	0.000
	Min	1.048	1.046	-0.018
	Std Dev	0.013	0.014	0.015

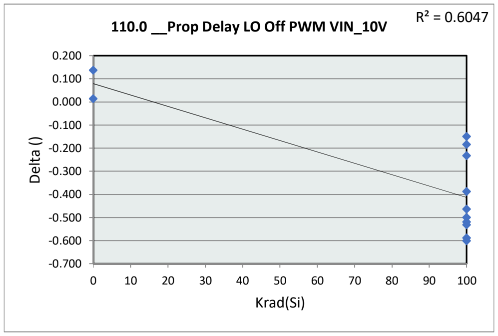


	107.2 __PGOOD Internal Resistance VIN_14	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.9	MOHMS
Min Limit	0.7	MOHMS
Krad(Si)	0	100
LL	0.700	0.700
Min	1.047	1.046
Average	1.052	1.063
Max	1.058	1.090
UL	1.900	1.900

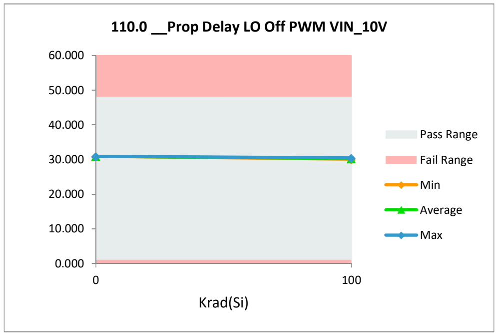


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		110.0 __Prop Delay LO Off PWM		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		48	48	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	30.896	30.913	0.017
0	2	30.822	30.963	0.140
100	23	30.609	30.427	-0.182
100	24	30.550	30.320	-0.230
100	25	30.746	30.149	-0.598
100	26	31.014	30.517	-0.497
100	27	30.575	30.113	-0.461
100	48u	30.555	30.408	-0.147
100	49u	30.640	30.124	-0.516
100	50u	30.680	30.295	-0.384
100	51u	30.894	30.308	-0.586
100	52u	30.815	30.287	-0.528
	Max	31.014	30.963	0.140
	Average	30.733	30.402	-0.331
	Min	30.550	30.113	-0.598
	Std Dev	0.155	0.279	0.246

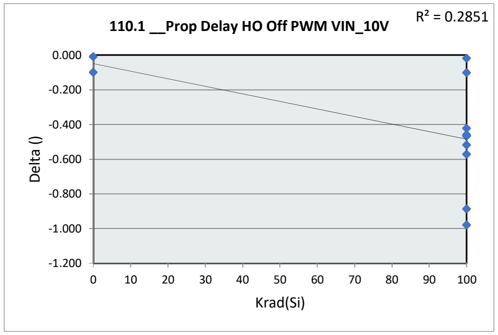


	110.0 __Prop Delay LO Off PWM VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	48	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	30.913	30.113
Average	30.938	30.295
Max	30.963	30.517
UL	48.000	48.000

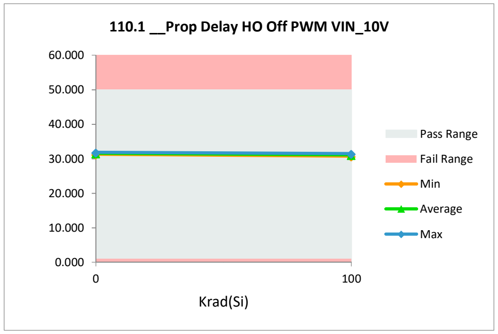


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		110.1 __Prop Delay HO Off PWM		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	50	50	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	31.879	31.875	-0.004
0	2	31.413	31.319	-0.094
100	23	31.842	31.381	-0.462
100	24	31.780	30.805	-0.975
100	25	31.603	31.037	-0.566
100	26	31.488	31.475	-0.013
100	27	31.655	31.194	-0.461
100	48u	31.732	31.278	-0.454
100	49u	31.465	30.951	-0.514
100	50u	31.466	31.048	-0.418
100	51u	31.617	30.736	-0.881
100	52u	31.099	31.003	-0.095
	Max	31.879	31.875	-0.004
	Average	31.587	31.175	-0.411
	Min	31.099	30.736	-0.975
	Std Dev	0.218	0.316	0.317

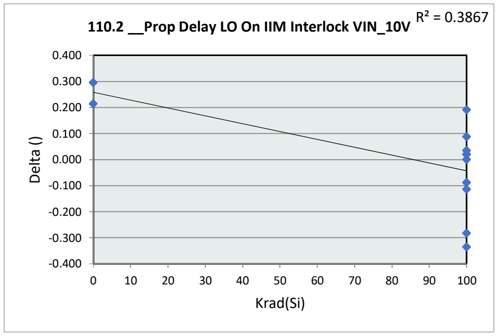


	110.1 __Prop Delay HO Off PWM VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	50	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	31.319	30.736
Average	31.597	31.091
Max	31.875	31.475
UL	50.000	50.000

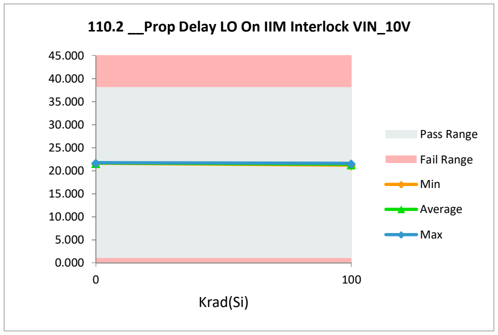


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		110.2 __Prop Delay LO On IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		38	38	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	21.501	21.718	0.218
0	2	21.319	21.619	0.299
100	23	21.396	21.487	0.092
100	24	21.468	21.383	-0.085
100	25	21.538	21.428	-0.110
100	26	21.542	21.545	0.003
100	27	21.592	21.260	-0.331
100	48u	21.457	21.495	0.038
100	49u	21.471	21.192	-0.278
100	50u	21.338	21.362	0.024
100	51u	21.449	21.472	0.023
100	52u	21.394	21.588	0.194
	Max	21.592	21.718	0.299
	Average	21.455	21.463	0.007
	Min	21.319	21.192	-0.331
	Std Dev	0.083	0.149	0.189

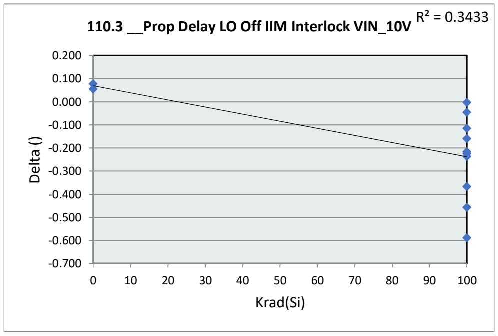


	110.2 __Prop Delay LO On IIM Interlock VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	21.619	21.192
Average	21.669	21.421
Max	21.718	21.588
UL	38.000	38.000

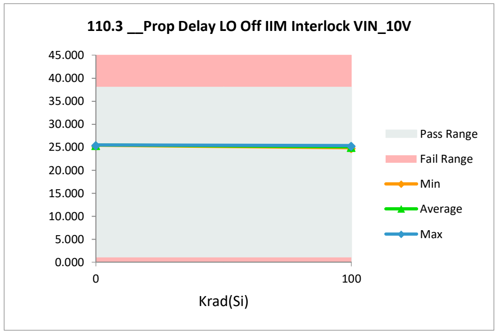


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		110.3 __Prop Delay LO Off IIM I		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	38	38	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	25.438	25.497	0.059
0	2	25.354	25.434	0.080
100	23	25.206	25.095	-0.111
100	24	25.268	25.055	-0.213
100	25	25.404	24.949	-0.454
100	26	25.577	25.355	-0.222
100	27	25.478	24.893	-0.585
100	48u	25.143	25.143	0.000
100	49u	25.227	24.863	-0.364
100	50u	25.225	24.991	-0.234
100	51u	25.331	25.288	-0.043
100	52u	25.461	25.305	-0.156
	Max	25.577	25.497	0.080
	Average	25.343	25.156	-0.187
	Min	25.143	24.863	-0.585
	Std Dev	0.132	0.216	0.204



	110.3 __Prop Delay LO Off IIM Interlock VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.434	24.863
Average	25.465	25.094
Max	25.497	25.355
UL	38.000	38.000

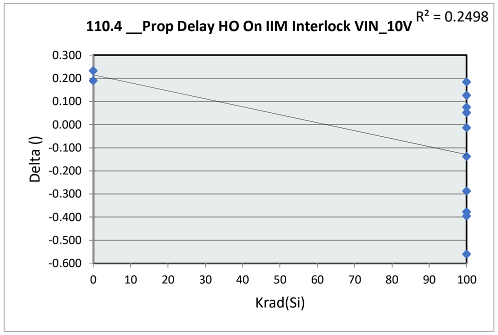


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

110.4 __Prop Delay HO On IIM I

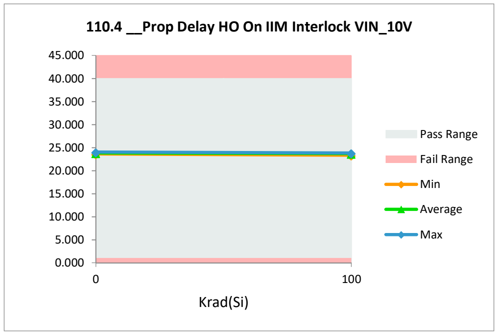
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	40	40
Min Limit	1	1

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	23.872	24.066	0.194
0	2	23.393	23.629	0.236
100	23	24.101	23.727	-0.374
100	24	24.308	23.751	-0.557
100	25	23.846	23.712	-0.134
100	26	23.644	23.832	0.188
100	27	23.771	23.825	0.055
100	48u	23.698	23.688	-0.011
100	49u	23.741	23.349	-0.392
100	50u	23.615	23.744	0.129
100	51u	23.775	23.492	-0.283
100	52u	23.558	23.637	0.079
	Max	24.308	24.066	0.236
	Average	23.777	23.704	-0.073
	Min	23.393	23.349	-0.557
	Std Dev	0.243	0.178	0.269



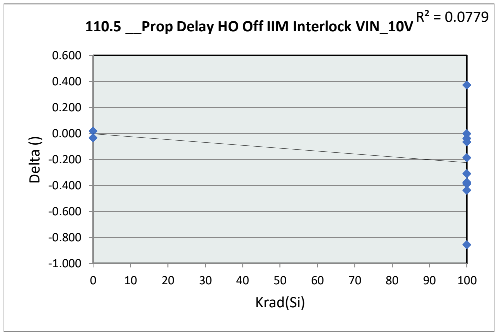
110.4 __Prop Delay HO On IIM Interlock VIN

Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	23.629	23.349
Average	23.847	23.676
Max	24.066	23.832
UL	40.000	40.000

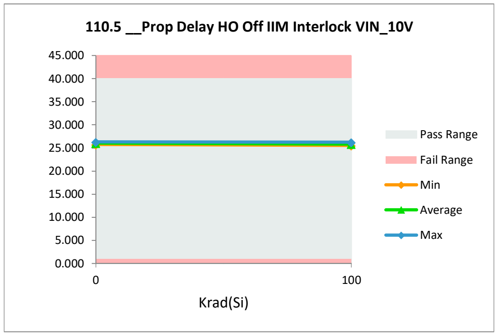


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		110.5 __Prop Delay HO Off IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		40	40	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	26.267	26.291	0.024
0	2	25.805	25.777	-0.028
100	23	26.334	25.951	-0.383
100	24	26.421	25.571	-0.851
100	25	26.093	25.912	-0.181
100	26	25.864	26.240	0.377
100	27	26.320	26.015	-0.304
100	48u	26.082	26.021	-0.061
100	49u	25.935	25.563	-0.372
100	50u	25.983	25.948	-0.035
100	51u	26.028	25.595	-0.433
100	52u	25.803	25.806	0.003
	Max	26.421	26.291	0.377
	Average	26.078	25.891	-0.187
	Min	25.803	25.563	-0.851
	Std Dev	0.214	0.241	0.309

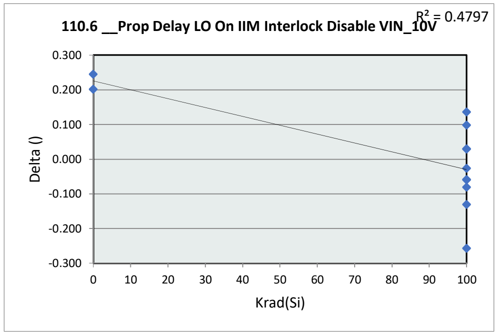


	110.5 __Prop Delay HO Off IIM Interlock VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.777	25.563
Average	26.034	25.862
Max	26.291	26.240
UL	40.000	40.000

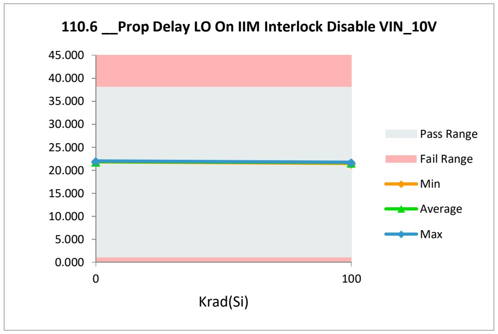


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		110.6 __Prop Delay LO On IIM I		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	38	38	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	21.751	21.998	0.247
0	2	21.600	21.804	0.204
100	23	21.652	21.684	0.031
100	24	21.682	21.714	0.032
100	25	21.733	21.676	-0.057
100	26	21.802	21.746	-0.056
100	27	21.834	21.579	-0.255
100	48u	21.586	21.724	0.138
100	49u	21.628	21.500	-0.128
100	50u	21.626	21.602	-0.024
100	51u	21.764	21.686	-0.078
100	52u	21.614	21.714	0.100
	Max	21.834	21.998	0.247
	Average	21.689	21.702	0.013
	Min	21.586	21.500	-0.255
	Std Dev	0.085	0.123	0.143

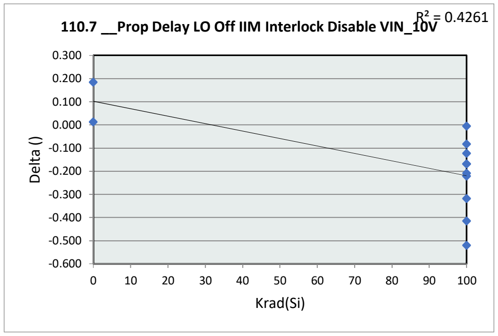


	110.6 __Prop Delay LO On IIM Interlock Dis	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	21.804	21.500
Average	21.901	21.663
Max	21.998	21.746
UL	38.000	38.000

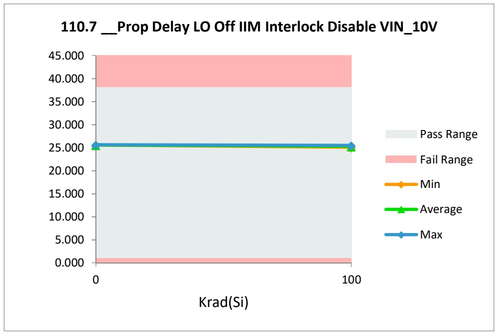


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		110.7 __Prop Delay LO Off IIM I		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	38	38	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	25.569	25.586	0.016
0	2	25.416	25.604	0.188
100	23	25.431	25.311	-0.120
100	24	25.396	25.230	-0.165
100	25	25.523	25.111	-0.412
100	26	25.721	25.503	-0.217
100	27	25.570	25.053	-0.517
100	48u	25.333	25.331	-0.002
100	49u	25.379	25.064	-0.315
100	50u	25.367	25.202	-0.165
100	51u	25.505	25.425	-0.080
100	52u	25.611	25.406	-0.205
	Max	25.721	25.604	0.188
	Average	25.485	25.319	-0.166
	Min	25.333	25.053	-0.517
	Std Dev	0.117	0.192	0.192

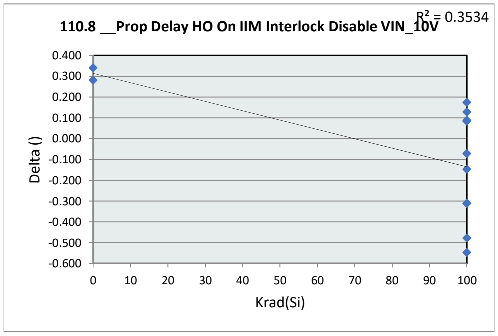


	110.7 __Prop Delay LO Off IIM Interlock Dis	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.586	25.054
Average	25.595	25.264
Max	25.604	25.503
UL	38.000	38.000

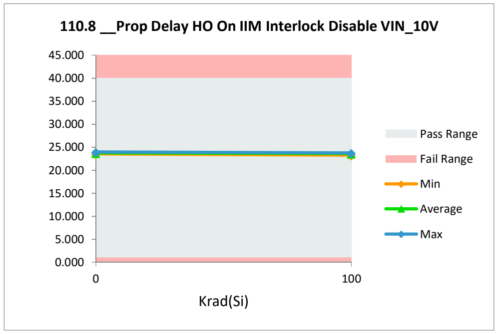


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		110.8 __Prop Delay HO On IIM I		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	40	40	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	23.676	23.959	0.284
0	2	23.190	23.534	0.344
100	23	23.989	23.681	-0.308
100	24	24.163	23.619	-0.544
100	25	23.796	23.651	-0.144
100	26	23.552	23.730	0.177
100	27	23.696	23.788	0.092
100	48u	23.717	23.650	-0.068
100	49u	23.720	23.246	-0.474
100	50u	23.598	23.685	0.087
100	51u	23.713	23.406	-0.307
100	52u	23.404	23.535	0.131
	Max	24.163	23.959	0.344
	Average	23.685	23.624	-0.061
	Min	23.190	23.246	-0.544
	Std Dev	0.250	0.182	0.294



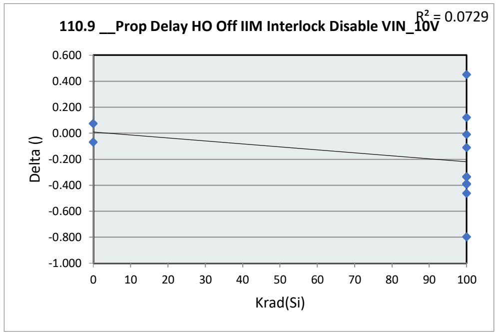
	110.8 __Prop Delay HO On IIM Interlock Dis	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	23.534	23.246
Average	23.747	23.599
Max	23.959	23.788
UL	40.000	40.000



TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

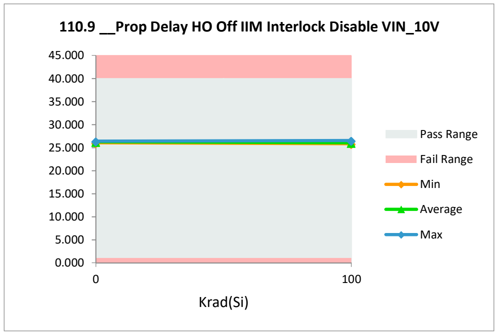
110.9 __Prop Delay HO Off IIM I

	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	40	40	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	26.467	26.405	-0.062
0	2	25.972	26.052	0.080
100	23	26.477	26.148	-0.329
100	24	26.645	25.856	-0.789
100	25	26.367	26.039	-0.328
100	26	26.047	26.504	0.457
100	27	26.520	26.134	-0.385
100	48u	26.304	26.200	-0.104
100	49u	26.236	25.853	-0.383
100	50u	26.175	26.173	-0.002
100	51u	26.288	25.832	-0.456
100	52u	25.933	26.060	0.127
	Max	26.645	26.504	0.457
	Average	26.286	26.105	-0.181
	Min	25.933	25.832	-0.789
	Std Dev	0.225	0.208	0.329



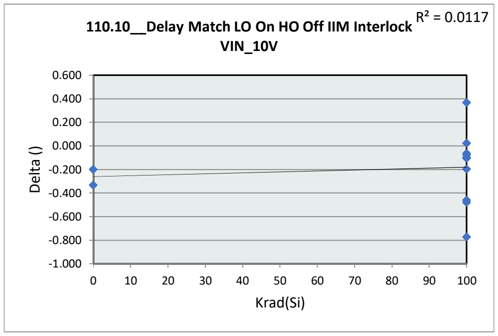
110.9 __Prop Delay HO Off IIM Interlock Dis

Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	26.053	25.832
Average	26.229	26.080
Max	26.405	26.505
UL	40.000	40.000

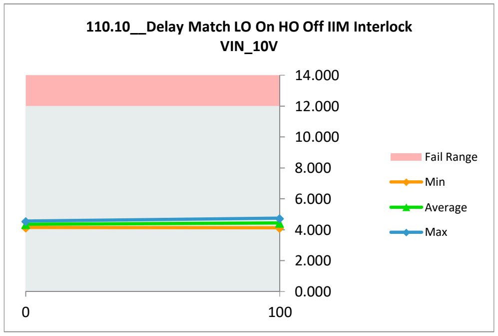


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		110.10__Delay Match LO On HO		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	12	12	
	Min Limit			
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.766	4.573	-0.194
0	2	4.486	4.158	-0.328
100	23	4.938	4.464	-0.474
100	24	4.953	4.188	-0.766
100	25	4.555	4.484	-0.071
100	26	4.322	4.695	0.373
100	27	4.727	4.755	0.027
100	48u	4.625	4.526	-0.099
100	49u	4.464	4.371	-0.093
100	50u	4.644	4.586	-0.058
100	51u	4.579	4.123	-0.456
100	52u	4.410	4.218	-0.192
	Max	4.953	4.755	0.373
	Average	4.623	4.428	-0.194
	Min	4.322	4.123	-0.766
	Std Dev	0.197	0.215	0.289

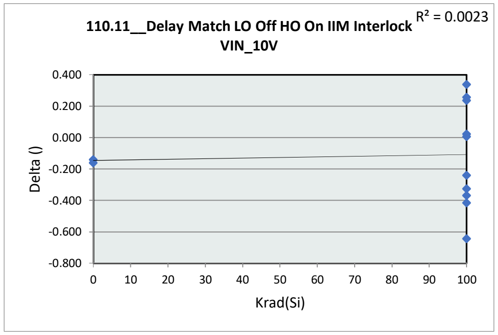


	110.10__Delay Match LO On HO Off IIM Inte	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit		
Krad(Si)	0	100
LL		
Min	4.158	4.123
Average	4.365	4.441
Max	4.573	4.755
UL	12.000	12.000

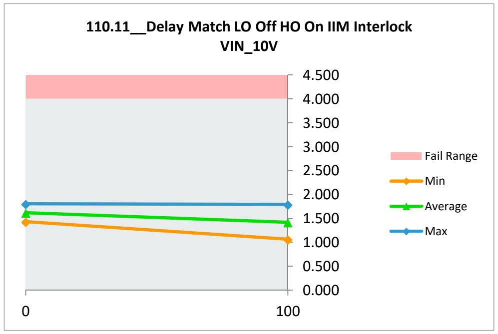


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		110.11__Delay Match LO Off HO		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		4	4	
Min Limit				
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.566	1.431	-0.135
0	2	1.961	1.805	-0.156
100	23	1.106	1.368	0.262
100	24	0.960	1.304	0.343
100	25	1.557	1.237	-0.320
100	26	1.933	1.523	-0.410
100	27	1.708	1.068	-0.640
100	48u	1.445	1.456	0.010
100	49u	1.486	1.514	0.028
100	50u	1.610	1.247	-0.363
100	51u	1.556	1.796	0.241
100	52u	1.903	1.668	-0.235
	Max	1.961	1.805	0.343
	Average	1.566	1.451	-0.114
	Min	0.960	1.068	-0.640
	Std Dev	0.305	0.226	0.301

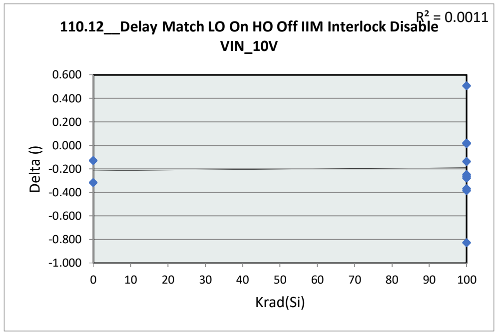


	110.11__Delay Match LO Off HO On IIM Inte	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	4	
Min Limit		
Krad(Si)	0	100
LL		
Min	1.431	1.068
Average	1.618	1.418
Max	1.805	1.797
UL	4.000	4.000

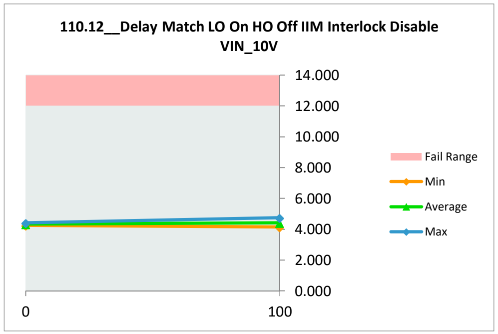


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		110.12__Delay Match LO On HO		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	12	12	
	Min Limit			
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.716	4.407	-0.309
0	2	4.372	4.249	-0.123
100	23	4.825	4.464	-0.360
100	24	4.963	4.142	-0.821
100	25	4.634	4.363	-0.271
100	26	4.245	4.759	0.514
100	27	4.686	4.555	-0.131
100	48u	4.718	4.476	-0.242
100	49u	4.608	4.352	-0.255
100	50u	4.549	4.571	0.022
100	51u	4.524	4.146	-0.378
100	52u	4.319	4.345	0.026
	Max	4.963	4.759	0.514
	Average	4.597	4.402	-0.194
	Min	4.245	4.142	-0.821
	Std Dev	0.210	0.179	0.314



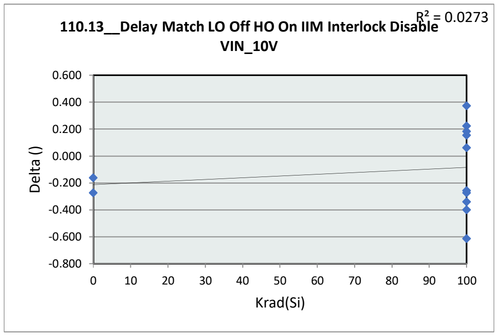
	110.12__Delay Match LO On HO Off IIM Inte	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit		
Krad(Si)	0	100
LL		
Min	4.249	4.142
Average	4.328	4.417
Max	4.407	4.759
UL	12.000	12.000



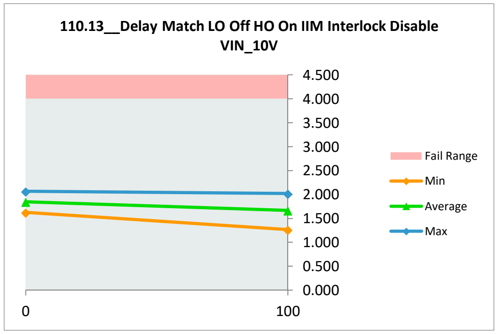
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	110.13__Delay Match LO Off HO	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	4	4
Min Limit		

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.894	1.626	-0.268
0	2	2.226	2.070	-0.156
100	23	1.442	1.630	0.188
100	24	1.232	1.611	0.379
100	25	1.727	1.460	-0.268
100	26	2.168	1.774	-0.395
100	27	1.874	1.265	-0.609
100	48u	1.616	1.682	0.066
100	49u	1.660	1.818	0.159
100	50u	1.769	1.517	-0.252
100	51u	1.792	2.019	0.227
100	52u	2.207	1.871	-0.336
	Max	2.226	2.070	0.379
	Average	1.801	1.695	-0.105
	Min	1.232	1.265	-0.609
	Std Dev	0.303	0.231	0.301

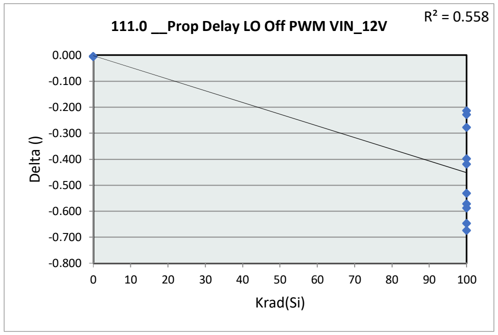


	110.13__Delay Match LO Off HO On IIM Inte	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	4	
Min Limit		
Krad(Si)	0	100
LL		
Min	1.626	1.265
Average	1.848	1.665
Max	2.070	2.019
UL	4.000	4.000

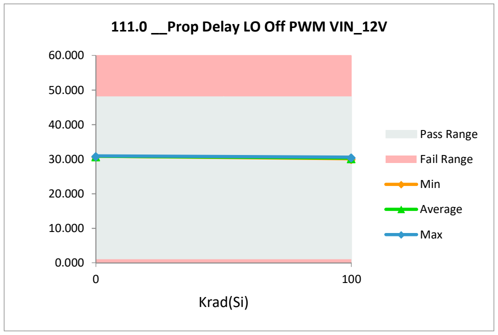


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		111.0 __Prop Delay LO Off PWM		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		48	48	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	30.919	30.918	-0.001
0	2	30.838	30.836	-0.003
100	23	30.642	30.432	-0.210
100	24	30.550	30.275	-0.275
100	25	30.781	30.111	-0.670
100	26	30.994	30.599	-0.394
100	27	30.644	30.115	-0.528
100	48u	30.583	30.358	-0.225
100	49u	30.673	30.088	-0.585
100	50u	30.678	30.262	-0.416
100	51u	30.959	30.316	-0.644
100	52u	30.865	30.296	-0.568
	Max	30.994	30.918	-0.001
	Average	30.760	30.384	-0.377
	Min	30.550	30.088	-0.670
	Std Dev	0.152	0.272	0.234

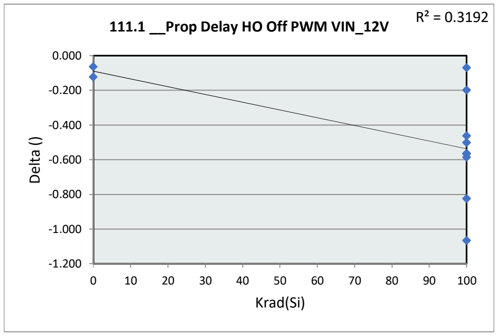


	111.0 __Prop Delay LO Off PWM VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	48	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	30.836	30.088
Average	30.877	30.285
Max	30.918	30.599
UL	48.000	48.000

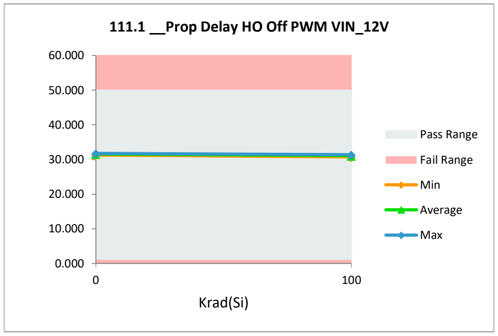


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		111.1 __Prop Delay HO Off PWM		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	50	50	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	31.891	31.771	-0.119
0	2	31.399	31.338	-0.060
100	23	31.864	31.367	-0.498
100	24	31.859	30.796	-1.063
100	25	31.595	31.035	-0.560
100	26	31.478	31.413	-0.065
100	27	31.634	31.176	-0.458
100	48u	31.764	31.201	-0.563
100	49u	31.512	30.930	-0.582
100	50u	31.570	31.009	-0.562
100	51u	31.588	30.768	-0.821
100	52u	31.255	31.060	-0.195
	Max	31.891	31.771	-0.060
	Average	31.617	31.155	-0.462
	Min	31.255	30.768	-1.063
	Std Dev	0.198	0.286	0.308



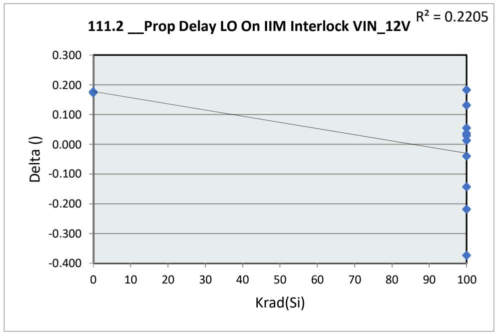
	111.1 __Prop Delay HO Off PWM VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	50	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	31.338	30.768
Average	31.555	31.075
Max	31.772	31.413
UL	50.000	50.000



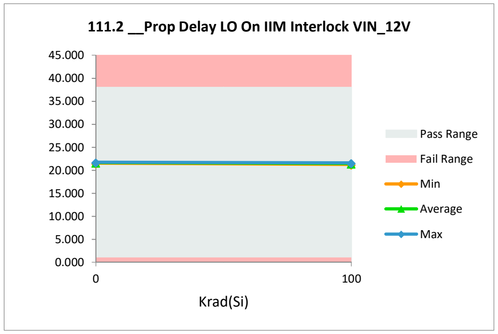
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	111.2 __Prop Delay LO On IIM I	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	38	38
Min Limit	1	1

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	21.586	21.765	0.179
0	2	21.387	21.564	0.176
100	23	21.471	21.510	0.040
100	24	21.430	21.462	0.032
100	25	21.604	21.389	-0.215
100	26	21.616	21.579	-0.037
100	27	21.644	21.274	-0.370
100	48u	21.425	21.558	0.134
100	49u	21.414	21.273	-0.141
100	50u	21.348	21.406	0.057
100	51u	21.463	21.479	0.016
100	52u	21.395	21.580	0.185
	Max	21.644	21.765	0.185
	Average	21.482	21.487	0.005
	Min	21.348	21.273	-0.370
	Std Dev	0.103	0.140	0.172

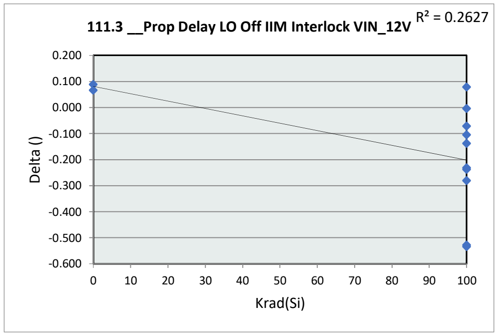


	111.2 __Prop Delay LO On IIM Interlock VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	21.564	21.273
Average	21.665	21.451
Max	21.766	21.580
UL	38.000	38.000

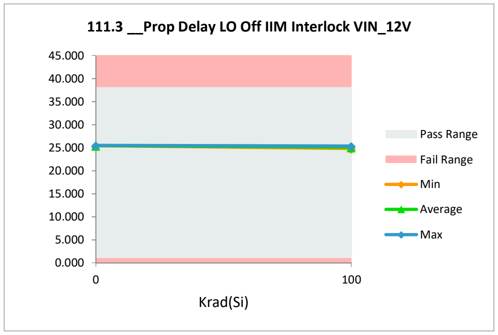


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		111.3 __Prop Delay LO Off IIM I		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	38	38	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	25.371	25.462	0.092
0	2	25.377	25.447	0.070
100	23	25.167	25.167	0.000
100	24	25.208	25.073	-0.135
100	25	25.453	24.929	-0.525
100	26	25.590	25.362	-0.228
100	27	25.348	24.818	-0.530
100	48u	25.087	25.170	0.082
100	49u	25.188	24.910	-0.278
100	50u	25.258	25.157	-0.101
100	51u	25.412	25.178	-0.234
100	52u	25.344	25.276	-0.068
	Max	25.590	25.462	0.092
	Average	25.317	25.162	-0.155
	Min	25.087	24.818	-0.530
	Std Dev	0.141	0.206	0.215

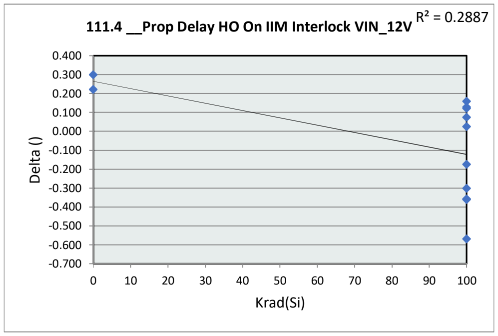


	111.3 __Prop Delay LO Off IIM Interlock VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.447	24.818
Average	25.455	25.104
Max	25.463	25.362
UL	38.000	38.000

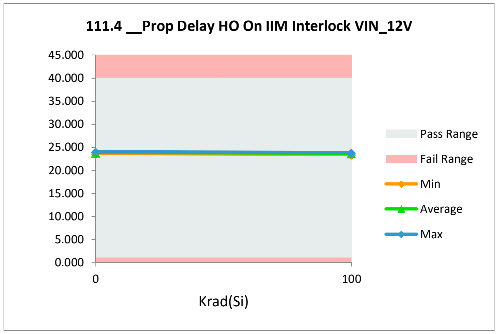


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		111.4 __Prop Delay HO On IIM I		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	40	40	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	23.840	24.065	0.225
0	2	23.332	23.635	0.304
100	23	24.085	23.728	-0.358
100	24	24.294	23.728	-0.566
100	25	23.833	23.662	-0.171
100	26	23.666	23.829	0.163
100	27	23.690	23.816	0.126
100	48u	23.710	23.738	0.029
100	49u	23.695	23.397	-0.299
100	50u	23.723	23.801	0.077
100	51u	23.911	23.557	-0.354
100	52u	23.487	23.619	0.133
	Max	24.294	24.065	0.304
	Average	23.772	23.715	-0.058
	Min	23.332	23.397	-0.566
	Std Dev	0.253	0.165	0.280

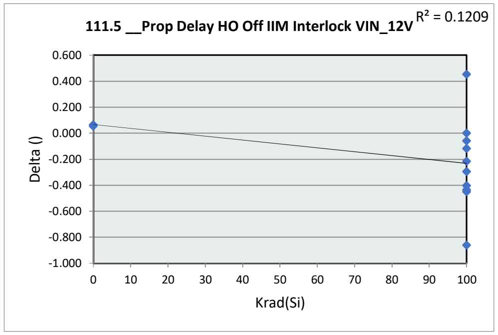


	111.4 __Prop Delay HO On IIM Interlock VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	23.636	23.397
Average	23.850	23.688
Max	24.065	23.829
UL	40.000	40.000

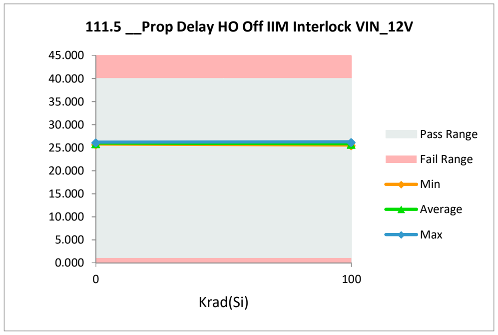


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		111.5 __Prop Delay HO Off IIM I		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	40	40	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	26.118	26.181	0.062
0	2	25.704	25.775	0.072
100	23	26.336	25.894	-0.442
100	24	26.454	25.599	-0.855
100	25	26.197	25.800	-0.397
100	26	25.811	26.270	0.459
100	27	26.252	26.043	-0.209
100	48u	26.023	25.970	-0.053
100	49u	25.924	25.635	-0.289
100	50u	26.051	25.940	-0.111
100	51u	26.014	25.585	-0.429
100	52u	25.770	25.776	0.006
	Max	26.454	26.270	0.459
	Average	26.054	25.872	-0.182
	Min	25.704	25.585	-0.855
	Std Dev	0.231	0.220	0.335

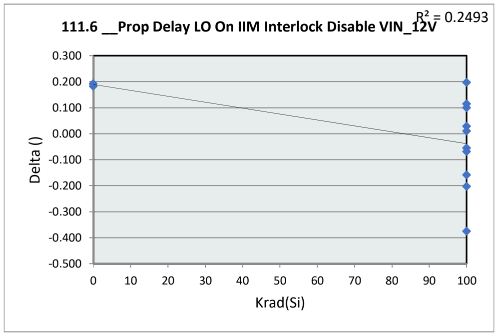


	111.5 __Prop Delay HO Off IIM Interlock VI	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.775	25.585
Average	25.978	25.851
Max	26.181	26.270
UL	40.000	40.000

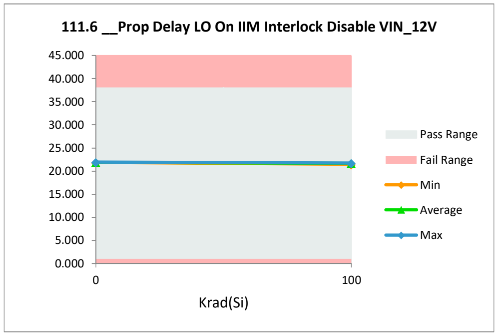


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		111.6 __Prop Delay LO On IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		38	38	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	21.738	21.922	0.184
0	2	21.664	21.859	0.194
100	23	21.624	21.727	0.103
100	24	21.702	21.715	0.012
100	25	21.774	21.618	-0.155
100	26	21.816	21.750	-0.066
100	27	21.829	21.457	-0.372
100	48u	21.572	21.771	0.199
100	49u	21.716	21.516	-0.199
100	50u	21.640	21.671	0.031
100	51u	21.703	21.651	-0.052
100	52u	21.653	21.771	0.118
	Max	21.829	21.922	0.199
	Average	21.703	21.702	0.000
	Min	21.572	21.457	-0.372
	Std Dev	0.078	0.132	0.177

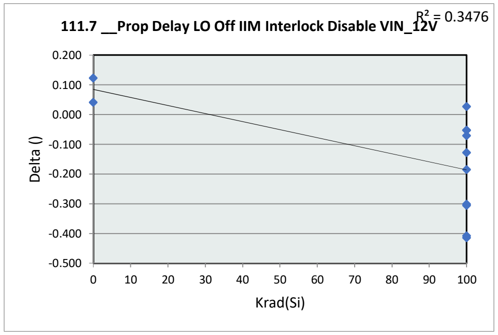


	111.6 __Prop Delay LO On IIM Interlock Dis	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	21.859	21.457
Average	21.891	21.665
Max	21.922	21.771
UL	38.000	38.000

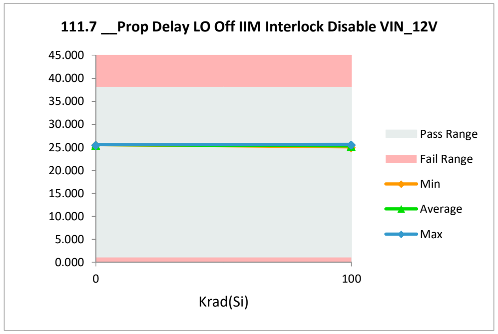


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		111.7 __Prop Delay LO Off IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		38	38	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	25.505	25.549	0.044
0	2	25.424	25.550	0.126
100	23	25.284	25.234	-0.050
100	24	25.484	25.182	-0.302
100	25	25.597	25.192	-0.405
100	26	25.674	25.607	-0.067
100	27	25.513	25.101	-0.412
100	48u	25.347	25.297	-0.050
100	49u	25.363	25.065	-0.298
100	50u	25.408	25.283	-0.125
100	51u	25.568	25.386	-0.182
100	52u	25.494	25.524	0.030
	Max	25.674	25.607	0.126
	Average	25.472	25.331	-0.141
	Min	25.284	25.065	-0.412
	Std Dev	0.112	0.188	0.179



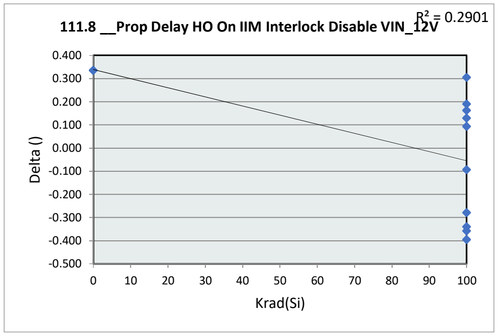
	111.7 __Prop Delay LO Off IIM Interlock Dis	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.549	25.065
Average	25.549	25.287
Max	25.550	25.607
UL	38.000	38.000



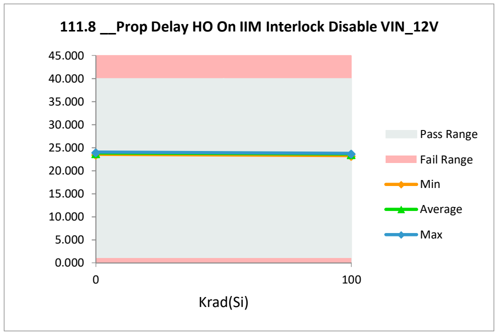
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	111.8 __Prop Delay HO On IIM I	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	40	40
Min Limit	1	1

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	23.695	24.033	0.339
0	2	23.243	23.583	0.340
100	23	23.980	23.704	-0.276
100	24	24.071	23.679	-0.392
100	25	23.730	23.640	-0.090
100	26	23.458	23.767	0.308
100	27	23.609	23.775	0.166
100	48u	23.564	23.661	0.097
100	49u	23.581	23.245	-0.336
100	50u	23.613	23.746	0.133
100	51u	23.762	23.408	-0.354
100	52u	23.379	23.574	0.194
	Max	24.071	24.033	0.340
	Average	23.641	23.651	0.011
	Min	23.243	23.245	-0.392
	Std Dev	0.233	0.196	0.285

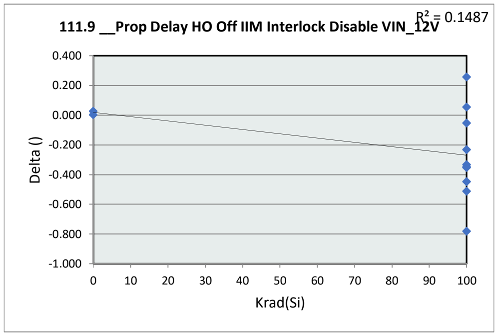


	111.8 __Prop Delay HO On IIM Interlock Dis	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	23.583	23.245
Average	23.808	23.620
Max	24.033	23.775
UL	40.000	40.000

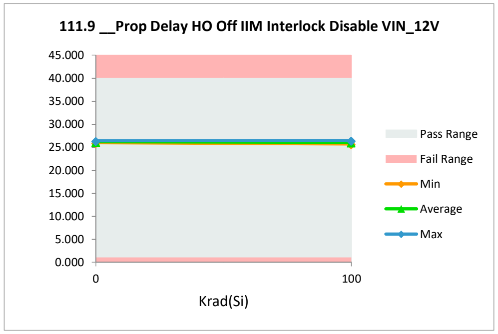


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		111.9 __Prop Delay HO Off IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		40	40	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	26.400	26.406	0.006
0	2	25.960	25.992	0.032
100	23	26.517	26.170	-0.347
100	24	26.588	25.813	-0.776
100	25	26.391	26.047	-0.344
100	26	26.185	26.446	0.262
100	27	26.499	26.170	-0.329
100	48u	26.353	26.126	-0.227
100	49u	26.165	25.722	-0.443
100	50u	26.202	26.153	-0.049
100	51u	26.299	25.793	-0.507
100	52u	25.969	26.028	0.059
	Max	26.588	26.446	0.262
	Average	26.294	26.072	-0.222
	Min	25.960	25.722	-0.776
	Std Dev	0.204	0.225	0.292

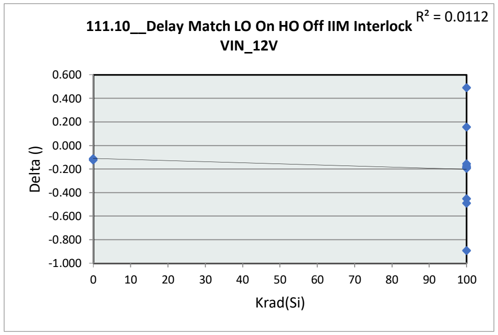


	111.9 __Prop Delay HO Off IIM Interlock Dis	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.992	25.722
Average	26.199	26.047
Max	26.406	26.446
UL	40.000	40.000

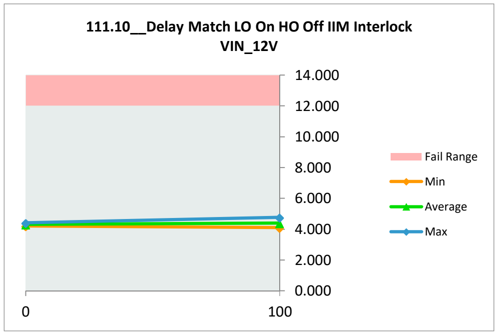


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		111.10__Delay Match LO On HO		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		12	12	
Min Limit				
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.532	4.415	-0.117
0	2	4.316	4.211	-0.105
100	23	4.865	4.383	-0.482
100	24	5.023	4.137	-0.886
100	25	4.593	4.411	-0.182
100	26	4.195	4.691	0.496
100	27	4.607	4.769	0.162
100	48u	4.598	4.412	-0.186
100	49u	4.510	4.362	-0.148
100	50u	4.703	4.534	-0.169
100	51u	4.551	4.106	-0.445
100	52u	4.375	4.196	-0.179
	Max	5.023	4.769	0.496
	Average	4.572	4.386	-0.187
	Min	4.195	4.106	-0.886
	Std Dev	0.226	0.207	0.336

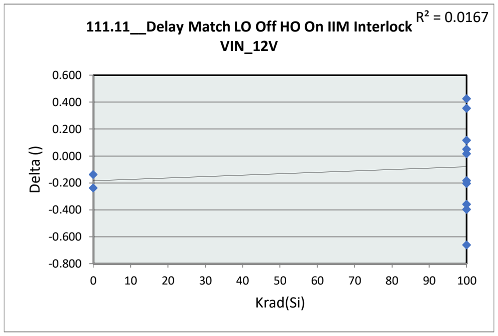


	111.10__Delay Match LO On HO Off IIM Inte	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit		
Krad(Si)	0	100
LL		
Min	4.211	4.106
Average	4.313	4.400
Max	4.415	4.769
UL	12.000	12.000

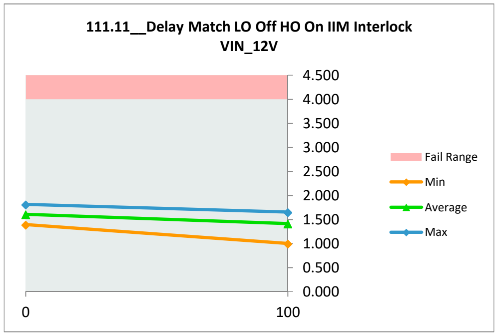


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		111.11__Delay Match LO Off HO		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		4	4	
Min Limit				
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.530	1.397	-0.133
0	2	2.045	1.812	-0.234
100	23	1.081	1.439	0.358
100	24	0.914	1.345	0.431
100	25	1.620	1.266	-0.354
100	26	1.924	1.532	-0.391
100	27	1.658	1.002	-0.656
100	48u	1.378	1.431	0.054
100	49u	1.493	1.514	0.021
100	50u	1.535	1.356	-0.179
100	51u	1.501	1.621	0.120
100	52u	1.857	1.657	-0.200
	Max	2.045	1.812	0.431
	Average	1.545	1.448	-0.097
	Min	0.914	1.002	-0.656
	Std Dev	0.324	0.207	0.312

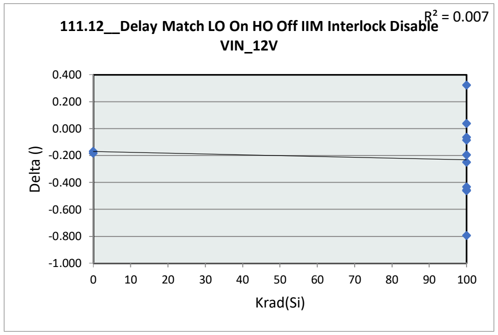


	111.11__Delay Match LO Off HO On IIM Inte	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	4	
Min Limit		
Krad(Si)	0	100
LL		
Min	1.397	1.002
Average	1.605	1.416
Max	1.812	1.657
UL	4.000	4.000

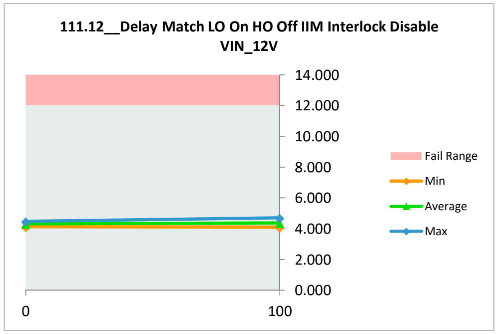


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		111.12__Delay Match LO On HO		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		12	12	
Min Limit				
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.662	4.484	-0.178
0	2	4.295	4.133	-0.163
100	23	4.893	4.443	-0.451
100	24	4.886	4.098	-0.788
100	25	4.618	4.429	-0.189
100	26	4.368	4.696	0.328
100	27	4.669	4.712	0.043
100	48u	4.781	4.355	-0.426
100	49u	4.450	4.206	-0.244
100	50u	4.562	4.482	-0.080
100	51u	4.596	4.142	-0.455
100	52u	4.315	4.257	-0.059
	Max	4.893	4.712	0.328
	Average	4.591	4.370	-0.222
	Min	4.295	4.098	-0.788
	Std Dev	0.205	0.209	0.285

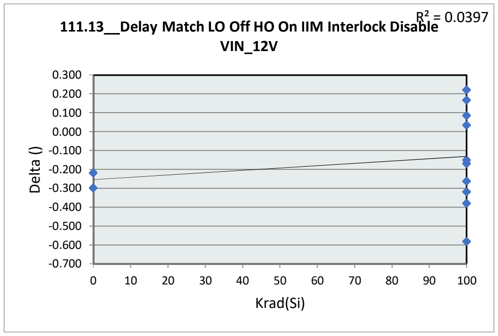


	111.12__Delay Match LO On HO Off IIM Inte	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit		
Krad(Si)	0	100
LL		
Min	4.133	4.098
Average	4.308	4.382
Max	4.484	4.712
UL	12.000	12.000

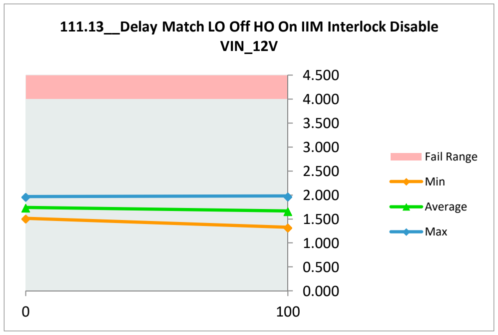


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		111.13__Delay Match LO Off HO		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	4	4	
	Min Limit			
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.810	1.515	-0.295
0	2	2.181	1.967	-0.214
100	23	1.304	1.530	0.226
100	24	1.413	1.503	0.090
100	25	1.867	1.552	-0.315
100	26	2.216	1.840	-0.376
100	27	1.903	1.326	-0.578
100	48u	1.783	1.636	-0.147
100	49u	1.782	1.820	0.038
100	50u	1.795	1.536	-0.258
100	51u	1.806	1.977	0.172
100	52u	2.114	1.950	-0.164
	Max	2.216	1.977	0.226
	Average	1.831	1.679	-0.152
	Min	1.304	1.326	-0.578
	Std Dev	0.273	0.220	0.240

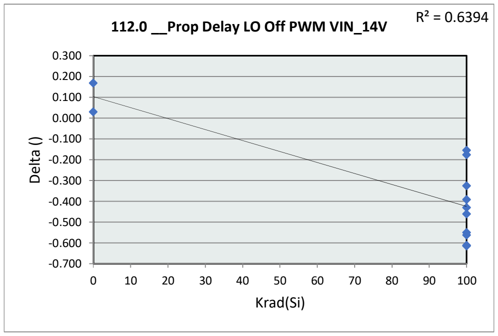


	111.13__Delay Match LO Off HO On IIM Inte	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	4	
Min Limit		
Krad(Si)	0	100
LL		
Min	1.515	1.326
Average	1.741	1.667
Max	1.967	1.977
UL	4.000	4.000

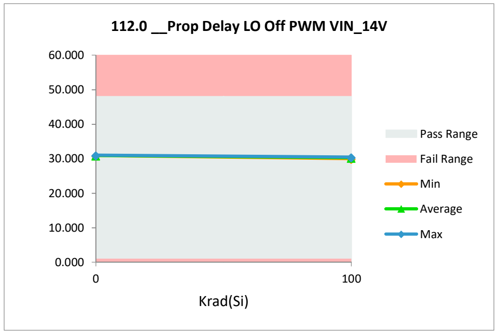


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		112.0 __Prop Delay LO Off PWM		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	48	48	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	30.874	31.046	0.172
0	2	30.873	30.907	0.034
100	23	30.568	30.416	-0.152
100	24	30.497	30.324	-0.173
100	25	30.737	30.179	-0.558
100	26	31.027	30.481	-0.546
100	27	30.573	30.115	-0.457
100	48u	30.628	30.306	-0.322
100	49u	30.654	30.043	-0.611
100	50u	30.664	30.237	-0.427
100	51u	30.916	30.308	-0.608
100	52u	30.748	30.359	-0.389
	Max	31.027	31.046	0.172
	Average	30.730	30.393	-0.337
	Min	30.497	30.043	-0.611
	Std Dev	0.162	0.300	0.257

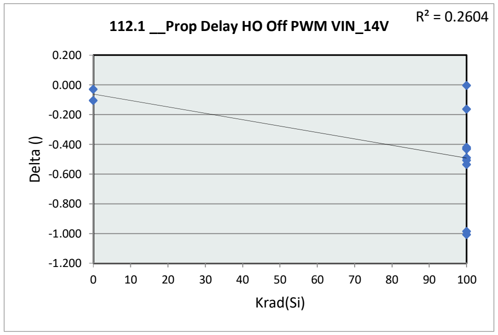


	112.0 __Prop Delay LO Off PWM VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	48	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	30.907	30.043
Average	30.976	30.277
Max	31.046	30.481
UL	48.000	48.000

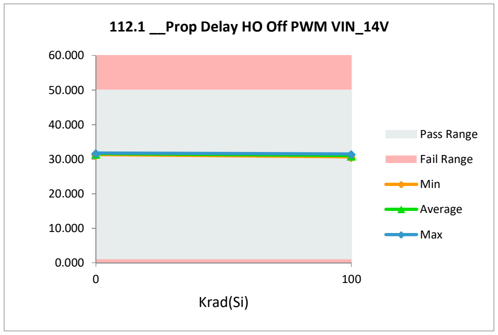


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		112.1 __Prop Delay HO Off PWM		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		50	50	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	31.819	31.794	-0.025
0	2	31.434	31.334	-0.100
100	23	31.733	31.319	-0.414
100	24	31.788	30.787	-1.001
100	25	31.493	31.066	-0.427
100	26	31.482	31.484	0.002
100	27	31.581	31.080	-0.501
100	48u	31.663	31.240	-0.423
100	49u	31.475	30.945	-0.530
100	50u	31.523	31.038	-0.485
100	51u	31.683	30.702	-0.981
100	52u	31.235	31.077	-0.158
	Max	31.819	31.794	0.002
	Average	31.576	31.156	-0.420
	Min	31.235	30.702	-1.001
	Std Dev	0.169	0.302	0.328

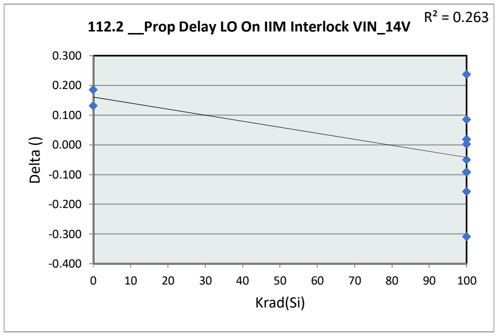


	112.1 __Prop Delay HO Off PWM VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	50	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	31.334	30.702
Average	31.564	31.074
Max	31.794	31.484
UL	50.000	50.000

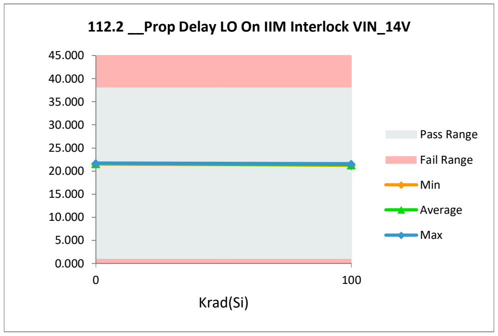


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		112.2 __Prop Delay LO On IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		38	38	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	21.580	21.767	0.187
0	2	21.386	21.521	0.134
100	23	21.468	21.420	-0.048
100	24	21.458	21.479	0.021
100	25	21.495	21.406	-0.090
100	26	21.561	21.471	-0.090
100	27	21.597	21.291	-0.307
100	48u	21.399	21.486	0.088
100	49u	21.463	21.309	-0.154
100	50u	21.387	21.392	0.005
100	51u	21.504	21.415	-0.089
100	52u	21.362	21.601	0.239
	Max	21.597	21.767	0.239
	Average	21.472	21.463	-0.009
	Min	21.362	21.291	-0.307
	Std Dev	0.079	0.129	0.154

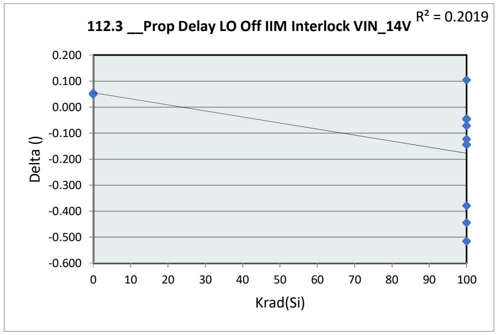


	112.2 __Prop Delay LO On IIM Interlock VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	21.521	21.291
Average	21.644	21.427
Max	21.767	21.601
UL	38.000	38.000

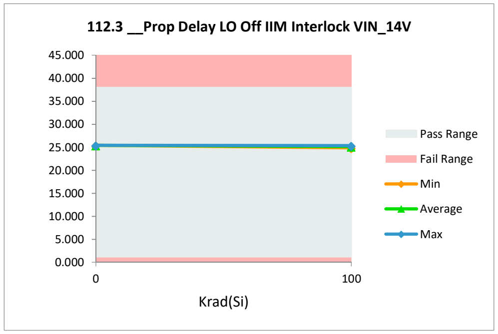


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		112.3 __Prop Delay LO Off IIM I		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	38	38	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	25.401	25.454	0.053
0	2	25.396	25.454	0.058
100	23	25.220	25.152	-0.068
100	24	25.211	25.170	-0.041
100	25	25.387	24.946	-0.440
100	26	25.478	25.337	-0.141
100	27	25.435	24.923	-0.512
100	48u	25.118	25.226	0.108
100	49u	25.237	24.861	-0.376
100	50u	25.250	25.109	-0.140
100	51u	25.311	25.268	-0.043
100	52u	25.394	25.274	-0.120
	Max	25.478	25.454	0.108
	Average	25.320	25.181	-0.139
	Min	25.118	24.861	-0.512
	Std Dev	0.111	0.196	0.202



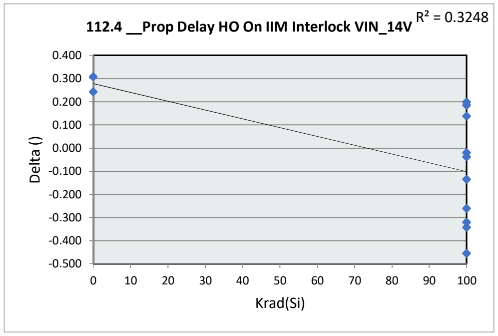
	112.3 __Prop Delay LO Off IIM Interlock VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.454	24.861
Average	25.454	25.127
Max	25.454	25.337
UL	38.000	38.000



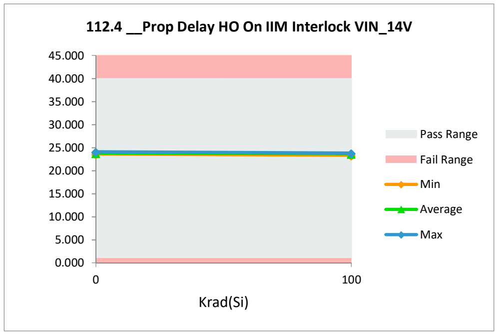
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	112.4 __Prop Delay HO On IIM I	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	40	40
Min Limit	1	1

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	23.776	24.087	0.311
0	2	23.348	23.594	0.246
100	23	24.011	23.755	-0.257
100	24	24.235	23.783	-0.451
100	25	23.785	23.654	-0.132
100	26	23.658	23.861	0.202
100	27	23.795	23.760	-0.034
100	48u	23.736	23.719	-0.017
100	49u	23.677	23.361	-0.317
100	50u	23.655	23.844	0.189
100	51u	23.884	23.545	-0.340
100	52u	23.459	23.601	0.141
	Max	24.235	24.087	0.311
	Average	23.752	23.714	-0.038
	Min	23.348	23.361	-0.451
	Std Dev	0.232	0.183	0.259

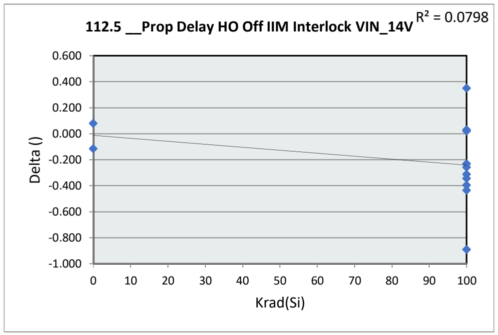


	112.4 __Prop Delay HO On IIM Interlock VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	23.594	23.361
Average	23.840	23.688
Max	24.087	23.861
UL	40.000	40.000

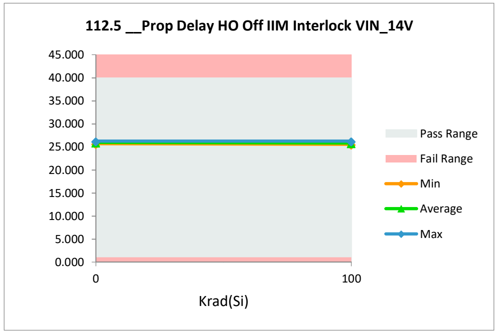


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		112.5 __Prop Delay HO Off IIM I		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	40	40	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	26.157	26.241	0.084
0	2	25.832	25.723	-0.109
100	23	26.337	25.945	-0.391
100	24	26.495	25.611	-0.884
100	25	26.156	25.849	-0.307
100	26	25.882	26.236	0.354
100	27	26.186	25.961	-0.225
100	48u	26.204	25.951	-0.253
100	49u	25.982	25.642	-0.340
100	50u	25.956	25.981	0.025
100	51u	26.010	25.581	-0.429
100	52u	25.787	25.823	0.036
	Max	26.495	26.241	0.354
	Average	26.082	25.879	-0.203
	Min	25.787	25.581	-0.884
	Std Dev	0.212	0.220	0.315

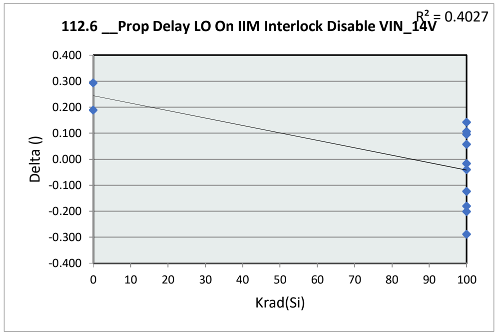


	112.5 __Prop Delay HO Off IIM Interlock VI	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.723	25.581
Average	25.982	25.858
Max	26.241	26.236
UL	40.000	40.000

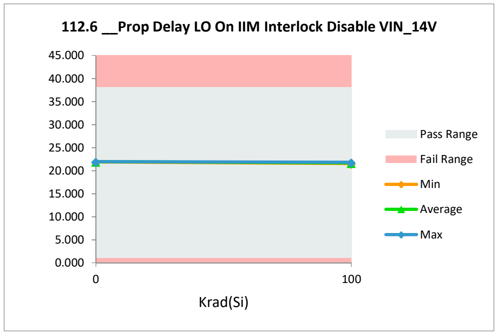


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		112.6 __Prop Delay LO On IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		38	38	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	21.780	21.972	0.192
0	2	21.583	21.880	0.297
100	23	21.605	21.750	0.145
100	24	21.711	21.674	-0.037
100	25	21.772	21.574	-0.198
100	26	21.894	21.717	-0.177
100	27	21.820	21.535	-0.285
100	48u	21.708	21.806	0.098
100	49u	21.642	21.521	-0.121
100	50u	21.606	21.666	0.060
100	51u	21.709	21.696	-0.013
100	52u	21.687	21.796	0.110
	Max	21.894	21.972	0.297
	Average	21.710	21.716	0.006
	Min	21.583	21.521	-0.285
	Std Dev	0.094	0.136	0.176

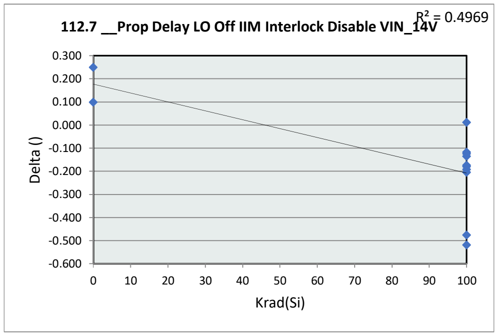


	112.6 __Prop Delay LO On IIM Interlock Dis	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	21.880	21.521
Average	21.926	21.674
Max	21.972	21.806
UL	38.000	38.000

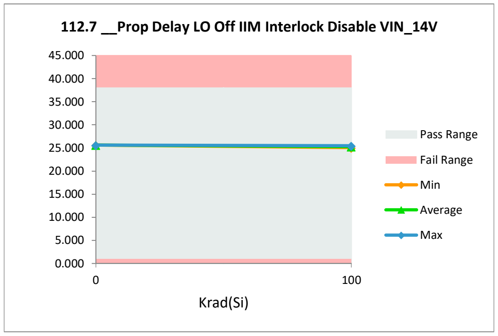


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		112.7 __Prop Delay LO Off IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		38	38	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	25.553	25.654	0.101
0	2	25.400	25.652	0.252
100	23	25.391	25.214	-0.177
100	24	25.419	25.248	-0.172
100	25	25.560	25.045	-0.516
100	26	25.711	25.521	-0.190
100	27	25.519	25.047	-0.472
100	48u	25.369	25.383	0.014
100	49u	25.210	25.077	-0.133
100	50u	25.420	25.219	-0.202
100	51u	25.556	25.435	-0.121
100	52u	25.531	25.416	-0.115
	Max	25.711	25.654	0.252
	Average	25.470	25.326	-0.144
	Min	25.210	25.045	-0.516
	Std Dev	0.128	0.218	0.213

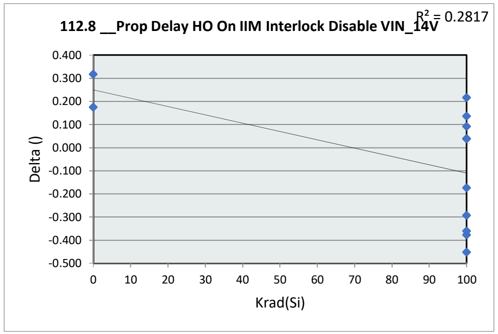


	112.7 __Prop Delay LO Off IIM Interlock Dis	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.652	25.045
Average	25.653	25.260
Max	25.654	25.521
UL	38.000	38.000

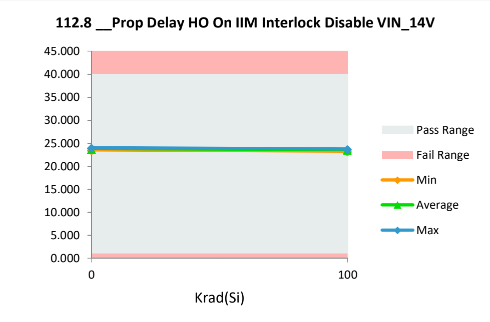


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		112.8 __Prop Delay HO On IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		40	40	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	23.704	24.026	0.322
0	2	23.380	23.558	0.178
100	23	23.969	23.595	-0.374
100	24	24.096	23.648	-0.448
100	25	23.792	23.621	-0.170
100	26	23.522	23.742	0.220
100	27	23.687	23.729	0.043
100	48u	23.637	23.678	0.041
100	49u	23.596	23.240	-0.357
100	50u	23.599	23.740	0.140
100	51u	23.745	23.455	-0.289
100	52u	23.395	23.490	0.095
	Max	24.096	24.026	0.322
	Average	23.677	23.627	-0.050
	Min	23.380	23.240	-0.448
	Std Dev	0.210	0.191	0.264

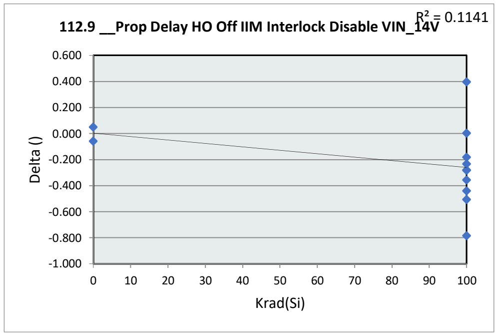


	112.8 __Prop Delay HO On IIM Interlock Dis	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	23.558	23.240
Average	23.792	23.594
Max	24.026	23.742
UL	40.000	40.000

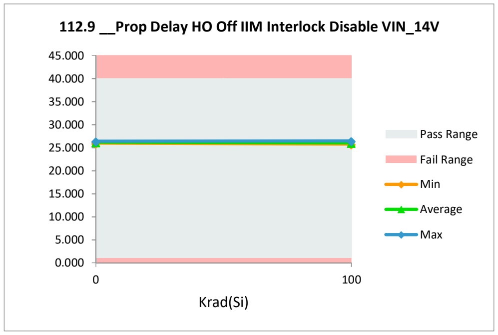


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		112.9 __Prop Delay HO Off IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		40	40	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	26.475	26.423	-0.052
0	2	25.955	26.011	0.057
100	23	26.503	26.153	-0.349
100	24	26.545	25.766	-0.779
100	25	26.410	26.135	-0.275
100	26	26.072	26.475	0.403
100	27	26.448	26.222	-0.226
100	48u	26.440	26.165	-0.275
100	49u	26.235	25.802	-0.434
100	50u	26.254	26.078	-0.176
100	51u	26.274	25.775	-0.500
100	52u	26.025	26.035	0.010
	Max	26.545	26.475	0.403
	Average	26.303	26.087	-0.216
	Min	25.955	25.766	-0.779
	Std Dev	0.200	0.231	0.302

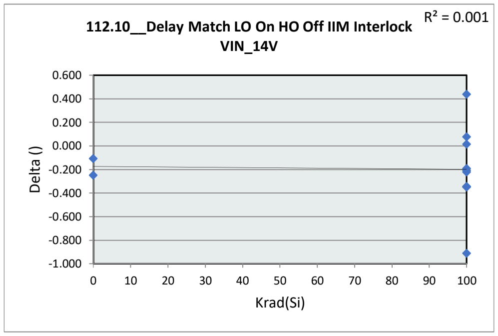


	112.9 __Prop Delay HO Off IIM Interlock Dis	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	26.011	25.766
Average	26.217	26.060
Max	26.423	26.475
UL	40.000	40.000

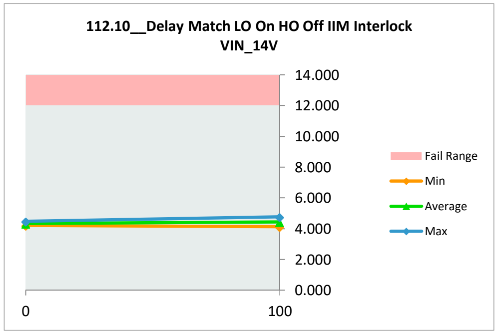


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		112.10__Delay Match LO On HO		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		12	12	
Min Limit				
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.577	4.474	-0.103
0	2	4.446	4.202	-0.244
100	23	4.869	4.525	-0.343
100	24	5.037	4.133	-0.904
100	25	4.661	4.444	-0.217
100	26	4.321	4.765	0.444
100	27	4.588	4.670	0.082
100	48u	4.806	4.465	-0.341
100	49u	4.519	4.333	-0.185
100	50u	4.569	4.589	0.020
100	51u	4.506	4.167	-0.339
100	52u	4.424	4.221	-0.203
	Max	5.037	4.765	0.444
	Average	4.610	4.416	-0.194
	Min	4.321	4.133	-0.904
	Std Dev	0.204	0.206	0.318

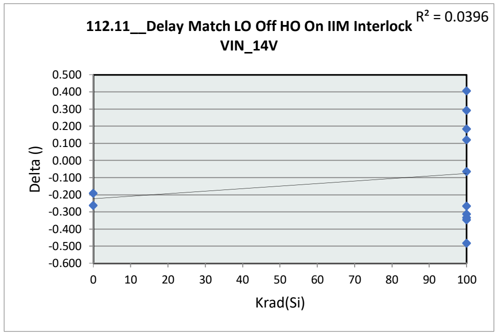


	112.10__Delay Match LO On HO Off IIM Inte	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit		
Krad(Si)	0	100
LL		
Min	4.202	4.133
Average	4.338	4.431
Max	4.474	4.765
UL	12.000	12.000

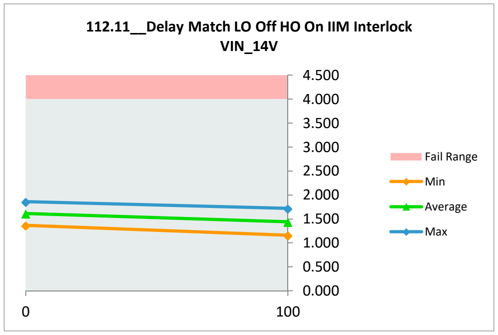


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		112.11__Delay Match LO Off HO		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	4	4	
	Min Limit			
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.625	1.367	-0.258
0	2	2.048	1.860	-0.188
100	23	1.208	1.397	0.189
100	24	0.976	1.386	0.410
100	25	1.602	1.293	-0.309
100	26	1.819	1.477	-0.343
100	27	1.641	1.163	-0.478
100	48u	1.382	1.507	0.124
100	49u	1.559	1.500	-0.059
100	50u	1.594	1.265	-0.329
100	51u	1.427	1.723	0.296
100	52u	1.935	1.673	-0.262
	Max	2.048	1.860	0.410
	Average	1.568	1.468	-0.100
	Min	0.976	1.163	-0.478
	Std Dev	0.297	0.203	0.288

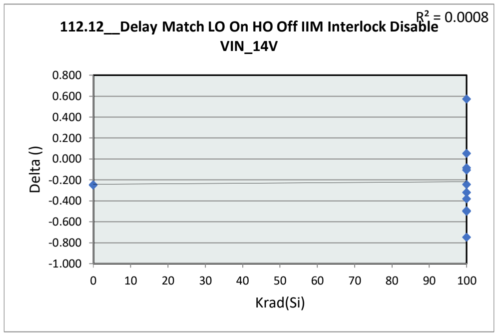


	112.11__Delay Match LO Off HO On IIM Inte	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	4	
Min Limit		
Krad(Si)	0	100
LL		
Min	1.367	1.163
Average	1.614	1.438
Max	1.861	1.723
UL	4.000	4.000

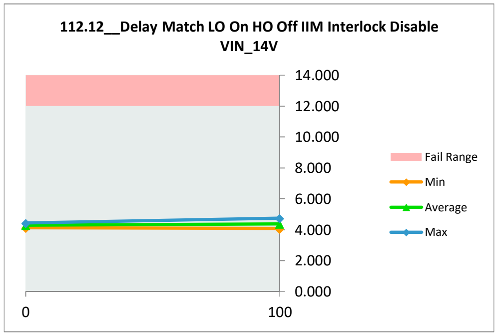


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		112.12__Delay Match LO On HO		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		12	12	
Min Limit				
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.695	4.452	-0.243
0	2	4.372	4.131	-0.240
100	23	4.897	4.403	-0.494
100	24	4.833	4.092	-0.742
100	25	4.638	4.561	-0.077
100	26	4.178	4.758	0.580
100	27	4.627	4.686	0.059
100	48u	4.733	4.359	-0.374
100	49u	4.593	4.280	-0.313
100	50u	4.648	4.412	-0.236
100	51u	4.565	4.079	-0.486
100	52u	4.339	4.238	-0.100
	Max	4.897	4.758	0.580
	Average	4.593	4.371	-0.222
	Min	4.178	4.079	-0.742
	Std Dev	0.208	0.222	0.331

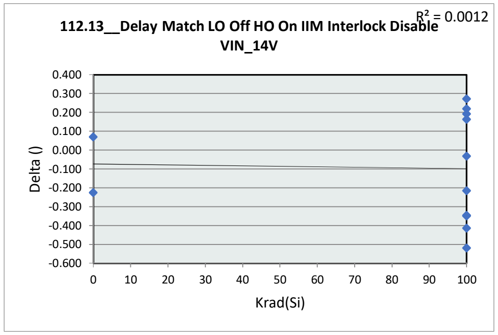


	112.12__Delay Match LO On HO Off IIM Inte	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit		
Krad(Si)	0	100
LL		
Min	4.131	4.079
Average	4.291	4.387
Max	4.452	4.758
UL	12.000	12.000

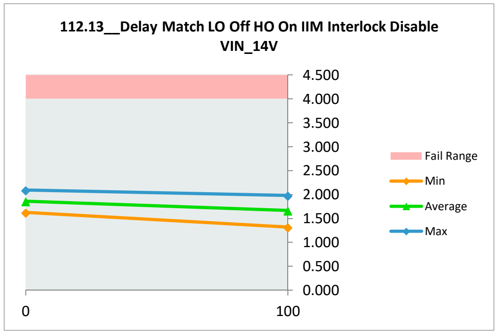


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		112.13__Delay Match LO Off HO		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		4	4	
Min Limit				
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	1.849	1.628	-0.221
0	2	2.020	2.094	0.074
100	23	1.423	1.620	0.197
100	24	1.324	1.600	0.276
100	25	1.769	1.423	-0.345
100	26	2.188	1.779	-0.409
100	27	1.833	1.317	-0.515
100	48u	1.732	1.705	-0.027
100	49u	1.614	1.838	0.224
100	50u	1.821	1.479	-0.342
100	51u	1.811	1.979	0.168
100	52u	2.136	1.926	-0.210
	Max	2.188	2.094	0.276
	Average	1.793	1.699	-0.094
	Min	1.324	1.317	-0.515
	Std Dev	0.257	0.234	0.279

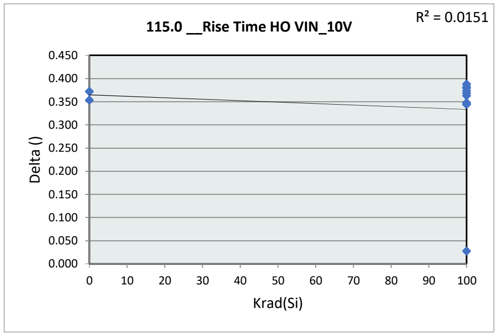


	112.13__Delay Match LO Off HO On IIM Inte	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	4	
Min Limit		
Krad(Si)	0	100
LL		
Min	1.628	1.318
Average	1.861	1.667
Max	2.094	1.979
UL	4.000	4.000

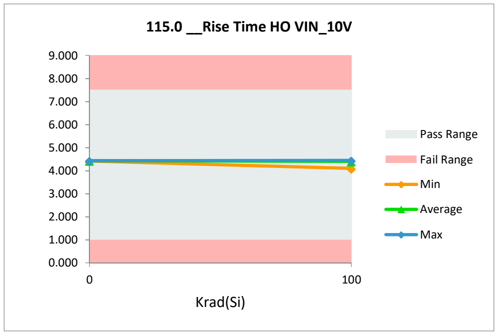


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		115.0 __Rise Time HO VIN_10V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	7.5	7.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.045	4.419	0.374
0	2	4.078	4.433	0.355
100	23	4.067	4.413	0.346
100	24	4.039	4.423	0.384
100	25	4.071	4.441	0.371
100	26	4.053	4.429	0.375
100	27	4.075	4.421	0.346
100	48u	4.066	4.448	0.382
100	49u	4.075	4.104	0.029
100	50u	4.071	4.436	0.365
100	51u	4.081	4.430	0.350
100	52u	4.056	4.446	0.390
	Max	4.081	4.448	0.390
	Average	4.065	4.404	0.339
	Min	4.039	4.104	0.029
	Std Dev	0.013	0.095	0.099

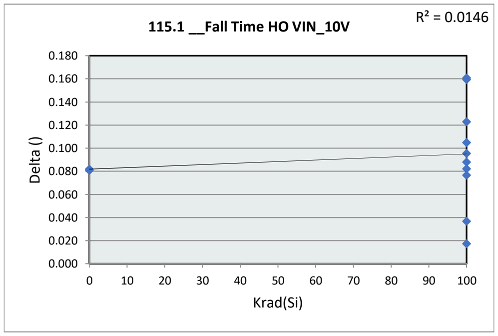


	115.0 __Rise Time HO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	4.419	4.104
Average	4.426	4.399
Max	4.433	4.448
UL	7.500	7.500

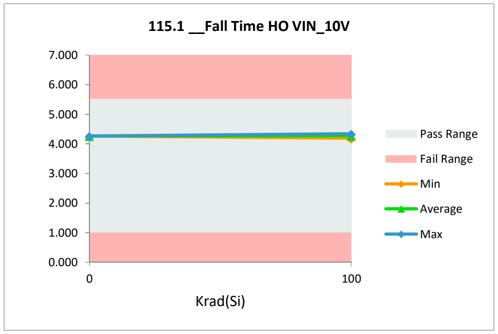


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		115.1 __Fall Time HO VIN_10V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		5.5	5.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.183	4.264	0.081
0	2	4.180	4.263	0.082
100	23	4.190	4.228	0.037
100	24	4.177	4.260	0.083
100	25	4.182	4.306	0.123
100	26	4.186	4.282	0.096
100	27	4.186	4.346	0.160
100	48u	4.198	4.303	0.105
100	49u	4.180	4.198	0.018
100	50u	4.189	4.278	0.089
100	51u	4.192	4.269	0.077
100	52u	4.174	4.335	0.161
	Max	4.198	4.346	0.161
	Average	4.185	4.278	0.093
	Min	4.174	4.198	0.018
	Std Dev	0.007	0.042	0.042

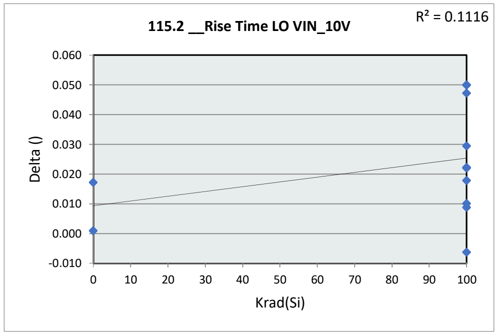


	115.1 __Fall Time HO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	4.263	4.198
Average	4.263	4.280
Max	4.264	4.346
UL	5.500	5.500

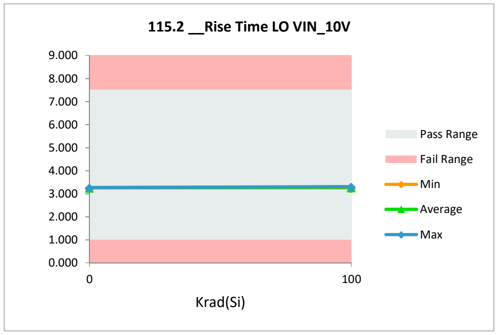


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		115.2 __Rise Time LO VIN_10V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	7.5	7.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.252	3.253	0.001
0	2	3.250	3.268	0.018
100	23	3.237	3.260	0.022
100	24	3.253	3.271	0.018
100	25	3.246	3.276	0.030
100	26	3.274	3.268	-0.006
100	27	3.245	3.268	0.023
100	48u	3.253	3.264	0.010
100	49u	3.234	3.285	0.050
100	50u	3.243	3.253	0.009
100	51u	3.238	3.288	0.050
100	52u	3.259	3.307	0.048
	Max	3.274	3.307	0.050
	Average	3.249	3.272	0.023
	Min	3.234	3.253	-0.006
	Std Dev	0.011	0.015	0.019

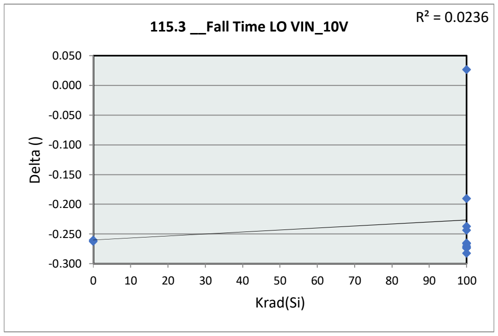


	115.2 __Rise Time LO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	3.254	3.253
Average	3.261	3.274
Max	3.268	3.307
UL	7.500	7.500

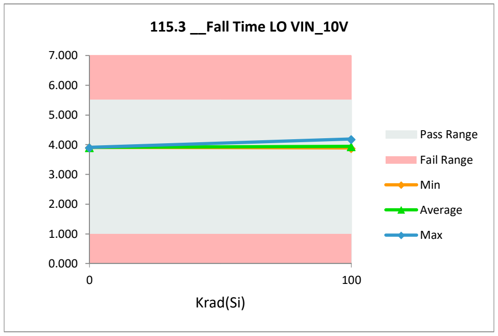


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		115.3 __Fall Time LO VIN_10V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	5.5	5.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.172	3.911	-0.261
0	2	4.170	3.911	-0.259
100	23	4.164	3.895	-0.269
100	24	4.172	3.900	-0.272
100	25	4.167	3.902	-0.265
100	26	4.187	3.906	-0.281
100	27	4.169	3.933	-0.236
100	48u	4.164	3.921	-0.243
100	49u	4.166	4.194	0.028
100	50u	4.172	3.899	-0.273
100	51u	4.184	3.920	-0.264
100	52u	4.162	3.973	-0.189
	Max	4.187	4.194	0.028
	Average	4.171	3.939	-0.232
	Min	4.162	3.895	-0.281
	Std Dev	0.008	0.083	0.085

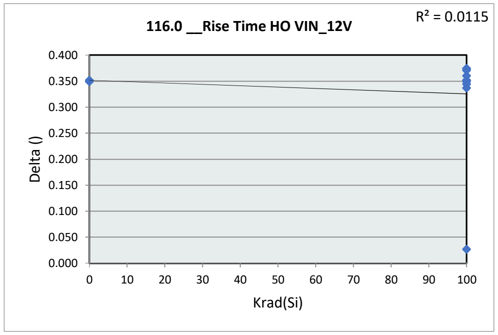


	115.3 __Fall Time LO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	3.911	3.895
Average	3.911	3.944
Max	3.911	4.194
UL	5.500	5.500

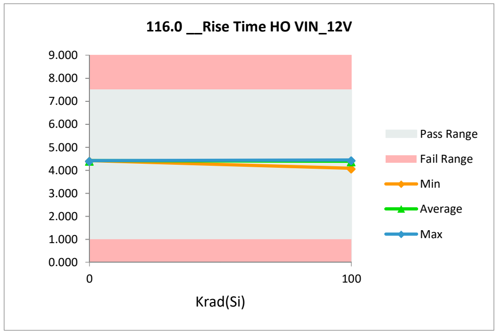


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		116.0 __Rise Time HO VIN_12V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	7.5	7.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.062	4.413	0.351
0	2	4.069	4.422	0.353
100	23	4.078	4.417	0.338
100	24	4.066	4.412	0.346
100	25	4.078	4.432	0.353
100	26	4.058	4.420	0.362
100	27	4.071	4.444	0.372
100	48u	4.066	4.442	0.376
100	49u	4.062	4.090	0.028
100	50u	4.065	4.441	0.375
100	51u	4.071	4.424	0.353
100	52u	4.087	4.437	0.351
	Max	4.087	4.444	0.376
	Average	4.069	4.399	0.330
	Min	4.058	4.090	0.028
	Std Dev	0.008	0.098	0.096

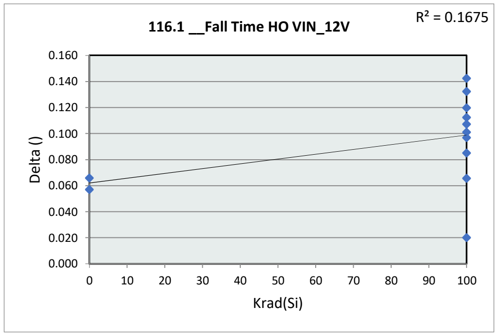


	116.0 __Rise Time HO VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	4.413	4.090
Average	4.417	4.396
Max	4.422	4.444
UL	7.500	7.500

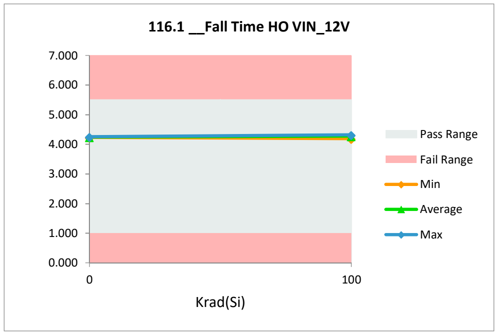


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		116.1 __Fall Time HO VIN_12V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		5.5	5.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.189	4.255	0.067
0	2	4.175	4.233	0.058
100	23	4.180	4.246	0.066
100	24	4.156	4.242	0.086
100	25	4.179	4.287	0.108
100	26	4.188	4.286	0.097
100	27	4.163	4.307	0.143
100	48u	4.192	4.313	0.120
100	49u	4.174	4.194	0.021
100	50u	4.161	4.274	0.113
100	51u	4.169	4.270	0.102
100	52u	4.186	4.319	0.133
	Max	4.192	4.319	0.143
	Average	4.176	4.269	0.093
	Min	4.156	4.194	0.021
	Std Dev	0.012	0.037	0.035

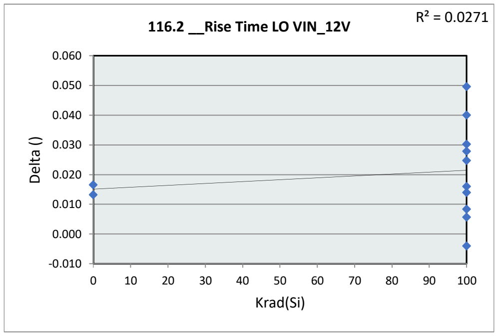


	116.1 __Fall Time HO VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	4.233	4.194
Average	4.244	4.274
Max	4.255	4.319
UL	5.500	5.500

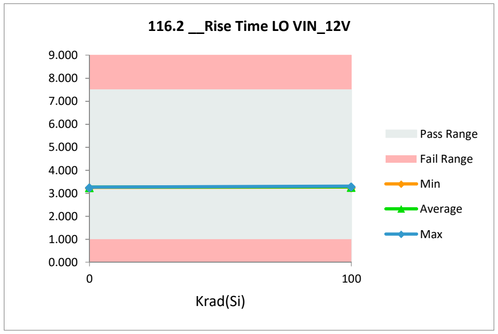


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		116.2 __Rise Time LO VIN_12V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	7.5	7.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.236	3.253	0.017
0	2	3.257	3.270	0.013
100	23	3.260	3.268	0.009
100	24	3.252	3.277	0.025
100	25	3.264	3.278	0.014
100	26	3.273	3.269	-0.004
100	27	3.266	3.272	0.006
100	48u	3.245	3.261	0.016
100	49u	3.249	3.289	0.040
100	50u	3.235	3.263	0.028
100	51u	3.260	3.290	0.030
100	52u	3.254	3.304	0.050
	Max	3.273	3.304	0.050
	Average	3.254	3.275	0.020
	Min	3.235	3.253	-0.004
	Std Dev	0.012	0.014	0.015

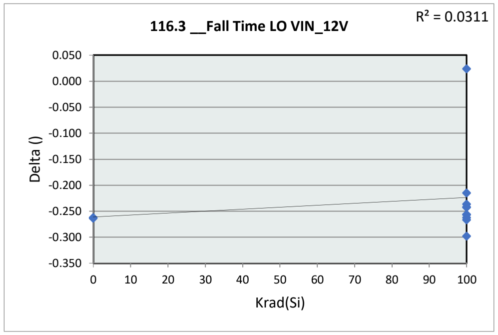


	116.2 __Rise Time LO VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	3.253	3.261
Average	3.262	3.277
Max	3.271	3.304
UL	7.500	7.500

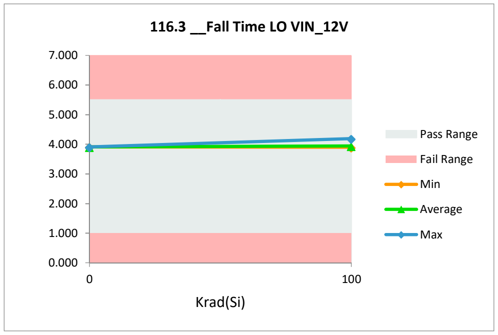


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		116.3 __Fall Time LO VIN_12V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		5.5	5.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.171	3.909	-0.262
0	2	4.171	3.910	-0.260
100	23	4.155	3.900	-0.255
100	24	4.170	3.906	-0.265
100	25	4.153	3.898	-0.255
100	26	4.202	3.906	-0.296
100	27	4.163	3.928	-0.235
100	48u	4.160	3.919	-0.241
100	49u	4.162	4.188	0.025
100	50u	4.162	3.901	-0.260
100	51u	4.160	3.920	-0.240
100	52u	4.176	3.963	-0.213
	Max	4.202	4.188	0.025
	Average	4.167	3.937	-0.230
	Min	4.153	3.898	-0.296
	Std Dev	0.013	0.081	0.083

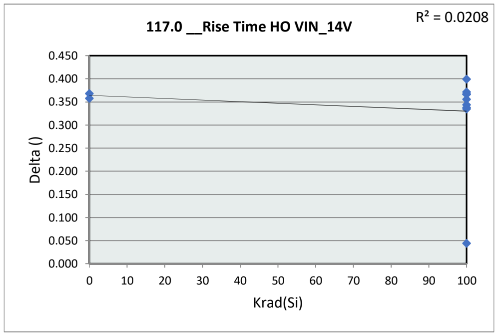


	116.3 __Fall Time LO VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	3.910	3.898
Average	3.910	3.943
Max	3.910	4.188
UL	5.500	5.500

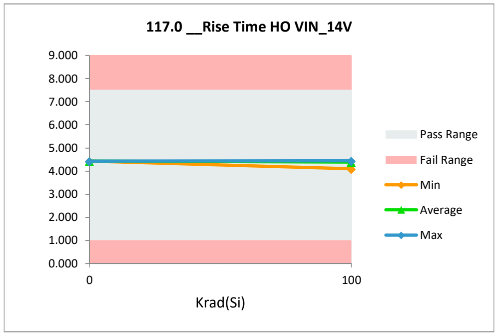


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		117.0 __Rise Time HO VIN_14V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	7.5	7.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.070	4.430	0.359
0	2	4.062	4.432	0.369
100	23	4.054	4.422	0.368
100	24	4.075	4.411	0.336
100	25	4.063	4.436	0.373
100	26	4.068	4.435	0.368
100	27	4.048	4.448	0.400
100	48u	4.089	4.427	0.339
100	49u	4.057	4.103	0.046
100	50u	4.047	4.415	0.368
100	51u	4.083	4.429	0.345
100	52u	4.076	4.433	0.357
	Max	4.089	4.448	0.400
	Average	4.066	4.402	0.336
	Min	4.047	4.103	0.046
	Std Dev	0.013	0.095	0.093

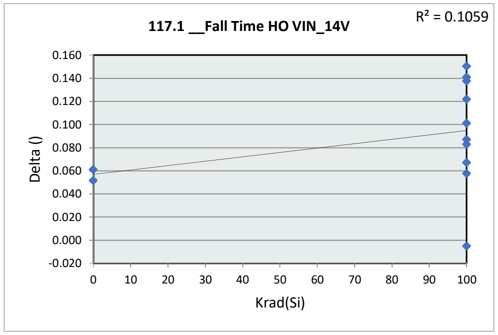


	117.0 __Rise Time HO VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	4.430	4.103
Average	4.431	4.396
Max	4.432	4.448
UL	7.500	7.500

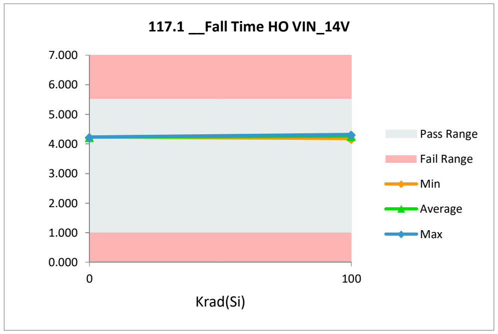


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		117.1 __Fall Time HO VIN_14V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	5.5	5.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.178	4.239	0.062
0	2	4.186	4.238	0.052
100	23	4.184	4.242	0.058
100	24	4.154	4.237	0.083
100	25	4.181	4.269	0.088
100	26	4.175	4.298	0.123
100	27	4.163	4.315	0.151
100	48u	4.185	4.286	0.102
100	49u	4.187	4.183	-0.004
100	50u	4.149	4.287	0.138
100	51u	4.184	4.252	0.068
100	52u	4.182	4.324	0.142
	Max	4.187	4.324	0.151
	Average	4.176	4.264	0.089
	Min	4.149	4.183	-0.004
	Std Dev	0.013	0.040	0.045

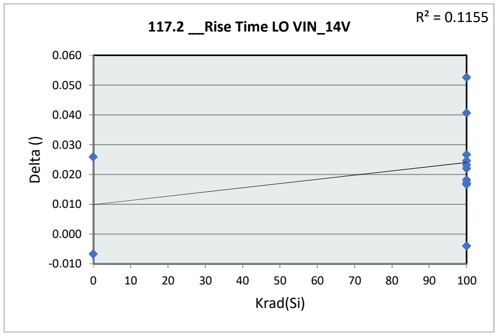


	117.1 __Fall Time HO VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	4.238	4.183
Average	4.239	4.269
Max	4.239	4.324
UL	5.500	5.500

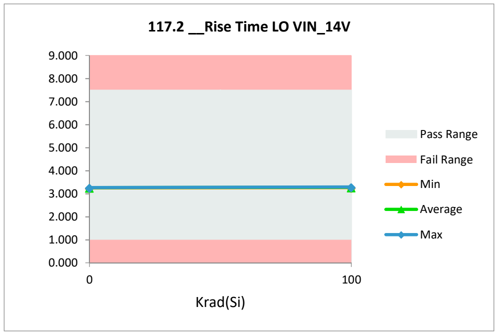


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		117.2 __Rise Time LO VIN_14V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		7.5	7.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.257	3.250	-0.006
0	2	3.244	3.270	0.026
100	23	3.248	3.275	0.027
100	24	3.258	3.283	0.025
100	25	3.259	3.278	0.019
100	26	3.267	3.263	-0.004
100	27	3.255	3.277	0.022
100	48u	3.241	3.265	0.024
100	49u	3.247	3.288	0.041
100	50u	3.251	3.268	0.017
100	51u	3.260	3.277	0.017
100	52u	3.246	3.298	0.053
	Max	3.267	3.298	0.053
	Average	3.253	3.274	0.022
	Min	3.241	3.250	-0.006
	Std Dev	0.008	0.013	0.016

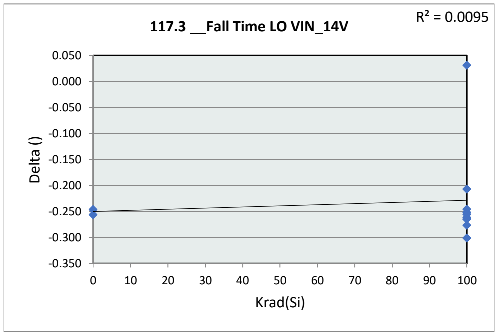


	117.2 __Rise Time LO VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	3.250	3.263
Average	3.260	3.277
Max	3.270	3.298
UL	7.500	7.500

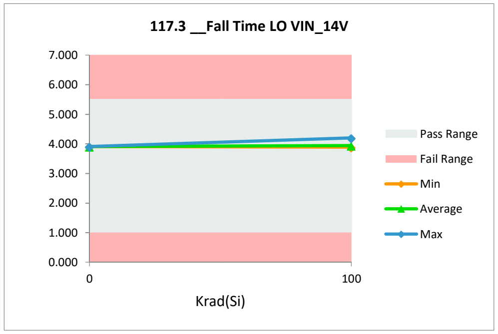


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		117.3 __Fall Time LO VIN_14V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		5.5	5.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.157	3.912	-0.245
0	2	4.169	3.914	-0.255
100	23	4.168	3.893	-0.275
100	24	4.156	3.906	-0.250
100	25	4.161	3.897	-0.263
100	26	4.205	3.905	-0.300
100	27	4.172	3.918	-0.254
100	48u	4.168	3.923	-0.244
100	49u	4.166	4.199	0.033
100	50u	4.151	3.887	-0.264
100	51u	4.184	3.924	-0.260
100	52u	4.165	3.959	-0.206
	Max	4.205	4.199	0.033
	Average	4.168	3.936	-0.232
	Min	4.151	3.887	-0.300
	Std Dev	0.014	0.085	0.086

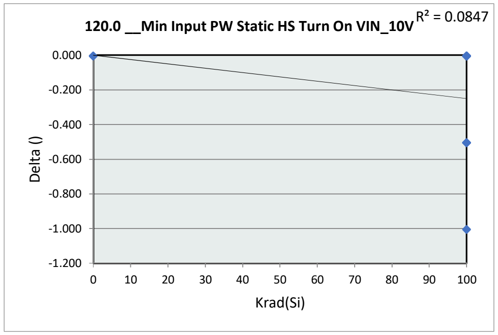


	117.3 __Fall Time LO VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	3.912	3.887
Average	3.913	3.941
Max	3.914	4.199
UL	5.500	5.500

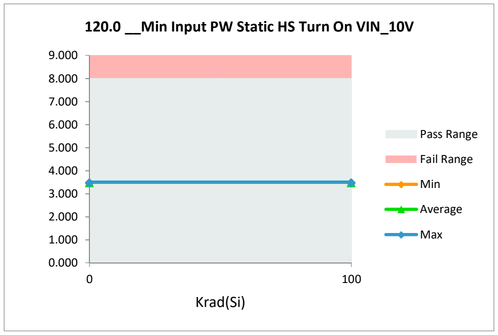


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		120.0 __Min Input PW Static HS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	8	8	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.500	3.500	0.000
0	2	3.500	3.500	0.000
100	23	4.000	3.500	-0.500
100	24	4.500	3.500	-1.000
100	25	4.000	3.500	-0.500
100	26	3.500	3.500	0.000
100	27	4.000	3.500	-0.500
100	48u	3.500	3.500	0.000
100	49u	3.500	3.500	0.000
100	50u	3.500	3.500	0.000
100	51u	3.500	3.500	0.000
100	52u	3.500	3.500	0.000
	Max	4.500	3.500	0.000
	Average	3.708	3.500	-0.208
	Min	3.500	3.500	-1.000
	Std Dev	0.334	0.000	0.334

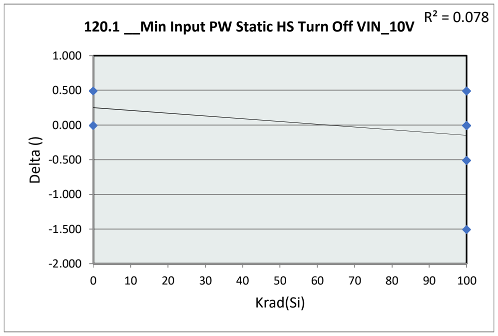


	120.0 __Min Input PW Static HS Turn On VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	3.500	3.500
Average	3.500	3.500
Max	3.500	3.500
UL	8.000	8.000

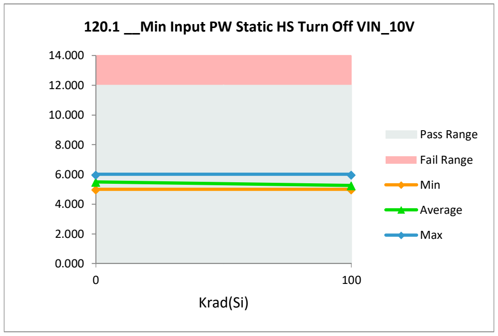


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		120.1 __Min Input PW Static HS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	12	12	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	6.000	6.000	0.000
0	2	4.500	5.000	0.500
100	23	5.500	5.000	-0.500
100	24	6.500	5.000	-1.500
100	25	5.500	5.000	-0.500
100	26	5.500	6.000	0.500
100	27	6.000	6.000	0.000
100	48u	5.000	5.000	0.000
100	49u	5.000	5.000	0.000
100	50u	5.000	5.500	0.500
100	51u	5.000	5.000	0.000
100	52u	5.000	5.000	0.000
	Max	6.500	6.000	0.500
	Average	5.375	5.292	-0.083
	Min	4.500	5.000	-1.500
	Std Dev	0.569	0.450	0.557

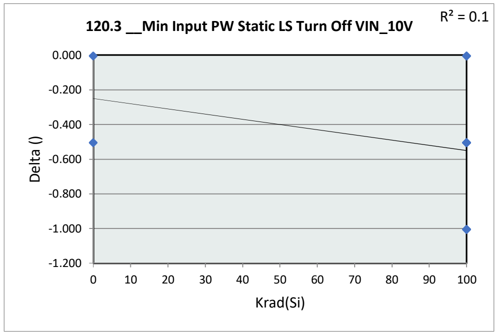


	120.1 __Min Input PW Static HS Turn Off VI	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.000	5.000
Average	5.500	5.250
Max	6.000	6.000
UL	12.000	12.000

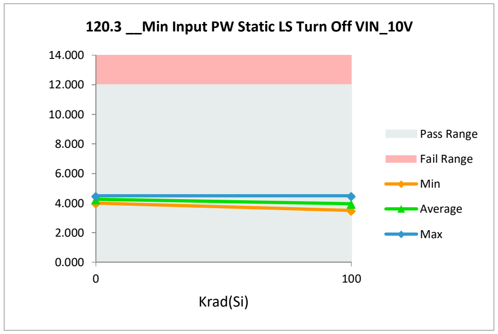


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		120.3 __Min Input PW Static LS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	12	12	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.500	4.000	-0.500
0	2	4.500	4.500	0.000
100	23	4.500	4.500	0.000
100	24	4.500	3.500	-1.000
100	25	4.500	3.500	-1.000
100	26	5.000	4.000	-1.000
100	27	4.500	4.000	-0.500
100	48u	4.000	4.000	0.000
100	49u	4.500	4.000	-0.500
100	50u	4.500	4.000	-0.500
100	51u	4.500	4.000	-0.500
100	52u	4.500	4.000	-0.500
	Max	5.000	4.500	0.000
	Average	4.500	4.000	-0.500
	Min	4.000	3.500	-1.000
	Std Dev	0.213	0.302	0.369



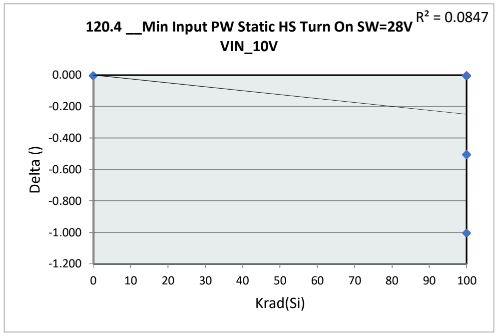
120.3 __Min Input PW Static LS Turn Off VIN		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.000	3.500
Average	4.250	3.950
Max	4.500	4.500
UL	12.000	12.000



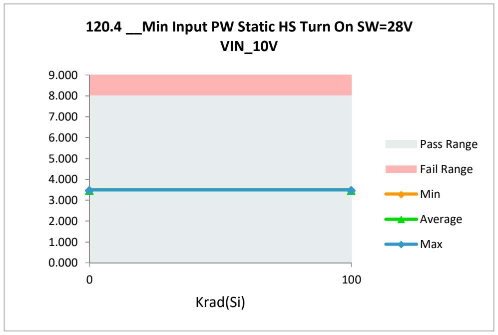
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	120.4 __Min Input PW Static HS	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	8	8
Min Limit	0	0

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.500	3.500	0.000
0	2	3.500	3.500	0.000
100	23	4.000	3.500	-0.500
100	24	4.500	3.500	-1.000
100	25	4.000	3.500	-0.500
100	26	3.500	3.500	0.000
100	27	4.000	3.500	-0.500
100	48u	3.500	3.500	0.000
100	49u	3.500	3.500	0.000
100	50u	3.500	3.500	0.000
100	51u	3.500	3.500	0.000
100	52u	3.500	3.500	0.000
	Max	4.500	3.500	0.000
	Average	3.708	3.500	-0.208
	Min	3.500	3.500	-1.000
	Std Dev	0.334	0.000	0.334

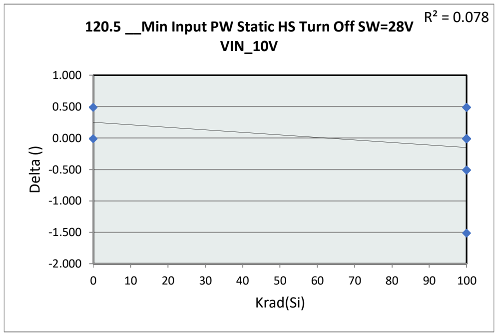


	120.4 __Min Input PW Static HS Turn On SW	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	3.500	3.500
Average	3.500	3.500
Max	3.500	3.500
UL	8.000	8.000

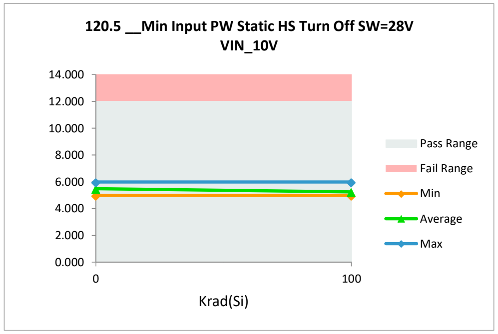


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		120.5 __Min Input PW Static HS		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		12	12	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	6.000	6.000	0.000
0	2	4.500	5.000	0.500
100	23	5.500	5.000	-0.500
100	24	6.500	5.000	-1.500
100	25	5.500	5.000	-0.500
100	26	5.500	6.000	0.500
100	27	6.000	6.000	0.000
100	48u	5.000	5.000	0.000
100	49u	5.000	5.000	0.000
100	50u	5.000	5.500	0.500
100	51u	5.000	5.000	0.000
100	52u	5.000	5.000	0.000
	Max	6.500	6.000	0.500
	Average	5.375	5.292	-0.083
	Min	4.500	5.000	-1.500
	Std Dev	0.569	0.450	0.557

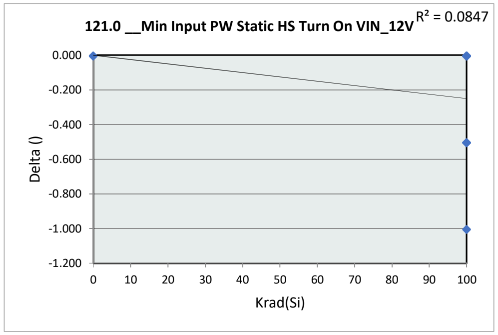


120.5 __Min Input PW Static HS Turn Off SW		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.000	5.000
Average	5.500	5.250
Max	6.000	6.000
UL	12.000	12.000

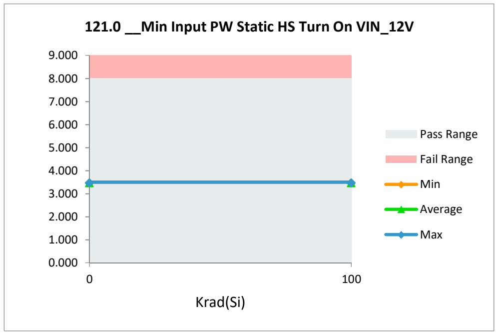


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
		121.0 __Min Input PW Static HS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	8	8	
	Min Limit	0	0	
0	1	3.500	3.500	0.000
0	2	3.500	3.500	0.000
100	23	4.000	3.500	-0.500
100	24	4.500	3.500	-1.000
100	25	4.000	3.500	-0.500
100	26	3.500	3.500	0.000
100	27	4.000	3.500	-0.500
100	48u	3.500	3.500	0.000
100	49u	3.500	3.500	0.000
100	50u	3.500	3.500	0.000
100	51u	3.500	3.500	0.000
100	52u	3.500	3.500	0.000
	Max	4.500	3.500	0.000
	Average	3.708	3.500	-0.208
	Min	3.500	3.500	-1.000
	Std Dev	0.334	0.000	0.334



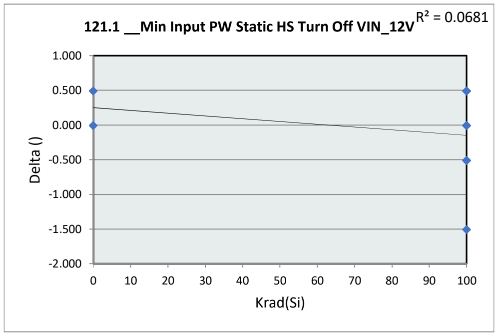
	121.0 __Min Input PW Static HS Turn On VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	3.500	3.500
Average	3.500	3.500
Max	3.500	3.500
UL	8.000	8.000



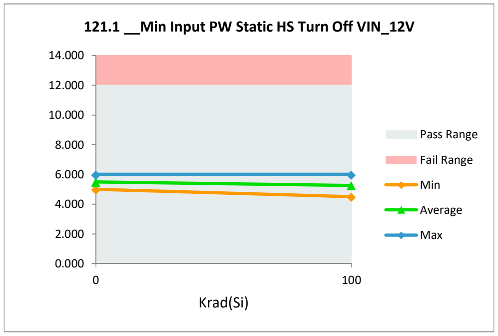
TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

	121.1 __Min Input PW Static HS	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	12	12
Min Limit	0	0

Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	6.000	6.000	0.000
0	2	4.500	5.000	0.500
100	23	5.500	5.000	-0.500
100	24	6.500	5.000	-1.500
100	25	5.500	5.000	-0.500
100	26	5.500	6.000	0.500
100	27	6.000	6.000	0.000
100	48u	5.000	5.500	0.500
100	49u	5.000	4.500	-0.500
100	50u	5.000	5.500	0.500
100	51u	5.000	5.000	0.000
100	52u	5.000	5.000	0.000
	Max	6.500	6.000	0.500
	Average	5.375	5.292	-0.083
	Min	4.500	4.500	-1.500
	Std Dev	0.569	0.498	0.597

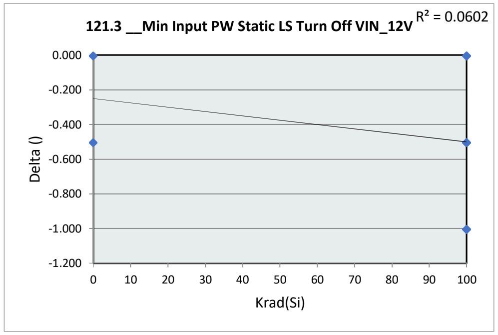


	121.1 __Min Input PW Static HS Turn Off VI	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.000	4.500
Average	5.500	5.250
Max	6.000	6.000
UL	12.000	12.000

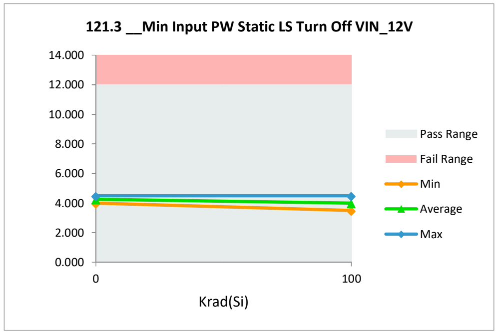


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		121.3 __Min Input PW Static LS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	12	12	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.500	4.000	-0.500
0	2	4.500	4.500	0.000
100	23	4.500	4.500	0.000
100	24	4.500	3.500	-1.000
100	25	4.500	3.500	-1.000
100	26	5.000	4.000	-1.000
100	27	4.500	4.000	-0.500
100	48u	4.000	4.000	0.000
100	49u	4.500	4.500	0.000
100	50u	4.500	4.000	-0.500
100	51u	4.500	4.000	-0.500
100	52u	4.500	4.000	-0.500
	Max	5.000	4.500	0.000
	Average	4.500	4.042	-0.458
	Min	4.000	3.500	-1.000
	Std Dev	0.213	0.334	0.396

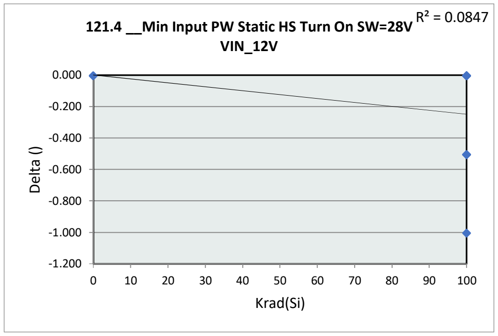


	121.3 __Min Input PW Static LS Turn Off VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.000	3.500
Average	4.250	4.000
Max	4.500	4.500
UL	12.000	12.000

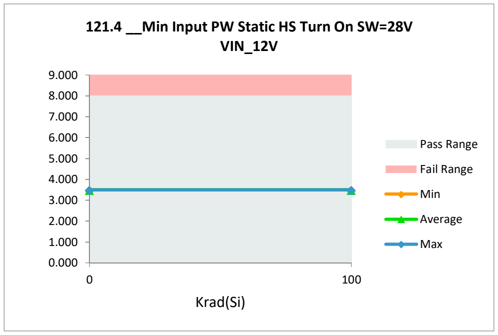


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		121.4 __Min Input PW Static HS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	8	8	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.500	3.500	0.000
0	2	3.500	3.500	0.000
100	23	4.000	3.500	-0.500
100	24	4.500	3.500	-1.000
100	25	4.000	3.500	-0.500
100	26	3.500	3.500	0.000
100	27	4.000	3.500	-0.500
100	48u	3.500	3.500	0.000
100	49u	3.500	3.500	0.000
100	50u	3.500	3.500	0.000
100	51u	3.500	3.500	0.000
100	52u	3.500	3.500	0.000
	Max	4.500	3.500	0.000
	Average	3.708	3.500	-0.208
	Min	3.500	3.500	-1.000
	Std Dev	0.334	0.000	0.334

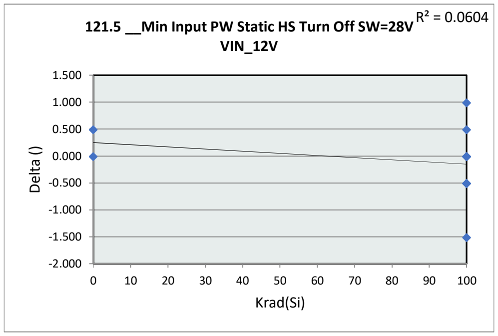


	121.4 __Min Input PW Static HS Turn On SW	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	3.500	3.500
Average	3.500	3.500
Max	3.500	3.500
UL	8.000	8.000

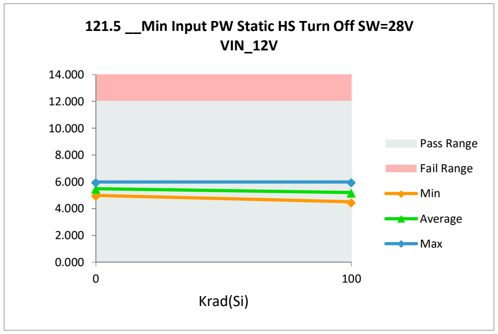


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		121.5 __Min Input PW Static HS		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		12	12	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	6.000	6.000	0.000
0	2	4.500	5.000	0.500
100	23	5.500	5.000	-0.500
100	24	6.500	5.000	-1.500
100	25	5.500	5.000	-0.500
100	26	5.000	6.000	1.000
100	27	6.000	6.000	0.000
100	48u	5.000	5.000	0.000
100	49u	5.000	4.500	-0.500
100	50u	5.000	5.500	0.500
100	51u	5.000	5.000	0.000
100	52u	5.000	5.000	0.000
	Max	6.500	6.000	1.000
	Average	5.333	5.250	-0.083
	Min	4.500	4.500	-1.500
	Std Dev	0.577	0.500	0.634

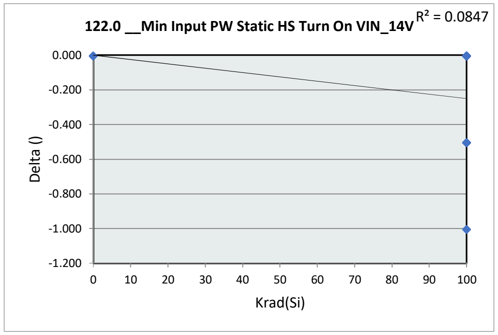


	121.5 __Min Input PW Static HS Turn Off SW	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.000	4.500
Average	5.500	5.200
Max	6.000	6.000
UL	12.000	12.000

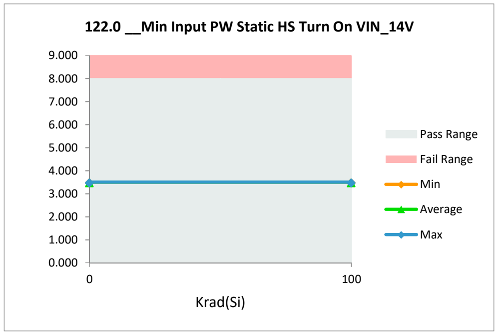


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		122.0 __Min Input PW Static HS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	8	8	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.500	3.500	0.000
0	2	3.500	3.500	0.000
100	23	4.000	3.500	-0.500
100	24	4.500	3.500	-1.000
100	25	4.000	3.500	-0.500
100	26	3.500	3.500	0.000
100	27	4.000	3.500	-0.500
100	48u	3.500	3.500	0.000
100	49u	3.500	3.500	0.000
100	50u	3.500	3.500	0.000
100	51u	3.500	3.500	0.000
100	52u	3.500	3.500	0.000
	Max	4.500	3.500	0.000
	Average	3.708	3.500	-0.208
	Min	3.500	3.500	-1.000
	Std Dev	0.334	0.000	0.334

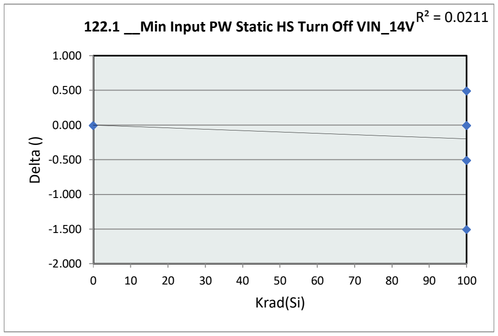


	122.0 __Min Input PW Static HS Turn On VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	3.500	3.500
Average	3.500	3.500
Max	3.500	3.500
UL	8.000	8.000

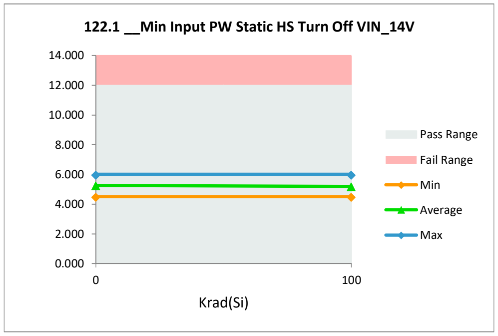


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		122.1 __Min Input PW Static HS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	12	12	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	6.000	6.000	0.000
0	2	4.500	4.500	0.000
100	23	5.500	5.000	-0.500
100	24	6.500	5.000	-1.500
100	25	5.500	5.000	-0.500
100	26	5.500	6.000	0.500
100	27	6.000	6.000	0.000
100	48u	5.000	5.000	0.000
100	49u	5.000	4.500	-0.500
100	50u	5.000	5.500	0.500
100	51u	5.000	5.000	0.000
100	52u	5.000	5.000	0.000
	Max	6.500	6.000	0.500
	Average	5.375	5.208	-0.167
	Min	4.500	4.500	-1.500
	Std Dev	0.569	0.542	0.537

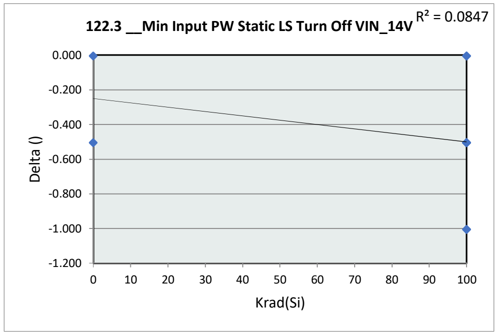


	122.1 __Min Input PW Static HS Turn Off VII	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.500	4.500
Average	5.250	5.200
Max	6.000	6.000
UL	12.000	12.000

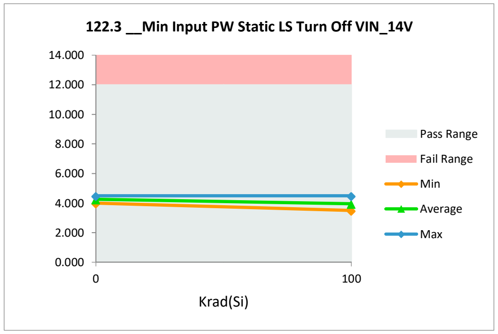


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		122.3 __Min Input PW Static LS		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		12	12	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	4.500	4.000	-0.500
0	2	4.500	4.500	0.000
100	23	4.500	4.000	-0.500
100	24	4.500	3.500	-1.000
100	25	4.500	3.500	-1.000
100	26	4.500	4.000	-0.500
100	27	4.500	4.000	-0.500
100	48u	4.000	4.000	0.000
100	49u	4.500	4.500	0.000
100	50u	4.500	4.000	-0.500
100	51u	4.500	4.000	-0.500
100	52u	4.500	4.000	-0.500
	Max	4.500	4.500	0.000
	Average	4.458	4.000	-0.458
	Min	4.000	3.500	-1.000
	Std Dev	0.144	0.302	0.334

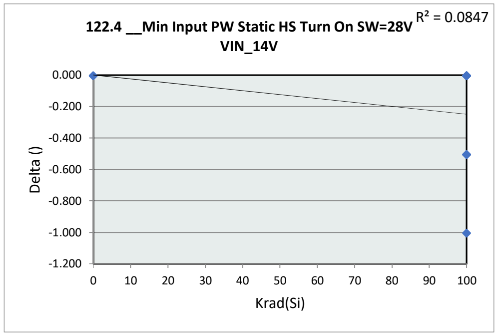


	122.3 __Min Input PW Static LS Turn Off VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.000	3.500
Average	4.250	3.950
Max	4.500	4.500
UL	12.000	12.000

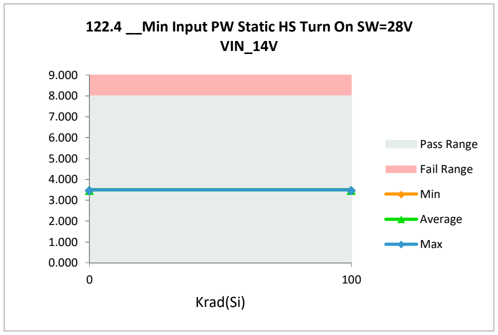


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		122.4 __Min Input PW Static HS		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		8	8	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	3.500	3.500	0.000
0	2	3.500	3.500	0.000
100	23	4.000	3.500	-0.500
100	24	4.500	3.500	-1.000
100	25	4.000	3.500	-0.500
100	26	3.500	3.500	0.000
100	27	4.000	3.500	-0.500
100	48u	3.500	3.500	0.000
100	49u	3.500	3.500	0.000
100	50u	3.500	3.500	0.000
100	51u	3.500	3.500	0.000
100	52u	3.500	3.500	0.000
	Max	4.500	3.500	0.000
	Average	3.708	3.500	-0.208
	Min	3.500	3.500	-1.000
	Std Dev	0.334	0.000	0.334

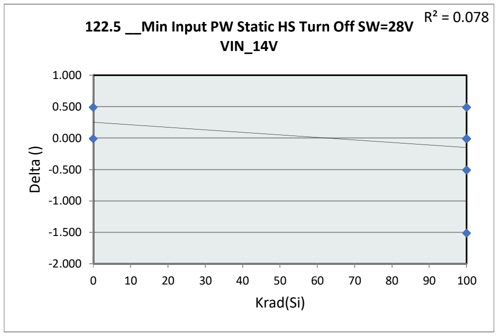


	122.4 __Min Input PW Static HS Turn On SW	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	3.500	3.500
Average	3.500	3.500
Max	3.500	3.500
UL	8.000	8.000

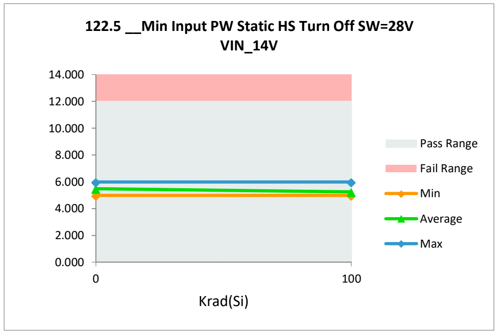


TID HDR Report
5962R2220105PYE (TPS7H6015-SP)

		122.5 __Min Input PW Static HS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	12	12	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6015	Post_6015	Delta
0	1	6.000	6.000	0.000
0	2	4.500	5.000	0.500
100	23	5.500	5.000	-0.500
100	24	6.500	5.000	-1.500
100	25	5.500	5.000	-0.500
100	26	5.500	6.000	0.500
100	27	6.000	6.000	0.000
100	48u	5.000	5.000	0.000
100	49u	5.000	5.000	0.000
100	50u	5.000	5.500	0.500
100	51u	5.000	5.000	0.000
100	52u	5.000	5.000	0.000
	Max	6.500	6.000	0.500
	Average	5.375	5.292	-0.083
	Min	4.500	5.000	-1.500
	Std Dev	0.569	0.450	0.557



	122.5 __Min Input PW Static HS Turn Off SW	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.000	5.000
Average	5.500	5.250
Max	6.000	6.000
UL	12.000	12.000



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES “AS IS” AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI’s products are provided subject to TI’s Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI’s provision of these resources does not expand or otherwise alter TI’s applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265
Copyright © 2025, Texas Instruments Incorporated